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**TEST METHODS FOR TELEMETRY  
SYSTEMS AND SUBSYSTEMS**

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**VOLUME IV**

**TEST METHODS FOR DATA  
MULTIPLEX EQUIPMENT**

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TEST METHODS FOR TELEMETRY SYSTEMS AND SUBSYSTEM, VOLUME IV: TEST METHODS  
FOR DATA MULTIPLEX EQUIPMENT

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New Mexico

DOCUMENT 118-79

TEST METHODS FOR TELEMETRY  
SYSTEMS AND SUBSYSTEMS

VOLUME IV

TEST METHODS FOR DATA MULTIPLEX EQUIPMENT

PREAMBLE

This document provides test methods only. No attempt has been made to establish an accept or reject criteria. Guidance for consistency of test setup and evaluation of results is included. Equipment model numbers have been intentionally omitted. Since step-by-step test equipment operating instructions are not provided, it is anticipated that supplemental test procedures may have to be prepared by the user to augment this document.

TELEMETRY GROUP  
INTER-RANGE INSTRUMENTATION GROUP  
RANGE COMMANDERS COUNCIL

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IV-ii

IV-ia IV-i-a

VOLUME I

END-TO-END TEST METHODS FOR TELEMETRY SYSTEMS

TABLE OF CONTENTS

	<u>PAGE</u>
CHAPTER 1 - SOLAR CALIBRATION. . . . .	I-1-1
1.0 General. . . . .	I-1-1
1.1 Solar Calibration Using Linear Receiver Method . . . . .	I-1-4
1.2 Solar Calibration Using Attenuator Method. . . . .	I-1-9
CHAPTER 2 - TEST METHODS FOR TRANSDUCER-BASED SYSTEM CALIBRATIONS. . . . .	
2.0 General. . . . .	I-2-1
2.1 Measurand End-to-End Calibration of Systems with Resistive Transducers. . . . .	I-2-3
2.2 Measurand Substitution Calibration of Systems with Resistive Transducers. . . . .	I-2-10
2.3 Electrical Substitution Calibration of Systems with Resistive Transducers. . . . .	I-2-10
2.3.1 Voltage Insertion Calibration for Potentiometric Transducers. . . . .	I-2-10
2.3.2 Electrical Substitution Calibration for Resistance Bridges. . . . .	I-2-11
2.4 Measurand End-to-End Calibration of Systems with Piezoelectric Transducers. . . . .	I-2-20
2.5 Measurand Substitution Calibration of Systems with Piezoelectric Transducers. . . . .	I-2-22
2.6 Electrical Substitution Calibration of Systems with Piezoelectric Transducers. . . . .	I-2-22
2.7 Measurand End-to-End Calibration of Systems with Servo Transducers. . . . .	I-2-29
2.8 Measurand Substitution Calibration of Systems with Servo Transducers. . . . .	I-2-29
2.9 Measurand End-to-End Calibration of Systems with Capacitive Transducers . . . . .	I-2-30
2.10 Electrical Substitution Calibration of Systems with Capacitive Transducers . . . . .	I-2-30
2.11 Measurand End-to-End Calibration of Systems with Inductive Transducers. . . . .	I-2-30
2.12 Electrical Substitution Calibration of Systems with Inductive Transducers. . . . .	I-2-31
2.13 Measurand End-to-End Calibration of Systems with Thermoelectric Transducers . . . . .	I-2-34
2.14 Electrical Substitution Calibration of Systems with Thermoelectric Transducers . . . . .	I-2-34

	<u>PAGE</u>
APPENDIXES	
I-A	ALTERNATE SOLAR CALIBRATION TEST METHOD. . . . . I-A-1
I-B	RF SYSTEM TEST APPLICATION NOTES . . . . . I-B-1
I-C	TEST FOR RECEIVER SYSTEM LINEARITY . . . . . I-C-1

LIST OF FIGURES

FIGURE NO.

CHAPTER 1 - SOLAR CALIBRATION

1.1-1	Block Diagram for Linear Receiver Method . . . . .	I-1-5
1.2-1	Block Diagram for Attenuator Method. . . . .	I-1-10

CHAPTER 2 - TEST METHODS FOR TRANSDUCER-BASED SYSTEM CALIBRATION

2.3-1	Voltage Insertion Calibration for Potentiometric Transducers. . . . .	I-2-11
2.3-2	Four-Wire System . . . . .	I-2-12
2.3-3	Six-Wire System. . . . .	I-2-13
2.3-4	Seven-Wire System. . . . .	I-2-14
2.3-5	Eight-Wire System. . . . .	I-2-14
2.3-6	Four-Wire Series System. . . . .	I-2-16
2.3-7	Five-Wire Series System. . . . .	I-2-16
2.3-8	Typical Low-Level Bridge System. . . . .	I-2-18
2.3-9	Shunt Resistor Adapter . . . . .	I-2-19
2.3-10	Oscillograph Frequency Response Display. . . . .	I-2-20
2.3-11	Shunt Resistor Bridge. . . . .	I-2-21
2.6-1	Piezoelectric Crystal Transducer Circuit . . . . .	I-2-23
2.6-2	Transducer Charge Generator Equivalent Circuit . . . . .	I-2-23
2.6-3	Voltage Generator Equivalent Circuit for a Piezoelectric Transducer . . . . .	I-2-23
2.6-4	Charge Generator Equivalent Circuit. . . . .	I-2-24
2.6-5	Response Curve for a High-Pass RC Filter . . . . .	I-2-25
2.6-6	Effect of Low-Frequency Response . . . . .	I-2-26
2.6-7	Acceleration Measuring System Frequency Response . . . . .	I-2-26
2.12-1	Variable Inductance Coil . . . . .	I-2-31
2.12-2	Inductance Transducer Used as a Current Source . . . . .	I-2-32
2.12-3	Basic A.C. Bridge and Shunt Calibration. . . . .	I-2-33
2.12-4	The Use of Inductance Transducers in Tank Circuits of an Oscillator . . . . .	I-2-33

Volume I - End-to-End Test Methods for Telemetry Systems (con.)

FIGURE NO.

PAGE

APPENDIX A - ALTERNATE SOLAR CALIBRATION TEST METHOD

I-A.1 Block Diagram of Antenna-RF Signal Generator Calibration . . . I-A-2

APPENDIX B - RF SYSTEM TEST APPLICATION NOTES

I-B.1 Solar Flux versus Reported Solar Flux Units. . . . . I-B-2  
I-B.2  $G/T_s$  versus Solar Flux . . . . . I-B-3  
I-B.3 System Noise Temperature versus Antenna Gain . . . . . I-B-4  
I-B.4 Test Utilizing Auxiliary Radiators . . . . . I-B-7  
I-B.5 Test Utilizing a Coaxial Switch. . . . . I-B-14

APPENDIX C - TEST FOR RECEIVER SYSTEM LINEARITY

I-C.1 Block Diagram for System Linearity Test. . . . . I-C-2

LIST OF DATA SHEETS

DATA SHEET NO.

CHAPTER 1 - SOLAR CALIBRATION

1.1.1 Solar Calibration Using Linear Receiver Method . . . . . I-1-7  
1.2.1 Solar Calibration Using Attenuator Method. . . . . I-1-11

VOLUME II

TEST METHODS FOR TELEMETRY RF SUBSYSTEMS

TABLE OF CONTENTS

	<u>PAGE</u>
CHAPTER 1 - TEST PROCEDURES FOR TELEMETRY ANTENNA SYSTEMS. . . . .	II-1-1
1.0 General. . . . .	II-1-1
1.1 Pedestal Drive System Velocity and Acceleration. . . . .	II-1-1
1.2 Tracking Error Voltage Gradient. . . . .	II-1-13
1.3 Dynamic Tracking Accuracy. . . . .	II-1-17
1.4 Antenna Boresight Test . . . . .	II-1-21
1.5 Antenna Gain Test. . . . .	II-1-25
1.6 Antenna Response Test. . . . .	II-1-31
CHAPTER 2 - TEST PROCEDURES FOR TELEMETRY RF PREAMPLIFIERS . . . . .	II-2-1
2.0 General. . . . .	II-2-1
2.1 Amplifier Gain Compression . . . . .	II-2-1
2.2 Bandwidth and Small Signal Power Gain. . . . .	II-2-7
2.3 Intermodulation (IM) Products and Intercept Point (IP) . . . . .	II-2-13
2.4 VSWR by Return Loss Method . . . . .	II-2-21
2.5 Noise Figure . . . . .	II-2-27
CHAPTER 3 - TEST PROCEDURES FOR TELEMETRY MULTICOUPLERS. . . . .	II-3-1
3.0 General. . . . .	II-3-1
3.1 Multicoupler Gain Compression. . . . .	II-3-1
3.2 Bandwidth and Small Signal Power Gain. . . . .	II-3-7
3.3 Intermodulation (IM) Products and Intercept Point (IP) . . . . .	II-3-13
3.4 VSWR by Return Loss Method . . . . .	II-3-21
3.5 Noise Figure . . . . .	II-3-27
3.6 Output Isolation . . . . .	II-3-31
CHAPTER 4 - TEST PROCEDURES FOR TELEMETRY RECEIVERS. . . . .	II-4-1
4.0 General. . . . .	II-4-1
4.1 Video Suppression. . . . .	II-4-1
4.2 Noise Figure . . . . .	II-4-7
4.3 IF SNR . . . . .	II-4-11
4.4 AGC Static Test. . . . .	II-4-15
4.5 AGC Dynamic Test - Response to Square Wave . . . . .	II-4-21
4.6 AGC Dynamic Test - Response to Sine Wave . . . . .	II-4-31
4.7 FM Capture Ratio Test. . . . .	II-4-37
4.8 Noise Power Ratio (NPR). . . . .	II-4-43
4.9 Local Oscillator (LO) Radiation Test . . . . .	II-4-51
4.10 Local Oscillator (LO) Stability Test . . . . .	II-4-55
4.11 AFC Correction Factor. . . . .	II-4-63

Volume II - Test Methods for Telemetry RF Subsystems (con.)

	<u>PAGE</u>
CHAPTER 5 - TEST PROCEDURES FOR DIVERSITY COMBINERS. . . . .	II-5-1
5.0 General. . . . .	II-5-1
5.1 Diversity Combiner Static Evaluation with Equal RF Signal Strengths . . . . .	II-5-1
5.2 Diversity Combiner Static Evaluation with Unequal RF Signal Strengths. . . . .	II-5-9
5.3 Diversity Combiner Dynamic Evaluation with In-Phase Fading and Equal RF Signal Strengths . . . . .	II-5-15
5.4 Diversity Combiner Dynamic Evaluation with Periodic In-Phase Fading and Unequal RF Signal Strengths. . . . .	II-5-23
5.5 Diversity Combiner Dynamic Evaluation with Periodic Out-of-Phase Fading and Equal RF Signal Strengths. . . . .	II-5-29
5.6 Diversity Combiner Dynamic Evaluation with Periodic Out-of-Phase Fading and Unequal RF Signal Strengths. . . . .	II-5-33
5.7 Diversity Combiner Break Frequency . . . . .	II-5-39
5.8 Diversity Combiner Evaluation with Random Fading . . . . .	II-5-43
 APPENDIXES	
II-A INTERMODULATION (IM) PRODUCTS AND INTERCEPT POINT (IP) . . . . .	II-A-1
II-B NOISE FIGURE MEASUREMENTS. . . . .	II-B-1

LIST OF FIGURES

FIGURE NO.

CHAPTER 1 - TEST PROCEDURES FOR TELEMETRY ANTENNA SYSTEMS

1.1-1 Velocity and Acceleration . . . . .	II-1-2
1.1-2 Synchro Setup (Method II) . . . . .	II-1-4
1.1-3 Velocity and Acceleration (Method II) . . . . .	II-1-5
1.1-4 Velocity and Acceleration (Method I). . . . .	II-1-8
1.5-1 Antenna Gain. . . . .	II-1-26
1.6-1 Antenna Response. . . . .	II-1-32

CHAPTER 2 - TEST PROCEDURES FOR TELEMETRY RF PREAMPLIFIERS

2.1-1 Test Setup for Measurement of Amplifier Gain Compression. . .	II-2-1
2.1-2 Amplifier Gain Compression. . . . .	II-2-3

Volume II - Test Methods for Telemetry RF Subsystems (con.)

<u>FIGURE NO.</u>		<u>PAGE</u>
2.2-1	Test Setup for Measurement of Bandwidth and Small Signal Power Gain . . . . .	II-2-7
2.2-2	Plot of Power Gain and Bandwidth versus Frequency . . . . .	II-2-9
2.3-1	Test Setup for Determination of Intercept Point . . . . .	II-2-13
2.3-2	Typical Display of Fundamental and 3rd Order Intermodulation Products. . . . .	II-2-15
2.3-3	Graphical Illustration of Intercept Point . . . . .	II-2-16
2.3-4	Spurious Response Nomograph . . . . .	II-2-18
2.4-1	Test Setup for Measurement of Return Loss (VSWR). . . . .	II-2-21
2.5-1	Test Setup for Measurement of Noise Figure. . . . .	II-2-27

CHAPTER 3 - TEST PROCEDURES FOR TELEMETRY MULTICOUPLERS

3.1-1	Test Setup for Measurement of Multicoupler Gain Compression Level . . . . .	II-3-1
3.1-2	Multicoupler Gain Compression . . . . .	II-3-3
3.2-1	Test Setup for Measurement of Bandwidth and Small Signal Power Gain . . . . .	II-3-7
3.2-2	Plot of Power Gain and Bandwidth versus Frequency . . . . .	II-3-9
3.3-1	Test Setup for Determination of Intercept Point . . . . .	II-3-13
3.3-2	Typical Display of Fundamental and 3rd Order Intermodulation Products. . . . .	II-3-15
3.3-3	Graphical Illustration of Intercept Point . . . . .	II-3-16
3.3-4	Spurious Response Nomograph . . . . .	II-3-18
3.4-1	Test Setup for Measurement of Return Loss (VSWR). . . . .	II-3-22
3.5-1	Test Setup for Measurement of Noise Figure. . . . .	II-3-27
3.6-1	Output Isolation. . . . .	II-3-31

CHAPTER 4 - TEST PROCEDURES FOR TELEMETRY RECEIVERS

4.1-1	Sensitivity Test. . . . .	II-4-2
4.1-2	Signal Suppression. . . . .	II-4-4
4.2-1	Noise Figure. . . . .	II-4-8
4.4-1	AGC Static Test . . . . .	II-4-15
4.4-2	AGC Characteristic and IF Level Control . . . . .	II-4-17
4.5-1	AGC Response to Square Wave AM. . . . .	II-4-22
4.6-1	AGC Response to Sine Wave AM. . . . .	II-4-32
4.7-1	Capture Ratio Test. . . . .	II-4-37
4.8-1	NPR Standard Test Setup . . . . .	II-4-44
4.8-2	Curve for Converting NPR and NPRF Data to NPRI. . . . .	II-4-47
4.8-3	Noise Power Ratio . . . . .	II-4-48
4.9-1	Local Oscillator Radiation Test . . . . .	II-4-51
4.10-1	Local Oscillator Stability Test . . . . .	II-4-55
4.11-1	AFC Correction Factor Test. . . . .	II-4-63

Volume II - Test Methods for Telemetry RF Subsystems (con.)

<u>FIGURE NO.</u>	<u>PAGE</u>
 CHAPTER 5 - DIVERSITY COMBINERS	
5.1-1	Static Evaluation Test Setup for Diversity Signal Combiner. . . II-5-2
5.3-1	Dynamic Evaluation Test Setup for Diversity Signal Combiner . . II-5-16
5.3-2	Diversity Signal Simulator. . . . . II-5-17
5.3-3	Phase Shifter Modulation and Receiver AGC Voltage . . . . . II-5-19
 APPENDIX A - INTERMODULATION (IM) PRODUCTS AND INTERCEPT POINT (IP)	
II-A.1	Illustration of Spectrum for Two Fundamental Frequencies f <sub>1</sub> and f <sub>2</sub> with 2nd and 3rd Order Responses. . . . . II-A-4
II-A.2	Graphical Representation of Intercept Point . . . . . II-A-5
 APPENDIX B - NOISE FIGURE MEASUREMENTS	
II-B.1	(No title). . . . . II-B-3
II-B.2	(No title). . . . . II-B-3
II-B.3	(No title). . . . . II-B-6
II-B.4	(No title). . . . . II-B-6

LIST OF TABLES

<u>TABLE NO.</u>	
 CHAPTER 2 - TEST PROCEDURES FOR TELEMETRY RF PREAMPLIFIERS	
2-4-1	Return Loss to Equivalent VSWR. . . . . II-2-23
 CHAPTER 3 - TEST PROCEDURES FOR TELEMETRY MULTICOUPLERS	
3-4-1	Return Loss to Equivalent VSWR. . . . . II-3-24

Volume II - Test Methods for Telemetry RF Subsystems (con.)

LIST OF DATA SHEETS

<u>DATA SHEET NO.</u>		<u>PAGE</u>
CHAPTER 1 - TEST PROCEDURES FOR TELEMETRY ANTENNA SYSTEMS		
1.1.1	Velocity and Acceleration . . . . .	II-1-11
1.2.1	Tracking Error Voltage Gradient . . . . .	II-1-15
1.3.1	Dynamic Tracking Accuracy . . . . .	II-1-19
1.4.1	Antenna Boresight Test. . . . .	II-1-23
1.5.1	Antenna Gain Test . . . . .	II-1-29
CHAPTER 2 - TEST PROCEDURES FOR TELEMETRY RF PREAMPLIFIERS		
2.1.1	Amplifier Gain Compression. . . . .	II-2-5
2.2.1	Bandwidth and Small Signal Power Gain Including Temperature and Supply Voltage Variations . . . . .	II-2-11
2.3.1	Intermodulation Products and Intercept Point. . . . .	II-2-19
2.4.1	VSWR by Return Loss Method Including Temperature Variations. . . . .	II-2-25
2.5.1	Noise Figure. . . . .	II-2-29
CHAPTER 3 - TEST PROCEDURES FOR TELEMETRY MULTICOUPLERS		
3.1.1	Multicoupler Gain Compression . . . . .	II-3-5
3.2.1	Bandwidth and Small Signal Power Gain Including Temperature and Supply Voltage Variations . . . . .	II-3-11
3.3.1	Intermodulation Products and Intercept Point. . . . .	II-3-19
3.4.1	VSWR by Return Loss Method Including Temperature Variations. . . . .	II-3-25
3.5.1	Noise Figure. . . . .	II-3-29
3.6.1	Output Isolation. . . . .	II-3-33
CHAPTER 4 - TEST PROCEDURES FOR TELEMETRY RECEIVERS		
4.1.1	Video Suppression . . . . .	II-4-5
4.2.1	Noise Figure. . . . .	II-4-9
4.3.1	IF SNR. . . . .	II-4-13
4.4.1	AGC Static Test . . . . .	II-4-19
4.5.1	AGC Dynamic Test - Response to Square Wave. . . . .	II-4-27
4.6.1	AGC Dynamic Test - Response to Sine Wave. . . . .	II-4-35
4.7.1	FM Capture Ratio Test . . . . .	II-4-41
4.8.1	Noise Power Ratio . . . . .	II-4-49
4.9.1	Local Oscillator (LO) Radiation Test. . . . .	II-4-53
4.10.1	Local Oscillator (LO) Stability Test (Crystal Mode) . . . . .	II-4-59
4.10.2	Local Oscillator (LO) Stability Test (VFO Mode) . . . . .	II-4-61
4.13.1	AFC Correction Factor . . . . .	II-4-65
CHAPTER 5 - DIVERSITY COMBINERS		
5.1.1	STATIC, Equal RF Signal Strength. . . . .	II-5-7
5.2.1	STATIC, Unequal RF Signal Strength. . . . .	II-5-11

Volume II - Test Methods for Telemetry RF Subsystems (con.)

<u>DATA SHEET NO.</u>		<u>PAGE</u>
5.2.2	STATIC, Unequal RF Signal Strength. . . . .	II-5-13
5.3.1	DYNAMIC, Equal RF Signal Strength (In-Phase Fading) . . . . .	II-5-21
5.4.1	DYNAMIC, Equal RF Signal Strength (In-Phase Fading) . . . . .	II-5-25
5.4.2	DYNAMIC, Unequal RF Signal Strength (In-Phase Fading) . . . . .	II-5-27
5.5.1	DYNAMIC, Equal RF Signal Strength (Out-of-Phase Fading, 180°) . . . . .	II-5-31
5.6.1	DYNAMIC, Unequal RF Signal Strength (Out-of-Phase Fading, 180°) . . . . .	II-5-35
5.6.2	DYNAMIC, Unequal RF Signal Strength (Out-of-Phase Fading, 180°) . . . . .	II-5-37
5.7.1	Dynamic, Break Frequency. . . . .	II-5-41

# VOLUME III

## TEST METHODS FOR RECORDER/REPRODUCER SYSTEMS AND MAGNETIC TAPE

### TABLE OF CONTENTS

	<u>PAGE</u>
CHAPTER 1 - HEAD TESTS . . . . .	III-1-3
1.0    General. . . . .	III-1-3
1.1    Head Polarity Tests. . . . .	III-1-3
1.2    Record Head-Stack Azimuth Alignment. . . . .	III-1-5
1.3    Reproduce Head-Stack Azimuth Alignment . . . . .	III-1-7
CHAPTER 2 - TAPE SPEED TESTS . . . . .	III-2-1
2.0    General. . . . .	III-2-1
2.1    Tape Speed - Laboratory Use - Method I . . . . .	III-2-2
2.2    Tape Speed - General and Field Use - Method II . . . . .	III-2-6
CHAPTER 3 - SPEED VARIATION AND TIMING ERROR TESTS . . . . .	III-3-1
3.0    General. . . . .	III-3-1
3.1    Flutter Measurement Test . . . . .	III-3-1
3.2    Time Base Error (TBE) Test . . . . .	III-3-7
3.3    Pulse-to-Pulse Jitter Test . . . . .	III-3-9
3.4    Interchannel Time-Displacement Error (ITDE) Test . . . . .	III-3-11
CHAPTER 4 - DIRECT RECORD SYSTEMS TESTS. . . . .	III-4-1
4.0    General. . . . .	III-4-1
4.1    Bias and Record Level Tests. . . . .	III-4-1
4.2    Frequency Response (Direct Recording) Test . . . . .	III-4-2
4.3    SNR Test . . . . .	III-4-4
4.4    Intermodulation (IM) Distortion Test . . . . .	III-4-5
4.5    Crosstalk Test . . . . .	III-4-7
4.6    Bias Leakage Test. . . . .	III-4-8
4.7    Multispeed Reproduce Transfer Level Test . . . . .	III-4-9
4.8    Record Transfer Characteristic Test. . . . .	III-4-10
4.9    Group Delay Variation and Transient Response Tests . . . . .	III-4-11
4.9.1    Group Delay Variation Test . . . . .	III-4-11
4.9.2    Transient Response Test. . . . .	III-4-13
CHAPTER 5 - FM SYSTEMS TESTS . . . . .	III-5-1
5.0    General. . . . .	III-5-1
5.1    Deviation, Center Frequency and Polarity Tests . . . . .	III-5-1
5.2    Frequency Response Test. . . . .	III-5-3
5.3    SNR Test . . . . .	III-5-3

	<u>PAGE</u>
CHAPTER 5 - FM SYSTEMS TEST (con.)	
5.4	Distortion Test . . . . . III-5-4
5.5	Spurious Component Test . . . . . III-5-5
5.6	D.C. Linearity Tests. . . . . III-5-5
5.7	D.C. Drift at Center Frequency Test . . . . . III-5-7
5.8	Multispeed Reproduce Transfer Levels Test . . . . . III-5-9
5.9	Group Delay Variation and Transient Response Test . . . . . III-5-9
APPENDIXES	
III-A	APPLICATION NOTES FOR MAGNETIC TAPE RECORDER/ REPRODUCER TESTING. . . . . III-A-1
III-B	MAGNETIC TAPE TEST PROCEDURES . . . . . III-B-1

LIST OF FIGURES

FIGURE NO.

CHAPTER 1 - HEAD TESTS

1.1-1	Typical Waveform Obtained from Head Polarity Test . . . . . III-1-4
1.2-1	Lissajous Oscilloscope Patterns . . . . . III-1-6

CHAPTER 2 - TAPE SPEED TESTS

2.1-1	Speed Test - Tape Preparation . . . . . III-2-4
2.1-2	Tape Speed - Method I . . . . . III-2-5

CHAPTER 3 - SPEED VARIATION AND TIMING ERROR TESTS

3.1-1	Flutter Measurement . . . . . III-3-4
3.1-2	Block Diagram, Level Detector for Digitized Flutter Measurement . . . . . III-3-5
3.2-1	TBE Measurement . . . . . III-3-8
3.3-1	Jitter Measurement. . . . . III-3-10
3.4-1	ITDE Measurement. . . . . III-3-13

CHAPTER 4 - DIRECT RECORD SYSTEMS TESTS

4.1-1	Frequency Response and Signal-to-Noise Ratio. . . . . III-4-3
4.4-1	Intermodulation Distortion Test . . . . . III-4-6
4.9.1-1	Group Delay Variation Test Procedure for Wideband Recorders . . III-4-14
4.9.2-1	Waveform Parameters for Transient Response Measurement. . . . . III-4-16

<u>FIGURE NO.</u>	<u>PAGE</u>
CHAPTER 5 - FM SYSTEMS TEST	
5.1-1	FM System Test Equipment Setup. . . . . III-5-2
5.6-1	D.C. Linearity Curves . . . . . III-5-8
APPENDIX A - MAGNETIC TAPE TEST PROCEDURES	
III-A.1	Bit Error Rate as a Function of Untracked Gaussian Time Base Error . . . . . III-A-5
III-A.2	Approximate Phase Error Transfer Function . . . . . III-A-6
III-A.3	Measured Time Base Error Spectrum . . . . . III-A-7
III-A.4	Typical 7-Track Equipment Configuration for Absolute Tape Speed Measurement. . . . . III-A-14
III-A.5	Flutter Spectrum Measurement Setup. . . . . III-A-16
III-A.6	Frequency Response Setup. . . . . III-A-17
III-A.7	NPR Test Setup. . . . . III-A-18
APPENDIX B - MAGNETIC TAPE TEST PROCEDURES	
50	Durability Test Analysis. . . . . III-B-7
51	Output Uniformity Test Analysis . . . . . III-B-8
52	Response Curves . . . . . III-B-18

LIST OF TABLES

<u>TABLE NO.</u>	
CHAPTER 3 - SPEED VARIATION AND TIMING ERROR TESTS	
3-1-1	Flutter Band-Pass Filter Characteristics. . . . . III-3-2
CHAPTER 4 - DIRECT RECORD SYSTEMS TESTS	
4-4-1	Intermodulation Test Frequencies. . . . . III-4-7
APPENDIX A - APPLICATION NOTES FOR MAGNETIC TAPE RECORDER/ REPRODUCER TESTING	
III-A-I	Speed Test Record Frequency . . . . . III-A-11
APPENDIX B - MAGNETIC TAPE TEST PROCEDURES	
6	Physical Requirements . . . . . III-B-11
7	Measurement Wavelengths . . . . . III-B-19

VOLUME IV

TEST METHODS FOR DATA MULTIPLEX EQUIPMENT

TABLE OF CONTENTS

	<u>PAGE</u>
CHAPTER 1 - FREQUENCY DIVISION MULTIPLEX (FDM) TEST PROCEDURES . . . . .	IV-1-1
1.0 General. . . . .	IV-1-1
1.1 Noise Power Ratio (NPR) Test . . . . .	IV-1-1
CHAPTER 2 - TIME DIVISION MULTIPLEX (TDM) SYSTEMS. . . . .	IV-2-1
2.0 General. . . . .	IV-2-1
2.1 Pulse Code Modulation (PCM) Testing. . . . .	IV-2-1
2.1.1 Bit Error Probability (BEP) Tests. . . . .	IV-2-1
2.1.2 Other PCM System Tests . . . . .	IV-2-11
2.2 Pulse Amplitude Modulation (PAM) Testing . . . . .	IV-2-11
CHAPTER 3 - SUBCARRIER OSCILLATORS . . . . .	
3.0 General. . . . .	IV-3-1
3.1 Control Range(s) . . . . .	IV-3-5
3.2 Linearity. . . . .	IV-3-9
3.3 Amplitude Modulation (AM). . . . .	IV-3-13
3.4 Output Distortion. . . . .	IV-3-17
3.5 Effect of Source Impedance . . . . .	IV-3-21
3.6 Effect of Grounding Input (Differential-Input Models Only) . . . . .	IV-3-25
3.7 Effect of Output Loading . . . . .	IV-3-29
3.8 Modulation Feedthrough . . . . .	IV-3-33
3.9 Long-Term Stability versus Time. . . . .	IV-3-37
3.10 Effect of Supply Voltage Variation and Ripple. . . . .	IV-3-41
3.11 Common-Mode Rejection (For Differential-Input Models Only) . . . . .	IV-3-45
3.12 Stability versus Temperature . . . . .	IV-3-49
3.13 Effect of Vibration. . . . .	IV-3-53
CHAPTER 4 - BIT SYNCHRONIZERS, . . . . .	IV-4-1
4.0 General. . . . .	IV-4-1
4.0.1 Standard Test Conditions for Testing with Gaussian Noise . . . . .	IV-4-1
4.0.2 Standard Test Conditions for PCM/FM Testing. . . . .	IV-4-4
4.1 Part I. Testing with Gaussian Noise . . . . .	IV-4-5
4.1.1 PCM Test Set Calibration . . . . .	IV-4-5

CHAPTER 4 - BIT SYNCHRONIZERS (con.)		<u>PAGE</u>
4.1.2	Bit Error Probability (BEP) Test . . . . .	IV-4-12
4.1.3	Bit Slippage Probability (BSP) Test. . . . .	IV-4-21
4.1.4	Acquisition Test . . . . .	IV-4-31
4.1.5	Jitter Test. . . . .	IV-4-45
4.1.6	Bit Stream Base-Line Wander and AM Test. . . . .	IV-4-57
4.2	Part II. PCM/FM Testing . . . . .	IV-4-77
4.2.1	Test Setup Calibration for Predetection SNR. . . . .	IV-4-77
4.2.2	Frequency Modulation (FM) Sensitivity of the RF Signal Generator . . . . .	IV-4-80
4.2.3	Bit Synchronizer Tests . . . . .	IV-4-82

APPENDIXES:

IV-A	THE SPECTRUM OF AN NRZ-PN SEQUENCE . . . . .	IV-A-1
IV-B	CALCULATION OF BIT ERROR MEASUREMENT INTERVALS <sup>AND</sup> . . . . .	IV-B-1
IV-C	DEFINITIONS AND SUGGESTED CIRCUITS FOR BIT SYNCHRONIZER TESTING . . . . .	IV-C-1

LIST OF FIGURES

FIGURE NO.

CHAPTER 1 - FREQUENCY DIVISION MULTIPLEX (FDM) TEST PROCEDURES

1.1-1	Block Diagram of Frequency Division System Test . . . . .	IV-1-2
1.1-2	NPR Test. . . . .	IV-1-3
1.1-3 a.	Example of NPR Test - Flat Taper. . . . .	IV-1-5
1.1-3 b.	Example of NPR Test - 6 dB/Octave Preemphasis . . . . .	IV-1-5
1.1-4	Noise Power Ratio versus Notch Frequency. . . . .	IV-1-6

CHAPTER 2 - TIME DIVISION MULTIPLEX (TDM) SYSTEMS

2.1.1.1-1	Bit Error Probability versus Power Flux Density . . . . .	IV-2-3
2.1.1.2-1	PCM Simulator Method (Real Time). . . . .	IV-2-5
2.1.1.2-2	PCM Simulator Method (Post Time). . . . .	IV-2-6
2.1.1.3-1	Noncoherent PN-PCM Synchronizer . . . . .	IV-2-7
2.1.1.3-2	Autocorrelation Method. . . . .	IV-2-8

<u>FIGURE NO.</u>		<u>PAGE</u>
CHAPTER 3 - SUBCARRIER OSCILLATORS		
3.1-1	Control Range(s) . . . . .	IV-3-5
3.2-1	Linearity Measurement . . . . .	IV-3-9
3.3-1	Amplitude Modulation . . . . .	IV-3-13
3.4-1	Output Distortion . . . . .	IV-3-17
3.5-1	Effect of Source Impedance . . . . .	IV-3-21
3.6-1	Effect of Grounding Input . . . . .	IV-3-25
3.7-1	Effect of Output Loading . . . . .	IV-3-29
3.8-1	Modulation Feedthrough . . . . .	IV-3-33
3.9-1	Stability versus Time . . . . .	IV-3-37
3.10-1	Effect of Supply Voltage Variation and Ripple . . . . .	IV-3-41
3.11-1	Common-Mode Rejection . . . . .	IV-3-45
3.12-1	Stability versus Temperature . . . . .	IV-3-49
3.13-1	Effect of Vibration . . . . .	IV-3-53
CHAPTER 4 - BIT SYNCHRONIZERS		
4.0-1	PCM Test Set . . . . .	IV-4-2
4.0.2-1	Test Setup Using Predetection Carrier Frequencies . . . . .	IV-4-6
4.0.2-2	Test Setup Using Signal Generator and Receiver . . . . .	IV-4-7
4.1.1-1	Calibration of PCM Test Set with Internal Noise Attenuator . . . . .	IV-4-9
4.1.1-2	SNR Calibration for Case in which the Noise Attenuator and Summing Amplifier are External to the PCM Test Set . . . . .	IV-4-11
4.1.2-1	Bit Error Probability Test Setup . . . . .	IV-4-13
4.1.2-2	Bit Error Probability Test Setup for the Case in which the Noise Attenuator and Summing Amplifier are External to the PCM Test Set . . . . .	IV-4-14
4.1.2-3	Sample of Data Sheet 4.1.2.1 . . . . .	IV-4-16
4.1.2-4	Sample Data Plot Presentation of Data Sheet 4.1.2.1 . . . . .	IV-4-17
4.1.3-1	Bit Slippage Probability Test Setup for Procedure 1 . . . . .	IV-4-22
4.1.3-2	Bit Slippage Probability Test Setup for Procedure 2 . . . . .	IV-4-24
4.1.3-3	Sample of Data Sheet 4.1.3.1 . . . . .	IV-4-26
4.1.3-4	Sample Plot Presentation of Data Sheet 4.1.3.1 . . . . .	IV-4-27
4.1.4-1	Acquisition Test Setup for Procedure 1 . . . . .	IV-4-32
4.1.4-2	Acquisition Test Setup for Procedure 2 . . . . .	IV-4-34
4.1.4-3	Sample of Data Sheet 4.1.4.1 . . . . .	IV-4-36
4.1.4-4	Sample of Data Sheet 4.1.4.2 . . . . .	IV-4-37
4.1.4-5	Sample Plot Presentation of Data Sheet 4.1.4.1 . . . . .	IV-4-38
4.1.4-6	Sample Plot Presentation of Data Sheet 4.1.4.2 . . . . .	IV-4-39
4.1.5-1	Jitter Test Setup Using PCM Test Set (Method I) . . . . .	IV-4-46
4.1.5-2	Jitter Test Setup for the Case in which the Noise Attenuator and Summing Amplifier are External to the PCM Test Set (Method II) . . . . .	IV-4-47
4.1.5-3	Bit Rate Jitter (Methods) . . . . .	IV-4-49
4.1.5-4	Sample of Data Sheet 4.1.5.1 . . . . .	IV-4-52
4.1.5-5	Sample Plot Presentation of Data Sheet 4.1.5.1 . . . . .	IV-4-53

<u>FIGURE NO.</u>		<u>PAGE</u>
4.1.6-1	Bit Stream Base-Line Wander and AM Test Setup with PCM Test Set. . . . .	IV-4-58
4.1.6-2	Bit Stream Base-Line Wander and AM Test Setup for the Case in which the Noise Attenuator and Summing Amplifier are External to the PCM Test Set. . . . .	IV-4-59
4.1.6-3	Sample of Data Sheet 4.1.6.1. . . . .	IV-4-61
4.1.6-4	Sample of Data Sheet 4.1.6.2. . . . .	IV-4-62
4.1.6-5	Sample of Data Sheet 4.1.6.3. . . . .	IV-4-63
4.1.6-6	Sample of Data Sheet 4.1.6.4. . . . .	IV-4-64
4.1.6-7	Sample Plot Presentation of Data Sheet 4.1.6.1. . . . .	IV-4-65
4.1.6-8	Sample Plot Presentation of Data Sheet 4.1.6.2. . . . .	IV-4-66
4.1.6-9	Sample Plot Presentation of Data Sheet 4.1.6.3. . . . .	IV-4-67
4.1.6-10	Sample Plot Presentation of Data Sheet 4.1.6.4. . . . .	IV-4-68
4.2.2-1	Test Setup for Frequency Modulation Sensitivity Calibration . .	IV-4-81
4.2.3-1	Sample of Data Sheet 4.2.3.1. . . . .	IV-4-83
4.2.3-2	Sample Plot Presentation of Data Sheet 4.2.3.1. . . . .	IV-4-84

APPENDIX A - THE SPECTRUM OF AN NRZ-PN SEQUENCE

IV-A.1	Random PCM Power Spectra. . . . .	IV-A-2
--------	-----------------------------------	--------

APPENDIX C - DEFINITIONS AND SUGGESTED CIRCUITS FOR BIT SYNCHRONIZER TESTING

IV-C.1	PCM Data Delay and PCM Gate . . . . .	IV-C-2
IV-C.2	Illustrations of Procedure 2 of the Acquisition Test. . . . .	IV-C-3
IV-C.3	Suggested Circuit for Amplitude Modulator . . . . .	IV-C-5
IV-C.4	Jitter Noise Shaping Circuit. . . . .	IV-C-6

LIST OF DATA SHEETS

DATA SHEET NO.

CHAPTER 3 - SUBCARRIER OSCILLATORS

3.0.1	SCO Performance Evaluation. . . . .	IV-3-3
3.1.1	Control Range . . . . .	IV-3-7
3.2.1	Linearity. . . . .	IV-3-11
3.3.1	Amplitude Modulation. . . . .	IV-3-15
3.4.1	Output Distortion . . . . .	IV-3-19
3.5.1	Effect of Source Impedance. . . . .	IV-3-23

Volume IV - Test Methods for Data Multiplex Equipment (con.)

<u>DATA SHEET NO.</u>	<u>PAGE</u>
3.6.1	Effect of Grounding Input . . . . . IV-3-27
3.7.1	Output Loading. . . . . IV-3-31
3.8.1	Modulation Feedthrough. . . . . IV-3-35
3.9.1	Stability versus Time . . . . . IV-3-39
3.10.1	Effect of Supply Voltage Variation. . . . . IV-3-43
3.11.1	Common-Mode Rejection . . . . . IV-3-47
3.12.1	Stability versus Temperature. . . . . IV-3-51
3.13.1	Effect of Vibration . . . . . IV-3-55
 CHAPTER 4 - BIT SYNCHRONIZERS	
4.1.2.1	Bit Error Probability Test. . . . . IV-4-19
4.1.3.1	Bit Slippage Probability Test . . . . . IV-4-29
4.1.4.1	Acquisition Test. . . . . IV-4-41
4.1.4.2	Acquisition Test (with Bit Rate Offset) . . . . . IV-4-43
4.1.5.1	Jitter Test. . . . . IV-4-55
4.1.6.1	Bit Error Probability Test with Bit Stream Amplitude Modulated . . . . . IV-4-69
4.1.6.2	Bit Error Probability Test with Base-Line Wander Added to Bit Stream . . . . . IV-4-71
4.1.6.3	Bit Error Probability Test with Base-Line Wander Added to Amplitude Modulated Bit Stream . . . . . IV-4-73
4.1.6.4	Bit Error Probability Test with AM Plus Base-Line Wander Plus Jitter. . . . . IV-4-75
4.2.3.1	Bit Synchronizer Tests. . . . . IV-4-85

## Chapter 1

### FREQUENCY DIVISION MULTIPLEX (FDM) TEST PROCEDURES

#### 1.0 General

The following test evaluates system performance characteristics. The end product of the frequency division multiplex (FDM) test is a plot or tabulation of  $\frac{S+N}{N}$  ratios vs. the equivalent received power flux ( $J_a$ ) at the surface of the receiving antenna for selected notch frequencies. It is assumed that prior to conducting the FDM system test, the prerequisite tests for determining  $J_a$  have been completed.

#### 1.1 Noise Power Ratio (NPR) Test

1.1.1 Purpose - This test determines the ratio of noise in the test channel when all channels are loaded with white noise, to noise in the test channel when all channels, except the test channel, are fully noise loaded.

#### 1.1.2 Test Equipment:

- Noise source
- Noise receiver
- Band reject filters
- Band-pass filters

#### 1.1.3 Test Method:

1.1.3.1 Setup - Connect the test equipment as shown in figure 1.1-1 to apply the general NPR procedure illustrated in figure 1.1-2.

1.1.3.2 Conditions - The test equipment used and test conditions employed should meet the following criteria:

1.1.3.2.1 The notch frequencies shall include 14, 34, 70, 105, 152, and 185 kHz. The capability shall be provided for additional notches at higher and lower notch frequencies as required.

1.1.3.2.2 Base-band frequencies shall include 12-108 kHz, 12-156 kHz and 12-204 kHz.

1.1.3.2.3 The notch filter shall be down at least 70 dB over a bandwidth of at least 3 kHz. The change in power between notch in and notch out shall be less than 1 dB for all base bands listed in subparagraph 1.1.3.2.2.

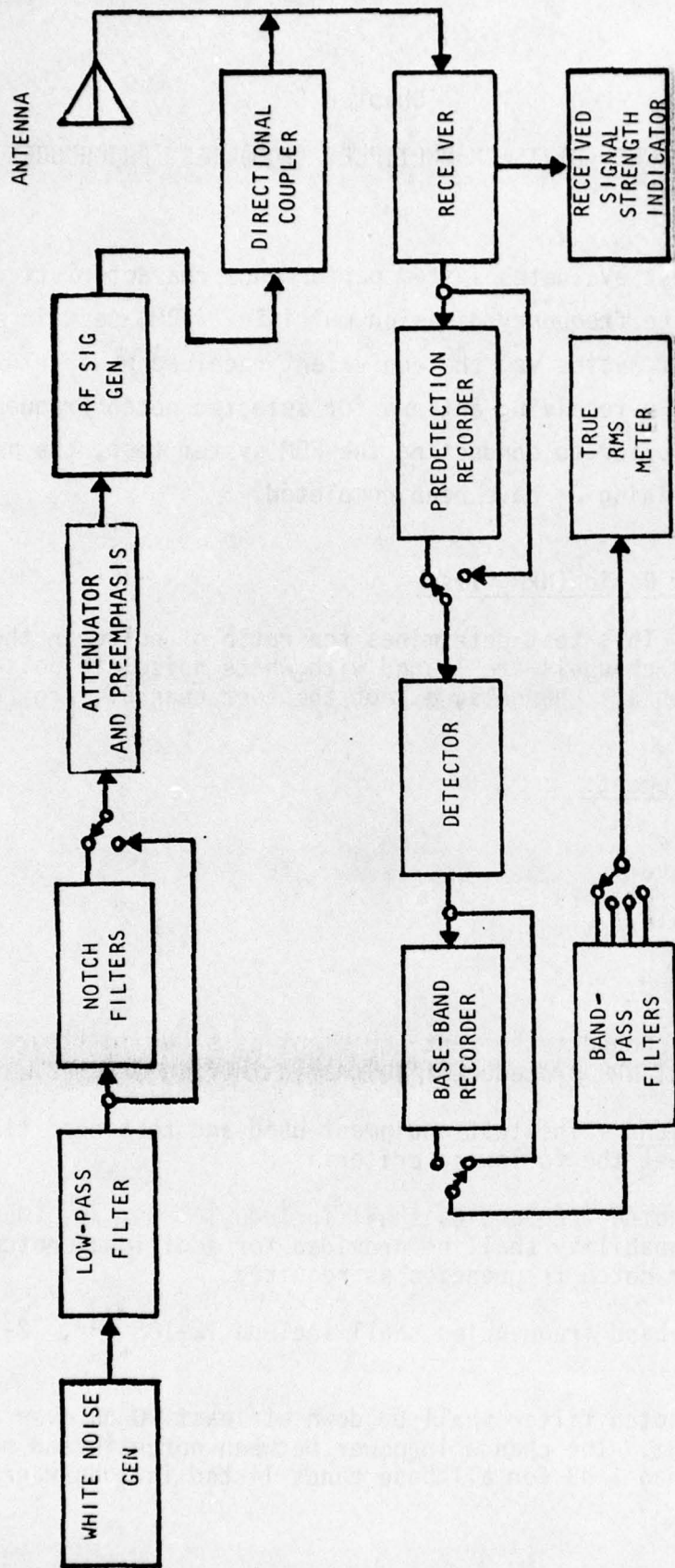


Figure 1.1-1 Block Diagram of Frequency Division System Test.

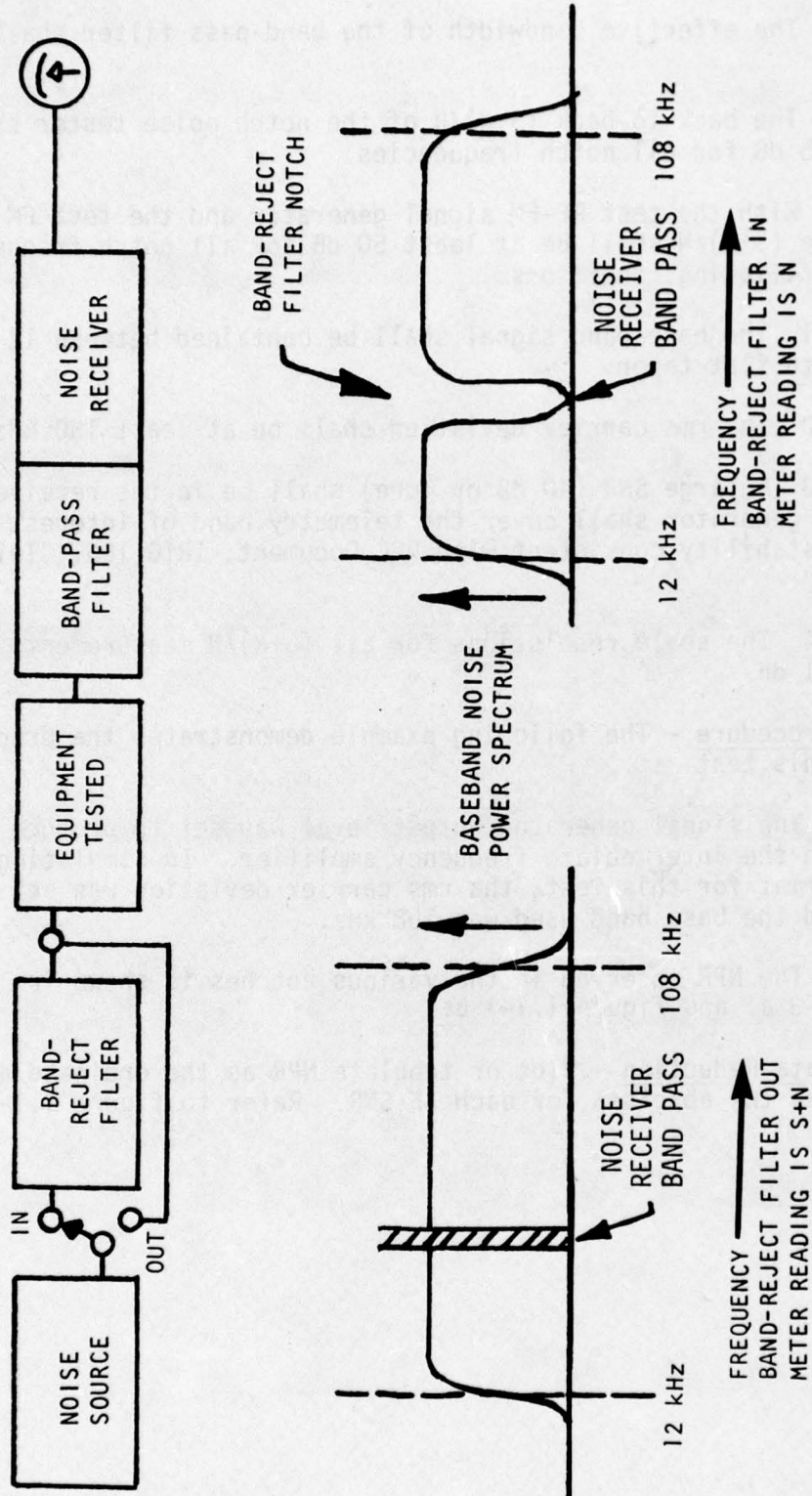


Figure 1.1-2 NPR Test.

1.1.3.2.4 The effective bandwidth of the band-pass filter shall be 1 kHz.

1.1.3.2.5 The back-to-back (S+N)/N of the notch noise tester shall be at least 65 dB for all notch frequencies.

1.1.3.2.6 With the test RF-FM signal generator and the test FM receiver, the (S+N)/N shall be at least 50 dB for all notch frequencies under the following conditions:

1.1.3.2.6.1 The base-band signal shall be contained between 12 kHz and 200 kHz with flat taper.

1.1.3.2.6.2 The rms carrier deviation shall be at least 150 kHz rms.

1.1.3.2.6.3 A large SNR (40 dB or more) shall be in the receiver IF. The signal generator shall cover the telemetry band of interest with a frequency stability consistent with RCC Document, IRIG 106, "Telemetry Standards."

1.1.3.2.6.4 The scale resolutions for all (S+N)/N measurements shall be less than 1 dB.

1.1.3.3 Procedure - The following example demonstrates the procedure used for this test.

1.1.3.3.1 The signal generator output level was set to produce an SNR of 20 dB in the intermediate frequency amplifier. In simulating a mission format for this test, the rms carrier deviation was set to 93 kHz, and the base band used was 108 kHz.

1.1.3.3.2 The NPR observed in the various notches is shown in figure 1.1-3 a. and figure 1.1-3 b.

1.1.3.4 Data Reduction - Plot or tabulate NPR as the ordinate and notch frequency as the abscissa for each IF SNR. Refer to figure 1.1-4.

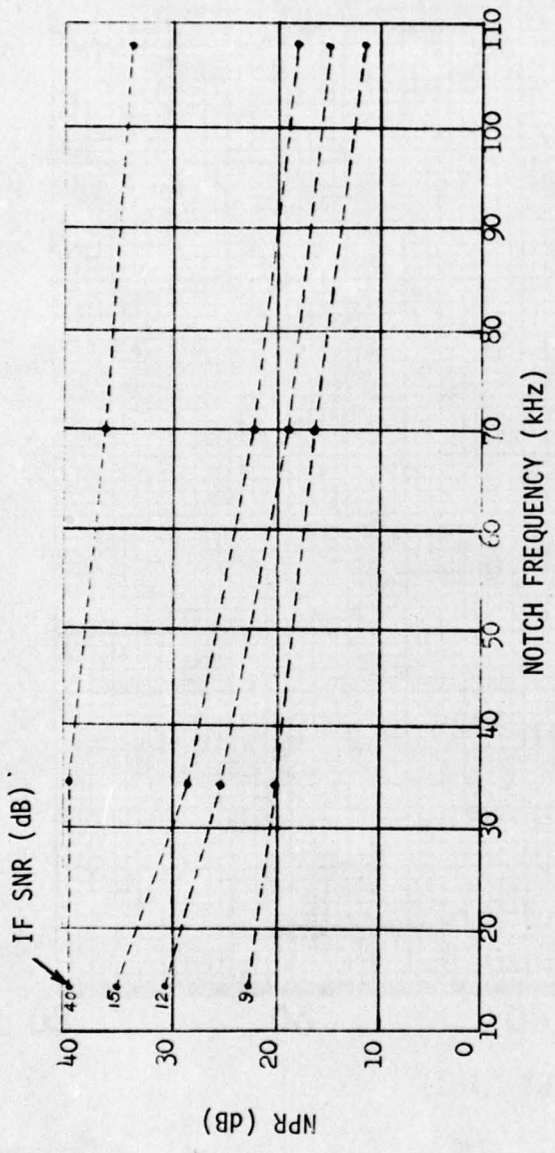


Figure 1.1-3 a. Example of NPR Test - Flat Taper.

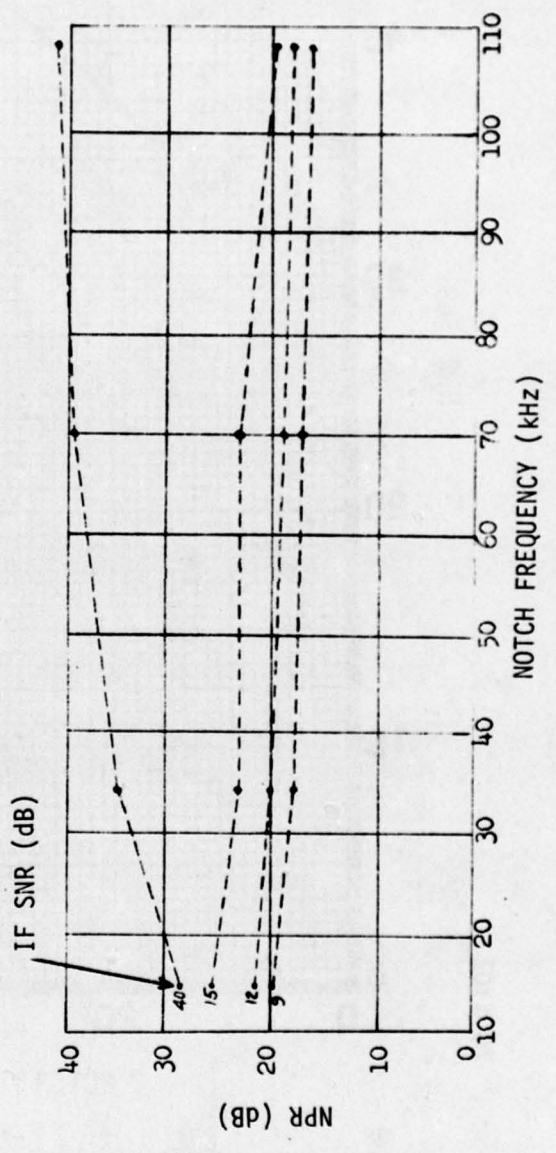


Figure 1.1-3 b. Example of NPR Test - 6 dB/Octave Preemphasis.

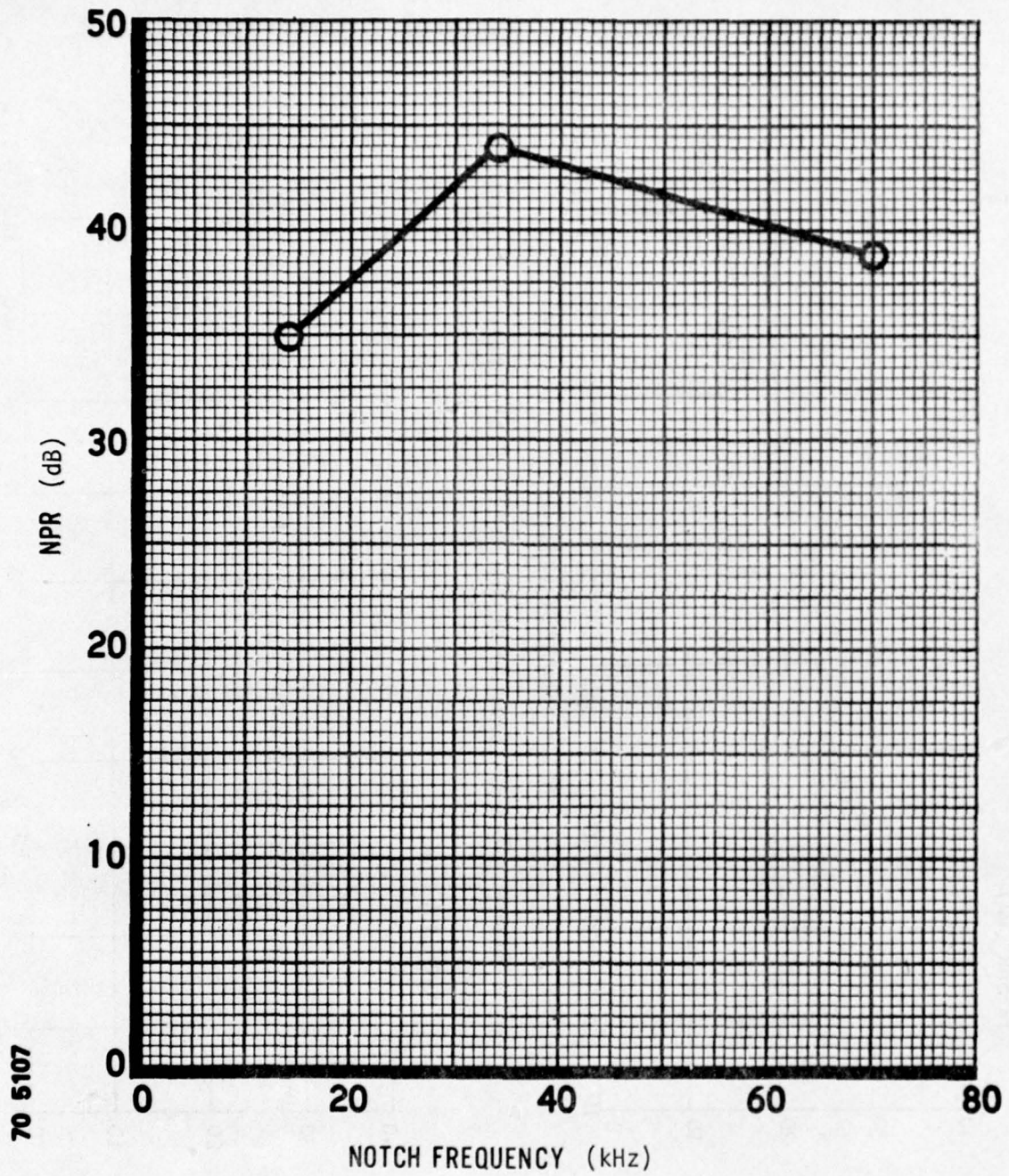


Figure 1.1-4 Noise Power Ratio versus Notch Frequency.

## Chapter 2

### TIME DIVISION MULTIPLEX (TDM) SYSTEMS

#### 2.0 General

2.0.1 System tests are those that include the entire telemetry ground station from the input to the antenna to the output of the system. More specifically, time division multiplex (TDM) system tests test the ground system to characterize its performance when the telemetry data format is a TDM format. The performance of the TDM system is plotted against the equivalent received power flux density falling at the surface of the receiving antenna. Since no single test may completely describe the performance of the ground system in support of a specific TDM format, several tests may be necessary as is the case in pulse code modulation (PCM).

2.0.2 System tests involve carrier modulated signals which are generally frequency or phase modulated although other types of modulation can also be used. Specific test signals are either pulse code modulation (PCM) or pulse amplitude modulation (PAM). It is assumed that prior to conducting TDM system tests, the prerequisite tests for determining  $J_a$ , the power flux density (watts/m<sup>2</sup>) at the surface of the receiving antenna, have been completed.

2.0.3 The RF test equipment for generating frequency (or phase) modulated TDM signals should cover the telemetry band of interest and should provide the capability to satisfy the mission requirements. Suggested test equipment requirements are:

2.0.3.1 Base-band response from d.c. to 1 MHz flat to  $\pm 2$  dB.

2.0.3.2 Peak-to-peak frequency modulation capability adjustable from 700 Hz to 7 MHz.

2.0.3.3 Peak frequency deviation meter to cover this range with an error not more than 10 percent of the meter reading.

2.0.3.4 Peak-to-peak carrier phase modulation from  $\pi/2$  to  $\pi$  radians continuously adjustable.

2.0.3.5 Peak phase deviation meter to cover this range with not more than 3 percent error.

#### 2.1 PCM Testing

##### 2.1.1 Bit Error Probability (BEP) Tests

###### 2.1.1.1 BEP vs. Equivalent Received Power Flux ( $J_a$ )

2.1.1.1.1 Purpose - This test characterizes the performance of a telemetry receiving system when the signal data is PCM. It also involves the

measurement of BEP vs.  $J_a$ . Three separate test configurations apply to measuring BEP. They are test conditions A, B and C and are presented in subparagraphs 2.1.1.2, 2.1.1.3 and 2.1.1.4, respectively.

2.1.1.1.2 Test Equipment:

RF signal generator - employ the same generator used in the calculation of  $\alpha$  in RF systems' tests described in IRIG 118-79, Volume II. Only the modulation signal needs to be changed.

BEP measuring equipment - refer to test configuration A, B or C.

2.1.1.1.3 Test Method:

2.1.1.1.3.1 Setup - none

2.1.1.1.3.2 Conditions - Refer to subparagraph 2.0.3.

2.1.1.1.3.3 Procedure:

2.1.1.1.3.3.1 Determine the carrier predetection bandwidth, PCM waveform test patterns, type and depth of modulation, bit rate, and range of BEP values to be tested.

2.1.1.1.3.3.2 Point the antenna at the quiet sky and at least 3-antenna beamwidths from any radio sources and set up in the mission configuration.

2.1.1.1.3.3.3 Vary the output ( $P_S$ ) of the RF test signal generator using the  $\alpha$  determined by the RF systems' test procedure. Tabulate BEP vs.  $P_S$  vs.  $J_a$ .

2.1.1.1.3.4 Data Reduction - Tabulate and plot BEP and  $P_S$ . Calculate and plot  $J_a$  as shown in the following sample.

<u>BEP</u>	<u><math>P_S</math> (dBw)</u>	<u>(Calculated) <math>J_a</math> watts/m<sup>2</sup> (dB)</u>
10 <sup>-1</sup>	-102	-139.5
10 <sup>-2</sup>	-97	-134.5
10 <sup>-3</sup>	-94	-131.5
10 <sup>-4</sup>	-92.5	-130.0
10 <sup>-5</sup>	-91	-128.5

The third column is calculated using  $\alpha$  as determined in IRIG 118-79, Volume I, Appendix I-A. A plot is made of BEP vs.  $J_a$  in dB (watts m<sup>-2</sup>) as shown in figure 2.1.1.1-1. A data sheet can be easily prepared as shown above with plotting done on standard 5-cycle semi-logarithmic paper.

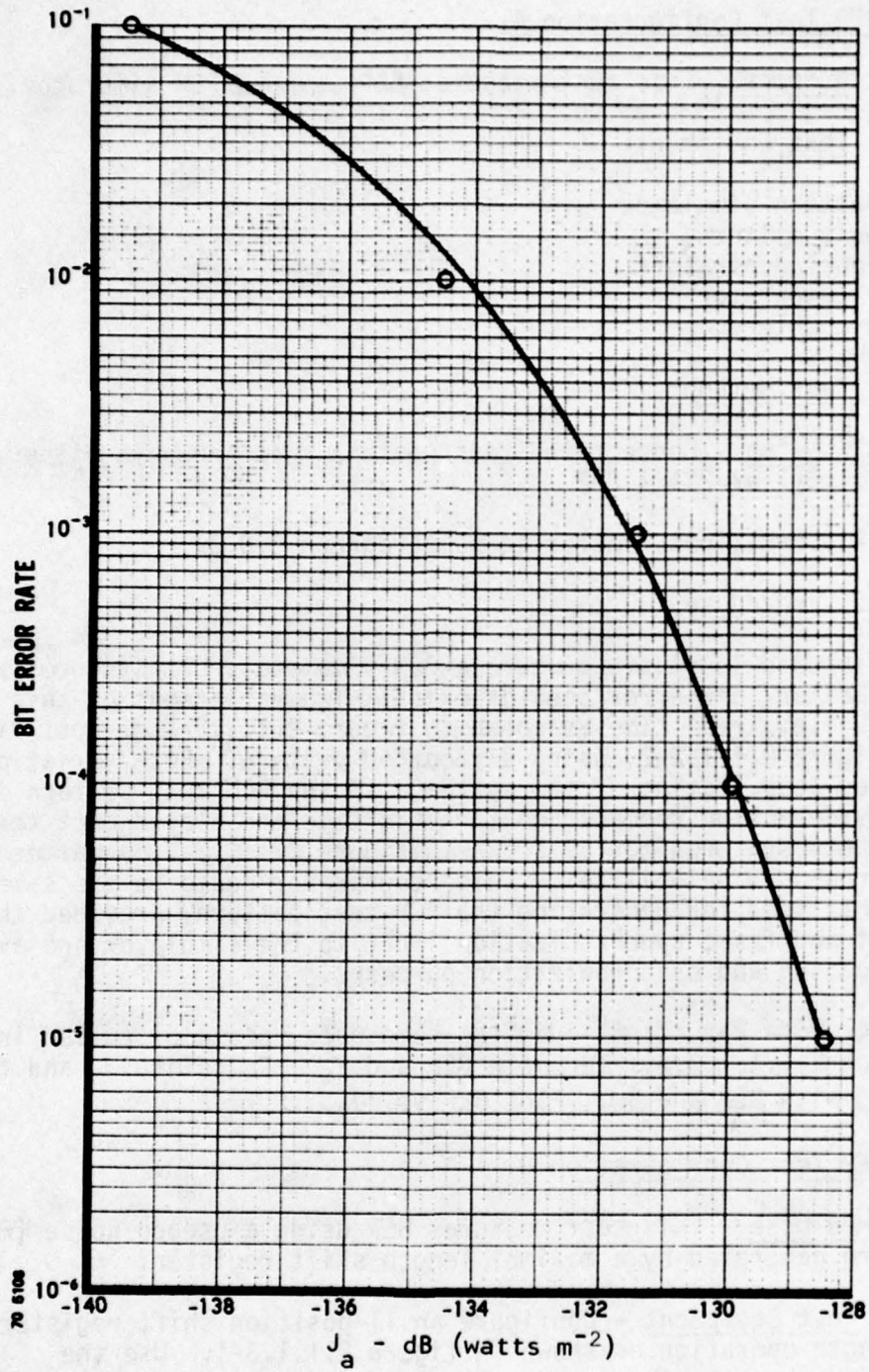


Figure 2.1.1.1-1 Bit Error Probability versus Power Flux Density.

### 2.1.1.2 BEP Test Configuration A

2.1.1.2.1 Purpose - This test measures BEP using a PCM simulator.

#### 2.1.1.2.2 Test Equipment:

PCM pattern simulator  
Low-pass filter  
RF signal generator  
Error comparator  
Error counter

#### 2.1.1.2.3 Test Method:

2.1.1.2.3.1 Setup - Connect the test equipment as shown in either figure 2.1.1.2-1 or 2.1.1.2-2.

2.1.1.2.3.2 Conditions - Refer to subparagraph 2.0.3.

#### 2.1.1.2.3.3 Procedure:

This test is used in stations where a PCM simulator, bit synchronizer, error comparator, and error counter exist. Two variations of this test can be run, i.e., real time as shown in figure 2.1.1.2-1 or post time as shown in figure 2.1.1.2-2, using a recorded pattern. Both variations allow closed-loop testing of the system. If the PCM test pattern is pre- or postdetection recorded on magnetic tape and played back through the system bit synchronizer as shown in figure 2.1.1.2-2, a pattern regenerator should be utilized. This regenerator could be the same PCM simulator utilized for generating the PCM test pattern, provided that a clock input and frame synchronization input to the simulator are available for loading and synchronization purposes.

2.1.1.2.3.4 Data Reduction - Use the same data sheets discussed in subparagraph 2.1.1.1.3.4. Tabulate BEP and  $P_s$ . Calculate  $J_a$  and tabulate along with BEP and  $B_s$ . Plot BEP vs.  $J_a$ .

### 2.1.1.3 BEP Test Configuration B

2.1.1.3.1 Purpose - This test measures BEP using a pseudo noise (PN) test pattern generated by a maximal length shift register.

2.1.1.3.2 Test Equipment - Configure an 11-position shift register for maximal length operation as shown in figure 2.1.1.3-1. Use the resistor with an external clock as the PN test pattern source.

#### 2.1.1.3.3 Test Method:

2.1.1.3.3.1 Setup - Connect the test equipment as shown in figure 2.1.1.3-2.

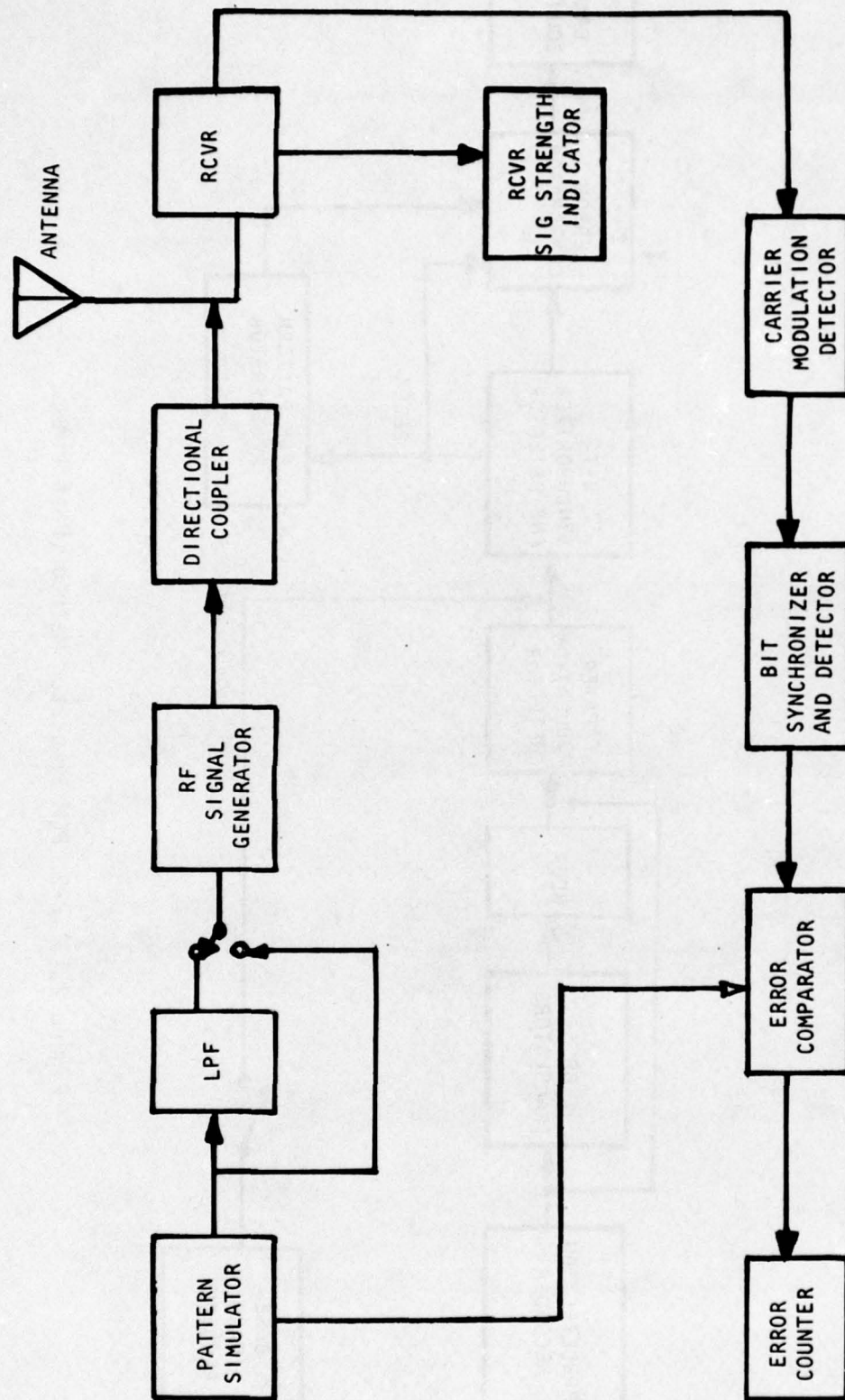


Figure 2.1.1.2-1 PCM Simulator Method (Real Time).

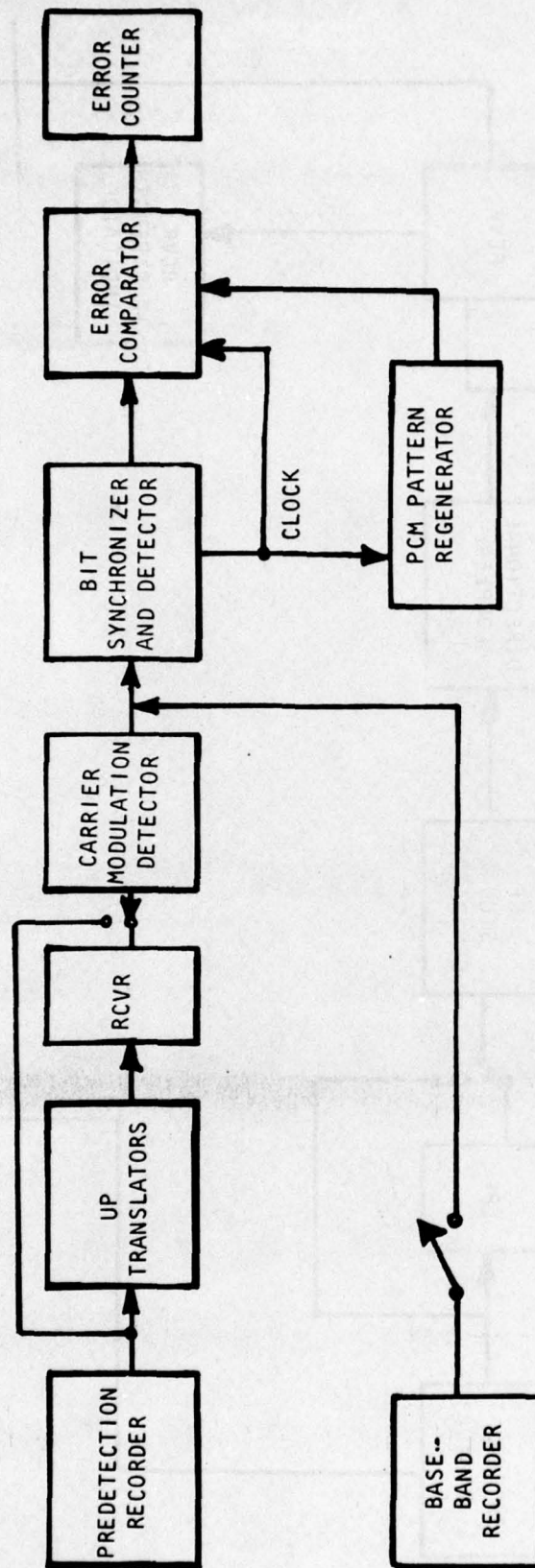


Figure 2.1.1.2-2 PCM Simulator Method (Post Time).

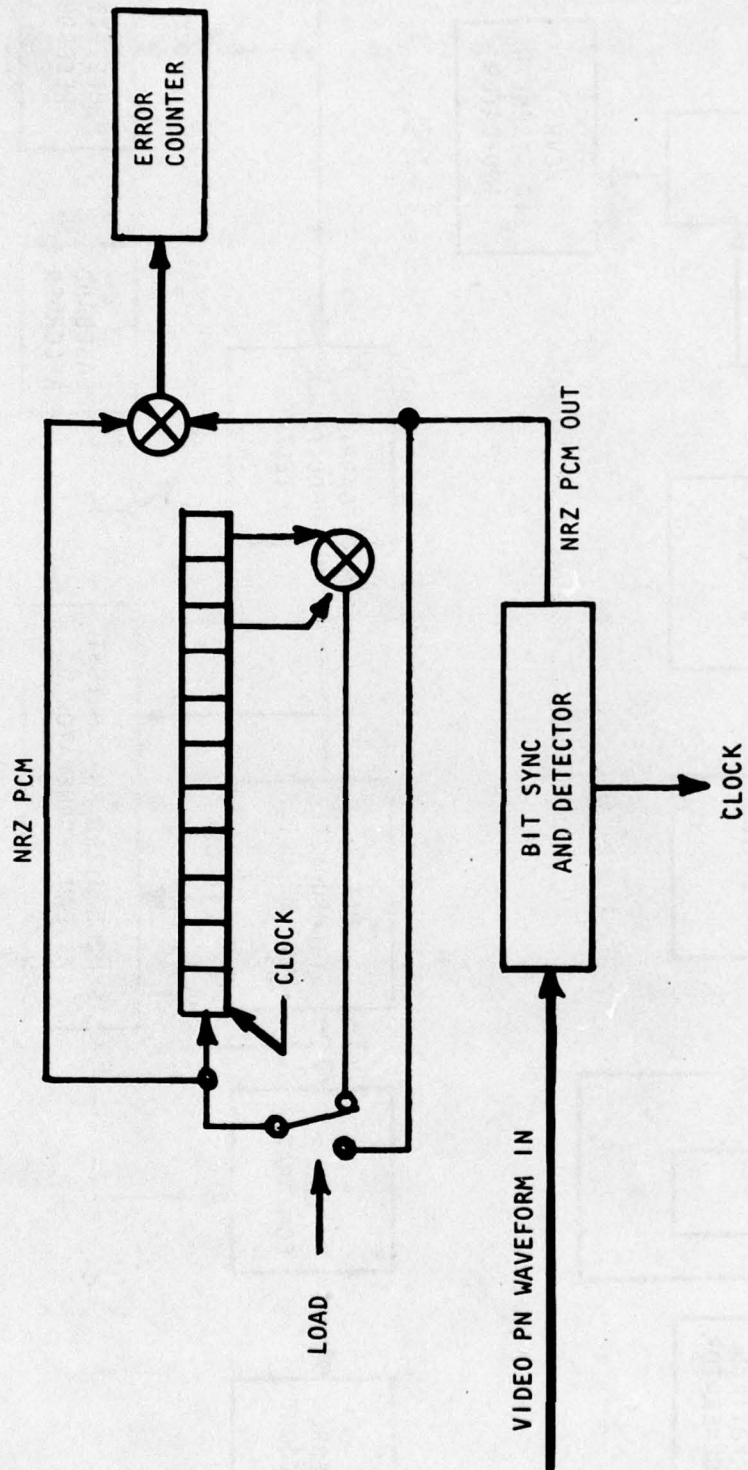


Figure 2.1.1.3-1 Noncoherent PN-PCM Synchronizer.

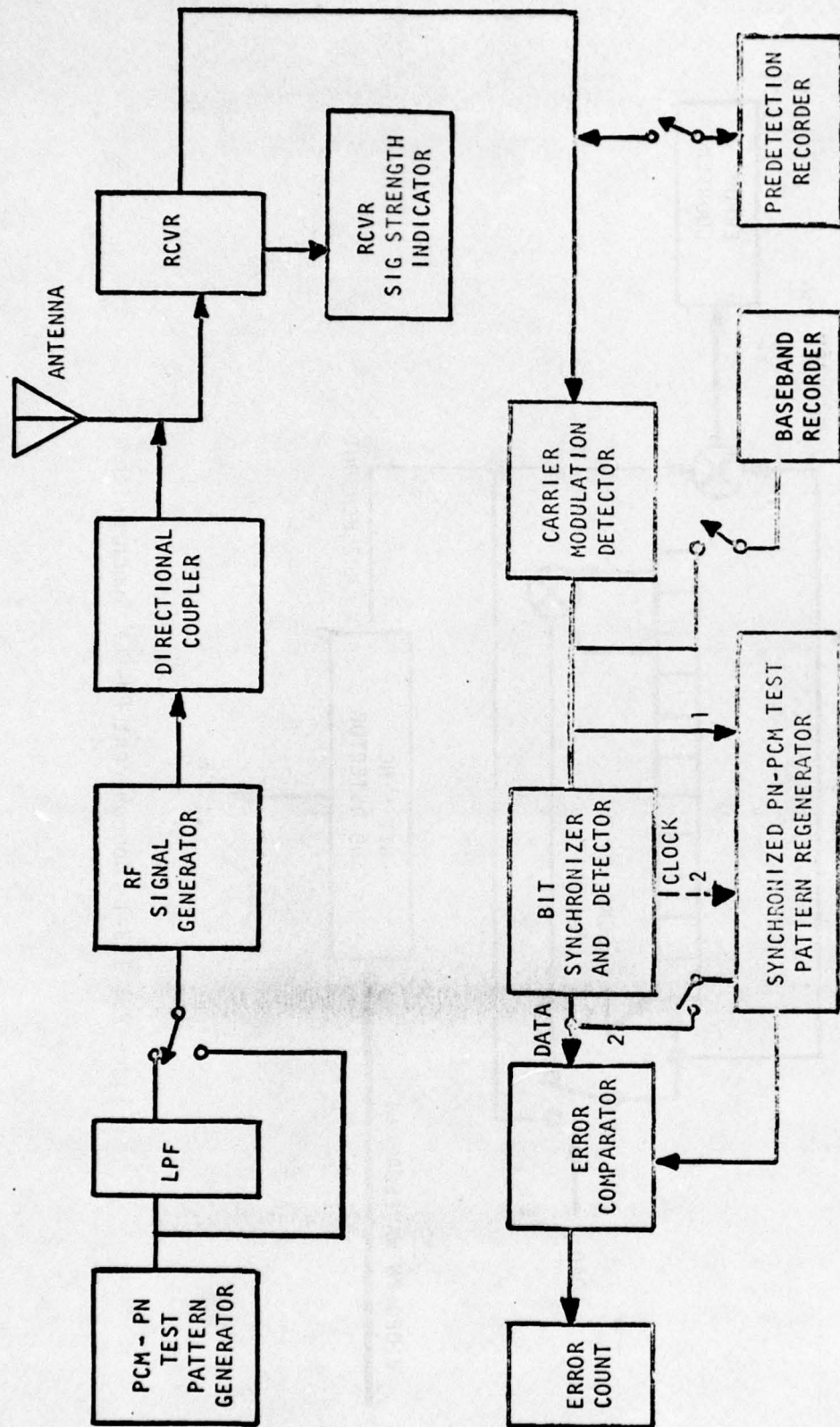


Figure 2.1.1.3-2 Autocorrelation Method.

2.1.1.3.3.2 Conditions - Refer to subparagraph 2.0.3.

2.1.1.3.3.3 Procedure:

2.1.1.3.3.3.1 It is recommended that a PN test pattern be utilized whenever possible. One reason for this is that a PN sequence can be generated and synchronized economically by a shift register with feedback configured for a maximum length sequence. The number of positions in the shift register and the feedback connections uniquely determine the test pattern which has been adopted by ranges and users and allows the exchange of test data without ambiguity. In this connection an 11-position shift register is recommended with feedback summed modulo two from positions 9 and 11. The sequence will be 2047 bits long which corresponds roughly to the frame lengths used for nonreturn to zero (NRZ) and exercises the low-frequency response of elements of the system. This is important because with NRZ the lack of d.c. response causes zero wander of the bit stream in accordance with the fractional amount of near-d.c. power lost. In addition, the sequence will contain 11 binary 1s followed by 9 binary 0s, thus exercising the bit synchronizer with only 1 NRZ transition in 19 bits, 3 in 29 bits, 5 in 39 bits, 7 in 49 bits, etc.

2.1.1.3.3.3.2 The synchronization of the PN-PCM test pattern regenerator shown in figure 2.1.1.3-1 is discussed in the reference. Because of the autocorrelation properties of a PN sequence, it is possible to synchronize a slave shift register to an incoming PN bit stream (plus noise) by cross correlation. This is carried out by coherent or noncoherent methods. The test data given in the reference indicate that the noncoherent method is adequate for tests in which the BEP is less than 0.01.

2.1.1.3.3.3.3 The noncoherent method of synchronization makes use of the clock from a data bit synchronizer. Since data bit transitions occur at random, a nonlinear operation is required in the data bit synchronizer to generate discrete frequency components at the bit rate and its harmonic. Figure 2.1.1.3-1 is a schematic of the noncoherent PN synchronizer. The clock from the bit synchronizer is used to drive the shift register and the NRZ bit stream out of the bit detector, and is used to load the shift register by throwing the switch to the load position. The switch is then thrown to the feedback position, and, if there are no errors in the loaded bits, the shift register is in lock with the input PN waveform. It will stay in lock until bit slippage occurs in the bit synchronizer. If one or more errors are loaded into the register, the shift register is not locked, and because of the autocorrelation properties of the PN sequence, the error rate is nearly 50 percent. If the error rate for example is  $10^{-2}$ , the register is locked. If it is not locked, (error rate approximately 0.5), the switch is returned to the load position and the process repeated until lock is obtained. In operational hardware, the whole loading operation can be done automatically.

2.1.1.3.3.4 Data Reduction - Use the same data sheets discussed in subparagraph 2.1.1.1.3.4. Tabulate BEP and  $P_s$ . Calculate  $J_a$  and tabulate along with BEP and  $P_s$ . Plot BEP vs.  $J_a$ .

#### 2.1.1.4 BEP Test Configuration C

2.1.1.4.1 Purpose - This test measures BEP using operational hardware, i.e., a PCM test set.

#### 2.1.1.4.2 Test Equipment:

PCM test set

#### 2.1.1.4.3 Test Method:

2.1.1.4.3.1 Setup - Connect the test equipment as shown in figure 2.1.1.3-2. The test set transmitter portion in this case will serve as the PCM/PN test pattern generator and the test set receiver portion will serve as the synchronized PN-PCM test pattern regenerator.

2.1.1.4.3.2 Conditions - Refer to subparagraph 2.0.3. In addition, PCM test sets which utilize PN autocorrelation methods with either coherent or noncoherent synchronization should have the following characteristics:

2.1.1.4.3.2.1 The test PN sequence shall be 2047 bits in length.

2.1.1.4.3.2.2 The PN generator shall include an internal clock continuously variable over the range of 10 bits/sec to  $10^6$  bits/sec. The stability shall conform to IRIG Standards for PCM which are contained in IRIG Standard 106. Provisions for acceptance of external clock shall be included.

2.1.1.4.3.2.3 Provision shall be made for including in the test format an arbitrary word of not more than 33 bits at selectable integer multiples of the PN sequence period.

2.1.1.4.3.2.4 Two bit pulse waveforms shall be selectable; namely, NRZ and split phase.

2.1.1.4.3.2.5 The PN test receiver shall include a PN sequence synchronizer, error comparator and error counter with a capacity for at least 1000 errors.

2.1.1.4.3.2.6 The PN test receiver shall provide PN sequence pattern and bit clock outputs.

2.1.1.4.3.2.7 The PN test receiver shall employ an integrate-and-dump bit detector using the bit clock output from subparagraph 2.1.1.4.3.2.6.

2.1.1.4.3.2.8 The PN receiver shift register clock shall be derived by efficient utilization of the autocorrelation of the PN waveform.

2.1.1.4.3.2.9 Provisions shall be made to indicate the time required to accumulate the bit error count.

2.1.1.4.3.3 Procedure - N/A

2.1.1.4.3.4 Data Reduction - Use the same data sheets discussed in subparagraph 2.1.1.1.3.4. Tabulate BEP and  $P_s$ . Calculate  $J_a$  and tabulate along with BEP and  $P_s$ . Plot BEP vs.  $J_a$ .

2.1.2 Other PCM System Tests

2.1.2.1 In addition to BEP system testing, other tests may be conducted using similar test methods. The use of the PCM test set is recommended for conducting bit slippage probability tests, bit synchronization acquisition tests and bit jitter tests.

2.1.2.2 The test set pattern generator shall be used in conjunction with the same RF generator used in the determination of  $\alpha$  and  $J_a$ . The major difference between system testing and component testing using PCM test sets is that system testing uses the received signal power flux density ( $J_a$ ) as the independent variable and component testing uses the predetected IF SNR as the independent variable.

2.1.2.3 It may be necessary to conduct all of the tests mentioned in subparagraph 2.1.2.1 as system tests. For any given ground station configured in support of a PCM format, it may be advantageous to conduct only BEP tests with the option of introducing base-line wander and AM effects to create a more realistic situation. Refer to chapter 4 of this volume for the test procedures for bit synchronizers which use PCM test sets.

2.2 PAM Testing

2.2.1 Test methods for PAM systems have not been established but may be included in later revisions of Document 118. Test sets such as those used for PCM systems are not readily available for PAM systems.

2.2.2 Some of the problems which can occur in PAM systems due to signal degradation include noise on the analog outputs, drift of the reference levels and loss of frame synchronization. As a minimum test, the performance of the PAM decommutator should be monitored as input levels are varied and noise is introduced.

#### REFERENCE

Lindsey, W.C., "Bit Synchronization System Performance Characterization, Modeling, and Tradeoff Study," Pacific Missile Test Center, Point Mugu, California, Technical Publication, TP-73-18, 4 September 1973.

## Chapter 3

### SUBCARRIER OSCILLATORS

#### 3.0 General

3.0.1 The purpose of subcarrier oscillator (SCO) evaluation is the acquisition and distribution of performance information that will be useful to groups engaged in telemetry and missile instrumentation activities. To be of maximum benefit, published performance information on a given model should be in a form that can be readily compared with information on other SCO models which may have been tested by other groups. Uniformity of test procedures used by testing groups is important for obtaining valid comparisons of SCO performance and for performing periodic checks on installed equipment, or acceptance tests on new equipment. The SCOs to be evaluated by this procedure are used for multiplexing data within a telemetry ground station.

3.0.2 Performance tests are recommended for all IRIG subcarrier bands intended for use in the particular application. To minimize measurement errors, energize the test equipment from a regulated line and conduct the tests in a room where ambient temperature variations are small. When tests require the measurement of voltages or currents with a high order of precision or when the measurement of low-level voltages or currents is required, particular care should be given to the design of the test setup to avoid the error-producing effects of ground-loop currents. The use of an isolation power transformer is desirable. Observe the practice of bringing all ground leads to one common point.

3.0.3 To assure uniformity of testing, the following setup procedures and preliminary adjustments should be completed before the individual tests are conducted.

3.0.3.1 Place the SCOs under test in a temperature-controlled chamber, and maintain the chamber at  $30^{\circ}\text{C}\pm 1^{\circ}\text{C}$  ( $303.2\text{K}\pm 1\text{K}$ ) unless otherwise indicated in the test procedure. If a temperature chamber is not available, ambient temperature variations must be kept as small as possible so that the effects of controlled test parameter variations are not influenced by temperature fluctuations. For similar reasons, the supply voltages for the SCOs under test must be carefully adjusted and regulated.

3.0.3.2 Adjust the supply voltage(s) to the level(s) recommended by the manufacturer and allow a 15-minute warmup. Adjust the appropriate controls on the SCO so that the input signal voltage level and excursion recommended by the manufacturer will produce full IRIG bandwidth output frequency excursion centered within the band. Also adjust the amplitude control to produce the maximum output signal amplitude. Apply the maximum output load comparable to the application.

### 3.1 Control Range(s)

3.1.1 Purpose - This test determines the ranges of controls which are provided to adjust deviation sensitivity, reference frequency and output level.

3.1.1.1 The sensitivity control adjusts the magnitude of input voltage excursion required to produce full IRIG bandwidth output frequency excursion. The reference frequency control adjusts the output frequency which is produced when the input signal terminals are shorted. Depending upon the manufacturer's design, the nominal reference frequency may correspond to the center of the band or to either of the band edges. The output level control adjusts the amplitude of the subcarrier output signal.

3.1.1.2 Certain models may feature all three of the controls, while other models may have only one or two controls. Still other models may have a control to adjust each of the band-edge frequencies but no reference frequency control. The following test procedure applies to models which include the three controls listed in subparagraph 3.1.1.

#### 3.1.2 Test Equipment:

- D.C. signal source
- D.C. voltmeter
- Frequency counter
- A. C. voltmeter (true rms)

#### 3.1.3 Test Method:

3.1.3.1 Setup - Connect the test equipment as shown in figure 3.1-1.

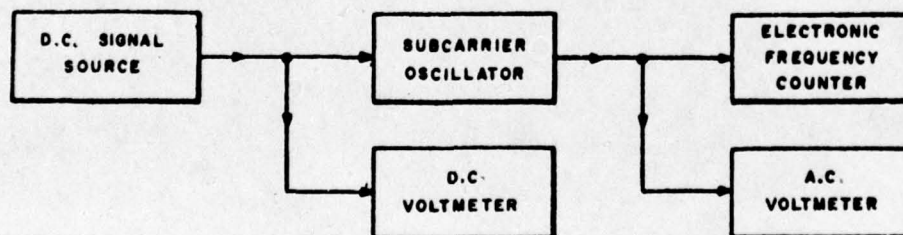


Figure 3.1-1 Control Range(s).

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3.1.3.2 Conditions - Refer to subparagraphs 3.0.2 through 3.0.4.

3.1.3.3 Procedure:

3.1.3.3.1 Measure the input voltage excursion required to produce a full bandwidth output frequency excursion with the sensitivity control set first to the maximum mechanical position and then to the minimum mechanical position.

3.1.3.3.2 Short-circuit the input terminals and measure both the minimum and maximum frequency produced by adjusting the reference frequency control through its full mechanical range.

3.1.3.3.3 Apply a d.c. input voltage to produce an output frequency corresponding to the band center. Measure both the minimum and maximum output signal amplitude for both minimum and maximum settings of the output level control.

3.1.3.3.4 Record data on Data Sheet 3.1.1.

CONTROL RANGES

BAND	SENSITIVITY (VOLTS <sub>p-p</sub> /BANDWIDTH)		REFERENCE FREQUENCY (Hz)		OUTPUT AMPLITUDE (VOLTS RMS)	
	MAXIMUM	MINIMUM	MAXIMUM	MINIMUM	MAXIMUM	MINIMUM
7						
14						
A						
E						

NOTE

## 3.2 Linearity

3.2.1 Purpose - This test determines the deviation of the output frequency vs. the input voltage characteristics from a straight line drawn through the end points (band edges).

### 3.2.2 Test Equipment:

Variable d.c. source  
Precision voltmeter  
Electronic frequency counter

3.2.2.1 Setup - Connect the test equipment as shown in figure 3.2-1.

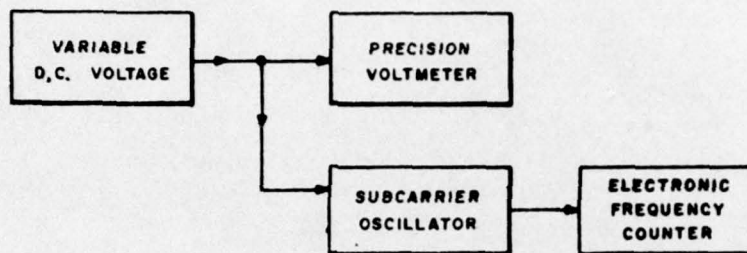


Figure 3.2-1 Linearity Measurement.

3.2.2.2 Conditions - Refer to subparagraphs 3.0.2 through 3.0.4.

### 3.2.2.3 Procedure:

3.2.2.3.1 Measure the input voltages required to produce 11 equally spaced output frequencies covering the subcarrier band by using the precision voltmeter and the frequency counter.

3.2.3.3.2 The measured data can be plotted on a scale with greatly increased resolution if an arbitrary slope (approximating the data slope) is first subtracted from the data. A straight line can then be passed through the end points and the deviation of each data point from the straight line can be determined with much higher resolution.

3.2.3.3.3 Express deviation from linearity as a percentage of bandwidth. Give such deviation a positive sign when, for a selected input voltage level, the output frequency is greater than the corresponding point on the line through the end points.

3.2.3.3.4 Record data on Data Sheet 3.2.1.

2. LINEARITY

DEVIATION FROM LINEARITY (%)	BAND 7											
	BAND 14											
	BAND A											
BAND E												
	-90	-40	-30	-20	-10	0	+10	+20	+30	+40	+80	
SUBCARRIER DEVIATION FROM BAND CENTER (% OF BANDWIDTH)												

NOTE

### 3.3 Amplitude Modulation (AM)

3.3.1 Purpose - This test determines the change of output signal amplitude as the subcarrier frequency is changed through the band from one band edge to the other.

#### 3.3.2 Test Equipment:

D.C. signal source  
Electronic frequency counter  
A.C. voltmeter (true rms)

#### 3.3.3 Test Method:

3.3.3.1 Setup - Connect the test equipment as shown in figure 3.3-1.

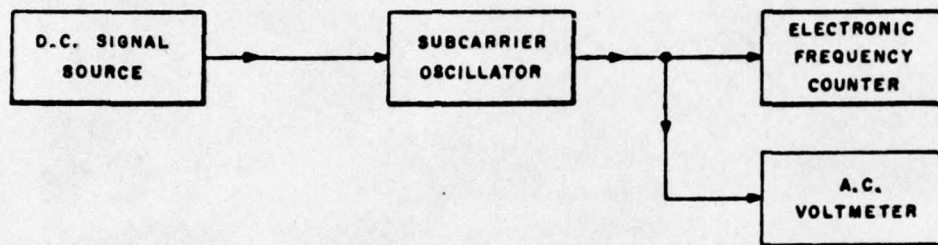


Figure 3.3-1 Amplitude Modulation.

3.3.3.2 Conditions - Refer to subparagraphs 3.0.2 through 3.0.4.

#### 3.3.3.3 Procedure:

3.3.3.3.1 With the input amplitude adjustment set at maximum, vary the d.c. input signal to cause the output frequency to cover the full excursion from one band edge to the other and measure the minimum and the maximum output signal amplitudes within the band.

3.3.3.3.2 Calculate percent AM from the equation:

$$\% \text{ AM} = ((E_{\text{max}} - E_{\text{min}}) / (E_{\text{max}} + E_{\text{min}})) \times 100$$

3.3.3.3.3 Adjust the output frequency to band center and reduce the output signal amplitude to 70 percent of its former value. Repeat the measurements of AM as outlined above.

3.3.3.3.4 Record data on Data Sheet 3.3.1.

## AMPLITUDE MODULATION

BAND	AMPLITUDE MODULATION (%)	
	AT MAXIMUM OUTPUT AMPLITUDE	AT 70% OUTPUT AMPLITUDE
7		
14		
A		
E		

NOTE

### 3.4 Output Distortion

3.4.1 Purpose - This test determines the distortion of the output sub-carrier waveform at selected output amplitudes and output loads (sine-wave outputs only). Use either a distortion analyzer or a wave analyzer to measure output distortion. If a distortion analyzer is used, the effects of all of the distortion producing components (within the bandwidth of the test instrument) are lumped together. If a wave analyzer is used, it is necessary to search for and measure the amplitude of the individual distortion components and then calculate the distortion. This test may be conducted concurrently with measurement of output loading, test 3.7.

#### 3.4.2 Test Equipment:

D.C. signal source  
Electronic frequency counter  
Distortion analyzer or wave analyzer

#### 3.4.3 Test Method:

3.4.3.1 Setup - Connect the test equipment as shown in figure 3.4-1.

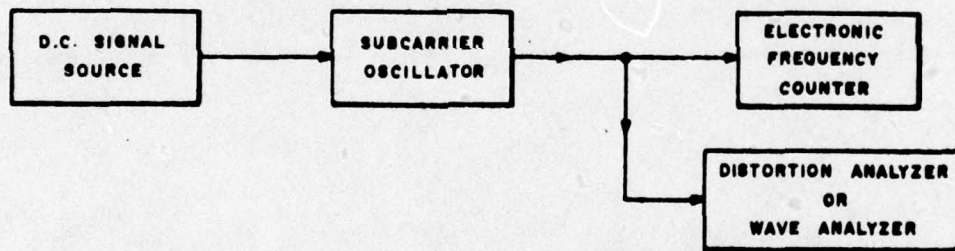


Figure 3.4-1 Output Distortion.

#### NOTE

*In making these measurements, care should be taken to use short, unshielded leads between the output terminal and the measuring instruments, since capacitive loading is one of the test parameters. Terminate the oscillator with a 2k $\Omega$  resistive load or lower, depending on its application.*

3.4.3.2 Conditions - Refer to subparagraphs 3.0.2 through 3.0.4.

3.4.3.3 Procedure:

3.4.3.3.1 With the output amplitude adjustment set at maximum, apply d.c. input voltages to produce output frequencies corresponding to band center, lower band edge and upper band edge, respectively. Measure the output distortion at each of these frequencies.

3.4.3.3.2 Reduce the output subcarrier amplitude to 70 percent of maximum amplitude and repeat the measurements outlined in step 3.4.3.3.1.

3.4.3.3.3 Readjust the output amplitude to maximum and apply a nominal capacitive load to the output terminals (in addition to the resistive load) consistent with the intended application.

3.4.3.3.4 Perform distortion measurements at the 3 frequencies corresponding to band center, lower band edge and upper band edge.

3.4.3.3.5 In the same manner, make distortion measurements with capacitive loads above and below the nominal value selected in subparagraph 3.4.3.3.3.

3.4.3.3.4 Record data on Data Sheet 3.4.1.

OUTPUT DISTORTION						
OUTPUT AMPLITUDE (% OF MAX.)	RESISTIVE LOAD (OHMS)	CAPACITIVE LOAD (pF)	OUTPUT DISTORTION (%)			
			BAND			
			E	A	14	7
(AT BAND CENTER)						
100		0				
70		0				
100		100				
100		500				
100		1000				
(AT UPPER BAND EDGE)						
100		0				
70		0				
100		100				
100		500				
100		1000				
(AT LOWER BAND EDGE)						
100		0				
70		0				
100		100				
100		500				
100		1000				

NOTE

### 3.5 Effect of Source Impedance

#### 3.5.1 Purpose:

3.5.1.1 This test determines the change of output frequency as a function of source impedance variations and determines the current that is fed back from the input terminals into the source.

3.5.1.2 This test is particularly important on solid-state models which receive input signals from variable-resistance transducers. Evaluation groups may also wish to conduct tests at temperatures which simulate selected systems applications in addition to room temperature tests.

#### 3.5.2 Test Equipment:

Resistance decade box  
Electronic frequency counter  
D.C. null voltmeter

#### 3.5.3 Test Method:

3.5.3.1 Setup - Connect the test equipment as shown in figure 3.5-1.

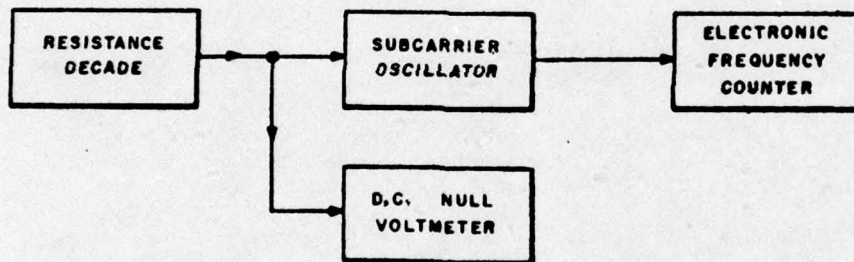


Figure 3.5-1 Effect of Source Impedance.

3.5.3.2 Conditions - Refer to subparagraphs 3.0.2 through 3.0.4.

#### 3.5.3.3 Procedure:

3.5.3.3.1 Short the input terminals and measure the output frequency.

3.5.3.3.2 Adjust the variable resistance decade to  $100\Omega$ . Measure the voltage appearing at the SCO input terminals (use a null voltmeter) and measure the output frequency.

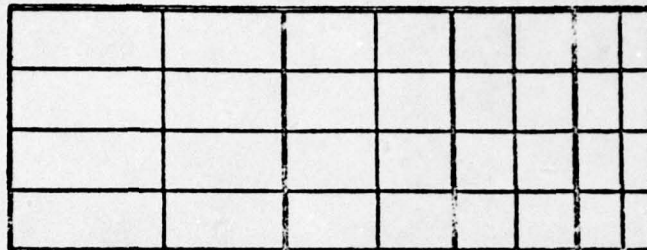
3.5.3.3.3 In the same manner, measure the input voltages and output frequencies with the following resistance values applied to the input:  $1k\Omega$ ,  $10k\Omega$ ,  $100k\Omega$ ,  $1M\Omega$  and  $10M\Omega$ .

3.5.3.3.4 Use the frequency measured with the input shorted as a reference for calculations and express frequency changes in percent of bandwidth. Calculate the feedback current for each of the input resistance levels.

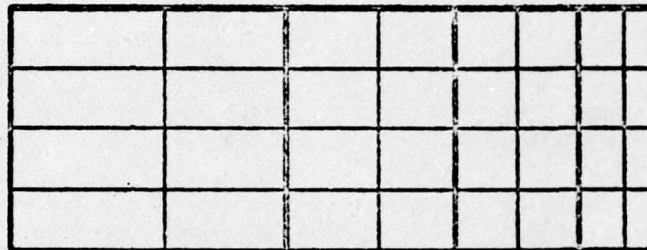
3.5.3.3.5 Record data on Data Sheet 3.5.1.

EFFECT OF SOURCE IMPEDANCE

OUTPUT FREQUENCY  
CHANGE (% of BW)



CURRENT FEEDBACK  
( $\mu$  Ampe)



10<sup>2</sup> 10<sup>3</sup> 10<sup>4</sup> 10<sup>5</sup> 10<sup>6</sup>  
SOURCE IMPEDANCE (OHMS)

NOTE

### 3.6 Effect of Grounding Input (Differential-Input Models Only)

3.6.1 Purpose - This test measures the effects of grounding the input terminals on the subcarrier output frequency and amplitude.

#### NOTE

*In making these measurements, care should be taken to use short, unshielded leads between the output terminals and the measuring instruments, since capacitive loading is one of the test parameters.*

#### 3.6.2 Test Equipment:

D.C. signal source  
D.C. voltmeter  
Electronic frequency counter  
A.C. voltmeter (true rms)

#### 3.6.3 Test Method:

3.6.3.1 Setup - Connect the test equipment as shown in figure 3.6-1.

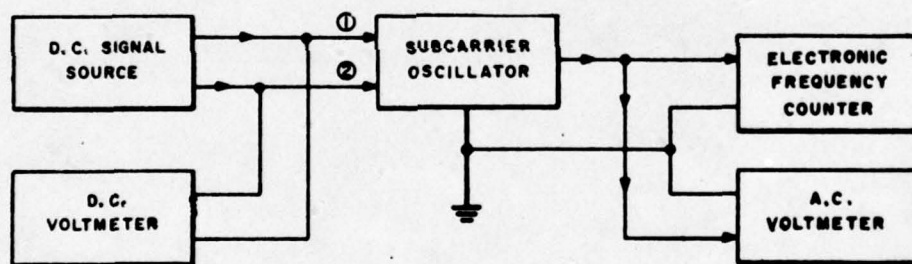


Figure 3.6-1 Effect of Grounding Input.

3.6.3.2 Conditions - Refer to subparagraphs 3.0.2 through 3.0.4.

#### 3.6.3.3 Procedure:

3.6.3.3.1 Ground the chassis of the SCO.

3.6.3.3.2 Apply the input voltages recommended by the manufacturer for subcarrier frequencies corresponding to lower band edge, band center and upper band edge. Do not ground input terminals. Measure the output subcarrier frequencies and amplitudes corresponding to each of these inputs.

3.6.3.3.3 Ground input terminal number 1 and apply the same input voltages used in step 3.6.3.3.2 and again measure the output frequencies and amplitudes.

3.6.3.3.4 Repeat step 3.6.3.3.3 with input terminal number 2 grounded rather than input terminal number 1.

3.6.3.3.5 Using the frequencies and amplitudes measured in step 3.6.3.3.2 as references for calculations, express the frequency changes as percentages of IRIG bandwidth and express amplitude changes directly in percent.

3.6.3.3.6 Record data on Data Sheet 3.6.1.

**EFFECTS OF GROUNDING INPUT (Differential-Input Models Only)**

BAND	OUTPUT FREQUENCY CHANGE (% of BW)			OUTPUT AMPLITUDE CHANGE (%)		
	LOWER BAND EDGE	BAND CENTER	UPPER BAND EDGE	LOWER BAND EDGE	BAND CENTER	UPPER BAND EDGE
<b>INPUT NUMBER 1 GROUNDED</b>						
7						
14						
A						
E						
<b>INPUT NUMBER 2 GROUNDED</b>						
7						
14						
A						
E						

NOTE

### 3.7 Effect of Output Loading

3.7.1 Purpose - This test determines the effects of output loading (both resistive and capacitive) on the amplitude and frequency of the output signal. This test may be conducted concurrently with measurement of output distortion, test 3.4.

#### 3.7.2 Test Equipment:

D.C. signal source  
D.C. voltmeter  
Resistance decade  
Capacitance decade  
Electronic frequency counter

#### 3.7.3 Test Method:

3.7.3.1 Setup - Connect the test equipment as shown in figure 3.7-1.

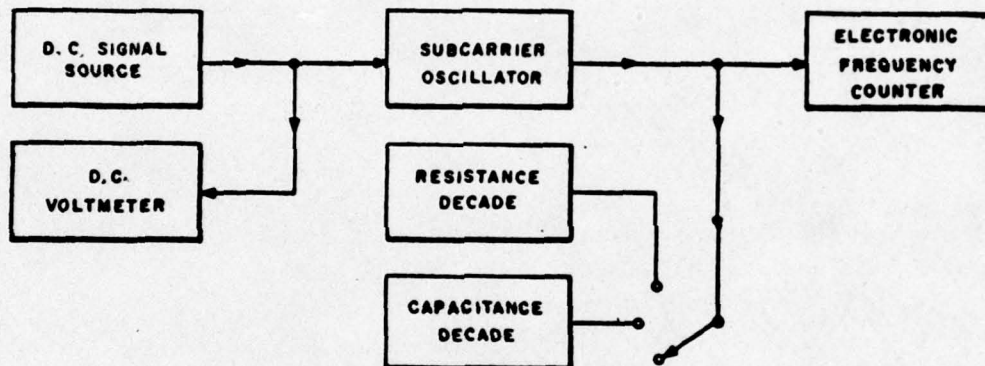


Figure 3.7-1 Effect of Output Loading.

3.7.3.2 Conditions - Refer to subparagraphs 3.0.2 through 3.0.4.

#### 3.7.3.3 Procedure:

3.7.3.3.1 Adjust the d.c. input signal to a level that will produce an output frequency corresponding to band center.

3.7.3.3.2 Measure the frequency and amplitude of the output signal with no load applied to the output.

3.7.3.3.3 Use the same input level applied in step 3.7.3.3.1 to measure the output frequencies and amplitudes for the resistive output loads selected in subparagraph 3.4.3.3 or others consistent with the intended applications.

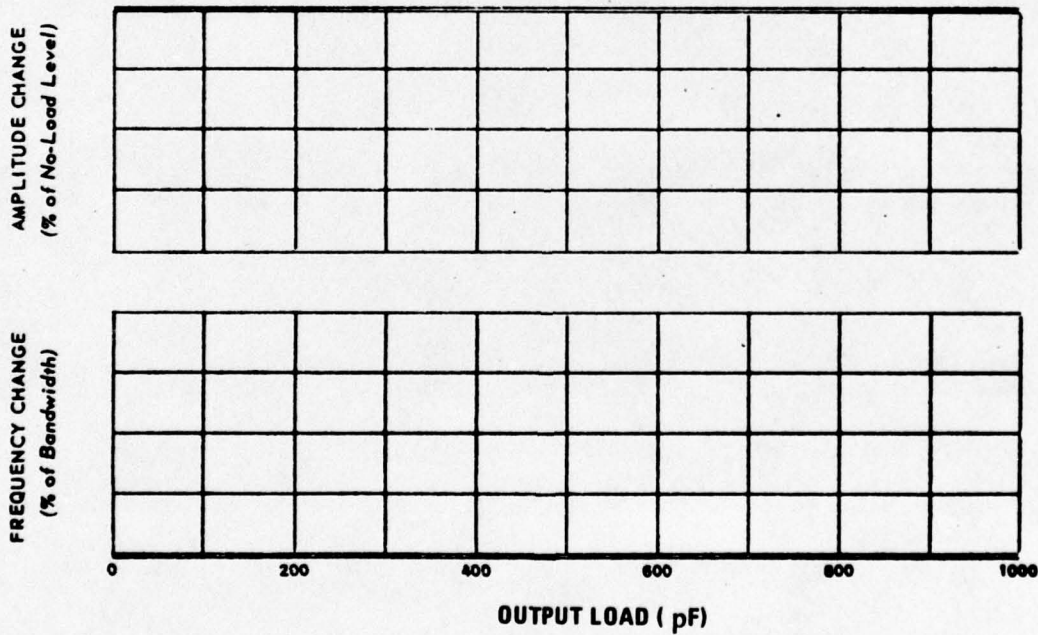
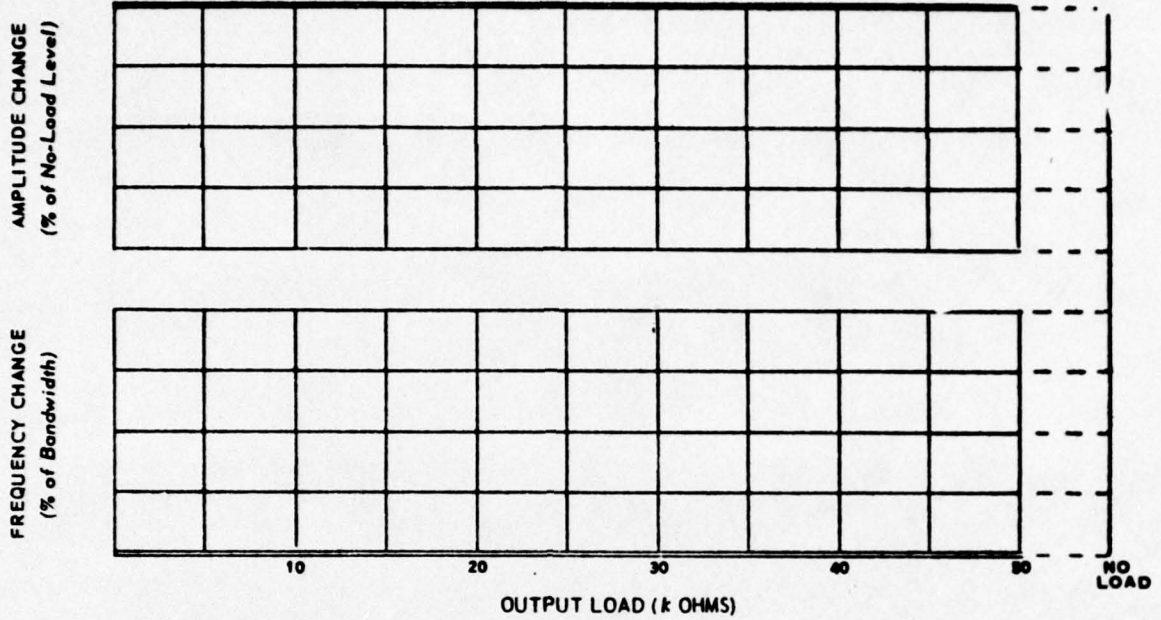
3.7.3.3.4 Remove the resistive load and recheck the output frequency and amplitude and readjust the d.c. input signal, if necessary, to produce band-center frequency.

3.7.3.3.5 Using the same input level applied in subparagraph 3.7.3.3.4, measure the output frequencies and amplitudes for capacitive output loads selected in subparagraph 3.4.3.3.

3.7.3.3.6 Use the frequencies and amplitudes measured under no-load conditions as references for calculations and express frequency changes in percent of bandwidth and express amplitude changes directly in percent.

3.7.3.3.7 Record data on Data Sheet 3.7.1.

OUTPUT LOADING



### 3.8 Modulation Feedthrough

3.8.1 Purpose - This test determines the amplitude of the modulation-frequency component appearing at the SCO output.

#### 3.8.2 Test Equipment:

A.C. signal source  
Electronic frequency counter  
A.C. voltmeter (true rms)  
Wave analyzer

#### 3.8.3 Test Method:

3.8.3.1 Setup - Connect the test equipment as shown in figure 3.8-1.

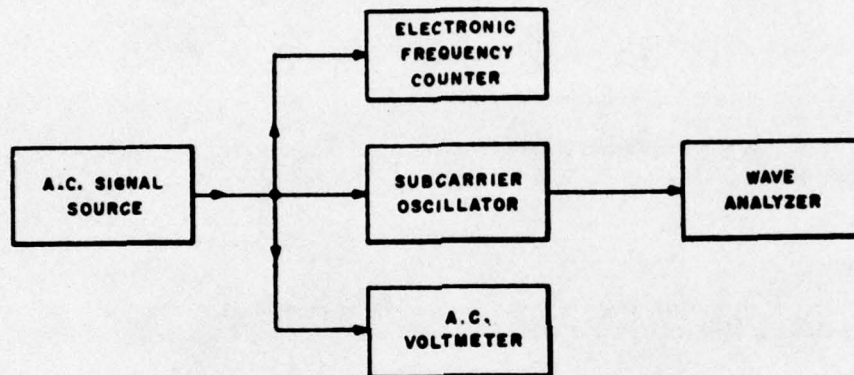


Figure 3.8-1 Modulation Feedthrough.

3.8.3.2 Conditions - Refer to subparagraphs 3.0.2 through 3.0.4.

#### 3.8.3.3 Procedure:

3.8.3.3.1 Adjust the frequency of the signal source to correspond to the maximum modulation frequency for a modulation index of 1. Adjust the peak-to-peak amplitude for the a.c. signal to produce full bandwidth subcarrier deviation.

3.8.3.3.2 Measure the amplitude of the modulation frequency component appearing at the SCO output terminals using a wave analyzer or similar frequency-selective voltmeter.

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3.8.3.3.3 Repeat step 3.8.3.3.2 at a modulation frequency of one-half of that selected in step 3.8.3.3.1 and then repeat step 3.8.3.3.2 at a frequency one-tenth of that selected in step 3.8.3.3.1.

3.8.3.3.4 Modulation feedthrough is expressed in dB below the sub-carrier and is calculated from the ratio of subcarrier component to the modulation component appearing at the output terminals.

3.8.3.3.5 Record data on Data Sheet 3.8.1.

---

MODULATION FEEDTHROUGH

---

BAND	MODULATION FEEDTHROUGH (dB below subcarrier)		
	(f <sub>1</sub> = mod freq for deviation ratio = 1)		
	f <sub>1</sub>	0,5f <sub>1</sub>	0,1f <sub>1</sub>
7			
14			
A			
E			

NOTE

### 3.9 Long-Term Stability Vs. Time

3.9.1 Purpose - This test determines warmup, reference frequency variations and sensitivity variations as a function of time.

3.9.1.1 Sensitivity instability is defined as the variation of full-scale output frequency excursion (resulting from full-scale input voltage excursion) expressed as a percentage of full-scale output excursion measured at an elapsed time of 30 minutes.

3.9.1.2 Reference frequency shift is defined as the variation of output frequency for 0 input expressed as a percentage of full-scale output frequency excursion measured at an elapsed time of 30 minutes.

3.9.1.3 Sensitivity change is given a positive sign when full-scale output excursion is greater than that measured at the reference time of 30 minutes.

3.9.1.4 Reference frequency shift is given a positive sign when the output frequency is greater than that measured at the reference time of 30 minutes.

#### 3.9.2 Test Equipment:

Reference voltage source  
Programmer (optional)  
Electronic frequency counter  
Printer

The block diagram (figure 3.9-1) includes a programmer which switches the SCO input voltages and provides a count command to the electronic counter. A printer is also shown associated with the counter. Although the test can be conducted without these two items of test equipment, they are included for convenience.

#### 3.9.3 Test Method:

3.9.3.1 Setup - Connect the test equipment as shown in figure 3.9-1.

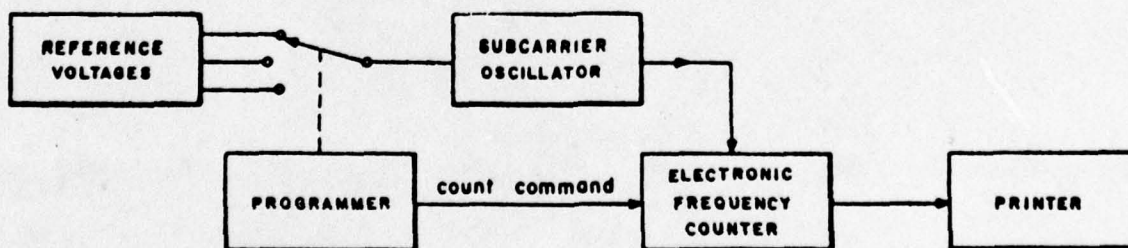


Figure 3.9-1 Stability versus Time.

3.9.3.2 Conditions - Measurements are conducted over a period of 8 hours and elapsed time is measured from cold start. Nominal settings of the sensitivity control and the reference frequency control should approximate those which will produce full bandwidth output frequency excursion, centered within the band, after 30 minutes or more of operation. Additional test conditions are contained in subparagraphs 3.0.2 through 3.0.4.

3.9.3.3 Procedure:

3.9.3.3.1 Adjust the reference voltages to the preselected levels for output frequencies corresponding to the lower band edge, band center and upper band edge.

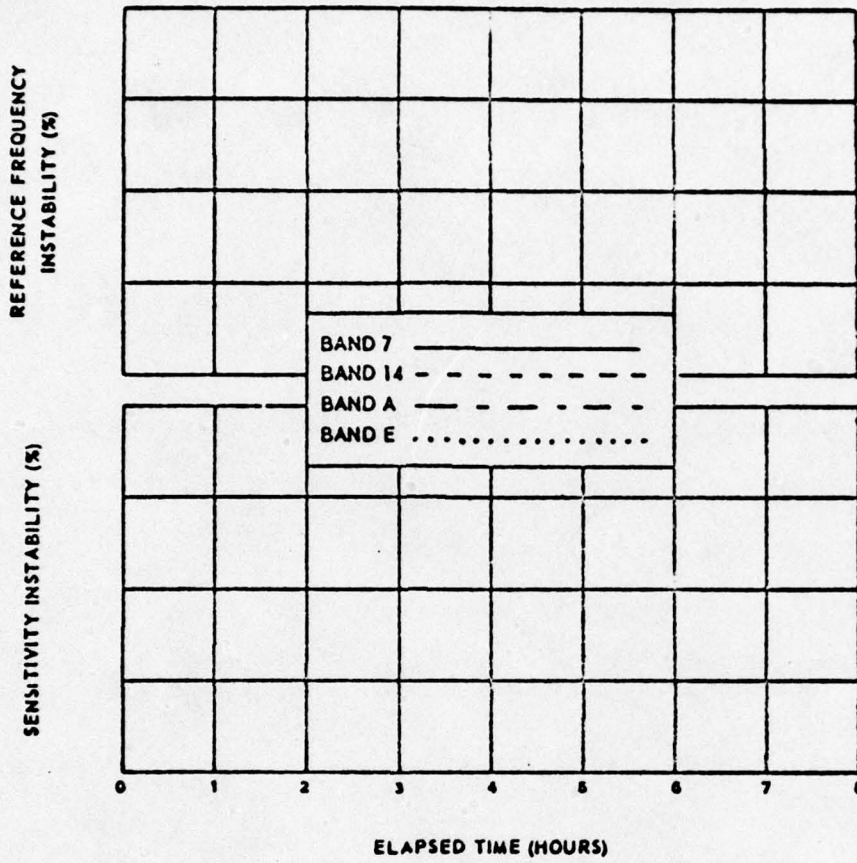
3.9.3.3.2 Energize the SCO and measure the output frequencies for each of the 3 input voltages at an elapsed time of 1 minute. Make similar measurements at 1-minute intervals for the first 10 minutes.

3.9.3.3.3 After 10 minutes, make measurements at 5-minute intervals until 1 hour has elapsed.

3.9.3.3.4 After 1 hour, make measurements at 30-minute intervals until 8 hours have elapsed.

3.9.3.3.5 Record data on Data Sheet 3.9.1.

STABILITY vs TIME



NOTE

### 3.10 Effect of Supply Voltage Variation and Ripple

3.10.1 Purpose - This test determines the effect of supply voltage changes and ripple on output frequency and amplitude.

#### 3.10.2 Test Equipment:

D.C. voltage source  
D.C. voltmeter  
A.C. supply  
Ripple source  
Electronic frequency counter  
Subcarrier discriminator  
A.C. voltmeter (true rms)

#### 3.10.3 Test Method:

3.10.3.1 Setup - Connect the test equipment as shown in figure 3.10-1.

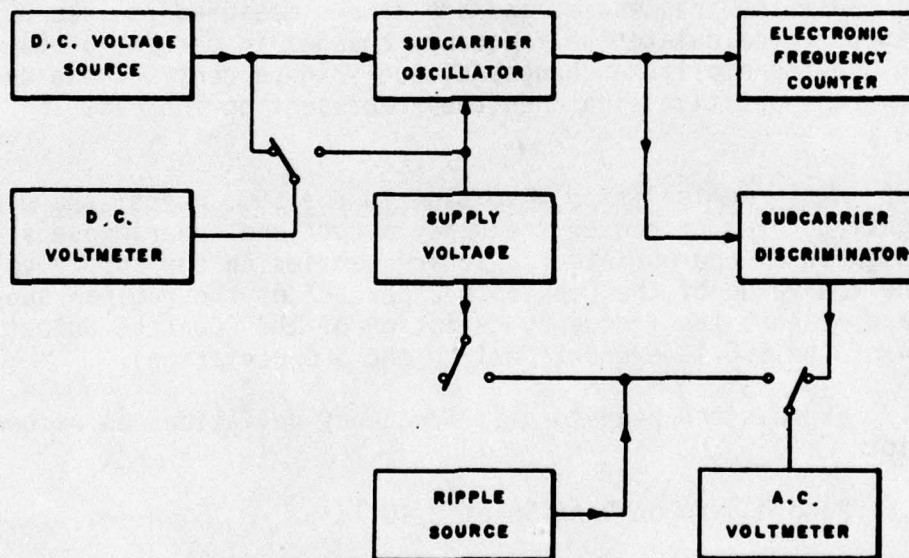


Figure 3.10-1 Effect of Supply Voltage Variation and Ripple.

3.10.3.2 Conditions - Refer to subparagraphs 3.0.2 through 3.0.4.

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### 3.10.3.3 Procedure:

3.10.3.3.1 Adjust the supply voltage to the nominal value recommended by the manufacturer (do not apply a ripple voltage).

3.10.3.3.2 Adjust the d.c. input signal to the SCO to produce first the lower band-edge frequency, then band center and finally upper band edge. Measure the subcarrier output frequencies and amplitudes at each of these voltage settings. (Note the input voltages required to produce each of the 3 output frequencies.)

3.10.3.3.3 Reduce the supply voltage by 10 percent of the nominal level and again measure the output frequencies and amplitudes for each of the 3 input signal voltage levels used in the previous measurement.

3.10.3.3.4 Make similar measurements with the supply voltages changed by -5 percent, +5 percent, +10 percent, and back to nominal level again. (The measurement range may be expanded to simulate selected system applications.)

3.10.3.3.5 Use the frequencies and amplitudes measured in step 3.10.3.3.2 as references to calculate the frequency changes in percent of bandwidth and calculate the amplitude changes directly in percent. These changes will be given a positive sign when they represent an increase in magnitude.

3.10.3.3.6 Apply nominal supply voltage to the SCO, adjust the d.c. input signal to produce center frequency output and superimpose sinusoidal signals of appropriate ripple frequencies on the supply voltage. Adjust the rms value of the ripple to 2 percent of the nominal supply voltage and measure the frequency deviation of the SCO (the output excursion of the SCO is proportional to the SCO deviation).

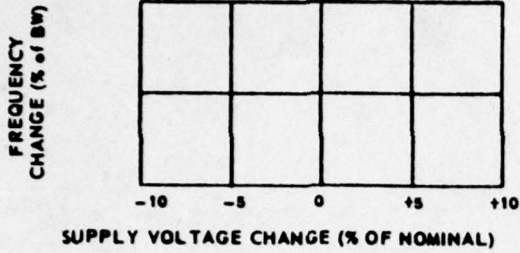
3.10.3.3.7 Express the peak-to-peak frequency deviations as percentages of bandwidth.

3.10.3.3.8 Record data on Data Sheet 3.10.1.

EFFECT OF SUPPLY VOLTAGE VARIATION

LEGEND:

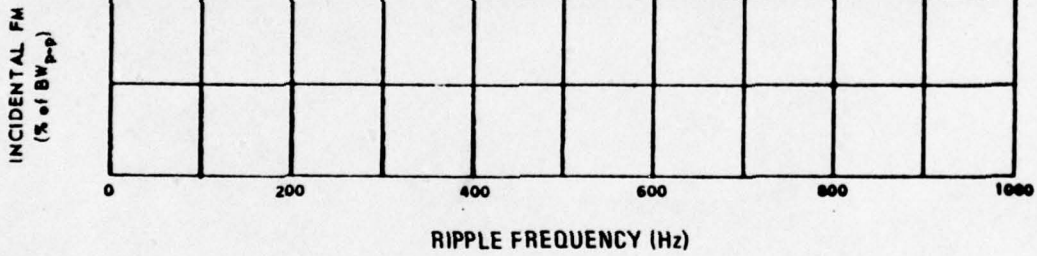
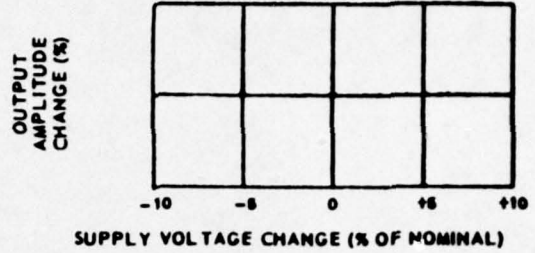
SENSITIVITY \_\_\_\_\_  
REF FREQ - - - - -



NOTE

LEGEND:

BAND CENTER \_\_\_\_\_  
HIGH BAND EDGE - - - - -  
LOW BAND EDGE . . . . .



NOTE

### 3.11 Common-Mode Rejection (For Differential-Input Models Only)

Common-mode rejection is the ratio of subcarrier bandwidth to subcarrier deviations, expressed in dB.

3.11.1 Purpose - This test determines the effect on output frequency resulting from application of a common signal to both input terminals.

#### 3.11.2 Test Equipment:

- A.C. signal source
- A.C. voltmeter (true rms)
- D.C. signal source
- D.C. voltmeter
- Low-noise subcarrier discriminator
- Electronic frequency counter

#### 3.11.3 Test Method:

3.11.3.1 Setup - Connect the test equipment as shown in figure 3.11-1.

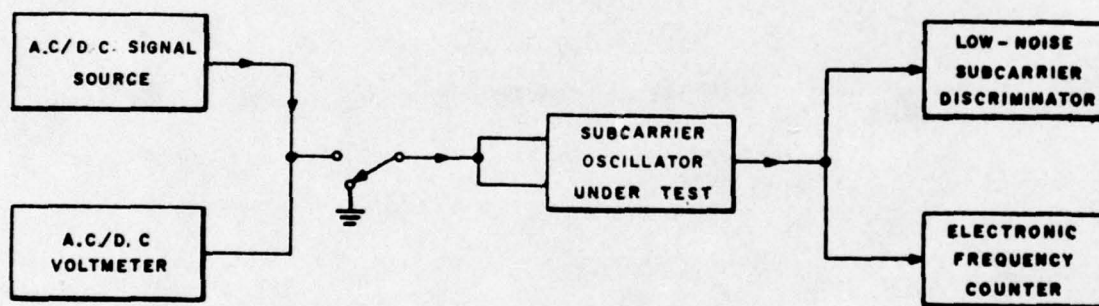


Figure 3.11-1 Common-Mode Rejection.

3.11.3.2 Conditions - Refer to subparagraphs 3.0.2 through 3.0.4.

#### 3.11.3.3 Procedure:

3.11.3.3.1 With the SCO terminals shorted together and connected to ground, measure the subcarrier output frequency.

3.11.3.3.2 Remove the ground applied in subparagraph 3.11.3.3.1 and connect the shorted input terminals to a d.c. voltage (reference to ground) and adjust the d.c. voltage to equal the magnitude of the full-scale differential input recommended by the manufacturer.

3.11.3.3.3 Measure the subcarrier output frequency, first with a positive polarity applied to the input and then with a negative polarity applied to the input.

3.11.3.3.4 Connect an a.c. voltage source to the shorted input terminals and adjust the peak-to-peak amplitude of the a.c. signal to equal the magnitude of the full-scale differential input recommended by the manufacturer.

3.11.3.3.5 Adjust the frequency of the a.c. input signal to that which produces a deviation ratio of 1 for the band under test. Use a low-noise subcarrier discriminator to measure the frequency deviation of the SCO output caused by the common-mode signal. Repeat the measurement at frequencies of 60 Hz and 400 Hz if these frequencies fall within the modulation-frequency range of the SCO under test. The discriminator must be calibrated at each of the modulation frequencies.

3.11.3.3.6 Compare the frequencies measured in step 3.11.3.3.3 with that measured in step 3.11.3.3.1 and calculate the output frequency deviations. Frequency deviations in subparagraph 3.11.3.3.5 are obtained from measuring the output of the calibrated discriminator.

3.11.3.3.8 Record data on Data Sheet 3.11.1.

COMMON-MODE REJECTION

BAND	COMMON-MODE REJECTION (dB)				
	D-C.		A-C. DEVIATION RATIO = 1	A-C.	
	+ D-C.	- D-C.		60 Hz	400 Hz
7					
14					
A					
E					

NOTE

### 3.12 Stability Vs. Temperature

3.12.1 Purpose - This test determines reference-frequency shift, sensitivity variations and output amplitude changes as a function of temperature.

#### 3.12.2 Test Equipment:

- D.C. signal source
- D.C. voltmeter
- Temperature chamber
- A.C. voltmeter (true rms)
- Electronic frequency counter

#### 3.12.3 Test Method:

3.12.3.1 Setup - Connect the test equipment as shown in figure 3.12-1.

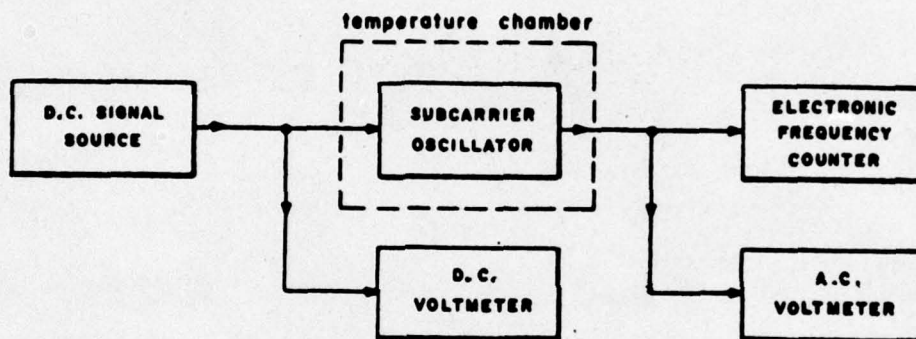


Figure 3.12-1 Stability versus Temperature.

3.12.3.2 Conditions - Refer to subparagraphs 3.0.2 through 3.0.4.

#### 3.12.3.3 Procedure:

3.12.3.3.1 Adjust the temperature chamber to 30°C (303.2K) and allow the SCO to stabilize for not less than 15 minutes.

3.12.3.3.2 Apply the input voltages recommended by the manufacturer to produce output frequencies corresponding to lower band edge, band center and upper band edge. Measure the output frequencies and amplitudes corresponding to each of these inputs.

3.12.3.3.3 Using the same inputs which were applied in step 3.12.3.3.2, repeat the measurements at chamber temperatures corresponding to the appropriate temperature extremes. Allow sufficient time at each temperature for the unit to stabilize before measurements are made.

3.12.3.3.4 Use the frequencies and amplitudes measured at 30°C (303.2 K) as references for calculations and express frequency changes in percent of bandwidth and amplitude changes directly in percent.

3.12.3.3.5 Calculate the reference frequency shift and sensitivity changes. Reference frequency shift is given a positive sign when the output frequency is greater than that measured at the temperature of 30°C (303.2 K). Sensitivity change is given a positive sign when full-scale output excursion is greater than that measured at 30°C (303.2 K).

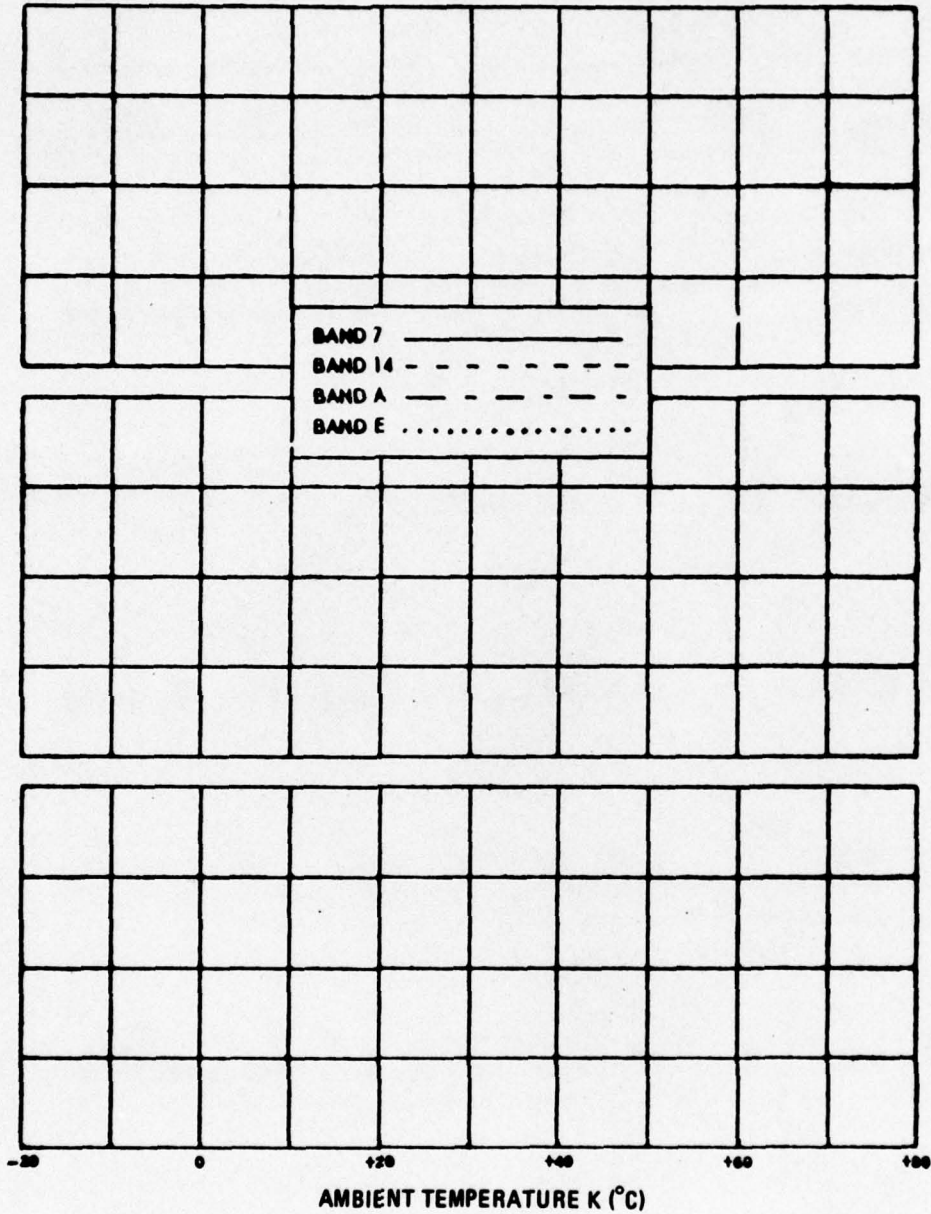
3.12.3.3.6 Record data on Data Sheet 3.12.1.

STABILITY vs TEMPERATURE

REFERENCE FREQUENCY  
INSTABILITY (%)

SENSITIVITY INSTABILITY (%)

OUTPUT AMPLITUDE  
INSTABILITY (%)



NOTE

### 3.13 Effect of Vibration

3.13.1 Purpose - This test determines the effect of vibration on output frequency and output amplitude.

#### 3.13.2 Test Equipment:

D.C. signal source  
Subcarrier discriminator  
Electronic frequency counter  
Vibration facility capable of providing the vibration amplitude/acceleration levels over the frequency ranges specified for the intended application.

#### 3.13.3 Test Method:

3.13.3.1 Setup - Connect the test equipment as shown in figure 3.13-1. The SCO should be securely mounted to the vibrator in a properly designed test fixture which will not impart vibration amplifications to the SCO. If a companion modular rack adapter is used for mounting the SCO in the actual application, the adapter should be included in the vibration setup.

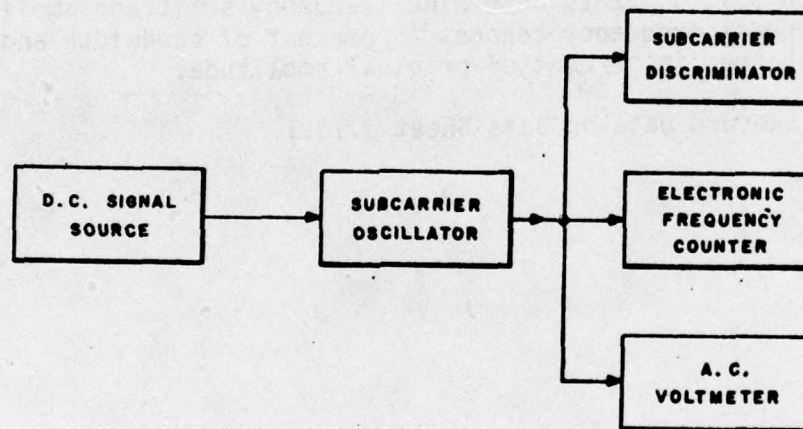


Figure 3.13-1 Effect of Vibration.

3.13.3.2 Conditions - An environment should be selected which is representative of the intended application. This environment could be selected from a standard such as MIL-STD-810. In addition, refer to subparagraphs 3.0.2 through 3.0.4.

3.13.3.3 Procedure:

3.13.3.3.1 Conduct a resonant search in accordance with MIL-STD-810, Method 514.2, to determine the vibration frequencies at which the greatest output frequency and amplitude changes occur.

3.13.3.3.2 Adjust the d.c. signal source to produce band-center frequency. Adjust the output amplitude to maximum and record the amplitude.

3.13.3.3.3 Conduct a resonant dwell in accordance with MIL-STD-810, Method 514.2.

3.13.3.3.4 Observe the output of the subcarrier discriminator to determine the incidental FM caused by vibration.

3.13.3.3.5 Stop the vibration and measure the output frequency and output amplitude. Compare these measurements with those made in subparagraph 3.13.3.3.2 to determine frequency shift and amplitude change. Express frequency changes in percent of bandwidth and express amplitude changes in percent of original amplitude.

3.13.3.3.6 Record data on Data Sheet 3.13.1.

**13. EFFECT OF VIBRATION**

BAND	VIBRATION FREQUENCY (Hz)	INCIDENTAL F-M (%)	FREQUENCY SHIFT (%)	AMPLITUDE CHANGE (%)
7				
14				
A				
E				

NOTE

## Chapter 4

### BIT SYNCHRONIZERS

#### 4.0 General

In the series of test procedures which follow, the PCM test set is the central feature of the test setups. Commercially available telemetry PCM test sets usually incorporate the IRIG Standard PN sequence with self-synchronized PN receiver function. These sets vary somewhat as to criteria for receiver PN lock, the restart function, and such special functions as addition of base-band noise and offset, frequency modulation of internal clock, variable delay of clock and bit stream, phase comparison of input and output bit clocks, etc. Depending upon which PCM test set is available, certain external functions such as gating and delay may be required for the bit slippage and acquisition tests. Detailed circuits for these functions are given in appendixes IV-B and IV-C. Figure 4.0-1 is a generalized block diagram of functions which can be utilized to perform the tests herein.

#### NOTE

*Since, as stated above, not all commercial models incorporate all of the functions internally, it may be necessary to perform some of these functions by the use of peripheral equipment.*

Because the full capability of the test set will not be required in any single test procedure, the full functional block diagram (figure 4.0-1) will not be repeated; only simplified block diagrams will be included with each individual test procedure. It may not be necessary to conduct all of the tests described in this chapter for any one bit synchronizer if it is used for a specific application. The test procedures are presented in two parts: Part I, Testing with Gaussian Noise; and Part II, PCM/FM Testing. Definitions for bit slippage probability (BSP) and acquisition testing are given in appendix IV-C.

#### 4.0.1 Standard Test Conditions for Testing with Gaussian Noise

The following discussion applies to preparing standard test conditions for Part I, Testing with Gaussian Noise. Regardless of the test approach used, it is important to preserve uniformity of testing so that valid comparisons and evaluations of a wide range of system designs may be accomplished. Therefore, the following standard test conditions should be determined for the following parameters and should be observed unless the individual test description requires otherwise. It is assumed that

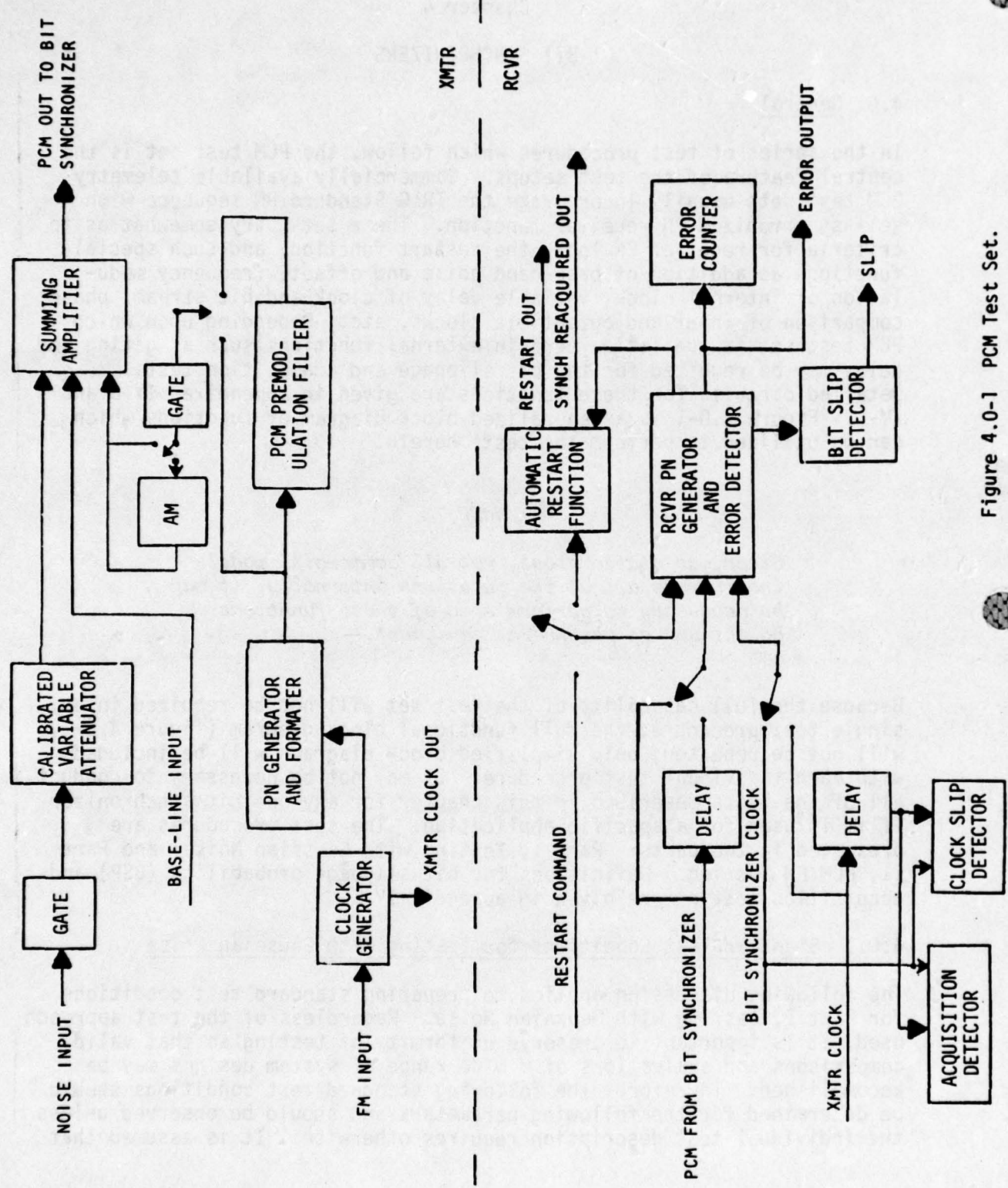


Figure 4.0-1 PCM Test Set.

the instruction manual for the test set is available, therefore, instructions for operating the test set will not be repeated in the individual test procedures.

#### 4.0.1.1 Bit Synchronizer:

PCM signal input level  
Bit rate  
Loop width  
Tracking bandwidth  
Bit detector type of clock (internal)  
Input code

#### 4.0.1.2 PCM Test Set:

Offset  
FM input  
Code  
Pattern                    Pseudo random:  
                              Use of the 2047-bit maximal length sequence is  
                              recommended. See Chapter 2, subparagraph 2.1.1.3.2  
                              for details.

#### NOTE

*Testing with fixed patterns may be necessary for specific applications.*

Bit rate clock

#### NOTE

*A PCM test set may possess two characteristics which must be checked before conducting bit synchronizer performance tests. The internal reference clock may contain excessive jitter components and the accuracy of the bit rate switch settings may be inadequate. When excessive clock jitter exists, it is recommended that an external reference clock be used; particularly when testing bit synchronizers with narrow loop bandwidth settings. The bit rate of the PCM output may be adjusted using one of the following methods:*

**METHOD 1:**

*Connect a variable d.c. voltage source to the FM input of the PCM test set and adjust the voltage until the required bit rate is obtained.*

**METHOD 2:**

*Adjust the bit rate on the PCM test set until the desired bit rate is indicated on a frequency counter. Disregard the bit rate indicated by the PCM test set display when using this method.*

**METHOD 3:**

*Connect an external clock generator to the external clock input of the PCM test set. Measure the bit rate at the clock output of the PCM test set with a frequency counter.*

**NOTE**

*Measures should be taken to assure that phase errors are not introduced by the test setup, e.g., when the setup includes a premodulation filter. Measurement difficulties may occur when detection circuitry is phase sensitive.*

**4.0.1.3 Premodulation Filter**

Filter type	-	linear-phase, low-pass
Cutoff frequency (-3 dB)	-	0.75 times the bit rate, or as required

**4.0.1.4 Noise Signal - gaussian**

**4.0.1.5 Noise Signal Filter:**

Type	-	constant amplitude ( $\geq 4$ pole)
Cutoff frequency (-3 dB) for calibration	-	equal to the bit rate

**4.0.2 Standard Test Conditions for PCM/FM Testing**

The following parameters must be added to the standard test conditions in subparagraph 4.0.1 for preparing the standard test conditions for Part II, PCM/FM testing.

#### 4.0.2.1 FM Test Link:

Frequency deviation	-	Peak-to-peak
Predetection (IF) bandwidth	-	3-dB points, kHz
Post detection bandwidth	-	3-dB points, kHz

4.0.2.2 Figures 4.0.2-1 and 4.0.2-2 are block diagrams of the PCM/FM test setup. Two options are shown. Figure 4.0.2-1 makes use of equipment normally used in connection with predetection recording. The band-pass filter (BPF) shown in figure 4.0.2-1 is used to confine the noise bandwidth to the neighborhood of the predetection band of the discriminator to prevent overloading the input circuits. The bandwidth of the BPF should be set to approximately twice the bandwidth of the discriminator and centered on the band of the discriminator. Figure 4.0.2-2 makes use of RF equipment.

#### 4.1 Part I. Testing with Gaussian Noise

Part I describes the test procedures to be used to determine if a selected bit synchronizer has the required characteristics essential for telemetry applications when the input signal contains additive gaussian noise.

##### 4.1.1 PCM Test Set Calibration

4.1.1.1 Purpose - The SNR is an important parameter in many of the performance tests conducted on PCM bit synchronizers. Calibration of the PCM test set is necessary for obtaining an accurate SNR to allow comparison of performance in satisfying performance specifications or evaluating competing designs.

##### 4.1.1.2 Test Equipment:

###### 4.1.1.2.1 Procedure 1:

Noise source - a flat frequency response from d.c. to > five times the bit rate

Premodulation filter - as required

Low-pass filter - cutoff frequency settable to the bit rate

True rms voltmeter

Oscilloscope

Frequency counter

Stable oscillator - as required

PCM test set

4.1.1.2.2 Procedure 2 - Same as Procedure 1 test equipment except replace PCM test set with summing amplifier and calibrated attenuator.

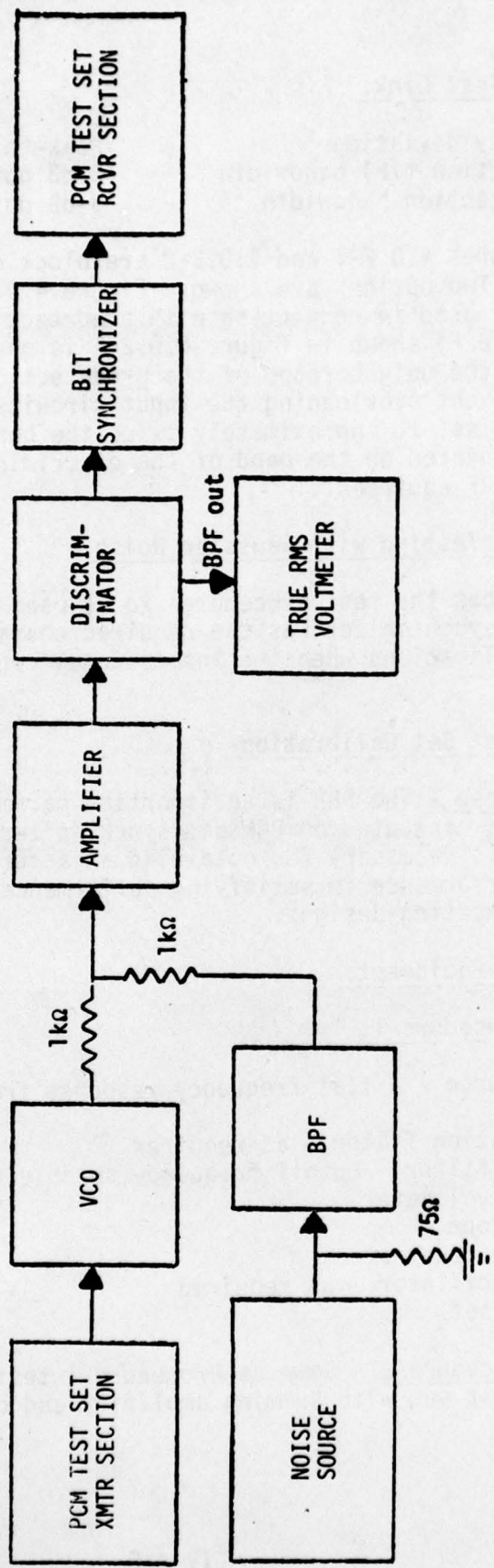


Figure 4.0.2-1 Test Setup Using Predetection Carrier Frequencies.

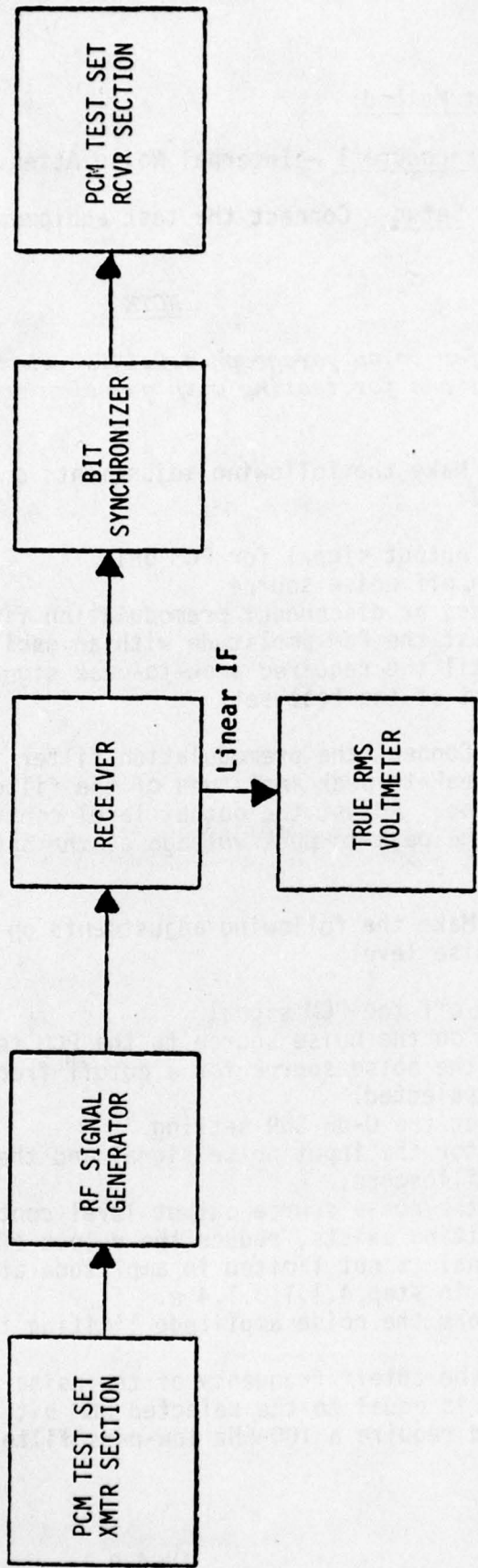


Figure 4.0.2-2 Test Setup Using Signal Generator and Receiver.

4.1.1.3 Test Method:

4.1.1.3.1 Procedure 1 - Internal Noise Attenuator

4.1.1.3.1.1 Setup - Connect the test equipment as shown in figure 4.1.1-1.

NOTE

*Refer to subparagraph 4.0.1 for standard test conditions for testing with gaussian noise.*

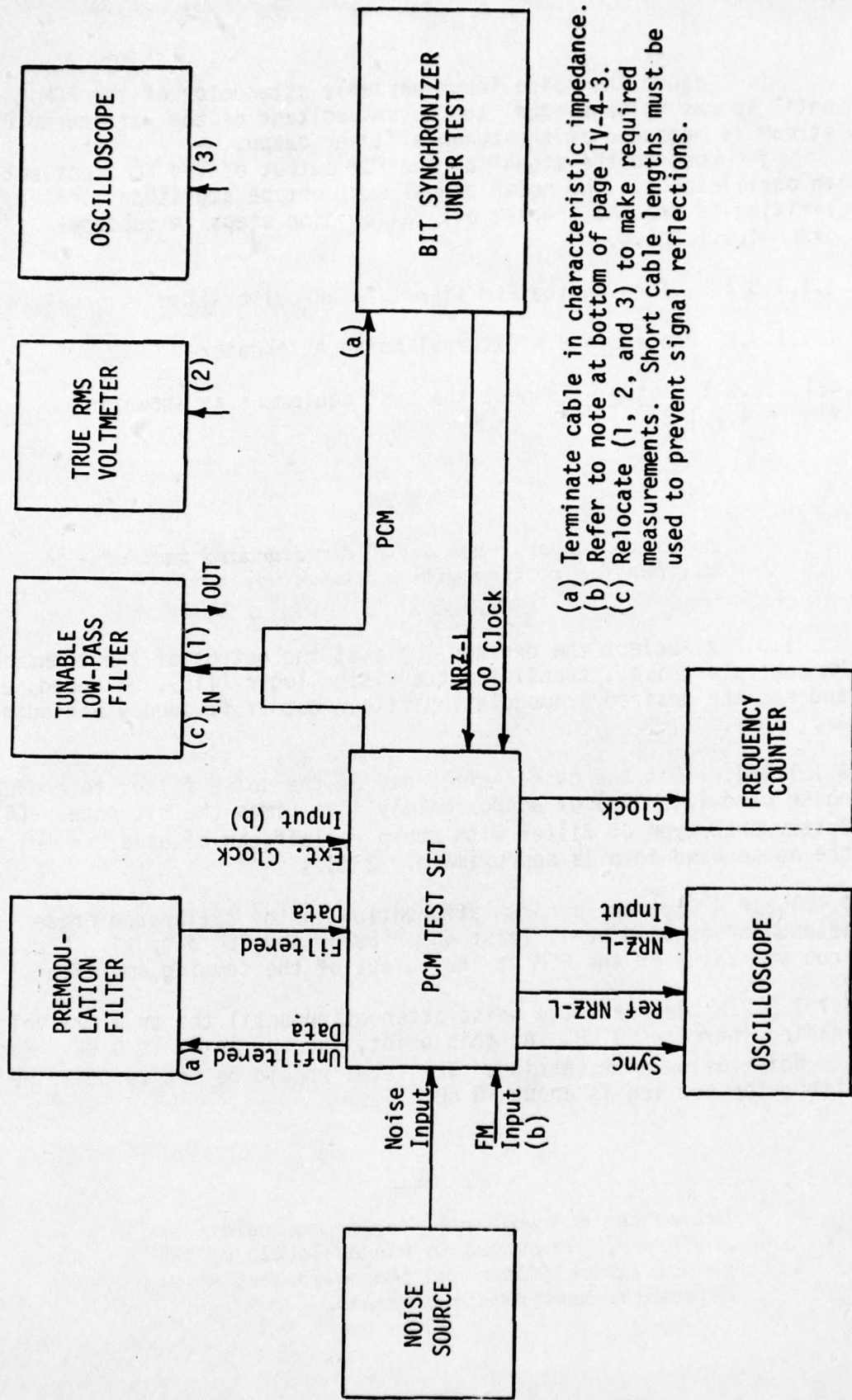
4.1.1.3.1.2 Make the following adjustments on the PCM test set to set the PCM level:

- a. Set output signal for PCM only
- b. Turn off noise source
- c. Bypass or disconnect premodulation filter
- d. Adjust the PCM amplitude with an oscilloscope or true rms voltmeter until the required peak-to-peak signal voltage is measured at the PCM output of the test set.

4.1.1.3.1.3 Connect the premodulation filter into the test setup. Observe the peak-to-peak amplitude of the filtered PCM bit stream with an oscilloscope. Adjust the output level control on the tunable filter to maintain the peak-to-peak voltage of the signal as established in step 4.1.1.3.1.2 d.

4.1.1.3.1.4 Make the following adjustments on the PCM test set to obtain the noise level:

- a. Turn off the PCM signal
- b. Turn on the noise source to the PCM test set
- c. Set the noise source for a cutoff frequency equal to five times the bit rate selected.
- d. Select the 0-dB SNR setting.
- e. Monitor the input noise signal and the PCM output of the test set on an oscilloscope.
- f. Set the noise source output level control to maximum. If noise amplitude limiting exists, reduce the output of the noise source until the noise signal is not limited in amplitude at either monitoring point as referenced in step 4.1.1.3.1.4 e.
- g. Perform the noise amplitude limiting test for each bit rate selected.
- h. Set the cutoff frequency of the noise source low-pass filter to a value which is equal to the selected PCM bit rate, e.g., a 100 kb/s bit rate would require a 100-kHz low-pass filter setting.



- (a) Terminate cable in characteristic impedance.
- (b) Refer to note at bottom of page IV-4-3.
- (c) Relocate (1, 2, and 3) to make required measurements. Short cable lengths must be used to prevent signal reflections.

Figure 4.1.1-1 Calibration of PCM Test Set with Internal Noise Attenuator.

i. Adjust the noise input variable attenuator of the PCM test set until an rms voltage equal to the rms voltage of the unfiltered PCM bit stream is measured at the tunable filter output.

j. Observe the signal at the PCM output of the PCM test set with an oscilloscope. The noise signal must not be amplitude limited. If limiting is present, repeat all calibration steps in subparagraph 4.1.1.3.1.4.

4.1.1.3.1.5 Turn on the PCM signal. SNR calibration is complete.

4.1.1.3.2 Procedure 2 - External Noise Attenuator

4.1.1.3.2.1 Setup - Connect the test equipment as shown in figure 4.1.1-2.

NOTE

*Refer to subparagraph 4.0.1 for standard test conditions for testing with gaussian noise.*

4.1.1.3.2.2 Select the desired logic at the output of the transmitter PN generator, i.e., transistor-transistor logic (TTL), balanced, etc., and set the desired premodulation filter cutoff frequency and output amplitude.

4.1.1.3.2.3 Set the cutoff frequency of the noise filter to produce a noise bandwidth ( $B_n$ ) of approximately five times the bit rate. (A Butterworth type of filter with sharp rolloff can be used, in which case the noise bandwidth is approximately 3 dB.)

4.1.1.3.2.4 Set the maximum attenuation in the calibrated noise attenuator (should be at least 40 dB below the PCM output). Measure the true rms value of the PCM at the output of the summing amplifier.

4.1.1.3.2.5 Decrease the noise attenuation until the true rms voltmeter reading increases 3 dB. At this point, the SNR in  $B_n$  is 0 dB. Record the noise attenuator setting. The level should be set so that the noise attenuator setting is about 10 dB.

NOTE

*Unless the summing amplifier is an operational amplifier, the output impedance levels of the premodulation filter and the calibrated noise attenuator must remain constant.*

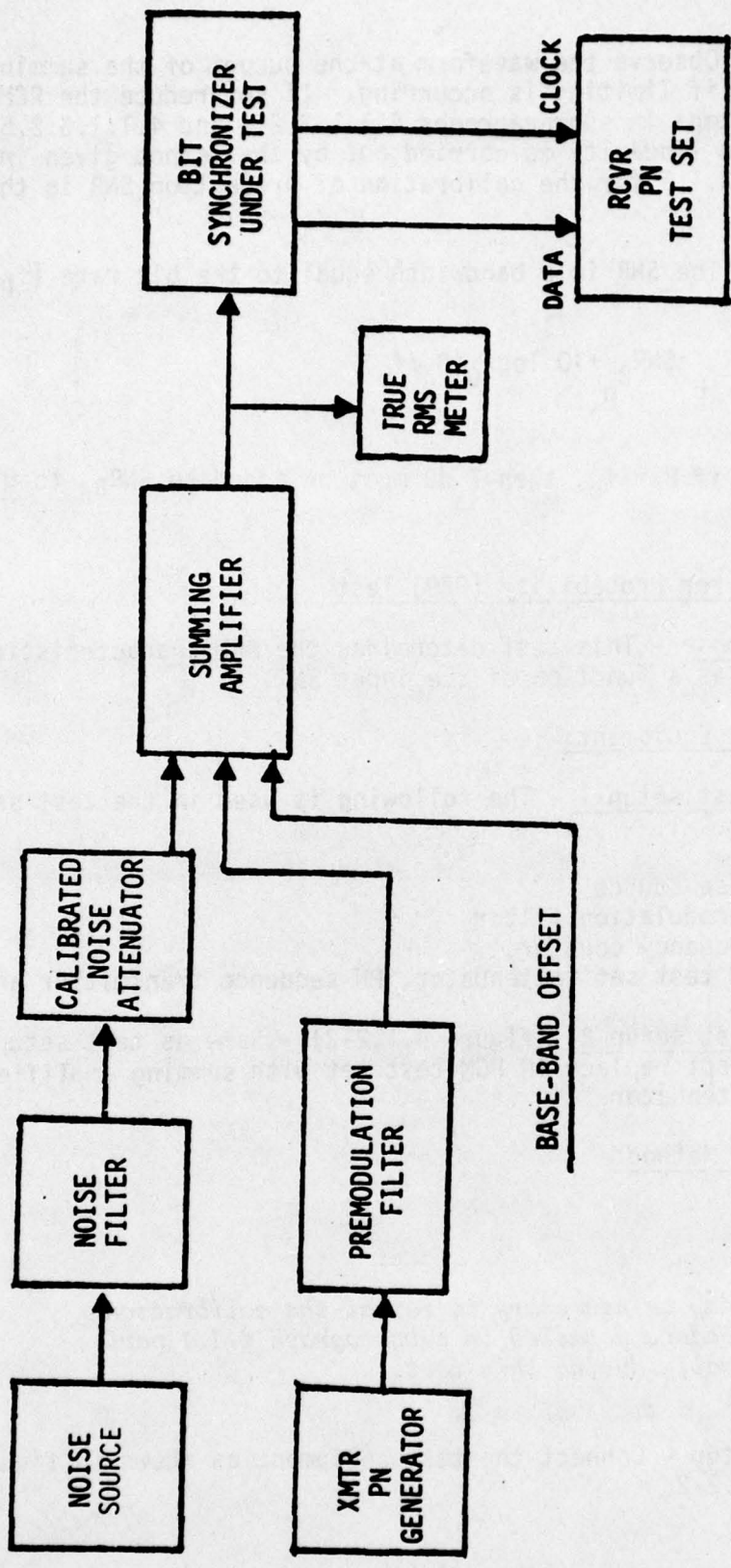


Figure 4.1.1-2 SNR Calibration for the Case in which the Noise Attenuator and Summing Amplifier are External to the PCM Test Set.

4.1.1.3.2.6 Observe the waveform at the output of the summing amplifier to determine if limiting is occurring. If so, reduce the PCM level and repeat the steps in subparagraphs 4.1.1.3.2.4 and 4.1.1.3.2.5. A further check in linearity is carried out by the method given in subparagraph 4.2.1.3.1.5 for the calibration of predetection SNR in the PCM/FM tests.

4.1.1.3.2.7 The SNR in a bandwidth equal to the bit rate ( $f_b$ ) is given in dB by

$$\text{SNR}_{f_b} = \text{SNR}_{B_n} + 10 \log_{10}(B_n/f_b)$$

For example, if  $B_n = 5f_b$ , then 7 dB must be added to  $\text{SNR}_{B_n}$  to give  $\text{SNR}_{f_b}$ .

#### 4.1.2 Bit Error Probability (BEP) Test

4.1.2.1 Purpose - This test determines the BEP characteristics of a bit synchronizer as a function of the input SNR.

#### 4.1.2.2 Test Equipment:

4.1.2.2.1 Test setup 1 - The following is used in the test setup shown in figure 4.1.2-1.

Noise source  
Premodulation filter  
Frequency counter  
PCM test set (attenuator, PN sequence transmitter and receiver)

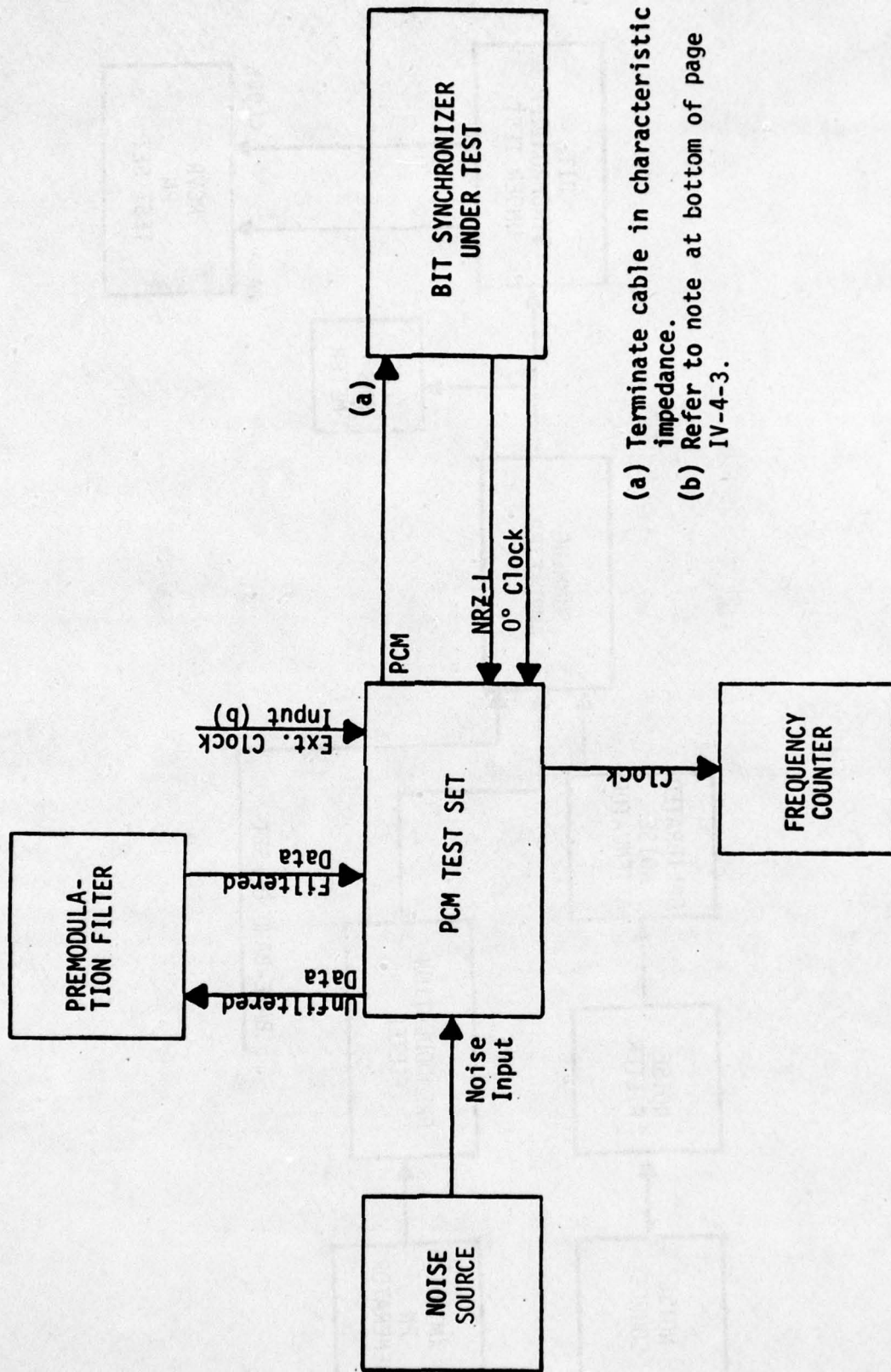
4.1.2.2.2 Test setup 2 (figure 4.1.2-2) - Same as test setup 1 test equipment except replace PN PCM test set with summing amplifier and calibrated attenuator.

#### 4.1.2.3 Test Method:

##### NOTE

*It may be necessary to repeat the calibration procedure detailed in subparagraph 4.1.1 periodically during this test.*

4.1.2.3.1 Setup - Connect the test equipment as shown in figure 4.1.2-1 or figure 4.1.2-2.



(a) Terminate cable in characteristic impedance.  
 (b) Refer to note at bottom of page IV-4-3.

Figure 4.1.2-1 Bit Error Probability Test Setup.

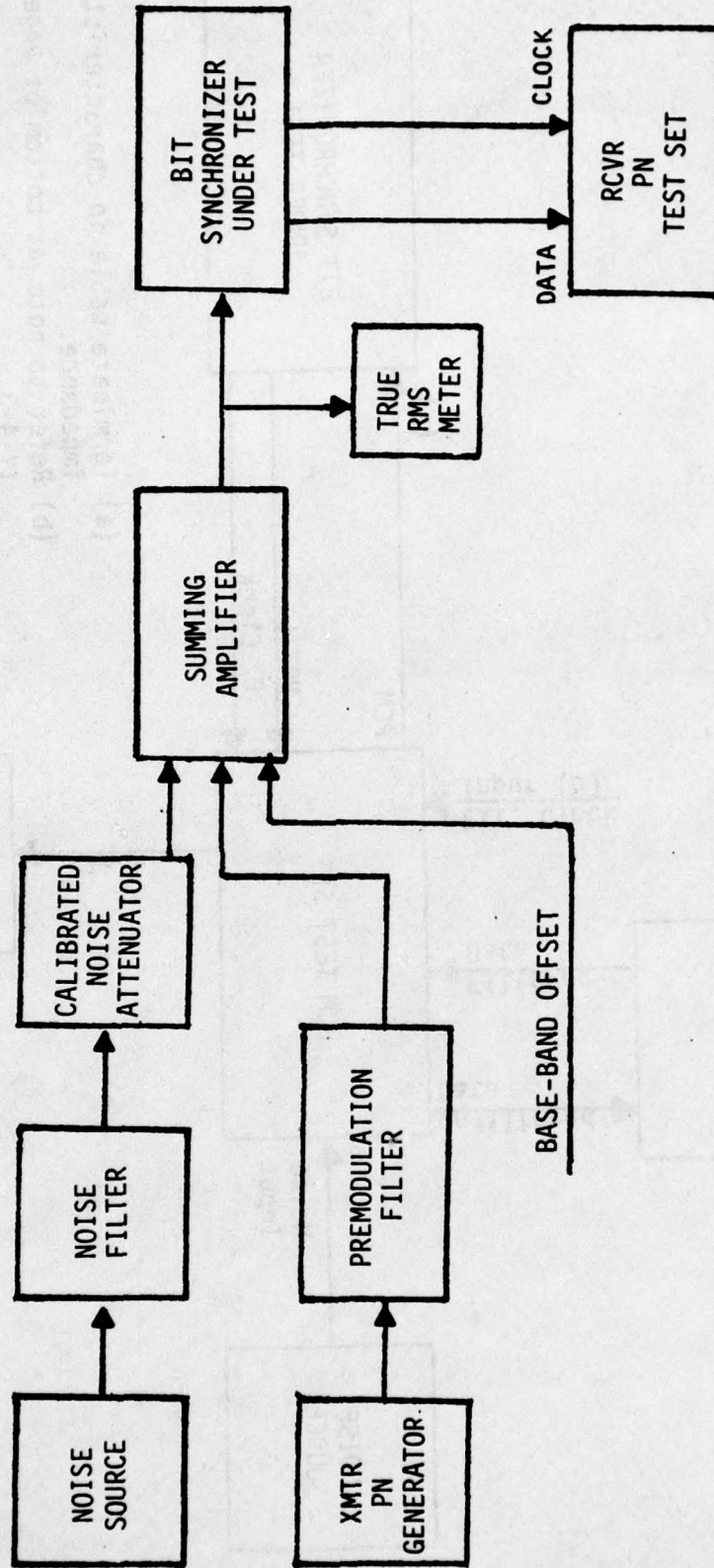


Figure 4.1.2-2 Bit Error Probability Test Setup for the Case in which the Noise Attenuator and Summing Amplifier are External to the PCM Test Set.

NOTE

*Refer to subparagraph 4.0.1 for standard test conditions for testing with gaussian noise.*

4.1.2.3.2 Calibrate the test setup for output SNR in accordance with the calibration instructions detailed in subparagraph 4.1.1.

4.1.2.3.3 Adjust the test set to measure bit errors in the measurement intervals shown on Data Sheet 4.1.2.1.

4.1.2.3.4 Set the test setup for an output SNR of 0 dB and measure total bit errors (sum of the 1s and 0s in error). It may be desirable to individually measure the 1s in error and the 0s in error to determine the performance symmetry of the bit synchronizer. Calculate and record the BEP from the relationship:

$$\text{BEP} = \frac{\text{Number of Bit Errors Measured}}{\text{Number of Bits Transmitted During Measurement Interval}}$$

Repeat the measurement of bit errors and BEP calculations for the other values of SNR shown on Data Sheet 4.1.2.1.

4.1.2.4 Data Reduction: - Record data on Data Sheet 4.1.2.1. An example of Data Sheet 4.1.2.1 use is shown in figure 4.1.2-3 and a corresponding sample data plot is shown in figure 4.1.2-4.

DATA SHEET 4.1.2.1 BIT ERROR PROBABILITY TEST

Test: 4.1.2 Bit Error Probability Test

Manufacturer \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

**SAMPLE DATA**  
**NOT TO BE USED FOR**  
**EQUIPMENT SPECIFICATIONS**

Bit Synchronizer Input Signal Conditions						
PCM Signal				Noise Signal (Gaussian)		Premodulation Filter
Bit Rate (kB/s)	Amplitude (V <sub>p-p</sub> )	Code	Word Pattern	Cal. B.W. (kHz)	Cal. (V rms)	Cutoff Freq. (kHz)
100	1.0	NRZ-L	PR	100	0.5	75

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)
F/S	0.1	1.0

SNR (dB)	Bit Error Probability			Measurement Interval * (Period 10 <sup>N</sup> Bits)
	Total (1's + 0's)	1's	0's	N
0	1.1 x 10 <sup>-1</sup>	5.3 x 10 <sup>-2</sup>	5.5 x 10 <sup>-2</sup>	5
+3	4.2 x 10 <sup>-2</sup>	2.0 x 10 <sup>-2</sup>	2.2 x 10 <sup>-2</sup>	5
+6	8.7 x 10 <sup>-3</sup>	4.0 x 10 <sup>-3</sup>	4.7 x 10 <sup>-3</sup>	5
+9	6.4 x 10 <sup>-4</sup>	2.6 x 10 <sup>-4</sup>	3.8 x 10 <sup>-4</sup>	6
+12	9.9 x 10 <sup>-6</sup>	1.9 x 10 <sup>-6</sup>	5.4 x 10 <sup>-6</sup>	8

\*Refer to Volume IV, Appendix IV-A for detailed explanation.

Figure 4.1.2-3 Sample of Data Sheet 4.1.2.1.

BIT ERROR PROBABILITY  
VERSUS  
SIGNAL-TO-NOISE RATIO

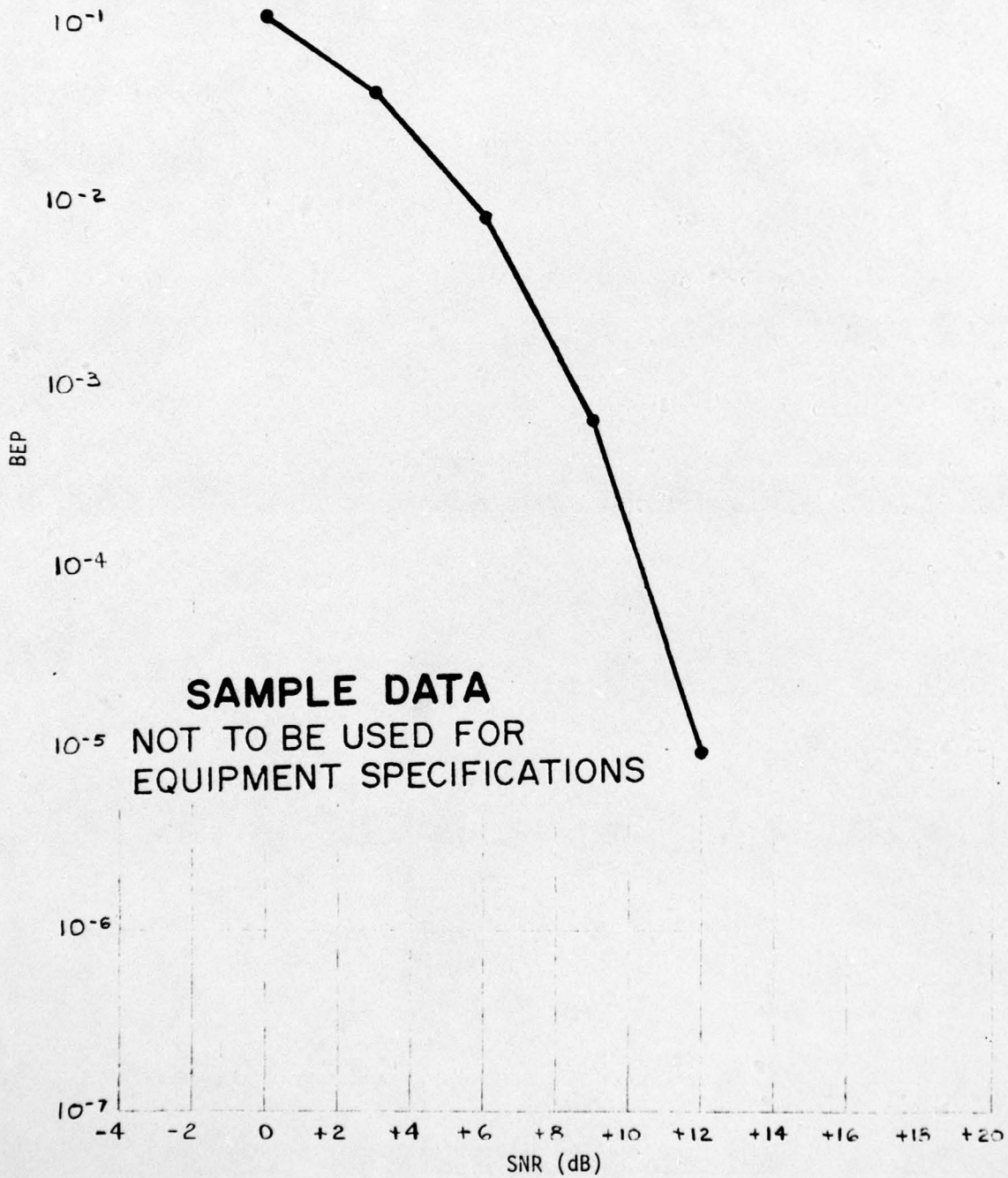


Figure 4.1.2-4 Sample Data Plot Presentation of Data Sheet 4.1.2.1.

DATA SHEET 4.1.2.1 BIT ERROR PROBABILITY TEST

Test: 4.1.2 Bit Error Probability Test

Manufacturer \_\_\_\_\_ Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_,

Date \_\_\_\_\_

Bit Synchronizer Input Signal Conditions						
PCM Signal				Noise Signal (Gaussian)		Premodulation Filter
Bit Rate (kB/s)	Amplitude (V <sub>p-p</sub> )	Code	Word Pattern	Cal. B.W. (kHz)	Cal. (V rms)	Cutoff Freq. (kHz)

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Trackng Range (% Bit Rate)

SNR (dB)	Bit Error Probability			Measurement Interval * (Period 10 <sup>N</sup> Bits)
	Total (1's + 0's)	1's	0's	N
0				5
+3				5
+6				5
+9				6
+12				8

\*Refer to Volume IV, Appendix IV-A for detailed explanation.

### 4.1.3 Bit Slippage Probability (BSP) Test

4.1.3.1 Purpose - This test determines the BSP characteristics of a bit synchronizer as a function of the input SNR. There are two basic procedures given here for this test. Laboratory tests comparing the two procedures indicate that both agree to within the limits of measurement error. The choice of procedure will depend primarily on the test equipment available. Procedure 1 compares the phase of the reference clock with the phase of the bit synchronizer output clock. If the phase difference exceeds  $\pm 360^\circ$ , bit slippage has occurred.

#### NOTE

*In some commercially available PCM test sets which are internally mechanized for this test, the criterion is  $\pm 180^\circ$ . Although it is possible for the instantaneous phase to exceed  $180^\circ$  and then, because of additional perturbation, to pull back without slippage, tests have shown that the phase is most likely to subsequently exceed  $\pm 360^\circ$ , thus producing bit slippage.*

Procedure 2 uses the loss of PCM test set synchronization to indicate slippage.

#### 4.1.3.2 Test Equipment:

##### 4.1.3.2.1 Procedure 1:

Noise source  
Premodulation filter  
Frequency counter  
PCM test set

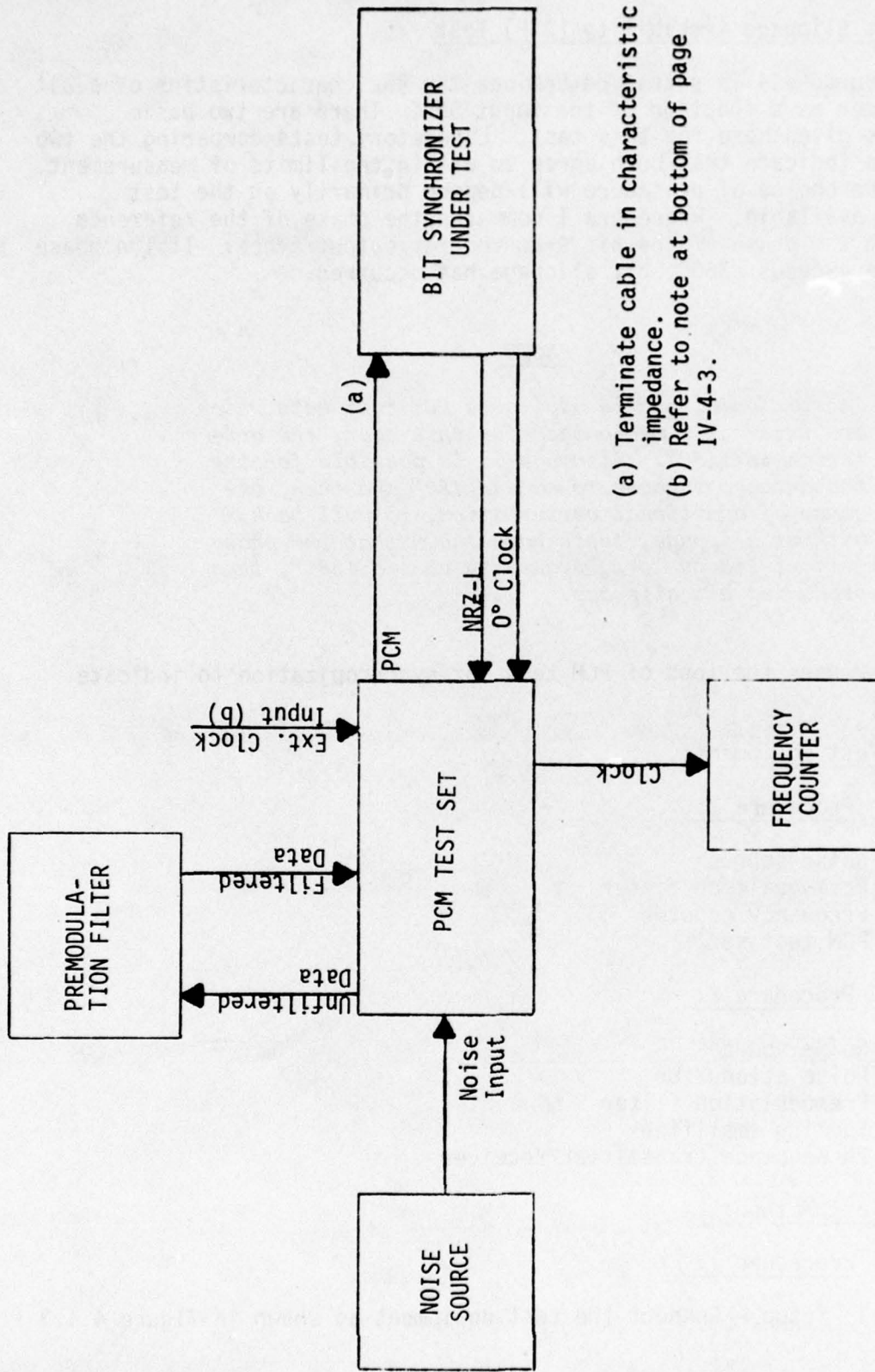
##### 4.1.3.2.2 Procedure 2:

Noise source  
Noise attenuator  
Premodulation filter  
Summing amplifier  
PN sequence transmitter/receiver

#### 4.1.3.3 Test Method:

##### 4.1.3.3.1 Procedure 1:

4.1.3.3.1.1 Setup - Connect the test equipment as shown in figure 4.1.3-1.



- (a) Terminate cable in characteristic impedance.
- (b) Refer to note at bottom of page IV-4-3.

Figure 4.1.3-1 Bit Slippage Probability Test Setup for Procedure 1.

NOTE

*Refer to subparagraph 4.0.1 for standard test conditions for testing with gaussian noise.*

4.1.3.3.1.2 Calibrate the PCM test set for an output SNR in accordance with the calibration instructions detailed in subparagraph 4.1.1.

4.1.3.3.1.3 Adjust the PCM test set to measure bit (clock) slips for the measurement intervals shown on Data Sheet 4.1.3.1.

4.1.3.3.1.4 Set the PCM test set for an output SNR of 0 dB, and measure the total number of bit (clock) slips (both plus and minus). It may be desirable to individually measure the plus slips and the minus slips to show performance trends. Most bit synchronizer designs exhibit a tendency to slip only in one direction rather than randomly. Calculate the BSP from the relationship:

$$BEP = \frac{\text{Number of Bit Slips Measured}}{\text{Number of Bits Transmitted During Measurement Interval}}$$

4.1.3.3.1.5 Repeat the measurement of bit slips and calculation of BSP for the other SNRs shown on Data Sheet 4.1.3.1.

4.1.3.3.2 Procedure 2:

4.1.3.3.2.1 Setup - Connect the test equipment as shown in figure 4.1.3-2.

NOTE

*Refer to subparagraph 4.0.1 for standard test conditions for testing with gaussian noise.*

4.1.3.3.2.2 Calibrate the test setup for output SNR in accordance with the calibration instructions.

4.1.3.3.2.3 Adjust the test set to count the number of restarts in the measurement intervals shown on Data Sheet 4.1.3.1. A restart is defined as a valid resynchronization of the receiver PN generator to the data.

4.1.3.3.2.4 Set the test setup for an SNR of 9 dB and count the number of restarts. Calculate the BSP from the relationship:

$$BSP = \frac{\text{Number of Restarts Counted}}{\text{Number of Bits Transmitted During Measurement Interval}}$$

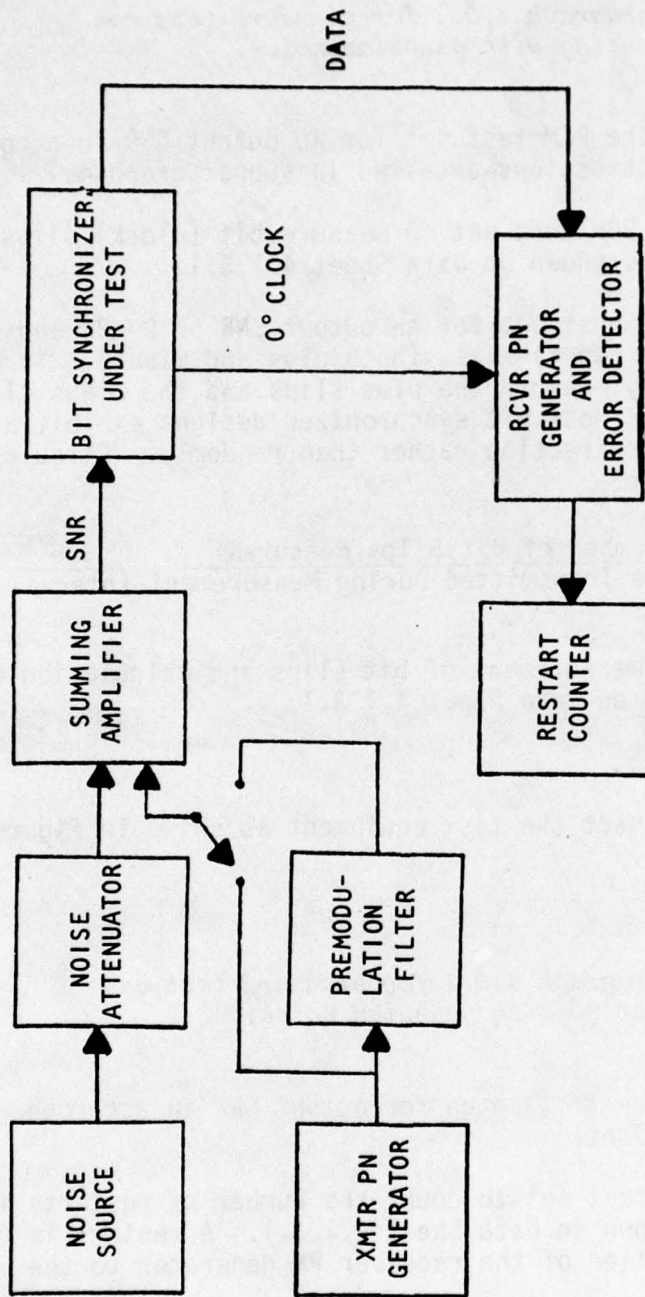


Figure 4.1.3-2 Bit Slippage Probability Test Setup for Procedure 2.

4.1.3.3.2.5 Repeat the count of restarts and calculation of BSP for the other SNRs shown on Data Sheet 4.1.3.1.

NOTE

*At high BEP, the number of restarts measured will be too large because unsuccessful tries are counted and because in some test sets it is also possible for errors to trigger the restart without slippage. The counts of synchronization reacquired will give results closer to the true value. Generally, the "plus slips" and "minus slips" count is not a reliable estimate of the number of restarts.*

4.1.3.4 Data Reduction - Record data on Data Sheet 4.1.3.1. An example of Data Sheet 4.1.3.1 use is shown in figure 4.1.3-3 and a corresponding sample data plot is shown in figure 4.1.3-4.

DATA SHEET 4.1.3.1 BIT SLIPPAGE PROBABILITY

Test: 4.1.3 Bit Slippage Probab'

Manufacturer \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

**SAMPLE DATA**  
**NOT TO BE USED FOR**  
**EQUIPMENT SPECIFICATIONS**

Bit Synchronizer Input Signal Conditions						
PCM Signal				Noise Signal (Gaussian)		Premodulation Filter
Bit Rate (kB/s)	Amplitude (V <sub>p-p</sub> )	Code	Word Pattern	Cal. B.W. (kHz)	Cal. (V rms)	Cutoff Freq. (kHz)
100	1.0	NRZ-L	PR	100	0.5	75

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)
F/S	1.0	10.0

SNR (dB)	Bit Slippage Probability			Measurement Interval * (Period 10 <sup>N</sup> Bits)
	TOTAL (+ and -)	+	-	
0	9.07 x 10 <sup>-2</sup>	3.0 x 10 <sup>-6</sup>	9.04 x 10 <sup>-2</sup>	7
+3	2.91 x 10 <sup>-2</sup>	4.8 x 10 <sup>-5</sup>	2.90 x 10 <sup>-2</sup>	7
+6	2.42 x 10 <sup>-5</sup>	6.0 x 10 <sup>-7</sup>	2.0 x 10 <sup>-5</sup>	7
+9	< 1 x 10 <sup>-7</sup>	< 1 x 10 <sup>-7</sup>	< 1 x 10 <sup>-7</sup>	7
+12	< 1 x 10 <sup>-7</sup>	< 1 x 10 <sup>-7</sup>	< 1 x 10 <sup>-7</sup>	7
+15	< 1 x 10 <sup>-7</sup>	< 1 x 10 <sup>-7</sup>	< 1 x 10 <sup>-7</sup>	7

\*A measurement interval of 1 x 10<sup>7</sup> bits will provide reliable data measurement repeatability for BSP ≥ 1 x 10<sup>-6</sup>.

*NOTE: Additional measurements may be required where the slope of the data changes abruptly.*

Figure 4.1.3-3 Sample of Data Sheet 4.1.3.1.

BIT SLIPPAGE PROBABILITY  
VERSUS  
SIGNAL-TO-NOISE RATIO

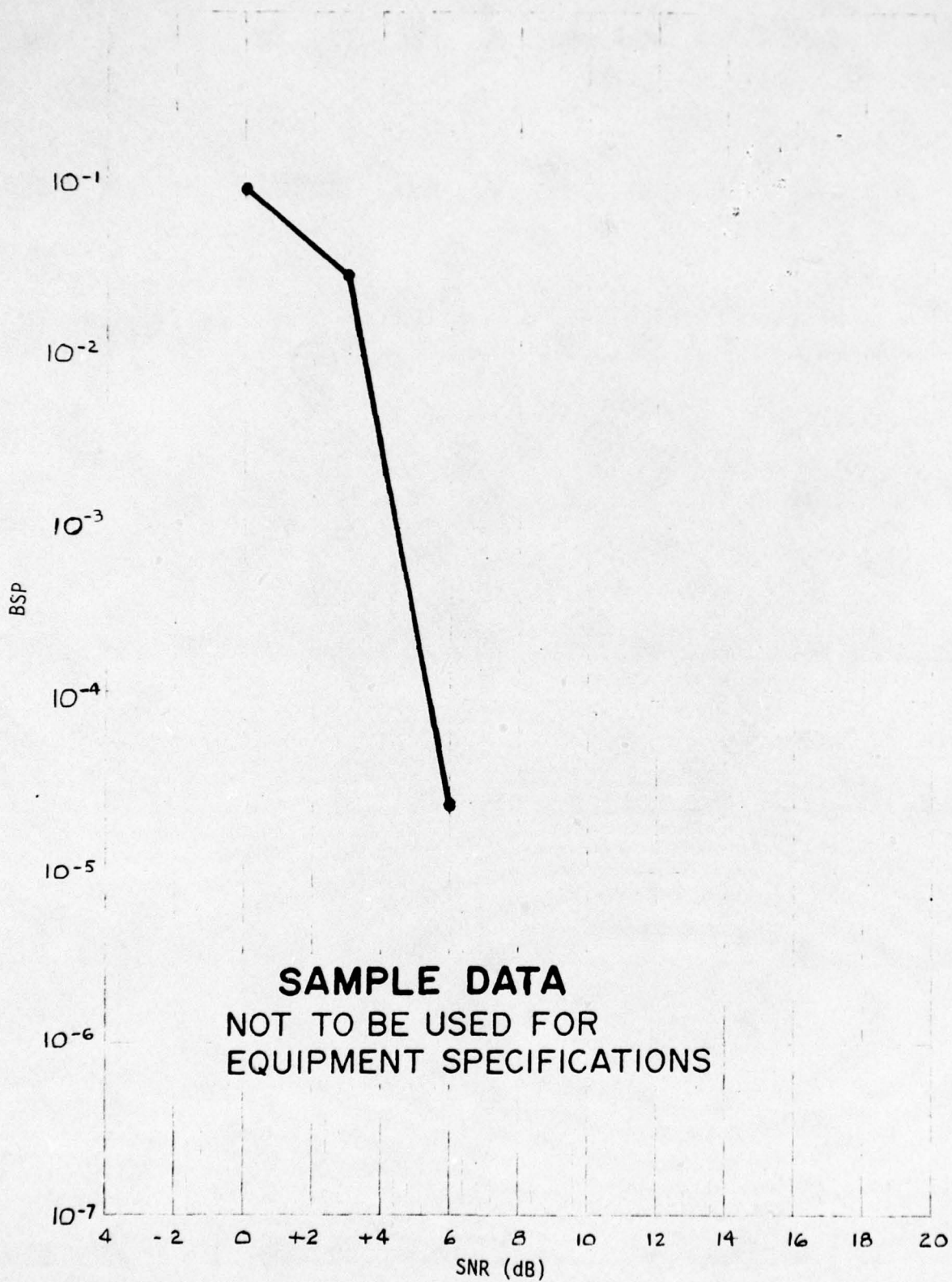


Figure 4.1.3-4 Sample Plot Presentation of Data Sheet 4.1.3.1.

Test: 4.1.3 Bit Slippage Probability

Manufacturer \_\_\_\_\_ Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

Bit Synchronizer Input Signal Conditions						
PCM Signal				Noise Signal (Gaussian)		Premodulation Filter
Bit Rate (kB/s)	Amplitude (V <sub>p-p</sub> )	Code	Word Pattern	Cal. B.W. (kHz)	Cal. (V rms)	Cutoff Freq. (kHz)

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)

SNR (dB)	Bit Slippage Probability			Measurement Interval * (Period 10 <sup>N</sup> Bits)
	TOTAL (+ and -)	+	-	
0				7
+3				7
+6				7
+9				7
+12				7
+15				7

\*A measurement interval of  $1 \times 10^7$  bits will provide reliable data measurement repeatability for  $BSP \geq 1 \times 10^{-6}$ .

NOTE: Additional measurements may be required where the slope of the data changes abruptly.

#### 4.1.4 Acquisition Test

4.1.4.1 Purpose - This test determines the average number of bit periods required to achieve clock synchronization (ACQ) from the time data is applied. There are two procedures given for this test. Laboratory tests have shown that the results obtained using either procedure are in agreement to within the error bounds. The choice of procedure will depend mainly on the test equipment available. Procedure 1 compares the phase of the reference clock with the phase of the bit synchronizer output clock. When the phase difference remains within a range, such as  $\pm 90^\circ$ , acquisition is achieved. Procedure 2 uses the drop of BEP from 0.5 to the value characteristic of the input SNR.

#### 4.1.4.2 Test Equipment:

##### 4.1.4.2.1 Procedure 1:

- Noise source
- Premodulation filter
- Frequency counter
- PCM test set

##### 4.1.4.2.2 Procedure 2:

- Noise source
- Summing amplifier
- PCM data
- Digital delay
- Oscilloscope
- PN sequence transmitter/receiver

#### 4.1.4.3 Test Method:

##### 4.1.4.3.1 Procedure 1:

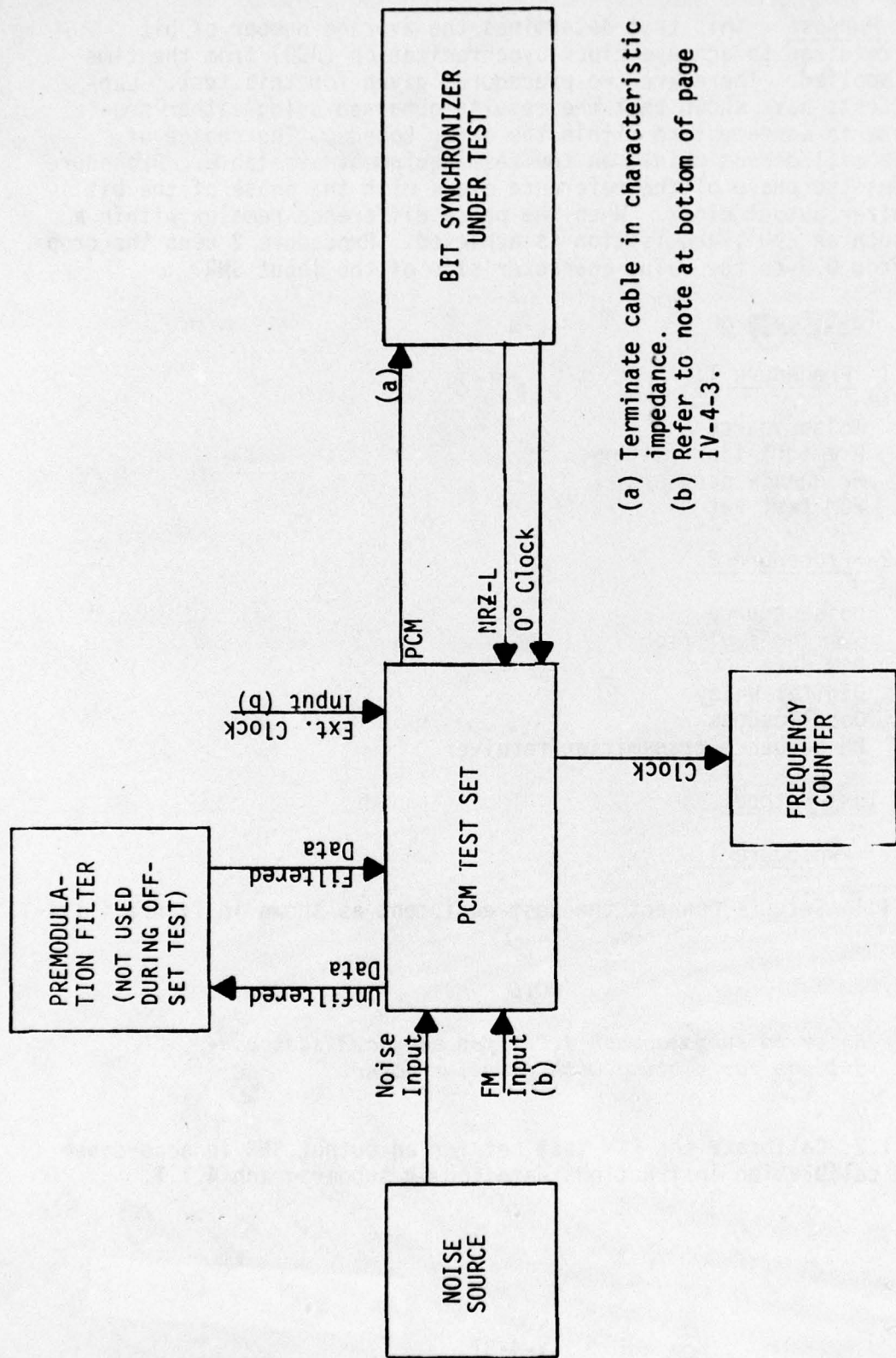
4.1.4.3.1.1 Setup - Connect the test equipment as shown in figure 4.1.4-1.

#### NOTE

*Refer to subparagraph 4.0.1 for standard test conditions for testing with gaussian noise.*

4.1.4.3.1.2 Calibrate the PCM test set for an output SNR in accordance with the calibration instructions detailed in subparagraph 4.1.1.

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- (a) Terminate cable in characteristic impedance.
- (b) Refer to note at bottom of page IV-4-3.

Figure 4.1.4-1 Acquisition Test Setup for Procedure 1.

4.1.4.3.1.3 Set the PCM output SNR to 0 dB and set the PCM test set to measure the number of bit periods required to achieve ACQ.

NOTE

*Measures should be taken to assure that phase errors are not introduced by the test setup, e.g., when the setup includes a premodulation filter. Measurement difficulties may occur when detection circuitry is phase sensitive.*

4.1.4.3.1.4 Monitor the clock output of the PCM test set with a counter to assure that the bit rate is correct. If the bit rate is not within the desired accuracy limit, use one of the methods contained in subparagraph 4.0.1.2 to adjust the bit rate.

4.1.4.3.1.5 Repeat measurements of the number of bit periods required to achieve ACQ for other SNR settings shown on Data Sheet 4.1.4.1.

4.1.4.3.1.6 Measure acquisition bit periods at selected SNRs for the bit rate offsets shown on Data Sheet 4.1.4.2. Note that the premodulation filter is not used during acquisition tests with bit rate offsets.

4.1.4.3.2 Procedure 2

4.1.4.3.2.1 Setup - Connect the test equipment as shown in figure 4.1.4-2.

NOTE

*Refer to subparagraph 4.0.1 for standard test conditions for testing with gaussian noise.*

4.1.4.3.2.2 Calibrate the test setup for output SNR in accordance with the calibration instructions detailed in subparagraph 4.1.1.

4.1.4.3.2.3 Use an oscilloscope to compare the phase of the transmitter PN generator clock with large SNR to the phase of the bit synchronizer clock output. Select the phase of the output bit clock of the bit synchronizer which is within  $\pm 45^\circ$  of the transmitter clock.

4.1.4.3.2.4 Set the PCM output SNR to the minimum SNR indicated on Data Sheet 4.1.4.1 which can be acquired by the bit synchronizer. Note setting of noise attenuator.

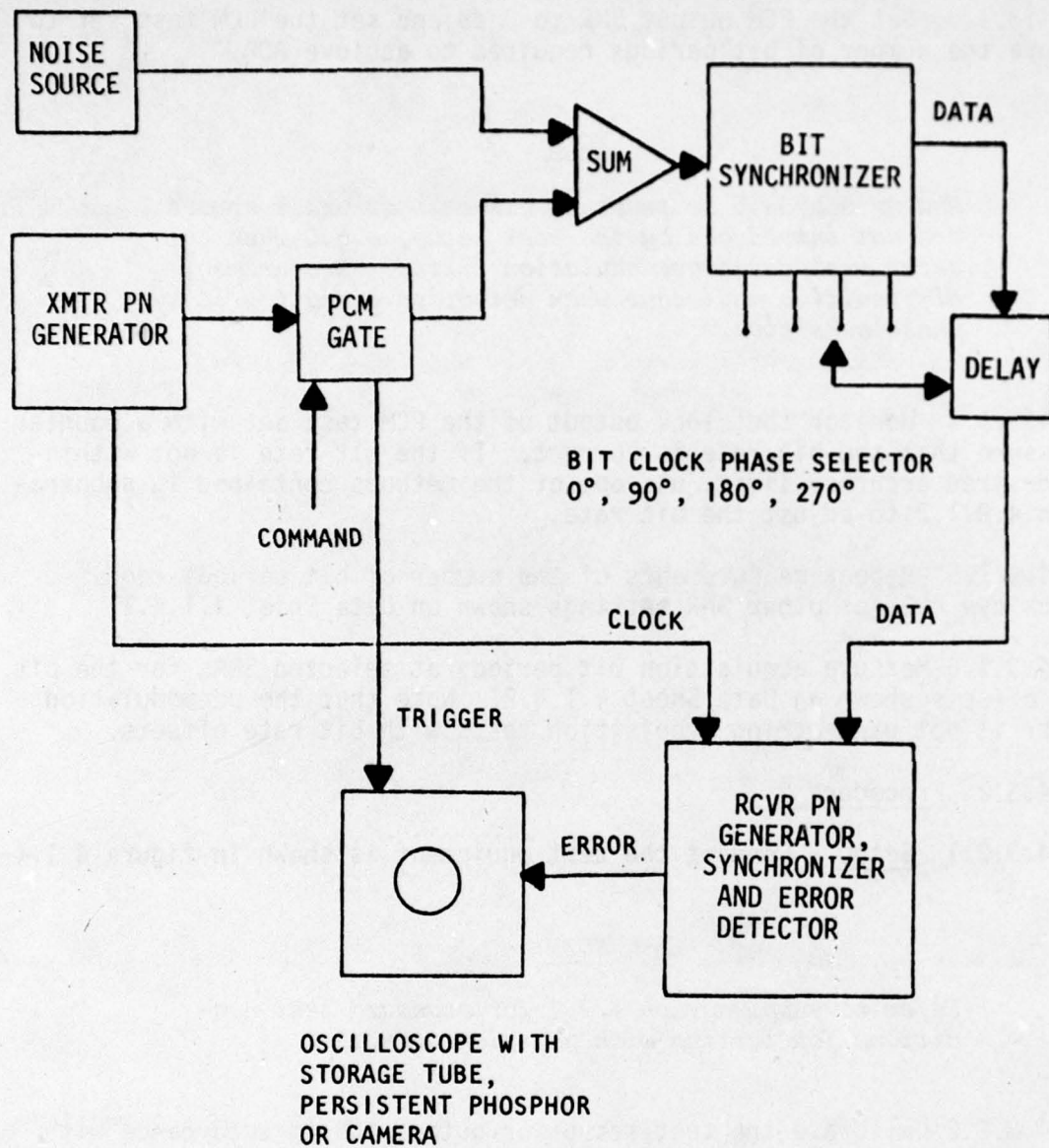


Figure 4.1.4-2 Acquisition Test Setup for Procedure 2.

4.1.4.3.2.5 To obtain initial synchronization of the receiver PN generator, increase noise attenuation to give a large SNR. Turn on the PCM gate to let the bit stream pass through. This will lock the receiver PN generator. It will stay in lock regardless of PCM input because the transmitter PN generator clock is fed directly to the receiver PN generator.

4.1.4.3.2.6 Disable the automatic restart function in the receiver PN generator.

NOTE

*Since some PCM test sets do not incorporate a disable switch, it is necessary to install a switch to break the automatic restart command function. Generally, the manual "reset" button also reloads and starts the PN generator on make or break.*

4.1.4.3.2.7 Turn off the PCM gate.

4.1.4.3.2.8 Set the oscilloscope for single sweep and adjust the sweep rate for display of acquisition. (See appendix IV-C.)

4.1.4.3.2.9 Set noise attenuator to the value given in step 4.1.4.3.2.4. Turn on the PCM gate. Observe time of acquisition from the oscilloscope display and record in terms of the number of bits on Data Sheet 4.1.4.1.

4.1.4.3.2.10 Repeat step 4.1.4.3.2.9 for the other SNR settings shown on Data Sheet 4.1.4.1.

4.1.4.3.2.11 Measure acquisition bit periods at selected SNRs for the bit rate offsets shown on Data Sheet 4.1.4.2.

NOTE

*By using a linear gate for the noise source in figure 4.1.4-2 and bypassing the PCM gate, the circuit can be used to measure BSP.*

4.1.4.3.3 Data Reduction - Record data on Data Sheet 4.1.4.1 or 4.1.4.2 as appropriate. Examples of inputs to Data Sheets 4.1.4.1 and 4.1.4.2 are shown in figures 4.1.4-3 and 4.1.4-4 respectively. Corresponding sample data plots are shown in figures 4.1.4-5 and 4.1.4-6.

Test: 4.1.4 Acquisition Test

Manufacturer \_\_\_\_\_

Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

**SAMPLE DATA**  
**NOT TO BE USED FOR**  
**EQUIPMENT SPECIFICATIONS**

Bit Synchronizer Input Signal Conditions						
PCM Signal				Noise Signal (Gaussian)		Premodulation Filter
Bit Rate (kB/s)	Amplitude (V <sub>p-p</sub> )	Code	Word Pattern	Cal. B.W. (kHz)	Cal. (V rms)	Cutoff Freq. (kHz)
100	1.0	NRZ-L	PR	100	0.5	75

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)
F/S	0.1	1.0

SNR (dB)	ACQUISITION BITS										
	Total Bits (avg)*	1.	2.	3.	4.	5.	6.	7.	8.	9.	10.
0	9.9x10 <sup>3</sup> **	**	**	**	**	**	**	**	**	**	**
+3	9.9x10 <sup>3</sup> **	**	**	**	**	**	**	**	**	**	**
+6	8.4x10 <sup>3</sup>	5.4x10 <sup>3</sup>	9.9x10 <sup>3</sup>	9.9x10 <sup>3</sup>	9.9x10 <sup>3</sup>	9.9x10 <sup>3</sup>	5.6x10 <sup>3</sup>	8.5x10 <sup>3</sup>	9.9x10 <sup>3</sup>	6.2x10 <sup>3</sup>	9.2x10 <sup>3</sup>
+9	526	367	394	570	371	608	545	327	393	620	572
+12	261	410	416	495	0	201	0	514	171	409	0
+15	196	345	0	182	0	412	24	0	396	410	190
PCM only	133	204	130	0	21	91	0	152	91	170	474

\*Record the calculated average for 10 discrete measurements.  
\*\*Limit of test set readout.

**NOTE:** Additional measurements may be required where the slope of the data changes abruptly.

Figure 4.1.4-3 Sample of Data Sheet 4.1.4.1.

Test: 4.1.4 Acquisition Test

Manufacturer \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

**SAMPLE DATA**  
**NOT TO BE USED FOR**  
**EQUIPMENT SPECIFICATIONS**

Serial No. \_\_\_\_\_

Bit Synchronizer Input Signal Conditions							
PCM Signal				Noise Signal (Gaussian)		Premod Filter	SNR
Bit Rate (kB/s)	Amplitude (V <sub>p-p</sub> )	Code	Word Pattern	Cal. B.W. (kHz)	Cal (V rms)	Cutoff Freq (kHz)	dB
100	1.0	NRZ-L	PR	100	0.5	None	15

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)
F/S	0.1	1.0

Bit Rate Offset (% Tracking Range)	Acquisition Bits										
	Total bits (avg) *	1.	2.	3.	4.	5.	6.	7.	8.	9.	10.
+100%	9.9x10 <sup>3</sup> **	9.7x10 <sup>3</sup> **	9.9x10 <sup>3</sup> **	9.9x10 <sup>3</sup> **	**	**	**	**	**	**	**
+80%	6.7x10 <sup>3</sup>	6.7x10 <sup>3</sup>	6.6x10 <sup>3</sup>	6.8x10 <sup>3</sup>	6.7x10 <sup>3</sup>	6.8x10 <sup>3</sup>	6.6x10 <sup>3</sup>	6.9x10 <sup>3</sup>	6.7x10 <sup>3</sup>	6.7x10 <sup>3</sup>	6.8x10 <sup>3</sup>
+60%	3.7x10 <sup>3</sup>	3.7x10 <sup>3</sup>	3.8x10 <sup>3</sup>	3.6x10 <sup>3</sup>	4.2x10 <sup>3</sup>	3.7x10 <sup>3</sup>	3.7x10 <sup>3</sup>	3.8x10 <sup>3</sup>	3.6x10 <sup>3</sup>	3.5x10 <sup>3</sup>	3.5x10 <sup>3</sup>
+40%	1.7x10 <sup>3</sup>	1.9x10 <sup>3</sup>	1.9x10 <sup>3</sup>	1.5x10 <sup>3</sup>	1.9x10 <sup>3</sup>	1.7x10 <sup>3</sup>	1.9x10 <sup>3</sup>	1.5x10 <sup>3</sup>	1.8x10 <sup>3</sup>	1.6x10 <sup>3</sup>	1.8x10 <sup>3</sup>
+30%	1.2x10 <sup>3</sup>	1.4x10 <sup>3</sup>	944	941	939	1.2x10 <sup>3</sup>	1.2x10 <sup>3</sup>	1.3x10 <sup>3</sup>	1.2x10 <sup>3</sup>	1.3x10 <sup>3</sup>	1.2x10 <sup>3</sup>
+20%	524	456	440	456	438	533	730	447	874	495	374
+10%	59	0	33	56	0	0	119	147	50	188	0
0%	78	156	0	0	0	0	71	149	141	132	131
-10%	70	0	0	0	204	0	350	0	0	70	84
-20%	94	0	0	0	162	0	446	282	0	0	54
-30%	58	35	0	258	0	0	0	201	83	0	0
-40%	63	0	81	244	78	0	0	0	74	154	0
-60%	700	370	1x10 <sup>3</sup>	422	779	797	618	610	829	839	734
-80%	1.7x10 <sup>3</sup>	1.6x10 <sup>3</sup>	1.6x10 <sup>3</sup>	1.9x10 <sup>3</sup>	1.8x10 <sup>3</sup>	1.8x10 <sup>3</sup>	1.6x10 <sup>3</sup>	1.8x10 <sup>3</sup>	1.7x10 <sup>3</sup>	1.7x10 <sup>3</sup>	1.8x10 <sup>3</sup>
-100%	3.7x10 <sup>3</sup>	3.9x10 <sup>3</sup>	3.6x10 <sup>3</sup>	3.9x10 <sup>3</sup>	3.7x10 <sup>3</sup>	3.9x10 <sup>3</sup>	3.6x10 <sup>3</sup>	3.7x10 <sup>3</sup>	3.9x10 <sup>3</sup>	3.7x10 <sup>3</sup>	3.6x10 <sup>3</sup>

\*Record the calculated average for 10 discrete measurements.  
 \*\*Limit of test set readout.

NOTE: Additional measurements may be required where the slope of the data changes abruptly.

Figure 4.1.4-4 Sample of Data Sheet 4.1.4.2

ACQUISITION  
VERSUS  
SIGNAL-TO-NOISE RATIO

ACQUISITION TIME (bit periods)

**SAMPLE DATA**  
NOT TO BE USED FOR  
EQUIPMENT SPECIFICATIONS

0 3 6 9 12 15 18 21 24 PCM ONLY  
SNR (dB)

Figure 4.1.4-5 Sample Plot Presentation of Data Sheet 4.1.4.1.

ACQUISITION  
VERSUS  
BIT RATE OFFSET

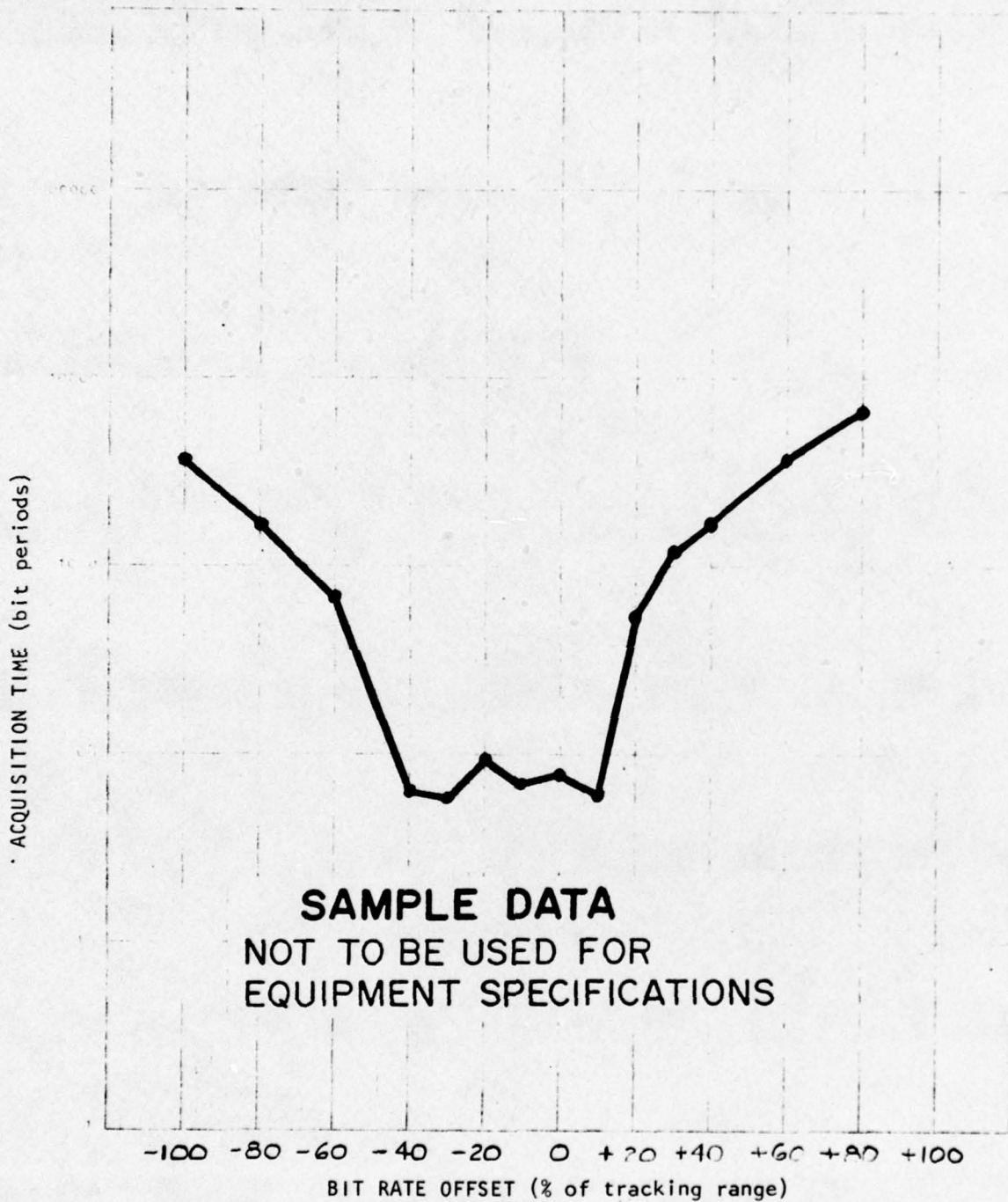


Figure 4.1.4-6 Sample Plot Presentation of Data Sheet 4.1.4.2.

Test: 4.1.4 Acquisition Test

Manufacturer \_\_\_\_\_ Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

Bit Synchronizer Input Signal Conditions						
PCM Signal				Noise Signal (Gaussian)		Premodulation Filter
Bit Rate (kB/s)	Amplitude (V <sub>p-p</sub> )	Code	Word Pattern	Cal. B.W. (kHz)	Cal. (V rms)	Cutoff Freq. (kHz)

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)

SNR (dB)	ACQUISITION BITS										
	Total Bits (avg)*	1.	2.	3.	4.	5.	6.	7.	8.	9.	10.
0											
+3											
+6											
+9											
+12											
+15											
PCM only											

\*Record the calculated average for 10 discrete measurements.

*NOTE: Additional measurements may be required where the slope of the data changes abruptly.*

Test: 4.1.4 Acquisition Test (with Bit Rate Offset)

Manufacturer \_\_\_\_\_ Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

Bit Synchronizer Input Signal Conditions							
PCM Signal				Noise Signal (Gaussian)		Premod Filter	SNR
Bit Rate (kB/s)	Amplitude (V <sub>p-p</sub> )	Code	Word Pattern	Cal. B.W. (kHz)	Cal (V rms)	Cutoff Freq (kHz)	dB
						None	

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Trackng Range (% Bit Rate)

Bit Rate Offset (% Tracking Range)	Acquisition Bits										
	Total bits (avg) *	1.	2.	3.	4.	5.	6.	7.	8.	9.	10.
+100%											
+80%											
+60%											
+40%											
+30%											
+20%											
+10%											
0%											
-10%											
-20%											
-30%											
-40%											
-60%											
-80%											
-100%											

\*Record the calculated average for 10 discrete measurements.

NOTE: Additional measurements may be required where the slope of the data changes abruptly.

#### 4.1.5 Jitter Test

4.1.5.1 Purpose - This test determines the effects of bit jitter on ACQ in the bit synchronizer. The criterion of performance is the BSP.

#### 4.1.5.2 Test Equipment:

4.1.5.2.1 The following is used in the test setup shown in figure 4.1.5-1 (Method I):

- Noise source
- Premodulation filter
- Frequency counter
- PCM test set
- Signal generator
- Noise source (jitter source)

4.1.5.2.2 The following is used in the test setup shown in figure 4.1.5-2 (Method II):

- Noise source
- Premodulation filter
- Frequency counter
- Signal generator (jitter frequency source)
- Signal generator (external clock source which can be frequency modulated)
- BER test set (transmitter and receiver)
- Calibrated attenuator
- Noise source (jitter source)

#### 4.1.5.3 Test Method:

4.1.5.3.1 Setup - Connect the test equipment as shown in figure 4.1.5-1 or 4.1.5-2. (The test method is the same for either test setup.)

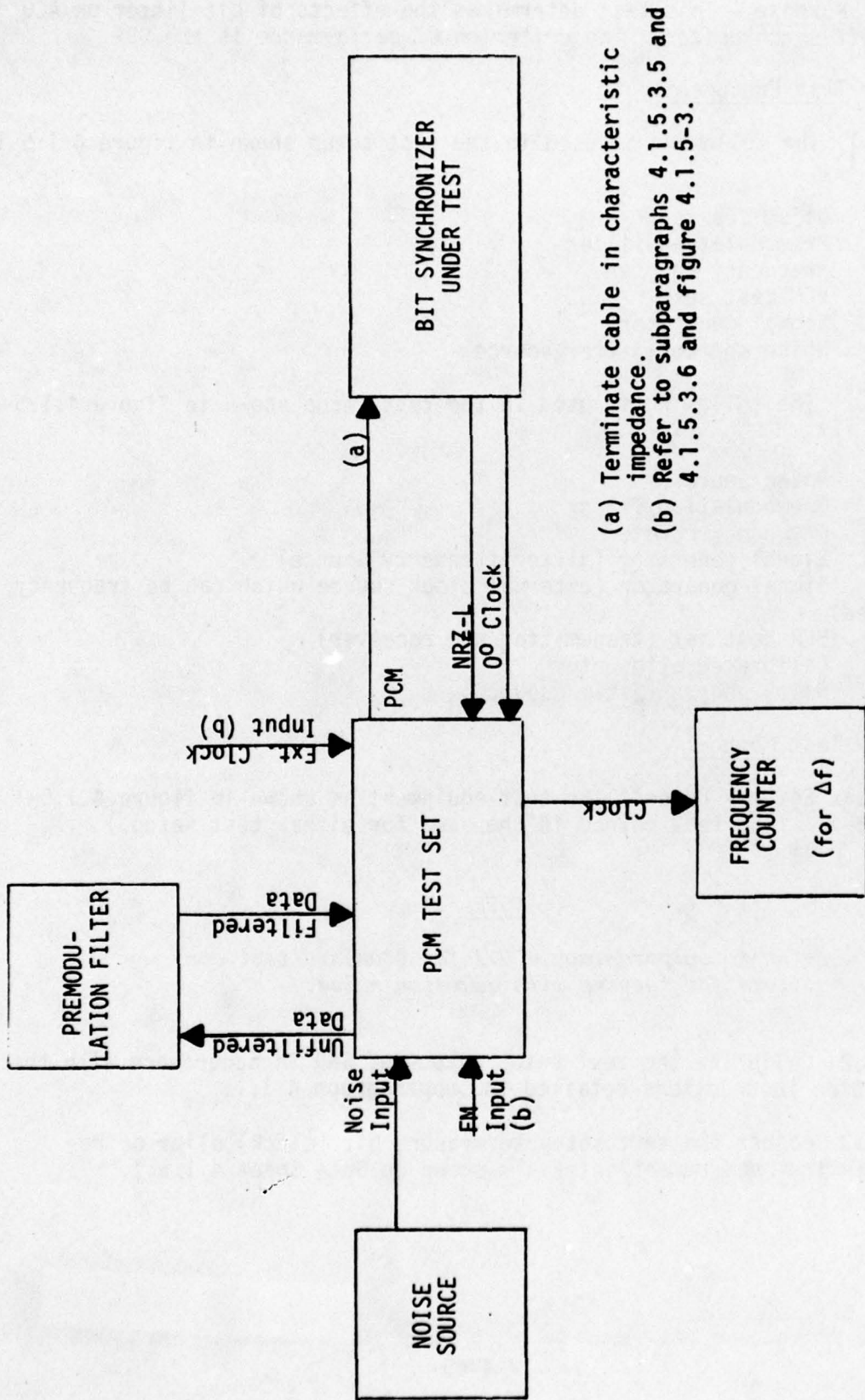
#### NOTE

*Refer to subparagraph 4.0.1 for standard test conditions for testing with gaussian noise.*

4.1.5.3.2 Calibrate the test setup output of SNR in accordance with the calibration instructions detailed in subparagraph 4.1.1.

4.1.5.3.3 Adjust the test setup to measure bit (clock) slips or re-starts in the measurement intervals shown on Data Sheet 4.1.5.1.

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- (a) Terminate cable in characteristic impedance.
- (b) Refer to subparagraphs 4.1.5.3.5 and 4.1.5.3.6 and figure 4.1.5-3.

Figure 4.1.5-1 Jitter Test Setup Using PCM Test Set (Method I).

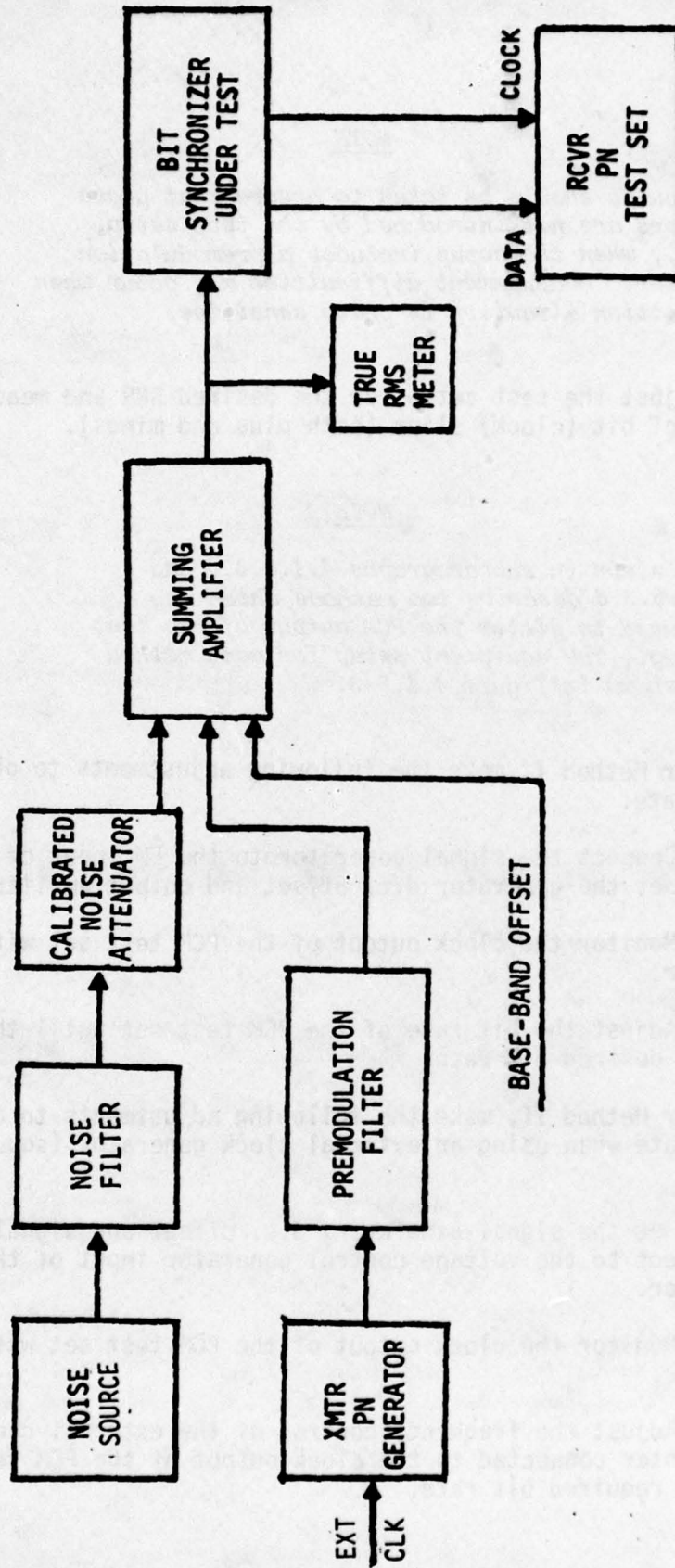


Figure 4.1.5-2 Jitter Test Setup for the Case in which the Noise Attenuator and Summing Amplifier are External to the PCM Test Set (Method II).

NOTE

*Measures should be taken to assure that phase errors are not introduced by the test setup, e.g., when the setup includes a premodulation filter. Measurement difficulties may occur when detection circuitry is phase sensitive.*

4.1.5.3.4 Adjust the test setup for the desired SNR and measure the total number of bit (clock) slips (both plus and minus).

NOTE

*The steps in subparagraphs 4.1.5.3.5 and 4.1.5.3.6 describe two methods which may be used to jitter the PCM output of the test setup. The equipment setup for each method is shown in figure 4.1.5-3.*

4.1.5.3.5 For Method I, make the following adjustments to obtain the desired bit rate:

4.1.5.3.5.1 Connect the signal generator to the FM input of the PCM test set and set the generator d.c. offset and output amplitude to 0.

4.1.5.3.5.2 Monitor the clock output of the PCM test set with a frequency counter.

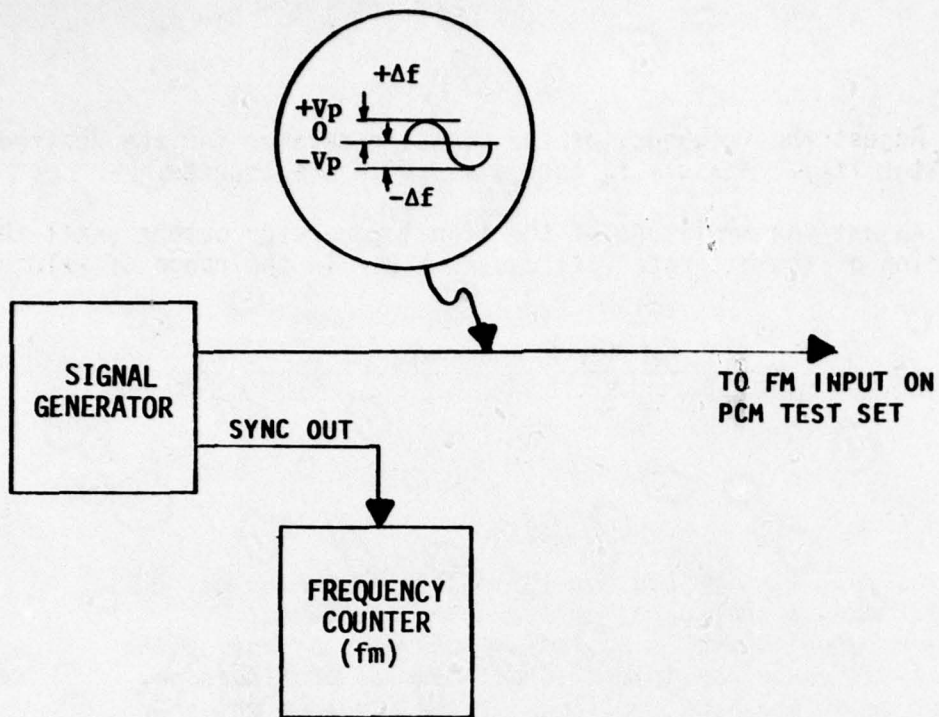
4.1.5.3.5.3 Adjust the bit rate of the PCM test set until the counter indicates the desired bit rate.

4.1.5.3.6 For Method II, make the following adjustments to obtain the desired bit rate when using an external clock generator (square-wave signal):

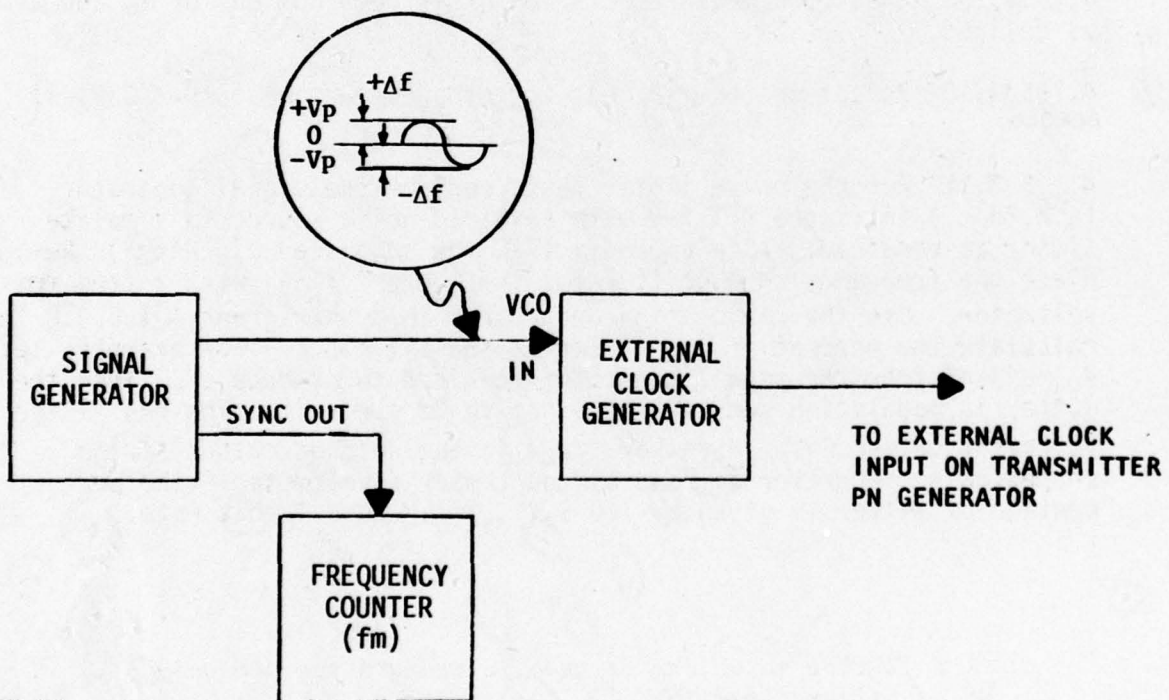
4.1.5.3.6.1 Set the signal generator, d.c. offset and signal amplitude to 0 and connect to the voltage control generator input of the external clock generator.

4.1.5.3.6.2 Monitor the clock output of the PCM test set with a frequency counter.

4.1.5.3.6.3 Adjust the frequency control of the external clock generator until the counter connected to the clock output of the PCM test set indicates the required bit rate.



METHOD I



METHOD II

Figure 4.1.5-3 Bit Rate Jitter (methods).

4.1.5.3.7 Adjust the frequency of the signal generator for the desired rate of jitter ( $f_m$ ). Measure  $f_m$  accurately with the counter.

4.1.5.3.8 Adjust the amplitude of the signal generator output until the peak deviation of the bit rate ( $\Delta f$ ) causes a BSP in the range of  $1 \times 10^{-6}$  to  $1 \times 10^{-5}$ .

$$\text{BSP} = \frac{\text{Total Bit Slips Measured}}{\text{Number of Bits Transmitted During Measurement Interval}}$$

NOTE

*The following method may be used to determine  $\Delta f$ :*

*1. Adjust the output amplitude of the signal generator to zero. 2. Adjust the d.c. offset of the signal generator (use a direct-coupled oscilloscope) to equal the peak amplitude of the waveform which produced the BSP just measured. 3. Calculate  $\Delta f$  from the change in the PCM test set clock frequency.*

4.1.5.3.9 Repeat the measurements for other combinations of  $f_m$  and  $\Delta f$  as desired.

4.1.5.3.10 Repeat the entire test for other values of output SNR, if needed.

4.1.5.3.11 For the noise jitter test, replace the signal generator (a.c./d.c.) in figure 4.1.5-3 with a shaped noise source to simulate jitter as required. (See appendix IV-C for suggested circuits.) Replace the frequency counter (for  $f_m$ ) in figure 4.1.5-3 with a true rms voltmeter. Use the calibration determined in subparagraph 4.1.5.3.8 to calculate the percent of rms jitter of the bit clock. For example, let  $V_{dc}$  = offset from the signal generator required to produce  $\Delta f$ . Then the jitter is modulation sensitivity  $S_j = \Delta f / V_{dc}$  Hz per volt. The rms jitter is then equal to  $S_j V_{rms}$  Hz, where  $V_{rms}$  is the voltage output of the shaped noise generator as read by the true rms voltmeter. The percentage of jitter is given by  $100 S_j V_{rms} / f_b$ , where  $f_b$  = bit rate.

NOTE

*A flutter meter can be used to measure the percentage of jitter directly.*

4.1.5.3.12 Adjust the rms voltage at the output of the shaped noise generator to produce a BSP in the range of  $10^{-6}$  to  $10^{-5}$  as in step 4.1.5.3.8.

4.1.5.3.14 Repeat the test for other values of the output SNR as required.

4.1.5.4 Data Reduction - Record data on Data Sheet 4.1.5.1. An example of Data Sheet 4.1.5.1 use is shown in figure 4.1.5-4 and a corresponding sample data plot is shown in figure 4.1.5-5.

Test: 4.1.5 Jitter Test

Manufacturer \_\_\_\_\_

Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

**SAMPLE DATA**  
**NOT TO BE USED FOR**  
**EQUIPMENT SPECIFICATIONS**

Bit Synchronizer Input Signal Conditions							
PCM Signal				Noise Signal (Gaussian)		Premod Filter	SNR
Bit Rate (kB/s)	Amplitude (V <sub>p-p</sub> )	Code	Word Pattern	Cal. B.W. (kHz)	Cal (V rms)	Cutoff Freq (kHz)	dB
100	1.0	NRZ-L	PR	100	0.5	75	9

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Trackng Range (% Bit Rate)
F/S	0.3	3.0

Jitter		BSP	Measurement Interval * (Period 10 <sup>N</sup> Bits)
f <sub>m</sub> (Hz)	Δf (Hz)	Hold constant in range 10 <sup>-5</sup> ≥ BSP ≥ 10 <sup>-6</sup>	N
0.1	3000	1 × 10 <sup>-6</sup>	6
1.0	3000	1 × 10 <sup>-6</sup>	6
10	3000	2 × 10 <sup>-6</sup>	6
20	3200	4 × 10 <sup>-6</sup>	6
30	2600	1 × 10 <sup>-5</sup>	6
50	1500	7 × 10 <sup>-6</sup>	6
100	812	1 × 10 <sup>-5</sup>	6
300	466	1 × 10 <sup>-6</sup>	6
700	1000	1 × 10 <sup>-6</sup>	6
1000	1700	1 × 10 <sup>-5</sup>	6
2000	2400	1 × 10 <sup>-5</sup>	6

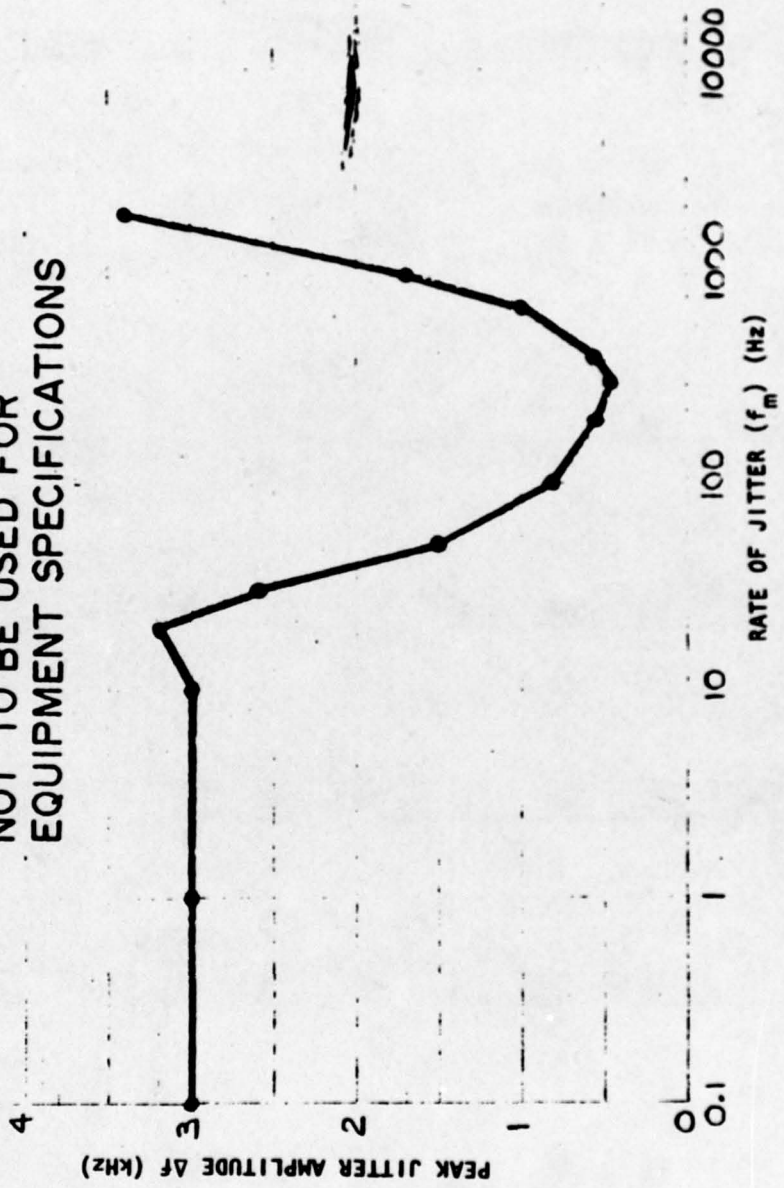
\*Measurement interval provides reliable repeatability for BSP ≥ 1 × 10<sup>-6</sup>.

*NOTE: Additional measurements may be required where the slope of the data changes abruptly.*

Figure 4.1.5-4 Sample of Data Sheet 4.1.5.1.

PEAK JITTER VERSUS JITTER RATE

**SAMPLE DATA**  
NOT TO BE USED FOR  
EQUIPMENT SPECIFICATIONS



IV-4-53

Figure 4.1.5-5 Sample Plot Presentation of Data Sheet 4.1.5.1.



#### 4.1.6 Bit Stream Base-Line Wander and AM Test

4.1.6.1 Purpose - This test determines the effects of bit stream base-line wander and AM. Base-line wander results from passage of the bit stream through devices lacking d.c. response, such as tape recorders and capacity-coupled circuits, and from incidental PM or FM in transmitters. A principal cause of bit stream AM is tape bounce.

#### 4.1.6.2 Test Equipment:

4.1.6.2.1 The following is used in the test setup shown in figure 4.1.6-1.

- Noise source
- Low-pass filter
- Signal generator (for base-line input)
- Signal generator (for AM input)
- Amplitude modulator
- Premodulation filter
- True rms voltmeter
- Frequency counter
- PCM test set

4.1.6.2.2 The test setup shown in figure 4.1.6-2 uses the same equipment listed in subparagraph 4.1.6.2.1 except it replaces the PCM test set with a PCM BER test set, a calibrated noise attenuator and a summing amplifier.

#### 4.1.6.3 Test Procedures:

4.1.6.3.1 Setup - Connect the test equipment as shown in figure 4.1.6-1 or 4.1.6-2.

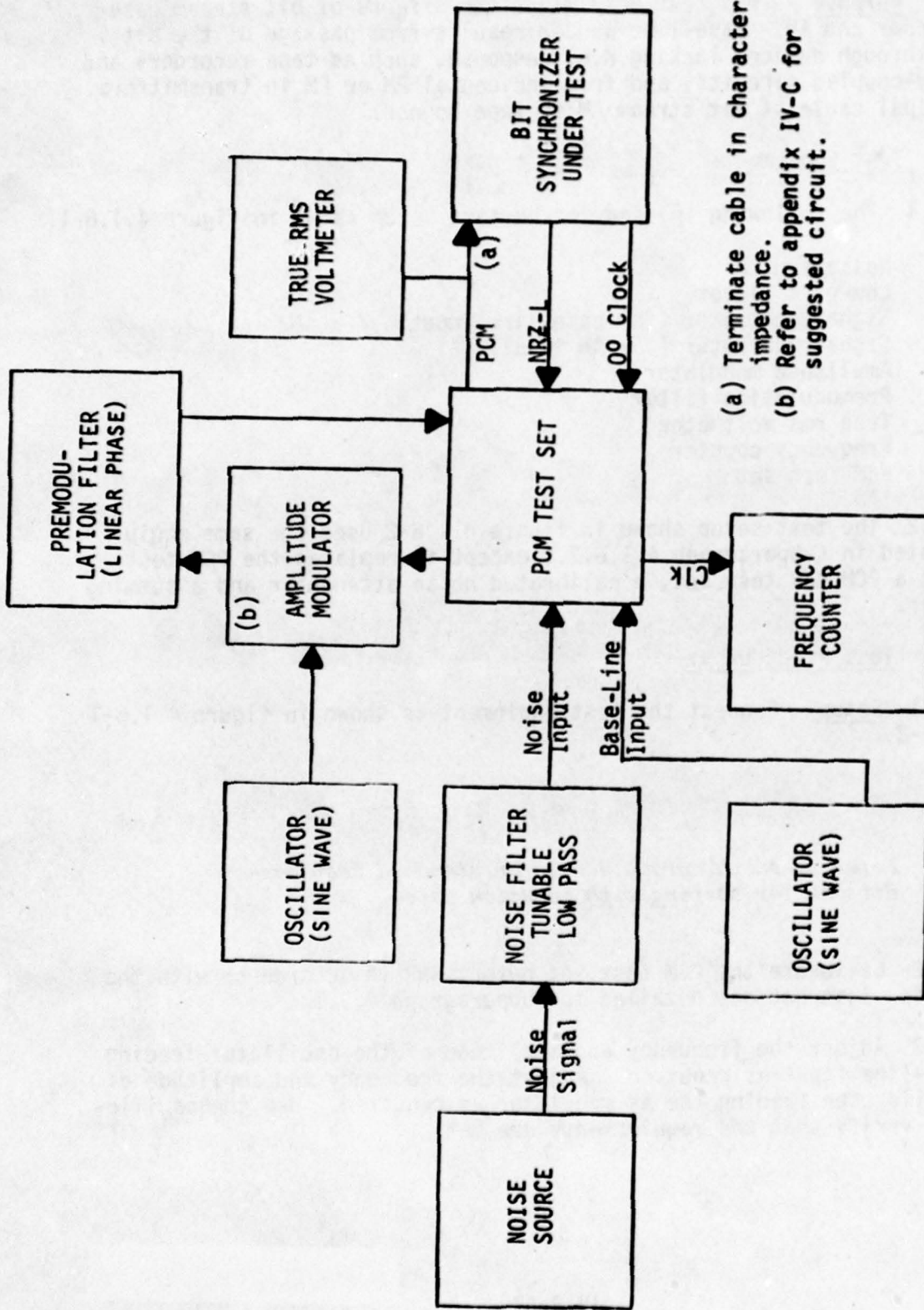
#### NOTE

*Refer to subparagraph 4.0.1 for standard test conditions for testing with gaussian noise.*

4.1.6.3.2 Calibrate the PCM test set output SNR in accordance with the calibration instructions detailed in subparagraph 4.1.1.

4.1.6.3.3 Adjust the frequency and amplitude of the oscillator feeding the base-line input as required. Adjust the frequency and amplitude of the oscilloscope feeding the AM modulator as required. Use the oscilloscope to verify that the requirements are met.

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(a) Terminate cable in characteristic impedance.  
 (b) Refer to appendix IV-C for suggested circuit.

Figure 4.1.6-1 Bit Stream Base-Line Wander and AM Test Setup with PCM Test Set.

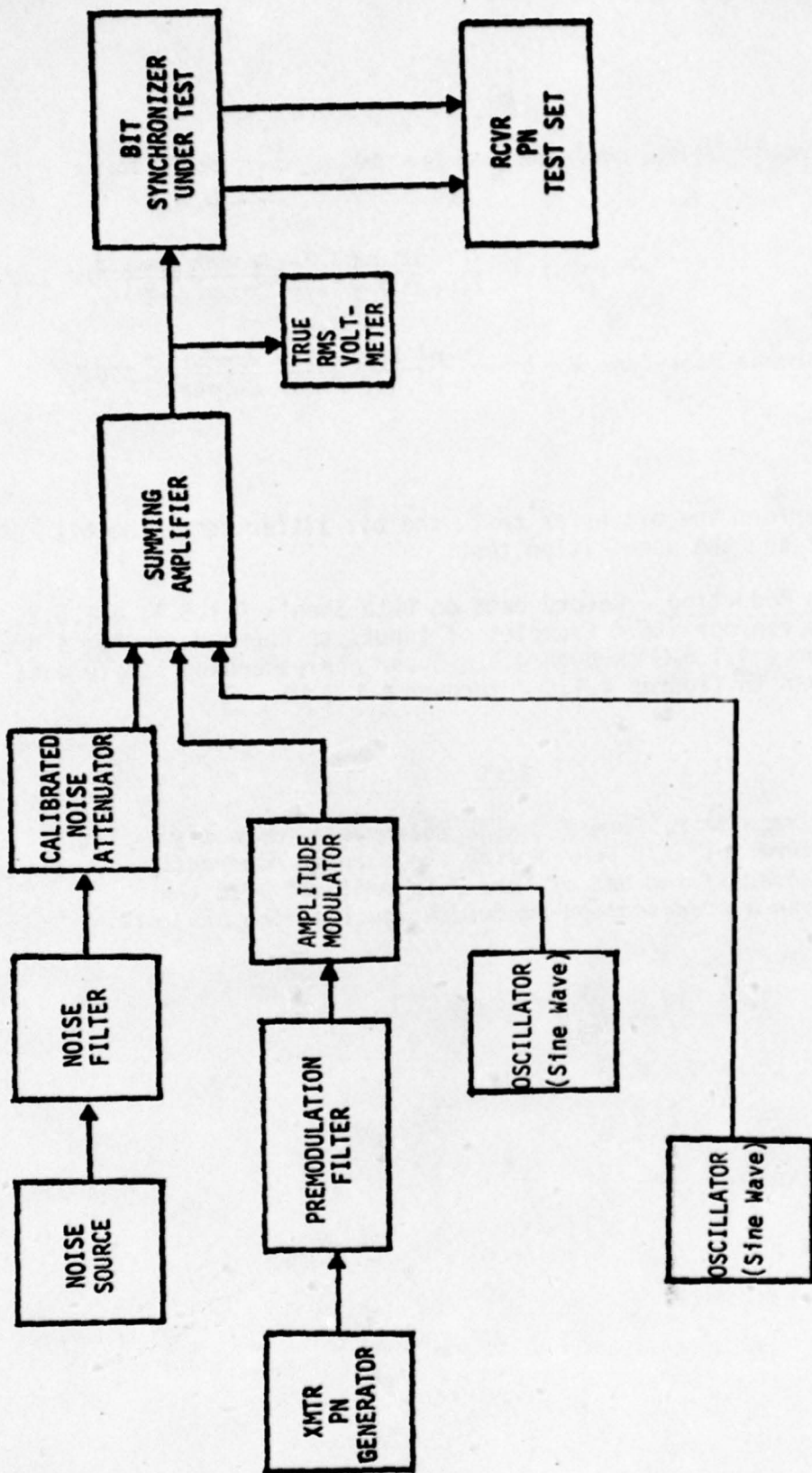


Figure 4.1.6-2 Bit Stream Base-Line Wander and AM Test Setup for the Case in which the Noise Attenuator and Summing Amplifier are External to the PCM Test Set.

NOTE

Percent AM and base-line wander are defined as follows:

$$\text{Percent AM} = \frac{(\text{Crest Ampl.}) - (\text{Trough Ampl.})}{(\text{Crest Ampl.}) + (\text{Trough Ampl.})} \times 100$$

$$\text{Percent Base-Line Wander} = \frac{(p-p) \text{ Base-Line Wander}}{(p-p) \text{ Bit Pulse Height}} \times 100$$

4.1.6.3.4 Perform the bit error test, the bit jitter test, the bit slippage test and the acquisition test.

4.1.6.4 Data Reduction - Record data on Data Sheets 4.1.6.1, 4.1.6.2, 4.1.6.3, or 4.1.6.4 as appropriate. Examples of inputs to these data sheets are shown in figures 4.1.6-3 through 4.1.6-6 and corresponding sample data plots are shown in figures 4.1.6-7 through 4.1.6-10.

NOTE

*The results of Part I can be interpreted directly in terms of  $\pm\pi/2$  PCM/FM with the carrier coherently detected if the SNR of Part I is replaced with the SNR in a predetection bandwidth equal to the bit rate.*

DATA SHEET 4.1.6.1      BEP TEST WITH BIT STREAM AM

Test: 4.1.6 Bit Stream Base-Line W<sub>2</sub>

Manufacturer \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

**SAMPLE DATA  
NOT TO BE USED FOR  
EQUIPMENT SPECIFICATIONS**

Bit Synchronizer Input Signal Conditions								
PCM Signal				FM Link Settings			AM	
Bit Rate kB/s	Premodulation Filter Bandwidth kHz	Code	Word Pattern	Carrier Deviation Peak-to- Peak, kHz	IF Bandwidth kHz	Post Detection Filter Bandwidth kHz	%	Freq. % Bit Rate
100	∞	NRZ	PR	140	180	70	50	5

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)
FS	0.3	3.0

Sig. Gen. Mfg. DCS  
 Model GOV-4 Serial No. 94386  
 Rcvr. Mfg. EMR  
 Model 4142 Serial No. 219  
 Carrier Freq. 450 KHz

IF SNR	BEP		Measurement Interval (Period 10 <sup>N</sup> bits)
	Perturbed	Not Perturbed	
dB			N
3	9 × 10 <sup>-2</sup>	9 × 10 <sup>-2</sup>	5
6	2.5 × 10 <sup>-2</sup>	2.3 × 10 <sup>-2</sup>	5
9	1.7 × 10 <sup>-3</sup>	1.4 × 10 <sup>-3</sup>	6
12	2.5 × 10 <sup>-5</sup>	5 × 10 <sup>-6</sup>	8
15			8

Figure 4.1.6-3 Sample of Data Sheet 4.1.6.1.

DATA SHEET 4.1.6.2

BEP TEST WITH BASE-LINE WANDER ADDED TO BIT STREAM

Test: 4.1.6 Bit Stream Base-Line W

Manufacturer \_\_\_\_\_

Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

**SAMPLE DATA  
NOT TO BE USED FOR  
EQUIPMENT SPECIFICATIONS**

Bit Synchronizer Input Signal Conditions								
PCM Signal				FM Link Settings			BLW	
Bit Rate kB/s	Premodulation Filter Bandwidth kHz	Code	Word Pattern	Carrier Deviation Peak-to- Peak, kHz	IF Bandwidth kHz	Post Detection Filter Bandwidth kHz	%	Freq. % Bit Rate
100	$\infty$	NRZ	PR	70	360	70	50	0.25

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)
FS	# 1	-

Sig. Gen. Mfg. DCS

Model GDV-4 Serial No. 94386

Rcvr. Mfg. EMR

Model 4142 Serial No. 219

Carrier Freq. 450 KHz

IF SNR	BEP		Measurement Interval (Period $10^N$ bits)
	Perturbed	Not Perturbed	
dB			N
3	$1.2 \times 10^{-1}$	$1.0 \times 10^{-1}$	5
6	$1.5 \times 10^{-2}$	$1.2 \times 10^{-2}$	5
9	$7.0 \times 10^{-4}$	$4.5 \times 10^{-4}$	6
12	$5.3 \times 10^{-6}$	$1.7 \times 10^{-6}$	8
15			8
18			8

Figure 4.1.6-4 Sample of Data Sheet 4.1.6.2.

DATA SHEET 4.1.6.3

BEP TEST WITH BASE-LINE WANDER ADDED TO AM BIT STREAM

Test: 4.1.6 Bit Stream Base-Line Wander Test

Manufacturer \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

**SAMPLE DATA  
NOT TO BE USED FOR  
EQUIPMENT SPECIFICATIONS**

Bit Synchronizer Input Signal Conditions										
PCM Signal				FM Link Settings			BLW		AM	
Bit Rate kB/s	Premodulation Filter Bandwidth kHz	Code	Word Pattern	Carrier Deviation Peak-to- Peak, kHz	IF Bandwidth kHz	Post Detection Filter Bandwidth kHz	%	Freq % Bit Rate	%	Freq. % Bit Rate
100	∞	NRZ	PR	70	360	70	50	0.25	50	0.02

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)
FS	# 4	

Sig. Gen. Mfg. DCS  
 Model GOV-4 Serial No. 94386  
 Rcvr. Mfg. EMR  
 Model 4142 Serial No. 219  
 Carrier Freq. 450 kHz

IF SNR	BEP		Measurement Interval (Period 10 <sup>N</sup> bits)
	Perturbed	Not Perturbed	
dB			N
3			5
6			5
9	2.0 X 10 <sup>-3</sup>	4.5 X 10 <sup>-4</sup>	6
12	5.5 X 10 <sup>-5</sup>	1.7 X 10 <sup>-6</sup>	8
15	1.1 X 10 <sup>-5</sup>		8
18	3 X 10 <sup>-6</sup>		

Figure 4.1.6-5 Sample of Data Sheet 4.1.6.3.

DATA SHEET 4.1.6.4

BIT ERROR PROBABILITY TEST WITH AM PLUS BASE-LINE  
WANDER PLUS JITTER

Test: 4.1.6 Bit Stream Base-Line "

Manufacturer \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

**SAMPLE DATA**  
**NOT TO BE USED FOR**  
**EQUIPMENT SPECIFICATIONS**

Bit Synchronizer Input Signal Conditions										
PCM Signal				FM Link Settings			BLW		AM	
Bit Rate kB/s	Premodulation Filter Bandwidth kHz	Code	Word Pattern	Carrier Deviation Peak-to- Peak, kHz	IF Bandwidth kHz	Post Detection Filter Bandwidth kHz	%	Freq % Bit Rate	%	Freq. % Bit Rate
100	∞	NRZ	PR	70	360	70	50	0.25	50	0.02

Bit Synchronizer Settings			Jitter	Jitter
Detector Type	Loop BW (% Bit Rate)	Tracking Range (%Bit Rate)	6 dB Point (%Bit Rate)	% (rms) Bit Rate
FS	#4	-	2	1

Sig. Gen. Mfg. DCS  
Model GDV-4 Serial No. 94386  
Rcvr. Mfg. EMR  
Model 4142 Serial No. 219  
Carrier Freq. 450 KHz

IF SNR	BEP		Measurement Interval (Period 10 <sup>N</sup> bits)
	Perturbed	Not Perturbed	
dB			N
3			5
6			5
9	1.0 X 10 <sup>-2</sup>	4.5 X 10 <sup>-4</sup>	6
12	6.0 X 10 <sup>-4</sup>	1.7 X 10 <sup>-6</sup>	8
15	1.8 X 10 <sup>-5</sup>		8
18	2 X 10 <sup>-6</sup>		

Figure 4.1.6-6 Sample of Data Sheet 4.1.6.4.

BIT ERROR PROBABILITY VERSUS IF  
 SIGNAL-TO-NOISE RATIO WITH FM LINK  
 AND AMPLITUDE MODULATED BIT STREAM

46 6463

K·E SEMI-LOGARITHMIC 7 CYCLES X 60 DIVISIONS  
 KEUFFEL & ESSER CO. MADE IN U.S.A.

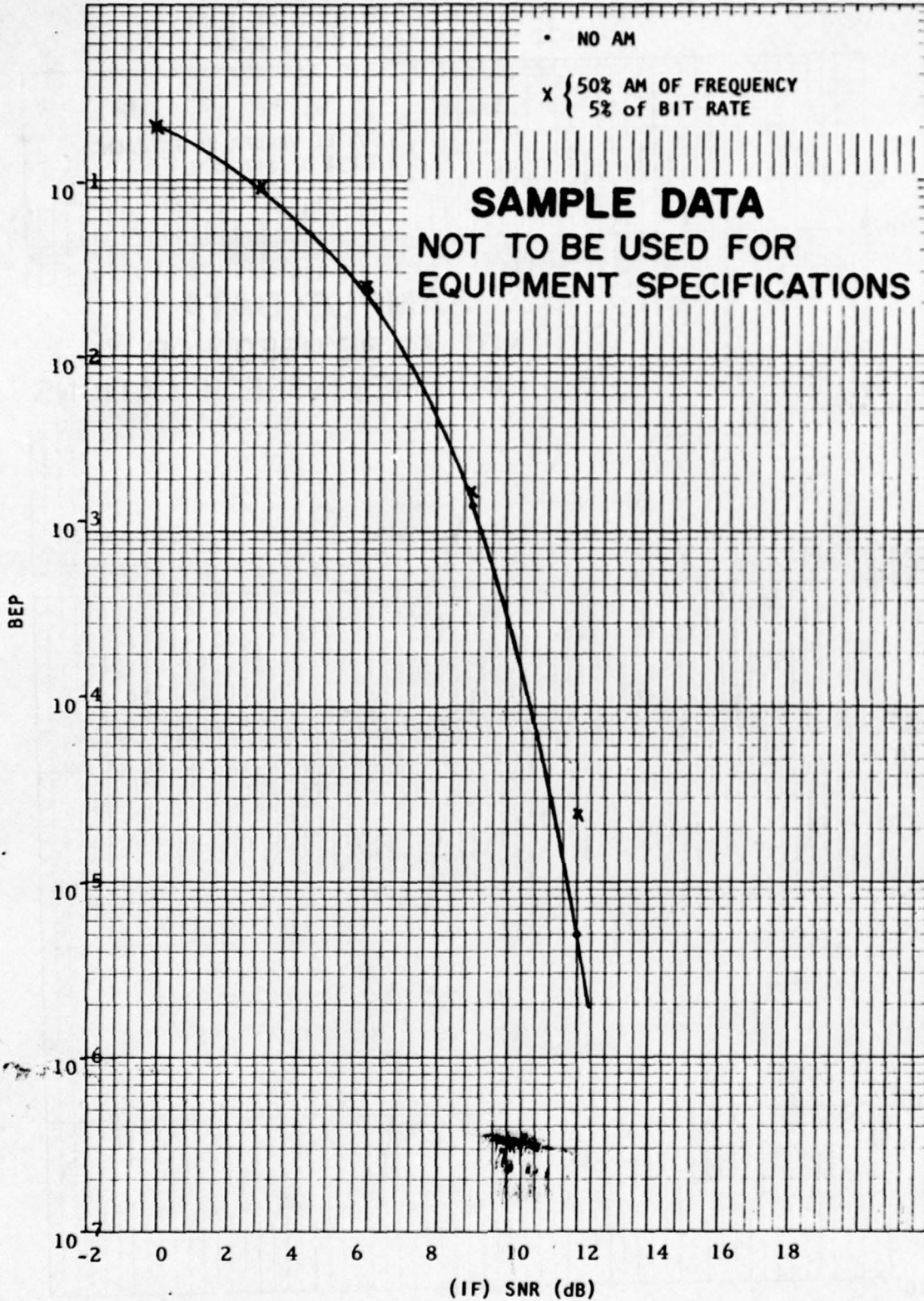
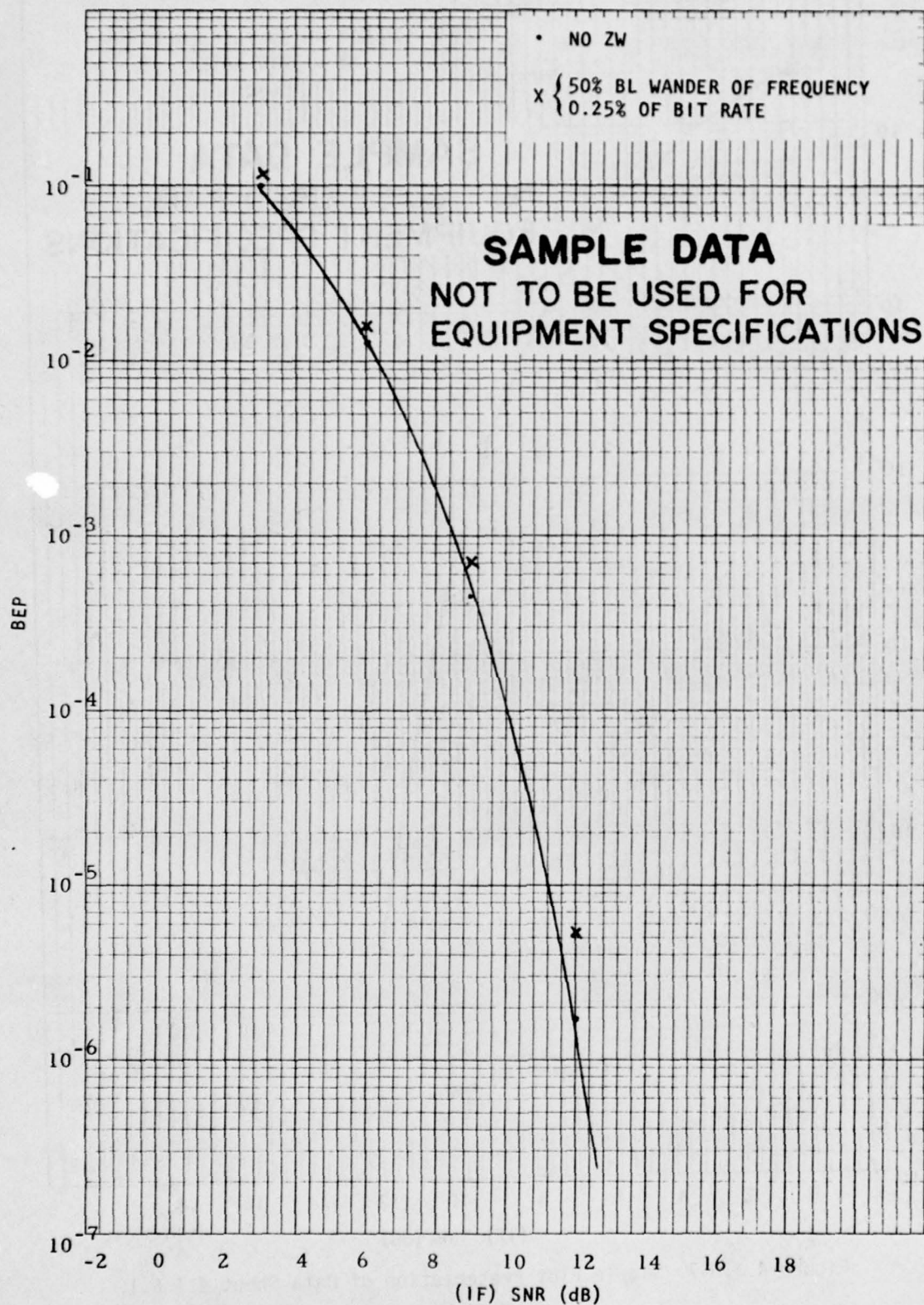


Figure 4.1.6-7 Sample Plot Presentation of Data Sheet 4.1.6.1.

IV-4-65

BIT ERROR PROBABILITY VERSUS IF  
SIGNAL-TO-NOISE RATIO WITH FM LINK  
AND BIT STREAM BASELINE WANDER

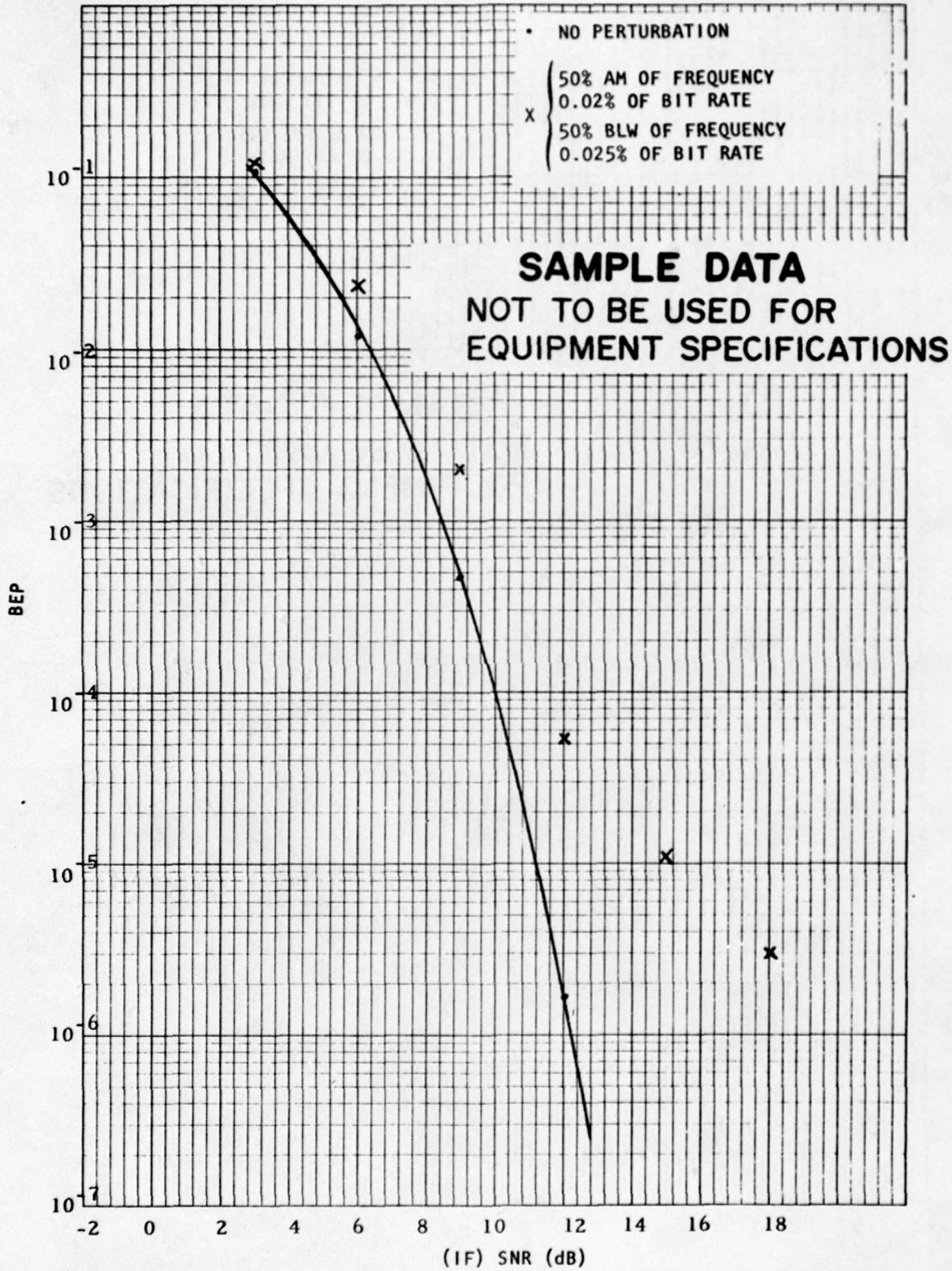


46 6463

K&E SEMI-LOGARITHMIC 7 CYCLES X 60 DIVISIONS  
KEUFFEL & ESSER CO. MADE IN U.S.A.

Figure 4.1.6-8 Sample Plot Presentation of Data Sheet 4.1.6.2.

BIT ERROR PROBABILITY VERSUS IF  
 SIGNAL-TO-NOISE RATIO WITH FM LINK AND  
 BL WANDER OF AMPLITUDE MODULATED BIT STREAM

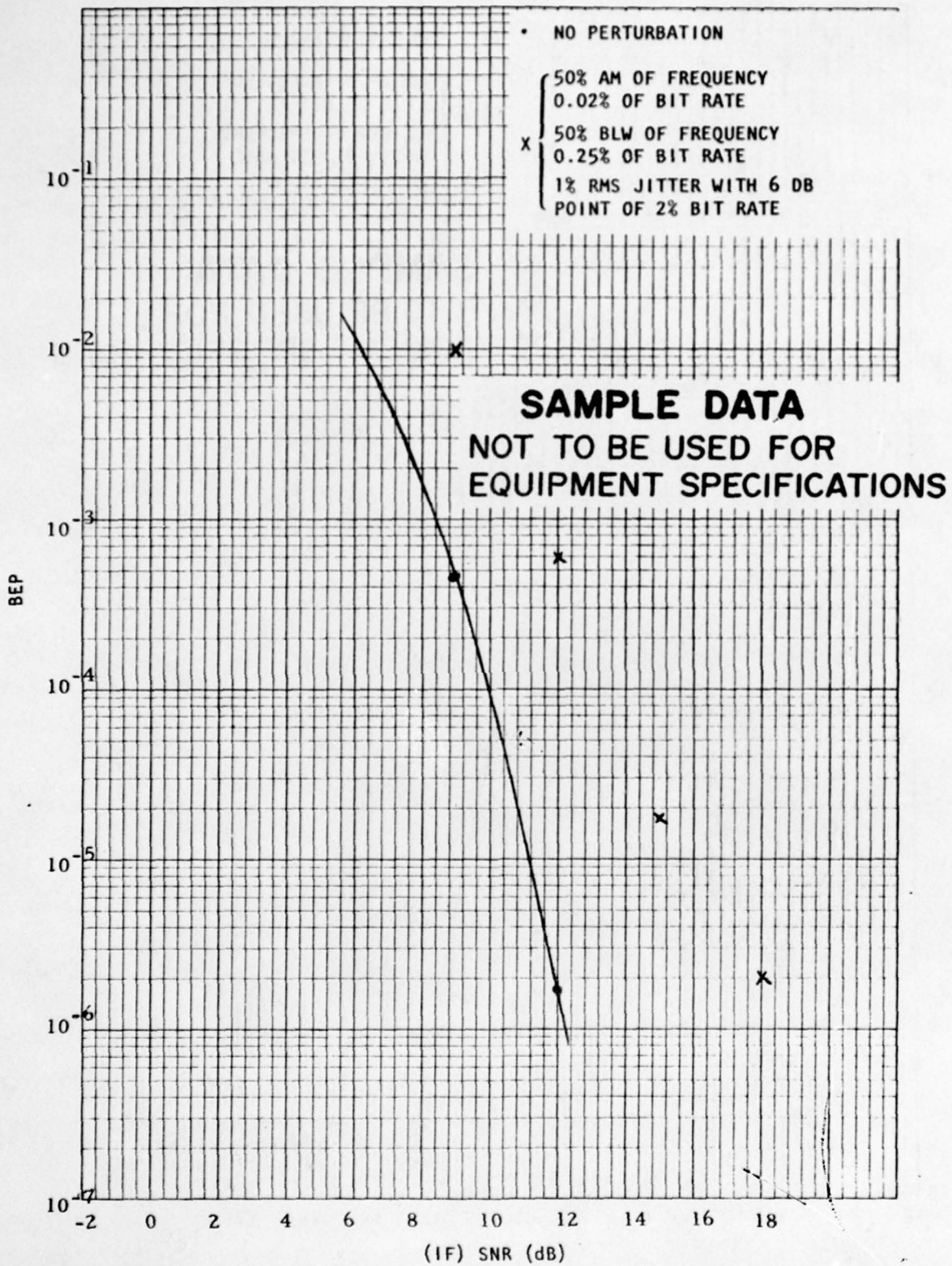


46 6463

K·E SEMI-LOGARITHMIC 7 CYCLES X 60 DIVISIONS  
 KEUFFEL & ESSER CO. MADE IN U.S.A.

Figure 4.1.6-9 Sample Plot Presentation of Data Sheet 4.1.6.3.

BIT ERROR PROBABILITY VERSUS IF SIGNAL-TO-NOISE  
 RATIO WITH FM LINK AND BL WANDER OF AMPLITUDE  
 MODULATED BIT STREAM PLUS BIT CLOCK JITTER



46 6463

K•E SEMI-LOGARITHMIC 7 CYCLES X 60 DIVISIONS  
 KEUFFEL & ESSER CO. MADE IN U.S.A.

Figure 4.1.6-10 Sample Plot Presentation of Data Sheet 4.1.6.4.

Test: 4.1.6 Bit Stream Base-Line Wander and AM Test

Manufacturer \_\_\_\_\_ Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

Bit Synchronizer Input Signal Conditions								
PCM Signal				FM Link Settings			AM	
Bit Rate kB/s	Premodulation Filter Bandwidth kHz	Code	Word Pattern	Carrier Deviation Peak-to- Peak, kHz	IF Bandwidth kHz	Post Detection Filter Bandwidth kHz	%	Freq. % Bit Rate

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)

Sig. Gen. Mfg. \_\_\_\_\_

Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Rcvr. Mfg. \_\_\_\_\_

Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Carrier Freq. \_\_\_\_\_

IF SNR	BEP		Measurement Interval (Period $10^N$ bits)
	Perturbed	Not Perturbed	
dB			N
3			5
6			5
9			6
12			8
15			8

Test: 4.1.6 Bit Stream Base-Line Wander and AM Test

Manufacturer \_\_\_\_\_ Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

Bit Synchronizer Input Signal Conditions								
PCM Signal				FM Link Settings			BLW	
Bit Rate kB/s	Premodulation Filter Bandwidth kHz	Code	Word Pattern	Carrier Deviation Peak-to- Peak, kHz	IF Bandwidth kHz	Post Detection Filter Bandwidth kHz	%	Freq. % Bit Rate

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)

Sig. Gen. Mfg. \_\_\_\_\_

Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Rcvr. Mfg. \_\_\_\_\_

Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Carrier Freq. \_\_\_\_\_

IF SNR	BEP		Measurement Interval (Period $10^N$ bits)
	Perturbed	Not Perturbed	
dB			N
3			5
6			5
9			6
12			8
15			8
18			8

DATA SHEET 4.1.6.3      BEP TEST WITH BASE-LINE WANDER ADDED TO AM BIT STREAM

Test: 4.1.6 Bit Stream Base-Line Wander and AM Test

Manufacturer \_\_\_\_\_ Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_, \_\_\_\_\_

Date \_\_\_\_\_

Bit Synchronizer Input Signal Conditions										
PCM Signal				FM Link Settings			BLW		AM	
Bit Rate kB/s	Premodulation Filter Bandwidth kHz	Code	Word Pattern	Carrier Deviation Peak-to- Peak, kHz	IF Bandwidth kHz	Post Detection Filter Bandwidth kHz	%	Freq % Bit Rate	%	Freq. % Bit Rate

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)

Sig. Gen. Mfg. \_\_\_\_\_

Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Rcvr. Mfg. \_\_\_\_\_

Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Carrier Freq. \_\_\_\_\_

IF SNR	BEP		Measurement Interval (Period $10^N$ bits)
	Perturbed	Not Perturbed	
dB			N
3			5
6			5
9			6
12			8
15			8

DATA SHEET 4.1.6.4 BEP TEST WITH AM PLUS BASE-LINE WANDER PLUS JITTER

Test: 4.1.6 Bit Stream Base-Line Wander and AM Test

Manufacturer \_\_\_\_\_ Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

Bit Synchronizer Input Signal Conditions										
PCM Signal				FM Link Settings			BLW		AM	
Bit Rate kB/s	Premodulation Filter Bandwidth kHz	Code	Word Pattern	Carrier Deviation Peak-to- Peak, kHz	IF Bandwidth kHz	Post Detection Filter Bandwidth kHz	%	Freq. % Bit Rate	%	Freq. % Bit Rate

Bit Synchronizer Settings			Jitter	Jitter
Detector Type	Loop BW (% Bit Rate)	Tracking Range (%Bit Rate)	6 dB Point (%Bit Rate)	% (rms) Bit Rate

Sig. Gen. Mfg. \_\_\_\_\_

Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Rcvr. Mfg. \_\_\_\_\_

Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Carrier Freq. \_\_\_\_\_

IF SNR	BEP		Measurement Interval (Period 10 <sup>N</sup> bits)
	Perturbed	Not Perturbed	
dB			N
3			5
6			5
9			6
12			8
15			8

## 4.2 Part II. PCM/FM Testing

Part II modifies the procedures of Part I and is to be used to determine if a selected bit synchronizer has the required characteristics essential for PCM/FM telemetry applications.

### 4.2.1 Test Setup Calibration for Predetection SNR

4.2.1.1 Purpose - The SNR is an important parameter in many of the performance tests conducted on PCM bit synchronizers. Calibration of the test setup is necessary for obtaining an accurate SNR to allow evaluation of performance in satisfying specifications or for comparing competing designs.

#### 4.2.1.2 Test Equipment:

4.2.1.2.1 For procedure using test setup shown in figure 4.0.2-1:

- BER test setup or PCM test set
- Voltage controlled oscillator
- Noise source
- Band-pass filter
- Amplifier
- Discriminator
- True rms voltmeter

4.2.1.2.2 For procedure using test setup shown in figure 4.0.2-2:

- BER test setup or PCM test set
- RF signal generator
- Receiver
- True rms voltmeter

#### 4.2.1.3 Test Method:

4.2.1.3.1 Procedure 1 (using setup in figure 4.0.2-1):

4.2.1.3.1.1 Setup - Connect the test equipment as shown in figure 4.0.2-1.

#### NOTE

*Refer to subparagraphs 4.0.1 and 4.0.2 for standard test conditions.*

4.2.1.3.1.2 Set output attenuation on the noise source to -40 dB and set the variable output level control to its minimum value.

4.2.1.3.1.3 Set the output of the voltage controlled oscillator (VCO) to a convenient level in the range of 0.1V to 0.3V rms as read on the true rms voltmeter.

4.2.1.3.1.4 Set the output attenuator on the noise source to 5 dB and adjust the variable level control so that the reading on the true rms voltmeter increases 3 dB. If the input circuits of the discriminator are linear in the range selected, the signal power from the VCO is equal to the noise power.

4.2.1.3.1.5 Check results against the following chart to test for linearity.

Noise Source Attenuator	Output Power	dB Increase on True RMS Voltmeter (relative to S)
40 dB	S	--
5	2S	3
2	3S	4.8
0	4S	6

4.2.1.3.1.6 If the results do not check, reduce the output of the VCO and repeat. Having found a linear range, SNR in the band-pass filter (BPF) output can be varied in 1-dB steps by the noise source output attenuator. For example, when the noise source output attenuator is set for 18 dB, SNR is 13 dB etc.

$$\text{BPF Output SNR (dB)} = \text{noise generator output attenuator (dB)} - 5 \text{ dB.}$$

4.2.1.3.2 Procedure 2 (using setup in figure 4.0.2-2)

4.2.1.3.2.1 Setup - Connect the test equipment as shown in figure 4.0.2-2.

NOTE

*Refer to subparagraphs 4.0.1 and 4.0.2 for standard test conditions.*

NOTE

*Here the noise source is the RF section of the receiver which has a fixed noise level. Therefore, it is convenient to use the output attenuator on the RF signal generator.*

4.2.1.3.2.2 Turn the output attenuator to -130 dBm or less.

4.2.1.3.2.3 Disable the receiver AGC and substitute a bias which provides linearity over the range N to 4N.

4.2.1.3.2.4 Increase the signal generator output power ( $P_s$ ) until the true rms voltmeter reading increases 3 dB. Call this  $P_{si}$ . If the receiver IF is operating in a linear range,  $P_{si}=N$ .

4.2.1.3.2.5 Test for linearity by checking results against the following chart.

$P_s$	Output Power	dB Increase (relative to N)
0 (or -130 dBm)	N	--
$P_{si}$	2N	3
$2P_{si}$ ( $P_{si}+3$ dB)	3N	4.8
$3P_{si}$ ( $P_{si}+4.8$ dB)	4N	6

4.2.1.3.2.6 If the results do not coincide, reduce the IF gain (by adjusting AGC bias) until a check is obtained. Restore AGC. The SNR in the linear IF can be varied by setting the output attenuator of the signal generator (assuming that its calibration is maintained).

4.2.1.3.2.7 Express the performance of the bit synchronizer in terms of the SNR in a predetection bandwidth equal to the bit rate ( $f_b$ ). Let the noise bandwidth of the IF be  $B_n$  (approximately equal to the 3-dB bandwidth). Let the SNR in  $B_n$  be  $(SNR)_{B_n}$ . Then,

$$(SNR)_{f_b} = \frac{B_n}{f_b} (SNR)_{B_n}$$

or, in dB,

$$(SNR)_{f_b} \text{ dB} = (SNR)_{B_n} \text{ dB} + 10 \log_{10} \frac{B_n}{f_b}$$

## 4.2.2 Frequency Modulation (FM) Sensitivity of the RF Signal Generator

4.2.2.1 Purpose - This test determines the modulation sensitivity of the signal generator, whether it is at RF or IF. The modulation sensitivity is required so that the correct carrier deviation is utilized during the performance tests.

### 4.2.2.2 Test Equipment:

Signal generator (RF or IF)  
Low frequency signal generator  
True rms voltmeter  
Spectrum analyzer (or internal receiver spectrum analyzer)

### 4.2.2.3 Test Method:

4.2.2.3.1 Setup - Connect the test equipment as shown in figure 4.2.2-1.

#### NOTE

*Refer to subparagraphs 4.0.1 and 4.0.2 for standard test conditions.*

4.2.2.3.2 Frequency modulate the carrier with a sinusoid of frequency ( $f_m$ ) about half of the desired peak deviation.

4.2.2.3.3 Increase amplitude of the sinusoid until the first carrier disappearance (as viewed on the receiver spectrum display) occurs.

4.2.2.3.4 The peak carrier deviation is then  $f_d=2.4f_m$ .

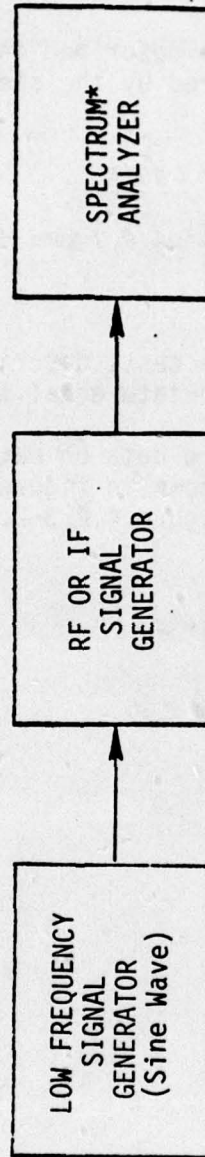
4.2.2.3.5 Read the rms value of the sinusoid. Call this  $V_{rms}$ .

4.2.2.3.6 The modulation sensitivity is:

$$S_m = \frac{2.4f_m}{2V_{rms}} \text{ Hz/volt}$$

4.2.2.3.7 Example: If it is desired to modulate the carrier  $0.7f_b$  peak-to-peak, where  $f_b$ =bit rate; the peak-to-peak voltage (v) of the bit stream is then:

$$v = \frac{0.7f_b}{S_m} \text{ volts}$$



*\*Spectrum analyzer may be either internal or external to the receiver used in the test.*

Figure 4.2.2-1 Test Setup for Frequency Modulation Sensitivity Calibration.

### 4.2.3 Bit Synchronizer Tests

4.2.3.1 Purpose - These tests determine the performance of the bit synchronizer under test when the input noise is obtained at the output of an FM receiver.

#### 4.2.3.2 Test Equipment:

Test equipment required is described in subparagraph 4.2.1.2 plus any additional equipment required by the specific test being conducted.

#### NOTE

*Refer to subparagraphs 4.0.1 and 4.0.2 for standard test conditions.*

4.2.3.3 Procedure - Repeat the tests described in Part I vs. pre-detection SNR expressed in a bandwidth equal to the bit rate.

4.2.3.4 Data Reduction - Record data on Data Sheet 4.2.3.1. An example of Data Sheet 4.2.3.1 use is shown in figure 4.2.3-1 and a corresponding sample data plot is shown in figure 4.2.3-2.

DATA SHEET 4.2.3.1 BIT SYNCHRONIZER TESTS

Test: 4.2.3 Bit Synchronizer Tests

Manufacturer \_\_\_\_\_

Tested by \_\_\_\_\_

Date \_\_\_\_\_

**SAMPLE DATA**  
**NOT TO BE USED FOR**  
**EQUIPMENT SPECIFICATIONS**

No. \_\_\_\_\_

Bit Synchronizer Input Signal Conditions						
PCM Signal				FM Link Settings		
Bit Rate kB/s	Premodulation Filter Bandwidth kHz	Code	Word Pattern	Carrier Deviation Peak-to- Peak, kHz	IF Bandwidth kHz	Post Detection Filter Bandwidth kHz
100	$\infty$	NRZ	PR	70	180	70

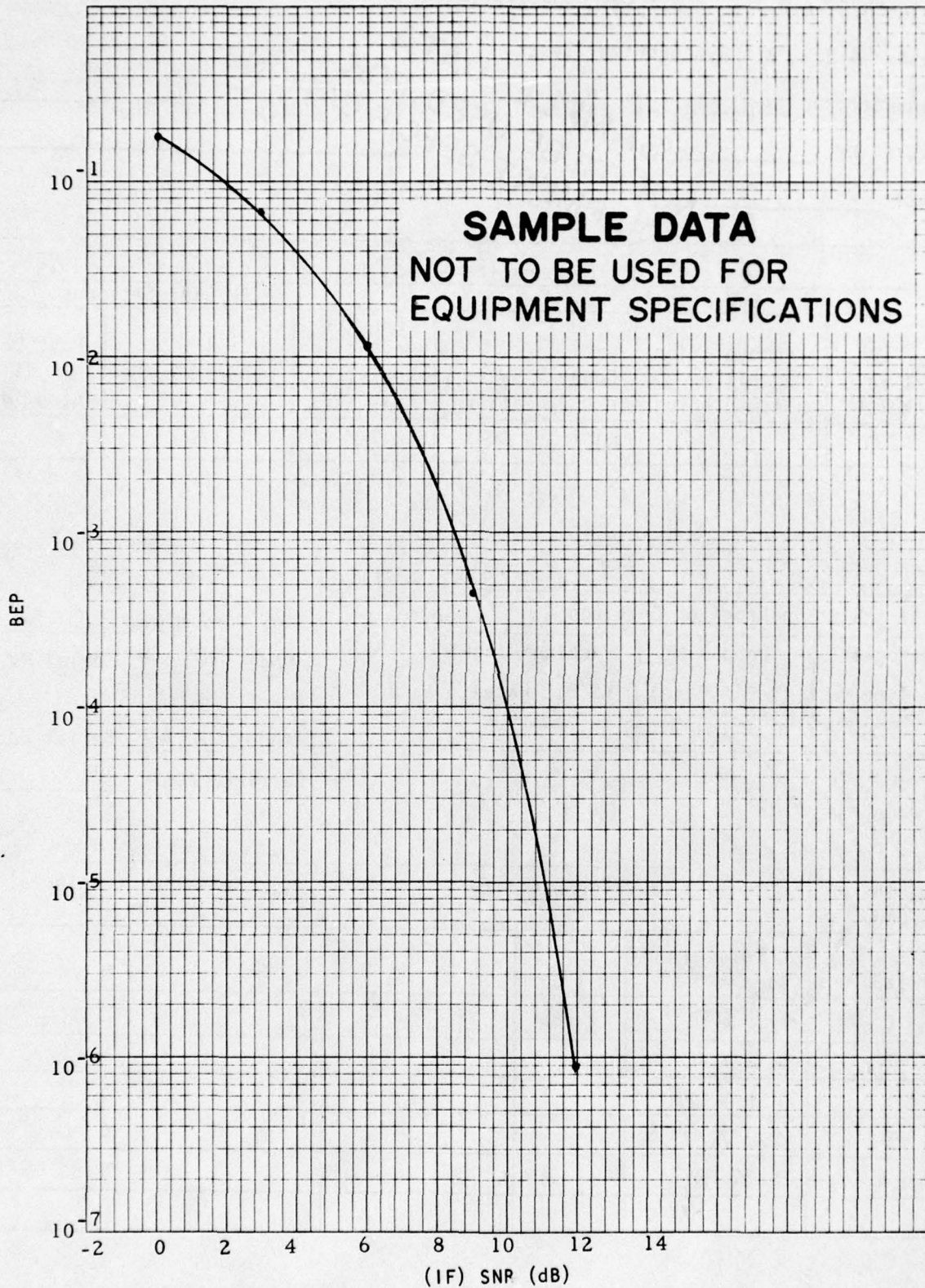
Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)
FS	0.1	-

Sig. Gen. Mfg. DCS  
 Model GOV-4 Serial No. 74386  
 Rcvr. Mfg. EMR  
 Model 4142 Serial No. 219  
 Carrier Freq. 450 KHz

IF SNR (dB)	Bit Error Probability			Measurement Interval (Period $10^n$ Bits)
	Total (1's + 0's)	1's	0's	
0	$1.8 \times 10^{-1}$			N
+3	$6.6 \times 10^{-2}$			5
+6	$1.1 \times 10^{-2}$			5
+9	$4.3 \times 10^{-4}$			6
+12	$9 \times 10^{-7}$			8

Figure 4.2.3-1 Sample of Data Sheet 4.2.3.1.

BIT ERROR PROBABILITY VERSUS IF  
SIGNAL-TO-NOISE RATIO WITH FM LINK



46 6463


 SEMI-LOGARITHMIC 7 CYCLES X 60 DIVISIONS  
KEUFFEL & ESSER CO. MADE IN U.S.A.

Figure 4.2.3-2 Sample Plot Presentation of Data Sheet 4.2.3.1.

DATA SHEET 4.2.3.1 BIT SYNCHRONIZER TESTS

Test: 4.2.3 Bit Synchronizer Tests

Manufacturer \_\_\_\_\_ Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Tested by \_\_\_\_\_, \_\_\_\_\_

Date \_\_\_\_\_

Bit Synchronizer Input Signal Conditions						
PCM Signal				FM Link Settings		
Bit Rate kB/s	Premodulation Filter Bandwidth kHz	Code	Word Pattern	Carrier Deviation Peak-to- Peak, kHz	IF Bandwidth kHz	Post Detection Filter Bandwidth kHz

Bit Synchronizer Settings		
Detector Type	Loop B.W. (% Bit Rate)	Tracking Range (% Bit Rate)

Sig. Gen. Mfg. \_\_\_\_\_

Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Rcvr. Mfg. \_\_\_\_\_

Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Carrier Freq. \_\_\_\_\_

IF SNR  (dB)	Bit Error Probability			Measurement Interval (Period $10^n$ Bits)  N
	Total (1's + 0's)	1's	0's	
0				5
+3				5
+6				5
+9				6
+12				8

## Appendix IV-A

### THE SPECTRUM OF AN NRZ-PN SEQUENCE

#### NOTE

*Appendix IV-A addresses material contained in chapter 2 of this volume.*

The spectrum of an NRZ-PN sequence consists of a Fourier series of sinusoids with a fundamental frequency equal to the sequence repetition rate with power values inscribed within the random PCM NRZ power spectrum depicted in figure IV-A.1. The fraction of the total power in each component near 0 frequency is approximately  $2/m$  where  $m$  is the number of bits in the sequence. Thus, when  $m$  is large, such as  $2 \times 10^3$ , the spectrum is nearly continuous and has the same shape as random NRZ. Similarly, for a splitphase PN sequence, the Fourier component frequencies are multiples of the sequence rate with power value inscribed within the random split-phase spectrum shown in figure IV-A.1.

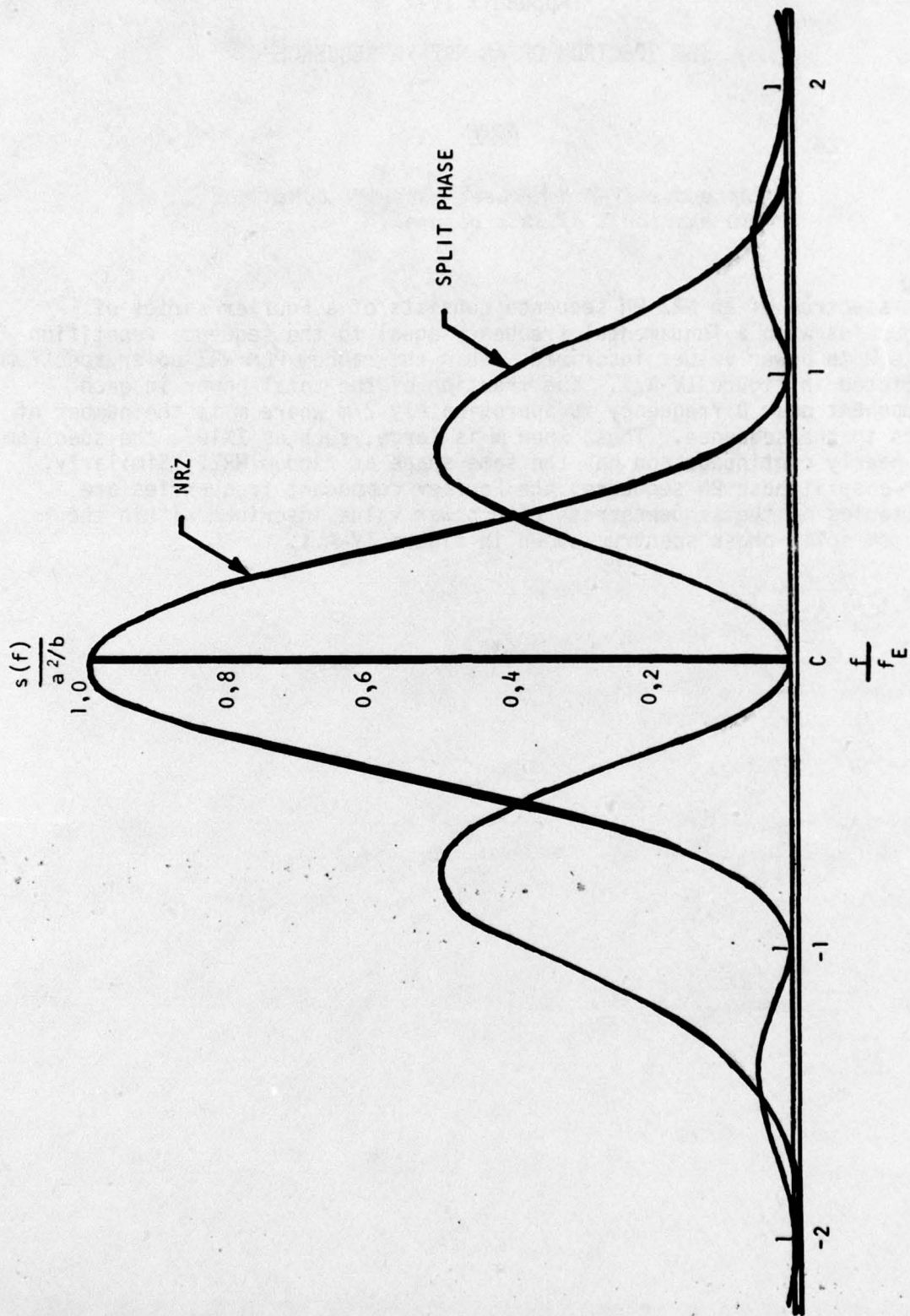


Figure IV-A.1 Random PCM Power Spectra.

## Appendix IV-B

### CALCULATION OF BIT ERROR MEASUREMENT INTERVALS

#### NOTE

*Appendix IV-B addresses material contained in chapter 4 of this volume.*

#### 1.0 General

This appendix describes the selection of measurement intervals and provides samples of experimental data and data plots. The description of interval selection is presented as a theoretical treatment of the calculation of bit error measurement interval. The sample experimental data and data plots are presented for illustration purposes only and are not to be used for equipment specifications. Sample data and data plots are provided for each of the tests indicated in the standard test procedures in chapter 4.

#### 1.1 Measurement Intervals:

1.1.1 Select measurement intervals which will provide statistically significant data with measurement repeatability equivalent to  $\pm 0.2$ -dB SNR variation. Measurements over intervals longer than the equivalent of  $10^7$  bit periods will require appropriate averaging of repeated measurements or the use of an external counter and timing arrangement. Some combinations of bit rate and SNR may require lengthy measurement intervals to obtain statistically significant data. The usefulness of such performance measurements will be dependent upon such things as the application in which the bit synchronizer is to be used and the purpose for which the measurements are made.

1.1.2 The measurement interval required for specified BEP measurement repeatability is a function of the BEP. However, the BEP can be expressed as a function of the signal energy per bit-to-noise power spectral density and this relationship can be used to derive a specified probability of a certain repeatability. The expression for the measurement interval (in bit periods) required to achieve a 0.95 probability of a  $\pm 0.2$ -dB repeatability is derived in this appendix. The derivation also shows the substitution required for other probabilities.

1.1.3 The BEP for unfiltered NRZ-L with additive gaussian noise and an optimum bit detector has been derived by Lindsey (see reference 1) to be:

$$\text{BEP} = \frac{1}{2} \text{erfc}(\sqrt{R}) = \frac{1}{\sqrt{\pi}} \int_{\sqrt{R}}^{\infty} e^{-t^2} dt$$

Where R=ratio of signal energy per bit to single-sided noise power spectral density in watts/Hz.

1.1.4 Hoel (see reference 2) states the following corollary: "The proportion of success  $x/n$  will be approximately normally distributed with mean  $P$  and standard deviation  $\sqrt{Pq/n}$  if  $n$  is sufficiently large. Where  $P=\text{BEP}$ ,  $q=1-P$ ,  $x$  is the number of bit errors in the interval, and  $n$  is the number of bits in the measurement interval for this appendix." Hoel also states that it is a good approximation when  $np > 5$ .

1.1.5 A normally distributed variable has a 0.95 probability of being within 1.96 standard deviations ( $\sigma$ ) of this mean. Therefore, if the change in BEP, caused by a 0.2-dB change in  $R$  is known and this change is forced to be larger than or equal to  $(1.96\sigma)$ , the probability of being within 0.2 dB of the actual BEP will be 0.95. Since the slope  $\left(\frac{d\text{BEP}}{dR} = \frac{e^{-R}}{\sqrt{\pi}}\right)$  of the BEP (linear) vs.  $R$  (dB) decreases for increasing  $R$ , it is necessary only to consider the case of  $R+0.2$  dB.

1.1.6 Therefore, the measurement interval required (in number of bit periods) can be derived as follows:

$$1.96\sigma \leq (\Delta P)\sigma = \sqrt{\frac{P(1-P)}{n}} = \sqrt{\frac{P}{n}} \sqrt{1-P} \approx \sqrt{\frac{P}{n}} \quad \text{for } P \ll 1.$$

$$1.96 \sqrt{\frac{P}{n}} \leq (\Delta P)$$

$$(\Delta P) \geq 1.96 \sqrt{\frac{P}{n}}$$

$$(\Delta P)^2 \geq 3.84 \left(\frac{P}{n}\right)$$

$$n \geq \frac{3.84P}{(\Delta P)^2}$$

$$n > \frac{3.84}{\left(\frac{\Delta P}{P}\right)^2} P$$

1.1.7 The BEPs calculated from  $BEP = \frac{1}{2} \operatorname{erfc}(\sqrt{R})$  are:

$\operatorname{erfc}(\sqrt{R})$  determined from NBS table (see reference 3).

<u>R</u>	<u>BEP</u>	<u>n Min</u>	<u>Expected Number of Bit Errors in n</u>
3.0	$2.29 \times 10^{-2}$	$1.5 \times 10^4$	350
3.2	$2.05 \times 10^{-2}$		
6.0	$2.39 \times 10^{-3}$	$4.6 \times 10^4$	110
6.2	$1.94 \times 10^{-3}$		
9.0	$3.37 \times 10^{-5}$	$1.1 \times 10^6$	38
9.2	$2.27 \times 10^{-5}$		
12.0	$9.0 \times 10^{-9}$	$1.5 \times 10^9$	13.5
12.2	$4.17 \times 10^{-9}$		
15.0	$9.1 \times 10^{-16}$		
15.2	$2.02 \times 10^{-16}$		

1.1.8 The measurement interval required for other probabilities within 0.2 dB can be calculated by replacing 1.96 by the K listed in the following chart.

<u>Probability</u>	<u>K</u>
0.90	1.64
0.95	1.96
0.99	2.58
0.999	3.30

1.1.9 The measurement intervals calculated for the theoretically optimum case will be longer than those required for the practical case with a physically realizable bit synchronizer. A longer measurement interval results in increased statistical accuracy.

#### REFERENCES

1. Lindsey, W.C., "Bit Synchronization System Performance Characterization, Modeling, and Tradeoff Study," Technical Publication TP-73-18, Pacific Missile Test Center, Point Mugu, California, 4 September 1973.
2. Hoel, Paul G., "Introduction to Mathematical Statistics," 4th edition, John Wiley and Sons, Inc., New York, 1971, pp 82-83.
3. National Bureau of Standards, "Tables of the Error Function and its Derivative," Applied Mathematics Series 41, 2nd edition, U.S. Government Printing Office, Washington, D.C., 1954.

## Appendix IV-C

### DEFINITIONS AND SUGGESTED CIRCUITS FOR BIT SYNCHRONIZER TESTING

#### NOTE

*Appendix IV-C addresses material contained in chapter 4 of this volume.*

#### 1.0 General

This appendix provides the definitions used for bit slippage probability (BSP) and acquisition testing and contains the suggested schematics for external delay and gate for procedure 2 (subparagraph 4.1.4.3.2) of the acquisition test.

#### 1.1 Definitions

1.1.1 Reference Clock - The reference clock is the clock of the test set PCM generator suitably delayed for phase coincidence with the bit synchronizer output clock when in stable locked condition.

1.1.2 Bit Slippage - Bit slippage is the gain or loss of one or more bits by the bit synchronizer.

1.1.3 Bit Acquisition - Bit acquisition has occurred when the BEP drops from approximately 0.5 to the BEP characteristic of the input SNR. In practice, there may be base-line offset due to logic, FM receiver mistuning, etc., which requires time to be balanced out by the bit synchronizer and detector. Thus, it is necessary to specify offset conditions in connection with this test.

#### 1.2 Auxiliary Circuits for Acquisition Test

1.2.1 Figure IV-C.1 gives circuits for the PCM delay and PCM gate included in figure 4.1.4-2.

1.2.2 Figure IV-C.2 illustrates the use of procedure 2 for acquisition time and consists of two photographs showing oscilloscope traces of eight acquisition tries for two different BEPs. Time to acquire can be easily determined by the photographic method with BEP as large as 0.4, as illustrated. Use of a storage scope would be faster because the times could be read directly and logged for each try.

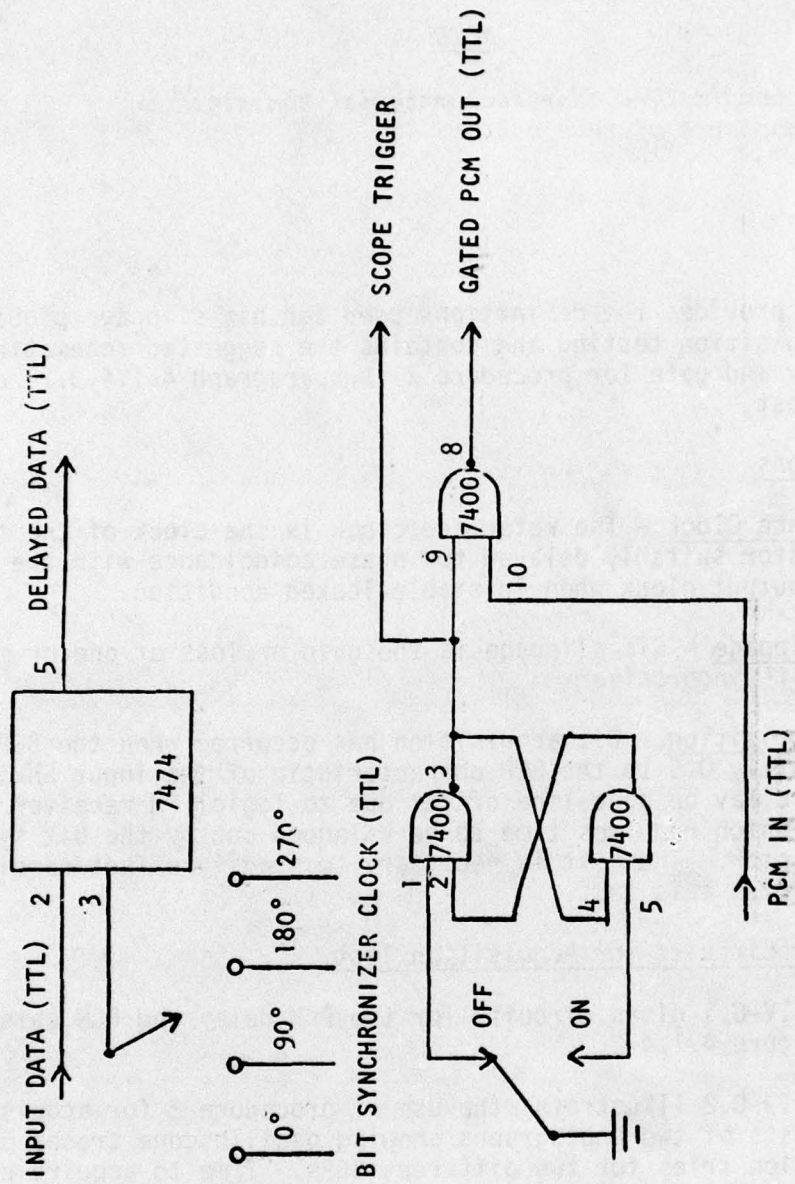
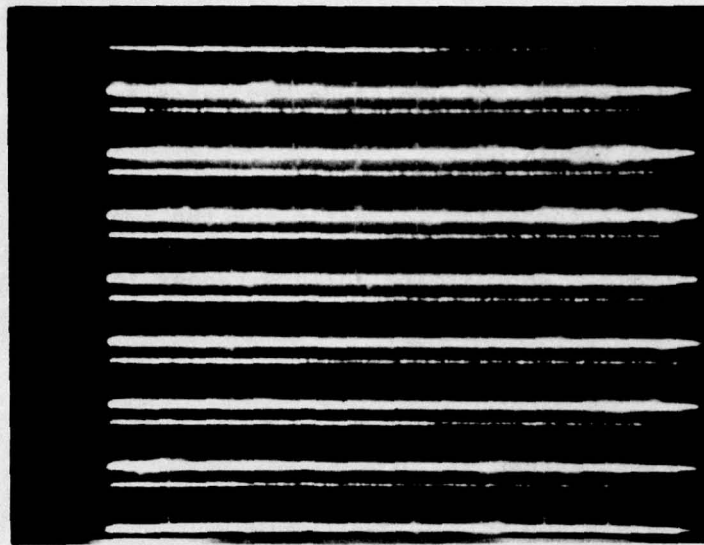
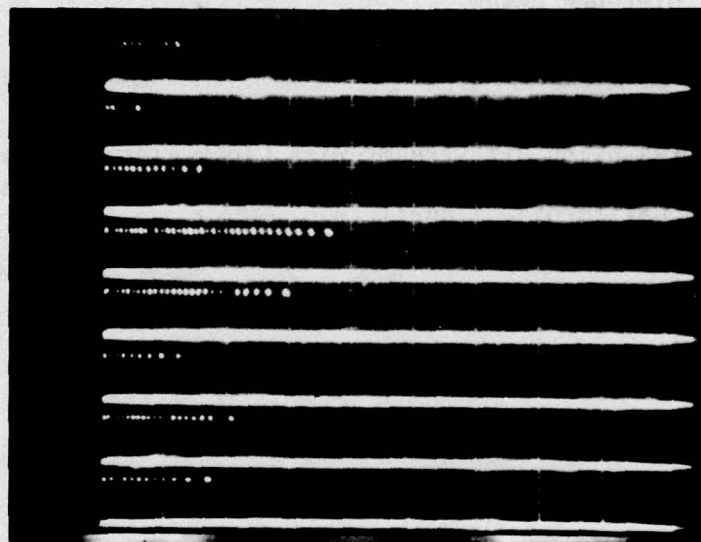


Figure IV-C-1 PCM Data Delay and PCM Gate.



$$P_e = 4 \times 10^{-2}$$

10 ms/div



$$P_e = 6 \times 10^{-6}$$

5 ms/div

Figure IV-C.2 Illustrations of Procedure 2 of the Acquisition Test.

### 1.3 Suggested Circuits for Amplitude Modulator and Noise Shaper

#### 1.3.1 Amplitude Modulator

Figure IV-C.3 is a suggested schematic for the amplitude modulator. This circuit, with some minor changes, was taken from the Motorola application sheets. Approximate voltage ranges for the two inputs are given. This circuit will work satisfactorily to at least  $10^6$  bits/sec.

#### 1.3.2 Noise Shaper

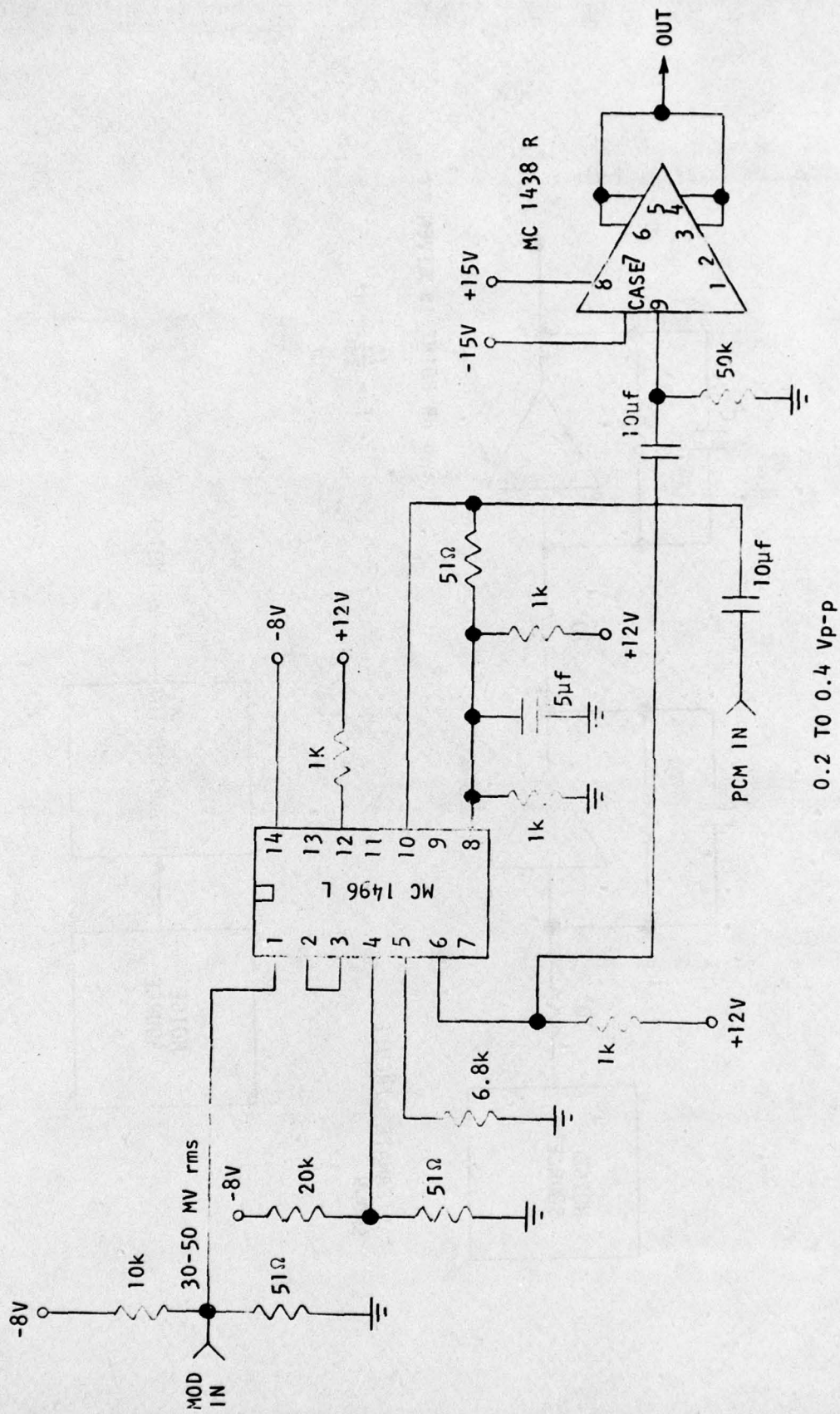
Figure IV-C.4 is a suggested schematic for shaping the noise for the jitter test, subparagraph 4.1.5.3.11.

#### 1.3.3 IF Bandwidth and Carrier Modulation for Base-Line Wander Plus Jitter Test

When base-line wander and AM are applied simultaneously to the bit stream, an IF bandwidth wider than the optimum for unperturbed bit streams is required. As an example, for 50-percent AM and 50-percent base-line wander, the IF bandwidth should be about  $4f_b$  and the carrier modulation should be about  $0.5f_b$  at the lowest point of the AM, i.e., with no AM it should be  $f_b$  (where  $f_b$  is the bit rate). For more details, see reference below.

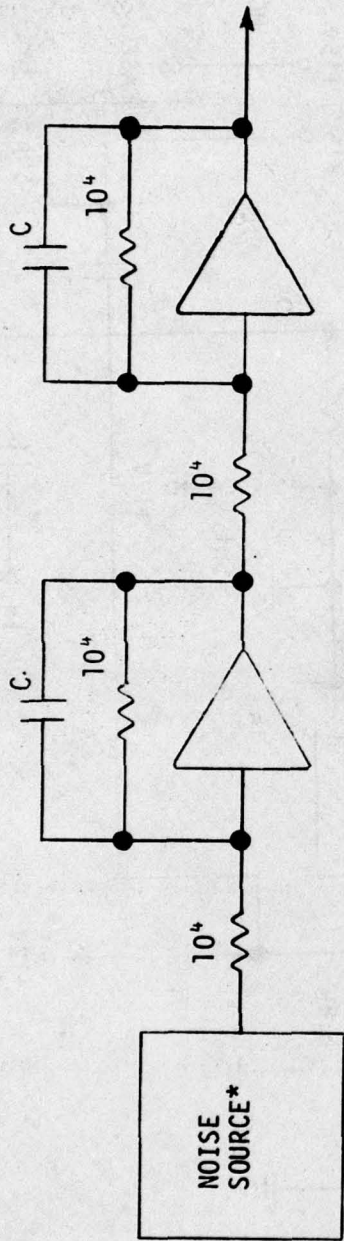
#### REFERENCE

Nichols, M. H., Consultant, "Bit Synchronizer and Signal Conditioner Test Procedures Using Bit Streams with Clock Flutter, Zero Wander and Amplitude Modulation," TOR-0076 (6550-38)-6, The Aerospace Corporation, Los Angeles, California, 1 April 1976.



0.2 TO 0.4 Vp-p

Figure IV-C.3 Suggested Circuit for Amplitude Modulator.



THE 6 dB POINT IS GIVEN BY:

$$f = \frac{10^{-4}}{2\pi C} \text{ Hz}$$

\*ALTERNATE CIRCUIT SHOWN

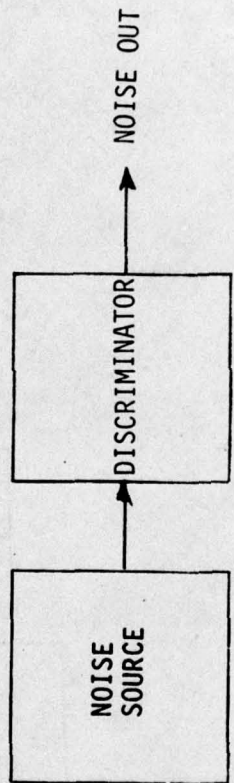


Figure IV-C.4 Jitter Noise Shaping Circuit.

**SUPPLEMENTARY**

**INFORMATION**

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REPLY TO  
ATTN OF:

STEWS-SA-R  
White Sands Missile Range, NM 88002

1 June 1989

SUBJECT:

Chapter 5 for Volume IV of Document 118-79

TO: All Holders of Document 118-79

Attached is Chapter 5 for Volume IV, Test Methods for Data Multiplex Equipment, of Document 118-79, Test Methods for Telemetry Systems and Subsystems. Please add this chapter to the document.

Encl  
as

*Diane H. Fulbright*

DIANE H. FULBRIGHT  
Technical Editor/Writer  
Range Commanders Council

CHAPTER 5 - FM DISCRIMINATORS

PAGE

5.0	General.....	5-1
5.1	Deviation Sensitivity and Static Linearity...	5-3
5.2	Zero and Band Edge Stability Test.....	5-14
5.3	Static Noise.....	5-18
5.4	Harmonic Distortion.....	5-24
5.5	Line Voltage Sensitivity.....	5-29
5.6	Output Impedance and Current.....	5-33
5.7	Amplitude Modulation Rejection Test.....	5-38
5.8	Signal-To-Noise Ratio.....	5-45
5.9	Band Pass Input Filter Shape.....	5-51
5.10	Out-of-Band Frequency Rejection.....	5-61
5.11	Pulse Response.....	5-66
5.12	Acquisition and Settling Time.....	5-72
5.13	Data Frequency Response.....	5-77
5.14	Tape Speed Compensation.....	5-82
5.15	Discriminator Phase Response.....	5-87
5.16	Two Tone Intermodulation Test.....	5-102

LIST OF FIGURES

FIGURE NO.

5.1.1	Test Setup for Deviation Sensitivity and Static Linearity.....	5-4
5.2.1	Test Setup for Zero and Band Edge Stability..	5-15
5.3.1	Test Setup for Static Noise.....	5-19
5.4.1	Test Setup for Harmonic Distortion.....	5-25
5.5.1	Test Setup for Line Voltage Sensitivity.....	5-30
5.6.1	Test Setup for Output Impedance and Current..	5-34
5.7.1	Test Setup for Amplitude Modulation Rejection.....	5-39
5.8.1	Test Setup for Signal-to-Noise Ratio.....	5-46
5.9.1	Test Setup for Bandpass Input Filter Frequency Response.....	5-53
5.9.2	Test Setup for Bandpass Input Filter Frequency Response.....	5-56
5.9.3	Test Setup for Bandpass Input Filter Frequency Response.....	5-57
5.10.1	Test Setup for Out-of-Band Frequency Response.....	5-62
5.11.1	Test Setup for Pulse Response.....	5-67
5.12.1	Test Setup for Acquisition and Settling Time.....	5-73
5.12.2	Photograph of Oscilloscope Display for Acquisition and Settling Time Test.....	5-75
5.13.1	Test Setup for Data Frequency Response.....	5-78
5.14.1	Test Setup for Tape Speed Compensation Test..	5-83
5.15.1	Test Setup for Discriminator Phase Response..	5-88
5.15.2	Test Setup for Discriminator Phase Response (Procedure 2).....	5-90
5.16.1	Test Setup for Two Tone Intermodulation Test.....	5-103

LIST OF DATA SHEETS

<u>DATA SHEET NO.</u>	<u>PAGE</u>
5.1.1 Deviation Sensitivity and Static Linearity (11 Point).....	5-5
5.1.2 Deviation Sensitivity and Static Linearity (5 Point).....	5-7
5.1.1 (Sample) - Deviation Sensitivity and Static Linearity (11 Point).....	5-10
5.1.2 (Sample) - Deviation Sensitivity and Static Linearity (5 Point).....	5-12
5.2.1 Zero and Band Edge Stability Test.....	5-16
5.2.1 (Sample) - Zero and Band Edge Stability Test.....	5-17
5.3.1 Static Noise Test.....	5-20
5.3.1 (Sample) - Static Noise Test.....	5-22
5.4.1 Harmonic Distortion.....	5-27
5.4.1 (Sample) - Harmonic Distortion.....	5-28
5.5.1 Line Voltage Sensitivity Test.....	5-31
5.5.1 (Sample) - Line Voltage Sensitivity Test.....	5-32
5.6.1 Output Impedance and Current.....	5-35
5.6.1 (Sample) - Output Impedance and Current.....	5-37
5.7.1 Amplitude Modulation Rejection.....	5-40
5.7.1 (Sample) - Amplitude Modulation Rejection....	5-41
5.7.1 (Sample) - Lower Band Edge.....	5-42
5.7.1 (Sample) - Center Frequency.....	5-43
5.7.1 (Sample) - Upper Band Edge.....	5-44
5.8.1 Signal-to-Noise Ratio.....	5-47
5.8.1 (Sample) - Signal-to-Noise Ratio.....	5-50
5.9.1 Bandpass Filter Frequency Response.....	5-54
5.9.1 (Sample) - Bandpass Filter Frequency Response.....	5-58
5.9.1 (Sample) - Bandpass Filter Characteristic - Sine Wave Input.....	5-59
5.9.1 (Sample) - Bandpass Filter Characteristic - White Noise Input.....	5-60
5.10.1 Adjacent Channel or Unwanted Frequency Rejection.....	5-63
5.10.1 (Sample) - Adjacent Channel or Unwanted Frequency Rejection.....	5-65
5.11.1 Pulse Response.....	5-68
5.11.1 (Sample) - Pulse Response.....	5-69
5.11.1 (Sample) - Pulse Response Peak Deviation - 4kHz.....	5-70
5.11.1 (Sample) - Pulse Response Peak Deviation - 2kHz.....	5-71
5.12.1 Acquisition and Settling Time.....	5-74
5.12.1 (Sample) - Acquisition and Settling Time.....	5-76
5.13.1 Data Frequency Response.....	5-80
5.13.1 (Sample) - Data Frequency Response.....	5-81
5.14.1 Tape Speed Compensation.....	5-85
5.14.1 (Sample) - Tape Speed Compensation.....	5-86

DATA SHEET NO.

PAGE

5.15.1	Discriminator Phase Response (Procedure 1)...	5-91
5.15.1	(Sample) - Discriminator Phase Response (Procedure 1).....	5-92
5.15.2	Discriminator Phase Response (Procedure 2)...	5-93
5.15.2	(Sample) - Discriminator Phase Response (Procedure 2).....	5-95
5.15.2	(Sample Number 1) (60Hz Noise) - Constant Amplitude Phase Response.....	5-96
5.15.2	(Sample Number 2) - Constant Amplitude Phase and Amplitude Response.....	5-97
5.15.2	(Sample Number 3) - Phase and Amplitude Response (Wider Frequency Scale).....	5-98
5.15.2	(Sample Number 4) - Constant Delay Phase Response.....	5-99
5.15.2	(Sample Number 5) - Phase and Amplitude Response.....	5-100
5.15.2	(Sample Number 6) - Phase Response (Wide Frequency Scale).....	5-101
5.16.1	Two Tone Intermodulation Test.....	5-105
5.16.1	(Sample) - Tone Tone Intermodulation Test....	5-106
5.16.1	(Sample) - Discriminator LPF Output Two Tone Test.....	5-107
5.16.1	(Sample) - Discriminator LPF Output Two Tone Test.....	5-108

## Chapter 5

### FM DISCRIMINATORS

#### 5.0 General

5.0.1 The FM discriminator evaluation is the acquisition and distribution of performance information that will be useful to groups engaged in telemetry activities. To this end, uniformity of test procedures used is important for obtaining valid comparisons of performance and periodic checks on installed equipment or testing of new equipment.

5.0.2 Performance tests are recommended for all IRIG subcarrier channels intended for use with the discriminators. Care should be taken to establish known environmental conditions such as temperature and humidity to minimize the uncertainty in performance. In addition, the equipment should be energized from a regulated line. Particular care should be taken in the test setup design to avoid the error-producing effects of ground-loop currents.

#### 5.0.3 Definition of Terms

5.0.3.1 Band Pass Input Filter (BPIF) - The channel selection filter centered at the channel center frequency and with a 3-dB bandwidth corresponding to the channel bandwidth.

5.0.3.2 Center Frequency ( $f_c$ ) - The center frequency for a given channel as defined in IRIG Standard 106-XX, Telemetry Standards, Appendix A, paragraph 5.4.

5.0.3.3 Deviation Ratio - The deviation ratio of a channel is defined as the ratio of one half the defined deviation bandwidth to the cutoff frequency of the discriminator low pass output filter.

5.0.3.4 Lower Band Edge (LBE) Frequency - The frequency which corresponds to the lower deviation limit defined in table 3-1, IRIG-106-XX, for a given channel.

5.0.3.5 Low Pass Output Filter (LPOF) - The output filter contained in or plugged into the discriminator with its cutoff frequency (3-dB point) defined as the maximum data frequency.

5.0.3.6 Modulation Index - In angle modulation with a sinusoidal modulating wave, the ratio of the peak frequency deviation to the frequency of the modulating wave:

$$m = \Delta f / f_{\max}$$

where  $\Delta f$  = the maximum frequency difference between the modulated carrier and the unmodulated carrier.

$f_{\max}$  = the maximum modulating frequency.

5.0.3.7 Upper Band Edge Frequency (UBE) - The frequency which corresponds to the upper deviation limit defined in IRIG-106-XX, subparagraph 7.2.25.

5.0.4 Standard Test Conditions - To ensure uniformity of testing, the following standard test conditions and preliminary adjustments should be completed before individual tests are conducted.

5.0.4.1 Input Signal Level - The standard input signal level for the specified procedures is 0.3 Vrms, except as modified in a specific procedure.

5.0.4.2 Output Load - The load placed on the discriminator shall be the maximum load specified.

5.0.4.3 Warm-up

5.0.4.3.1 The discriminator under test shall be allowed to warm up prior to the start of a test according to the performance specification.

5.0.4.3.2 Test equipment used in test procedures shall be allowed to warm up so that drifts and other variations caused by the test equipment shall be minimized. Generally, a 30 minute warm-up period is recommended.

5.0.4.4 Output Voltage - The output voltage shall be adjusted prior to the start of a test to conform to the following requirements:

5.0.4.4.1 With the input signal set to the center frequency of the desired channel and unmodulated, the output voltage shall be  $0 \pm 10$  mVdc.

5.0.4.4.2 With the upper (lower) band edge frequency applied to the discriminator input, the output voltage shall be  $+10(-10)$  Vdc or the maximum specified for operation within  $\pm 10$  mV dc.

5.0.4.5 Tolerances - The measurements which are identified in the following test methods should be made with sufficient precision to satisfy the intended purpose. It is recommended that the maximum tolerance used conform to the following:

Frequency	$\pm 0.1\%$ or 1 Hz whichever is smaller
Voltage	$\pm 1.0$ mV
dB	$\pm 0.1$ dB.

5.0.4.6 An oscilloscope is connected to the discriminator output in most tests. It is used to observe glitches and to identify anomalous behavior which may not be detected by other instrumentation.

## 5.1 Deviation Sensitivity and Static Linearity

5.1.1 Purpose - This test determines the deviation sensitivity and static linearity of an FM discriminator.

### 5.1.2 Test Equipment

Signal generator  
Frequency counter  
Digital voltmeter (dc)

### 5.1.3 Test Method

5.1.3.1 Setup - Connect the test equipment as shown in figure 5.1.1.

#### 5.1.3.2 Conditions

5.1.3.2.1 Set the discriminator low pass output filter to cut off frequency of interest.

5.1.3.2.2 Maximize output load according to specification.

#### 5.1.3.3 Procedure

5.1.3.3.1 Set the signal generator frequency to center frequency and adjust output voltage to zero.

5.1.3.3.2 Set the input frequency to LBU and adjust output voltage to specified maximum output level.

5.1.3.3.3 Repeat steps 5.1.3.3.1 and 5.1.3.3.2 as necessary to achieve desired accuracy.

5.1.3.3.4 The test may be performed with either 5 or 11 data points. Generally the 11-step data collection is used for acceptance testing, and the 5-step data collection is used for rapid revalidation of discriminator performance.

5.1.3.3.5 Eleven Point Test - Record the input frequency and output voltage for frequencies equivalent to the LBE deviation limit frequency  $f_c - 0.8(\Delta f)$ ,  $f_c - 0.6(\Delta f)$ ,  $f_c - 0.4(\Delta f)$ ,  $f_c - 0.2(\Delta f)$ ,  $f_c$ ,  $f_c + 0.2(\Delta f)$ ,  $f_c + 0.4(\Delta f)$ ,  $f_c + 0.6(\Delta f)$ ,  $f_c + 0.8(\Delta f)$  and UBE deviation limit frequency on data sheet 5.1.1, where  $\Delta f = f_c - \text{LBE} = \text{UBE} - f_c$ .

5.1.3.3.6 Five Point Test - Record the input frequency and output voltage for frequencies equivalent to the LBE deviation limit,  $f_c - 0.5(\Delta f)$ ,  $f_c$ ,  $f_c + 0.5(\Delta f)$ , UBE deviation limit on data sheet 5.1.2.

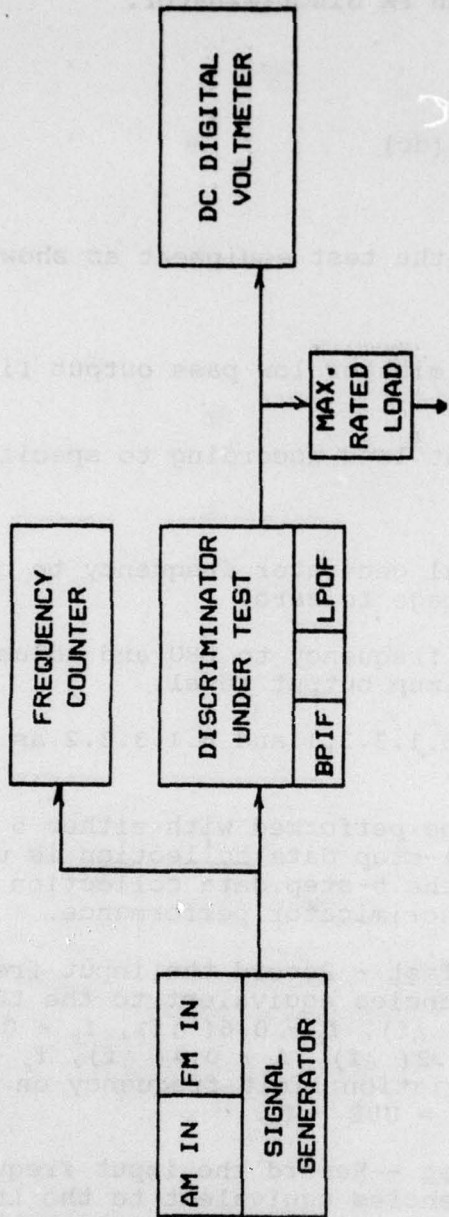


Figure 5.1.1 Test Setup for Deviation Sensitivity and Static Linearity.

## FM DISCRIMINATORS

DATA SHEET 5.1.1

TEST Deviation Sensitivity and Static Linearity (11 Point)

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_

SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz

LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz

LOW PASS FILTER TYPE:     CA         CD         Other \_\_\_\_\_

TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Calculate:  $\Delta f = \text{Center Freq} - \text{Lower Band Edge Freq} = \underline{\hspace{2cm}}$  kHz  
 $= \text{Upper Band Edge Freq} - \text{Center Freq} = \underline{\hspace{2cm}}$  kHz

i	Equation	Frequency Calculated (kHz)
1	$f_c - \Delta f$	_____
2	$f_c - 0.8 \Delta f$	_____
3	$f_c - 0.6 \Delta f$	_____
4	$f_c - 0.4 \Delta f$	_____
5	$f_c - 0.2 \Delta f$	_____
6	$f_c$	_____
7	$f_c + 0.2 \Delta f$	_____
8	$f_c + 0.4 \Delta f$	_____
9	$f_c + 0.6 \Delta f$	_____
10	$f_c + 0.8 \Delta f$	_____
11	$f_c + \Delta f$	_____

Record the actual input frequency and output voltage in the table below and calculate the remaining information:

i	Input Frequency (kHz)	Output Voltage (Vdc)	$\Delta f_i = f_i - f_c$	$(\Delta f_i)^2$	$\Delta f_i \times V_i$
1	_____	_____	_____	_____	_____
2	_____	_____	_____	_____	_____
3	_____	_____	_____	_____	_____
4	_____	_____	_____	_____	_____
5	_____	_____	_____	_____	_____
6	$f_c$	_____	_____	_____	_____
7	_____	_____	_____	_____	_____
8	_____	_____	_____	_____	_____
9	_____	_____	_____	_____	_____
10	_____	_____	_____	_____	_____
11	_____	_____	_____	_____	_____
Add columns: $\Sigma V_i =$		$\Sigma \Delta f_i =$	$\Sigma (\Delta f_i)^2 =$	$\Sigma \Delta f_i \times V_i =$	
			$(\Sigma \Delta f_i)^2 =$		

DATA SHEET 5.1.1 (Continued)

DEVIATION SENSITIVITY=

$$b = \frac{11 \left( \sum_{i=1}^{11} \Delta f_i \times V_i \right) - \left( \sum_{i=1}^{11} V_i \right) \left( \sum_{i=1}^{11} \Delta f_i \right)}{11 \left( \sum_{i=1}^{11} (\Delta f_i)^2 \right) - \left( \sum_{i=1}^{11} \Delta f_i \right)^2} = \text{_____ volts/kHz,}$$

and

ZERO OFFSET=

$$a = \left( \sum_{i=1}^{11} V_i - b \times \sum_{i=1}^{11} \Delta f_i \right) / 11 = \text{_____ volts.}$$

Calculate the following:

i	$\Delta f_i$	$a + b \Delta f_i$	$V_i$	DEVIATION FROM LINEAR FIT $(a + b \Delta f_i) - V_i$
1	_____	_____	_____	_____
2	_____	_____	_____	_____
3	_____	_____	_____	_____
4	_____	_____	_____	_____
5	_____	_____	_____	_____
6	_____	_____	_____	_____
7	_____	_____	_____	_____
8	_____	_____	_____	_____
9	_____	_____	_____	_____
10	_____	_____	_____	_____
11	_____	_____	_____	_____

## FM DISCRIMINATORS

DATA SHEET 5.1.2

TEST Deviation Sensitivity and Static Linearity (5 Point)

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_  
 SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz  
 LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz  
 LOW PASS FILTER TYPE:     CA     CD     Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Calculate:  $\Delta f = \text{Center Freq} - \text{Lower Band Edge Freq} = \underline{\hspace{2cm}} \text{ kHz}$   
 $\hspace{10em} = \text{Upper Band Edge Freq} - \text{Center Freq} = \underline{\hspace{2cm}} \text{ kHz}$

i	Equation	Frequency Calculated (kHz)
1	$f_c - \Delta f$	_____
2	$f_c - 0.5 \Delta f$	_____
3	$f_c$	_____
4	$f_c + 0.5 \Delta f$	_____
5	$f_c + \Delta f$	_____

Record the actual input frequency and output voltage in the table below and calculate the remaining information:

i	Input Frequency (kHz)	Output Voltage (Vdc)	$\Delta f_i = f_i - f_c$	$(\Delta f_i)^2$	$\Delta f_i \times V_i$
1	_____	_____	_____	_____	_____
2	_____	_____	_____	_____	_____
3	$f_c$ _____	_____	_____	_____	_____
4	_____	_____	_____	_____	_____
5	_____	_____	_____	_____	_____
Add columns:		$\Sigma V_i =$ _____	$\Sigma \Delta f_i =$ _____	$\Sigma (\Delta f_i)^2 =$ _____	$\Sigma \Delta f_i \times V_i =$ _____
			$(\Sigma \Delta f_i)^2$ _____		

DATA SHEET 5.1.2 (Continued)

DEVIATION SENSITIVITY=

$$b = \frac{5 \left( \sum_{i=1}^5 \Delta f_i \times V_i \right) - \left( \sum_{i=1}^5 V_i \right) \left( \sum_{i=1}^5 \Delta f_i \right)}{5 \left( \sum_{i=1}^5 (\Delta f_i)^2 \right) - \left( \sum_{i=1}^5 \Delta f_i \right)^2} = \text{_____ volts/kHz,}$$

and

$$\text{ZERO OFFSET} = a = \left( \sum_{i=1}^5 V_i - b \times \sum_{i=1}^5 \Delta f_i \right) / 5 = \text{_____ volts.}$$

Calculate the following:

i	$\Delta f_i$	$a + b \Delta f_i$	$V_i$	DEVIATION FROM LINEAR FIT $(a + b \Delta f_i) - V_i$
1	_____	_____	_____	_____
2	_____	_____	_____	_____
3	_____	_____	_____	_____
4	_____	_____	_____	_____
5	_____	_____	_____	_____

#### 5.1.4 Data Reduction

5.1.4.1 Eleven Point Test. The best fit straight line is of the form

$$a + b (f - f_c) = V$$

where a is the center frequency output voltage offset in volts, and b is the deviation sensitivity in volts per kilohertz. The coefficients a and b are obtained from the equations

$$b = \frac{11 \left( \sum_{i=1}^{11} \Delta f_i \times V_i \right) - \left( \sum_{i=1}^{11} V_i \right) \left( \sum_{i=1}^{11} \Delta f_i \right)}{11 \left( \sum_{i=1}^{11} (\Delta f_i)^2 \right) - \left( \sum_{i=1}^{11} \Delta f_i \right)^2}$$

and

$$a = \left( \sum_{i=1}^{11} V_i - b \times \sum_{i=1}^{11} \Delta f_i \right) / 11,$$

where  $\Delta f_i$  is the ith frequency difference ( $f_i - f_c$ )

$V_i$  is the ith output voltage.

The deviation sensitivity (b) and offset (a) should be compared to the specified value. The difference between the actual output voltage,  $V_i$ , and that calculated from the best fit curve defined by the coefficients a and b should be compared to the static linearity specification (see data sheet 5.1.1 sample).

5.1.4.2 Five Point Test - The equations for determining a and b are

$$b = \frac{5 \left( \sum_{i=1}^5 \Delta f_i \times V_i \right) - \left( \sum_{i=1}^5 V_i \right) \left( \sum_{i=1}^5 \Delta f_i \right)}{5 \left( \sum_{i=1}^5 (\Delta f_i)^2 \right) - \left( \sum_{i=1}^5 \Delta f_i \right)^2}$$

and

$$a = \left( \sum_{i=1}^5 V_i - b \times \sum_{i=1}^5 \Delta f_i \right) / 5,$$

where a, b,  $\Delta f_i$  and  $V_i$  are defined in subparagraph 5.1.4.1. The deviation sensitivity (b), offset (a) and the deviation from best fit straight line should be compared to the specification as in subparagraph 5.1.4.1 (see data sheet sample 5.1.2).

FM DISCRIMINATORS

DATA SHEET 5.1.1 (Sample)

TEST Deviation Sensitivity and Static Linearity (11 Point)

MANUFACTURER XYZ MODEL DEF  
 SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY 70. kHz UPPER BAND EDGE 80.5 kHz  
 LOWER BAND EDGE 59.5 kHz LOW PASS FILTER CUTOFF 2.1 kHz  
 LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Calculate:  $\Delta f = \text{Center Freq} - \text{Lower Band Edge Freq} = \underline{10.5}$  kHz  
 $= \text{Upper Band Edge Freq} - \text{Center Freq} = \underline{10.5}$  kHz

i	Equation	Frequency Calculated(kHz)
1	$f_c - \Delta f$	<u>59.5</u>
2	$f_c - 0.8 \Delta f$	<u>61.1</u>
3	$f_c - 0.6 \Delta f$	<u>63.7</u>
4	$f_c - 0.4 \Delta f$	<u>65.8</u>
5	$f_c - 0.2 \Delta f$	<u>67.9</u>
6	$f_c$	<u>70.0</u>
7	$f_c + 0.2 \Delta f$	<u>72.1</u>
8	$f_c + 0.4 \Delta f$	<u>74.2</u>
9	$f_c + 0.6 \Delta f$	<u>76.3</u>
10	$f_c + 0.8 \Delta f$	<u>78.4</u>
11	$f_c + \Delta f$	<u>80.5</u>

Record the actual input frequency and output voltage in the table below and calculate the remaining information:

i	Input Frequency (kHz)	Output Voltage (Vdc)	$\Delta f_i = f_i - f_c$	$(\Delta f_i)^2$	$\Delta f_i \times V_i$
1	<u>59.500</u>	<u>-10.012</u>	<u>-10.5</u>	<u>110.25</u>	<u>105.126</u>
2	<u>61.600</u>	<u>-8.010</u>	<u>-8.4</u>	<u>70.56</u>	<u>67.284</u>
3	<u>63.700</u>	<u>-6.009</u>	<u>-6.3</u>	<u>39.69</u>	<u>37.8567</u>
4	<u>65.800</u>	<u>-4.007</u>	<u>-4.2</u>	<u>17.64</u>	<u>16.8294</u>
5	<u>67.900</u>	<u>-2.006</u>	<u>-2.1</u>	<u>4.41</u>	<u>4.2126</u>
6	<u><math>f_c</math> 70.000</u>	<u>-0.006</u>	<u>0</u>	<u>0.00</u>	<u>0.000</u>
7	<u>72.100</u>	<u>+1.995</u>	<u>2.1</u>	<u>4.41</u>	<u>4.1895</u>
8	<u>74.200</u>	<u>+3.996</u>	<u>4.2</u>	<u>17.64</u>	<u>16.7832</u>
9	<u>76.300</u>	<u>+5.997</u>	<u>6.3</u>	<u>39.69</u>	<u>37.7811</u>
10	<u>78.400</u>	<u>+7.998</u>	<u>8.4</u>	<u>70.65</u>	<u>67.1832</u>
11	<u>80.500</u>	<u>+9.997</u>	<u>10.5</u>	<u>110.25</u>	<u>104.9685</u>
Add columns:		<u><math>\Sigma V_i = -0.063</math></u>	<u><math>\Sigma \Delta f_i = 0</math></u>	<u><math>\Sigma (\Delta f_i)^2 = 485.1</math></u>	<u><math>\Sigma \Delta f_i \times V_i = 470.6142</math></u>
			<u><math>(\Sigma \Delta f_i)^2 = 0</math></u>		

DATA SHEET 5.1.1 (Sample) (Continued)

DEVIATION SENSITIVITY=

$$b = \frac{11 \left( \sum_{i=1}^{11} \Delta f_i \times V_i \right) - \left( \sum_{i=1}^{11} V_i \right) \left( \sum_{i=1}^{11} \Delta f_i \right)}{11 \left( \sum_{i=1}^{11} (\Delta f_i)^2 \right) - \left( \sum_{i=1}^{11} \Delta f_i \right)^2} = \underline{0.95282 \text{ volts/kHz}},$$

and

ZERO OFFSET=

$$a = \left( \sum_{i=1}^{11} V_i - b \times \sum_{i=1}^{11} \Delta f_i \right) / 11 = \underline{-0.00573 \text{ volts}}.$$

Calculate the following:

i	$\Delta f_i$	$a + b \Delta f_i$	$V_i$	DEVIATION FROM LINEAR FIT $(a + b \Delta f_i) - V_i$
1	-10.5	-10.010	-10.012	0.002
2	-8.4	-8.009	-8.010	0.001
3	-6.3	-6.008	-6.009	0.001
4	-4.2	-4.008	-4.007	-0.001
5	-2.1	-2.007	-2.006	-0.001
6	0	-0.006	-0.006	0
7	2.1	1.995	1.995	0
8	4.2	3.996	3.996	0
9	6.3	5.997	5.997	0
10	8.4	7.998	7.998	0
11	10.5	9.999	9.997	0.002

FM DISCRIMINATORS

DATA SHEET 5.1.2 (Sample)

TEST Deviation Sensitivity and Static Linearity (5 Point)

MANUFACTURER XYZ MODEL DEF

SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY 80 kHz UPPER BAND EDGE 84 kHz

LOWER BAND EDGE 76 kHz LOW PASS FILTER CUTOFF 1 kHz

LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_

TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Calculate:  $\Delta f = \text{Center Freq} - \text{Lower Band Edge Freq} = \underline{4}$  kHz  
 $= \text{Upper Band Edge Freq} - \text{Center Freq} = \underline{4}$  kHz

i	Equation	Frequency Calculated (kHz)
1	$f_c - \Delta f$	<u>76</u>
2	$f_c - 0.5 \Delta f$	<u>78</u>
3	$f_c$	<u>80</u>
4	$f_c + 0.5 \Delta f$	<u>82</u>
5	$f_c + \Delta f$	<u>84</u>

Record the actual input frequency and output voltage in the table below and calculate the remaining information:

i	Input Frequency (kHz)	Output Voltage (Vdc)	$\Delta f_i = f_i - f_c$	$(\Delta f_i)^2$	$\Delta f_i \times V_i$
1	<u>76</u>	<u>8.953</u>	<u>-4</u>	<u>16.</u>	<u>-35.812</u>
2	<u>78</u>	<u>4.476</u>	<u>-2</u>	<u>4.</u>	<u>-8.952</u>
3	$f_c$ <u>80</u>	<u>0.001</u>	<u>0</u>	<u>0.0</u>	<u>0.000</u>
4	<u>82</u>	<u>-4.475</u>	<u>2</u>	<u>4.0</u>	<u>-8.950</u>
5	<u>84</u>	<u>-8.951</u>	<u>4</u>	<u>16.0</u>	<u>-35.804</u>
Add columns:		$\Sigma V_i =$ <u>0.004</u>	$\Sigma \Delta f_i =$ <u>0</u>	$\Sigma (\Delta f_i)^2 =$ <u>40</u>	$\Sigma \Delta f_i \times V_i =$ <u>-89.518</u>
			$(\Sigma \Delta f_i)^2 =$ <u>0</u>		

DATA SHEET 5.1.2 (Sample) (Continued)

DEVIATION SENSITIVITY=

$$b = \frac{5 \left( \sum_{i=1}^5 \Delta f_i \times V_i \right) - \left( \sum_{i=1}^5 V_i \right) \left( \sum_{i=1}^5 \Delta f_i \right)}{5 \left( \sum_{i=1}^5 (\Delta f_i)^2 \right) - \left( \sum_{i=1}^5 \Delta f_i \right)^2} = \underline{-2.238 \text{ volt/kHz}},$$

and

$$\text{ZERO OFFSET} = a = \left( \sum_{i=1}^5 V_i - b \times \sum_{i=1}^5 \Delta f_i \right) / 5 = \underline{0.001 \text{ volts}}.$$

Calculate the following:

i	$\Delta f_i$	$a + b \Delta f_i$	$V_i$	DEVIATION FROM LINEAR FIT $(a + b \Delta f_i) - V_i$
1	-4	8.953	8.953	0
2	-2	4.477	4.476	0.001
3	0	0.001	0.001	0
4	2	-4.475	-4.475	0
5	4	-8.951	-8.951	0

## 5.2 Zero and Band Edge Stability Test

5.2.1 Purpose - This test determines the zero and band edge stability of an FM discriminator over a one-hour period.

### 5.2.2 Test Equipment

Signal generator with frequency stability of  $+10^{-6}$ /day  
Frequency counter  
Digital voltmeter (dc)  
Oscilloscope

### 5.2.3 Test Method

5.2.3.1 Setup - Connect the test equipment as shown in figure 5.2.1.

#### 5.2.3.2 Conditions

5.2.3.2.1 Warm up all equipment according to specifications.

5.2.3.2.2 Set discriminator low pass output filter to cutoff frequency of interest.

5.2.3.2.3 Maximize output load according to specification.

#### 5.2.3.3 Procedures

5.2.3.3.1 Adjust signal generator output level and discriminator balance and output levels in accordance with paragraph 5.0 of General Procedures.

5.2.3.3.2 Apply LBE frequency to discriminator and record time, input frequency, and output voltage on data sheet

5.2.1. Repeat procedure for center and UBE frequencies.

5.2.3.3.3 Repeat step 5.2.3.3.2 approximately one hour later, using the same frequencies recorded earlier without adjusting discriminator balance and output voltage levels.

5.2.4 Data Reduction - Compare change in discriminator output voltages obtained at center and band edge frequencies with specifications. Subtract voltage readings of second test from first test and record in  $\Delta V$  column on data sheet. Calculate percentage change and record in percentage change column (see data sheet 5.2.1 sample).

#### NOTE

If uniform change in discriminator output voltage is noted between groups of data and this change can be corrected by resetting zero output at center frequency within drift specification, then discriminator is operating normally.

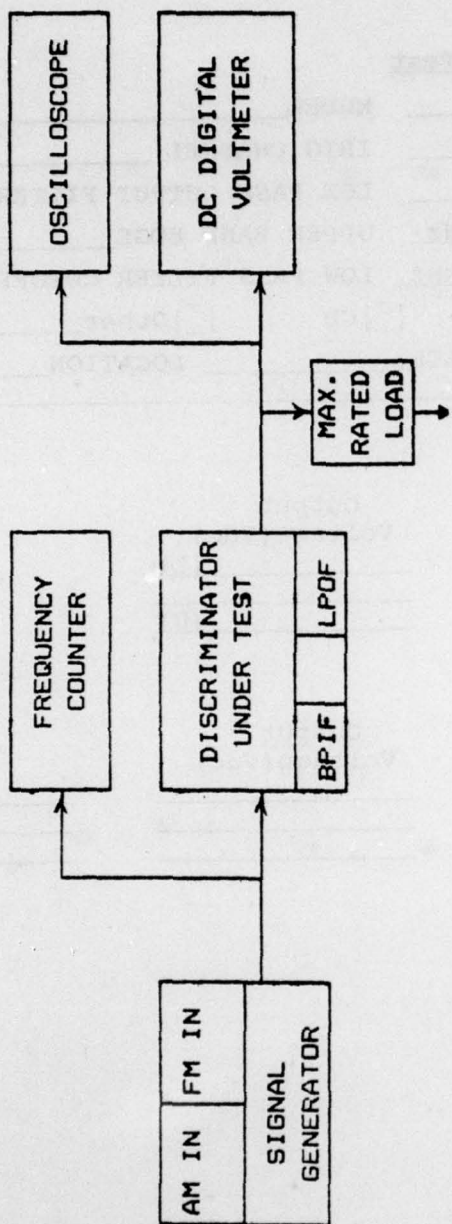


Figure 5.2.1 Test Setup for Zero and Band Edge Stability.

FM DISCRIMINATORS

DATA SHEET 5.2.1

TEST Zero and Band Edge Stability Test

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_  
 SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz  
 LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz  
 LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Time: \_\_\_\_\_

Input Frequency	Frequency (kHz)	Output Voltage (Vdc)
Lower Band Edge	_____	_____ (L)
Center Freq.	_____	_____
Upper Band Edge	_____	_____ (U)

Time: \_\_\_\_\_

Input Frequency	Frequency (kHz)	Output Voltage (Vdc)	$\Delta V$
Lower Band Edge	_____	_____	_____
Center Freq.	_____	_____	_____
Upper Band Edge	_____	_____	_____

Percent Change (  $\Delta V \times 100 / (U-L)$  )  
 Lower Band Edge \_\_\_\_\_  
 Center Freq. \_\_\_\_\_  
 Upper Band Edge \_\_\_\_\_

**FM DISCRIMINATORS**

DATA SHEET 5.2.1 (Sample)

TEST Zero and Band Edge Stability Test

MANUFACTURER XYZ MODEL DEF  
 SERIAL NO. 70 IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY 70.0 kHz UPPER BAND EDGE 80.5 kHz  
 LOWER BAND EDGE 59.5 kHz LOW PASS FILTER CUTOFF 2.1 kHz  
 LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Time: 1300

Input Frequency	Frequency (kHz)	Output Voltage (Vdc)
Lower Band Edge	<u>59.500</u>	<u>-10.009 (L)</u>
Center Freq.	<u>70.000</u>	<u>-0.008</u>
Upper Band Edge	<u>80.500</u>	<u>-9.990 (U)</u>

Time: 1400

Input Frequency	Frequency (kHz)	Output Voltage (Vdc)	$\Delta V$
Lower Band Edge	<u>59.500</u>	<u>-10.010</u>	<u>0.001</u>
Center Freq.	<u>70.000</u>	<u>-0.008</u>	<u>0</u>
Upper Band Edge	<u>80.500</u>	<u>+9.989</u>	<u>0.001</u>

Percent Change	( $\Delta V \times 100 / (U - L)$ )
Lower Band Edge	<u>0.005%</u>
Center Freq.	<u>0</u>
Upper Band Edge	<u>0.005%</u>

### 5.3 Static Noise

5.3.1 Purpose - This test measures the amount of static noise at the FM discriminator output.

#### 5.3.2 Test Equipment

Frequency counter  
Signal generator  
Oscilloscope  
True rms voltmeter  
Digital voltmeter (dc)

#### 5.3.3 Test Method

5.3.3.1 Setup - Connect the test equipment as shown in figure 5.3.1.

#### 5.3.3.2 Conditions

5.3.3.2.1 Warm up all equipment according to specifications.

5.3.3.2.2 Maximize output load according to specification.

#### 5.3.3.3 Procedure

#### NOTE

Incidental phase or frequency modulation in signal generator will affect test results. Generator used should contribute less than 10 percent to parameter being measured.

5.3.3.3.1 Place a low pass output filter in test discriminator to reflect the deviation ratio at which the discriminator will typically be used.

5.3.3.3.2 Adjust signal generator output level and discriminator balance and output levels in accordance with paragraph 5.0 of General Procedures.

5.3.3.3.3 Adjust signal generator to LBE frequency, measure discriminator dc and rms output voltages and record on data sheet 5.3.1.

5.3.3.3.4 Repeat step 5.3.3.3.3 for center frequency and UBE frequency.

5.3.3.3.5 Repeat steps 5.3.3.3.3 and 5.3.3.3.4 for other deviation ratios as needed.

5.3.4 Data Reduction - Compare data obtained with specifications. Calculate percent noise by dividing rms voltages by peak-to-peak dc voltage and multiply by 100 (see data sheet 5.3.1 sample).

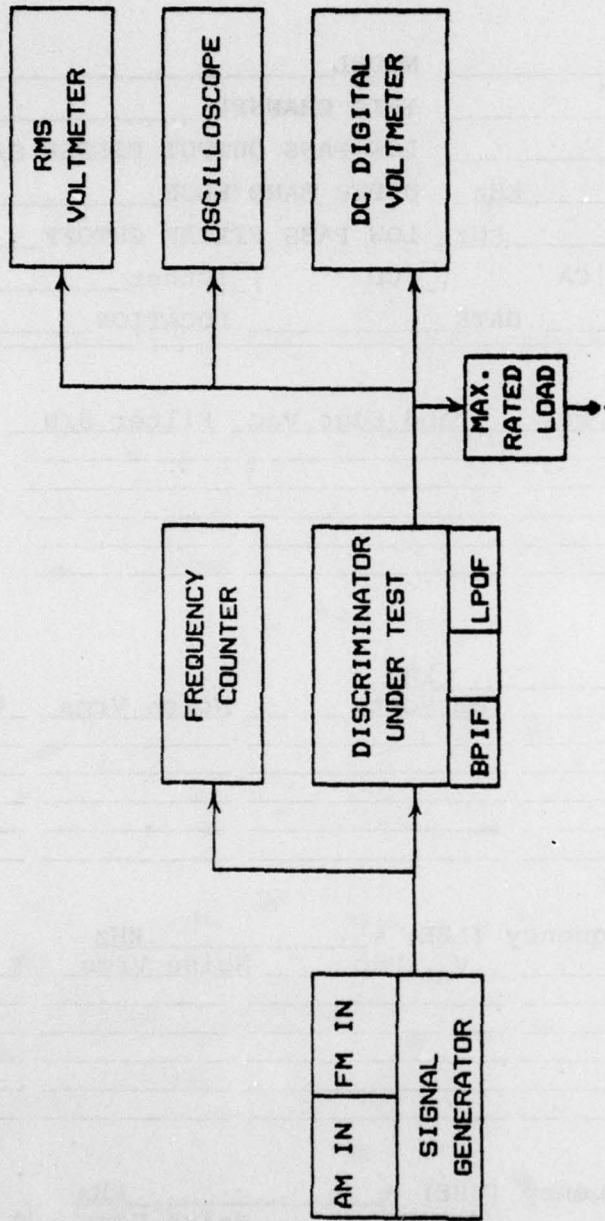


Figure 5.3.1 Test Setup for Static Noise.

FM DISCRIMINATORS

DATA SHEET 5.3.1

TEST Static Noise Test

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_  
 SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz  
 LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz  
 LOW PASS FILTER TYPE:     CA         CD         Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Specifications:

Dev. Ratio	LPOF Freq.	Noise rms	Band Edge Vdc	Filter S/N

Performance data:

Center Frequency = \_\_\_\_\_ kHz

Dev. Ratio	BPIF BW	LPOF	dc Volts	Noise Vrms	% Noise

Lower Band Edge Frequency (LBE) = \_\_\_\_\_ kHz

Dev. Ratio	BPIF BW	LPOF	V <sub>LBE</sub> Vdc	Noise Vrms	% Noise

Upper Band Edge Frequency (UBE) = \_\_\_\_\_ kHz

Dev. Ratio	BPIF BW	LPOF	V <sub>UBE</sub> Vdc	Noise Vrms	% Noise

DATA SHEET 5.3.1 (Continued)

To calculate % Noise use the following:

$$\% \text{ Noise} = \frac{\text{Noise rms}}{|V_{UBE} - V_{LBE}|} \times 100.$$

FM DISCRIMINATORS

DATA SHEET 5.3.1 (Sample)

TEST Static Noise Test

MANUFACTURER XYZ MODEL DEF

SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY 70.0 kHz UPPER BAND EDGE 80.5 kHz

LOWER BAND EDGE 59.5 kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz

LOW PASS FILTER TYPE:  CA  CD  other \_\_\_\_\_

TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Specifications:

Dev. Ratio	LPOF Freq.	Noise rms	Band Edge Vdc	Filter S/N
<u>1</u>	<u>10.5 kHz</u>	_____	_____	_____
<u>2</u>	<u>5.25 kHz</u>	_____	_____	_____
<u>5</u>	<u>2.1 kHz</u>	_____	_____	_____
_____	_____	_____	_____	_____
_____	_____	_____	_____	_____

Performance data:

Center Frequency = 70.0 kHz

Dev. Ratio	BPIF BW	LPOF	dc Volts	Noise Vrms	% Noise
<u>1</u>	<u>21 kHz</u>	<u>10.5 kHz</u>	<u>-0.004</u>	<u>0.007</u>	<u>0.035</u>
<u>2</u>	<u>21</u>	<u>5.25</u>	<u>-0.005</u>	<u>0.003</u>	<u>0.015</u>
<u>5</u>	<u>21</u>	<u>2.1</u>	<u>-0.008</u>	<u>0.001</u>	<u>0.005</u>
_____	_____	_____	_____	_____	_____
_____	_____	_____	_____	_____	_____

Lower Band Edge Frequency (LBE) = 59.5 kHz

Dev. Ratio	BPIF BW	LPOF	V <sub>LBE</sub> Vdc	Noise Vrms	% Noise
<u>1</u>	<u>21 kHz</u>	<u>10.5 kHz</u>	<u>-10.000</u>	<u>0.0093</u>	<u>0.045</u>
<u>2</u>	<u>21</u>	<u>5.25</u>	<u>-10.003</u>	<u>0.004</u>	<u>0.02</u>
<u>5</u>	<u>21</u>	<u>2.1</u>	<u>-10.007</u>	<u>0.002</u>	<u>0.01</u>
_____	_____	_____	_____	_____	_____
_____	_____	_____	_____	_____	_____

Upper Band Edge Frequency (UBE) = 80.5 kHz

Dev. Ratio	BPIF BW	LPOF	V <sub>UBE</sub> Vdc	Noise Vrms	% Noise
<u>1</u>	<u>21 kHz</u>	<u>10.5 kHz</u>	<u>+9.985</u>	<u>0.006</u>	<u>0.03</u>
<u>2</u>	<u>21</u>	<u>5.25</u>	<u>+9.996</u>	<u>0.004</u>	<u>0.02</u>
<u>5</u>	<u>21</u>	<u>2.1</u>	<u>+9.989</u>	<u>0.002</u>	<u>0.01</u>
_____	_____	_____	_____	_____	_____
_____	_____	_____	_____	_____	_____

**DATA SHEET 5.3.1 (Sample) (Continued)**

To calculate % Noise use the following:

$$\% \text{ Noise} = \frac{\text{Noise rms}}{|V_{UBE} - V_{LBE}|} \times 100.$$

#### 5.4 Harmonic Distortion

5.4.1 Purpose - This test measures the amount of harmonic distortion present at the discriminator output.

##### NOTE

This test does not discriminate between distortion introduced in the signal source and distortion introduced in the discriminator under test. One method of verifying that the signal source is not introducing appreciable distortion is to perform this test using the same signal source settings and modulating signal but using a wideband discriminator with excellent linearity. If the distortion values from this test are significantly lower than with the discriminator under test, the signal source can be eliminated as a source of distortion. If, however, the distortion is sufficiently low with the discriminator under test, there is no need to be concerned about the cause of the distortion.

#### 5.4.2 Test Equipment

Audio oscillator with all harmonics at least 60 dB below amplitude of fundamental output frequency  
Signal generator or voltage controlled oscillator which can be frequency modulated  
Frequency counter  
Distortion analyzer  
Spectrum analyzer or wave analyzer  
Digital voltmeter

#### 5.4.3 Test Method

5.4.3.1 Setup - Connect the test equipment as shown in figure 5.4.1.

5.4.3.2 Conditions - Set the signal generator to the following (see paragraph 5.0 for general test conditions):

Output frequency - discriminator center frequency  
Output amplitude - 0.3 Vrms  
Peak deviation - discriminator band edge

The discriminator LPOF should be chosen to reflect a deviation ratio of one, that is, equal to peak deviation of discriminator. The audio oscillator output should be a sine wave at a frequency of 0.1 times the discriminator LPOF cutoff frequency.

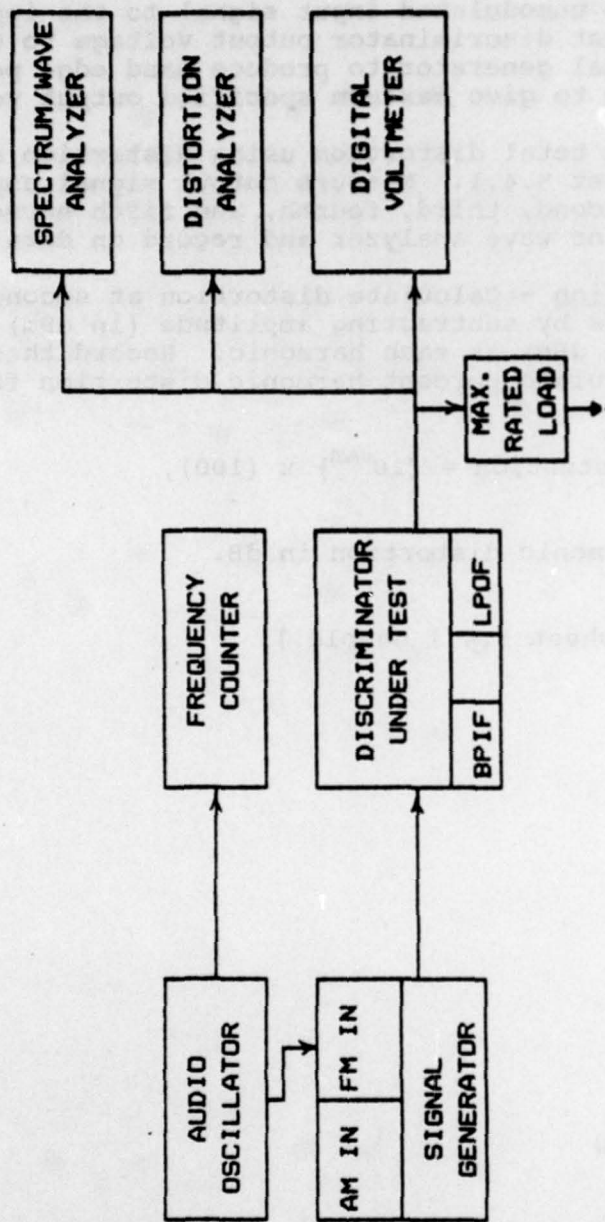


Figure 5.4.1 Test Setup for Harmonic Distortion.

### 5.4.3.3 Procedure

5.4.3.3.1 Set the unmodulated input signal to the input center frequency and adjust discriminator output voltage to 0 V. Apply modulation to signal generator to produce band edge peak deviation. Adjust output gain to give maximum specified output voltage swing.

5.4.3.3.2 Measure total distortion using distortion analyzer and record on data sheet 5.4.1. Measure output signal amplitude at fundamental and second, third, fourth, and fifth harmonics using spectrum analyzer or wave analyzer and record on data sheet 5.4.1.

5.4.4 Data Reduction - Calculate distortion at second, third, fourth, and fifth harmonics by subtracting amplitude (in dBm) at fundamental from amplitude (in dBm) at each harmonic. Record these values on data sheet 5.4.1. Calculate percent harmonic distortion from

$$\% \text{ harmonic distortion} = (10^{d/20}) \times (100),$$

Where d = harmonic distortion in dB.

(See data sheet 5.4.1 sample.)

FM DISCRIMINATORS

DATA SHEET 5.4.1

TEST Harmonic Distortion

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_

SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz

LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz

LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_

TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Modulating Frequency \_\_\_\_\_ Hz

Total Harmonic Distortion \_\_\_\_\_ dB \_\_\_\_\_ %

<u>Frequency</u>	<u>Output Amplitude</u>	<u>Distortion</u>
Fundamental	_____ dBm	
Second Harmonic	_____ dBm	_____ dB _____ %
Third Harmonic	_____ dBm	_____ dB _____ %
Fourth Harmonic	_____ dBm	_____ dB _____ %
Fifth Harmonic	_____ dBm	_____ dB _____ %

FM DISCRIMINATORS

DATA SHEET 5.4.1 (Sample)

TEST Harmonic Distortion

MANUFACTURER XYZ MODEL DEF

SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY 70.0 kHz UPPER BAND EDGE 80.5 kHz

LOWER BAND EDGE 59.5 kHz LOW PASS FILTER CUTOFF 10.5 kHz

LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_

TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Modulating Frequency \_\_\_\_\_ 1050 Hz

Total Harmonic Distortion -44.4 dB 0.6 %

Frequency	Output Amplitude	Distortion	
Fundamental	<u>-3.1</u> dBm		
Second Harmonic	<u>-51.4</u> dBm	<u>-48.3</u> dB	<u>0.38</u> %
Third Harmonic	<u>-50.9</u> dBm	<u>-47.8</u> dB	<u>0.41</u> %
Fourth Harmonic	<u>-</u> dBm	<u>-</u> dB	<u>0</u> %
Fifth Harmonic	<u>-55.8</u> dBm	<u>-52.7</u> dB	<u>0.23</u> %

## 5.5 Line Voltage Sensitivity

5.5.1 Purpose - This test determines the effect of variations in ac line voltage on FM discriminator signal output.

### 5.5.2 Test Equipment

Frequency counter  
Voltmeter (ac)  
Variable autotransformer  
Oscilloscope  
Voltmeter (dc)  
Signal generator

### 5.5.3 Test Method

5.5.3.1 Setup - Connect test equipment as shown in figure 5.5.1.

#### 5.5.3.2 Conditions

5.5.3.2.1 Warm up all equipment according to specifications.

5.5.3.2.2 Maximize output load according to specification.

#### 5.5.3.3 Procedure

5.5.3.3.1 Adjust signal generator output level and discriminator balance and output levels in accordance with paragraph 5.0.

5.5.3.3.2 Set the input frequency to the LBE frequency.

5.5.3.3.3 Record on Data Sheet 5.5.1 Input Frequency, dc Output Voltage and ac Line Voltage as ac line voltage is increased in increments of approximately 5 percent of normal operating voltage from minimum operating voltage to maximum operating voltage. Observe output waveform with oscilloscope and note any change on data sheet 5.5.1 as ac line voltage is varied.

Example: If normal operating voltage is 120 Vac and specified operating range is 105 Vac to 135 Vac, data points should be approximately 6 Vac apart.

5.5.3.3.4 Repeat step 5.5.3.3.3 for center frequency and UBE frequency.

5.5.4 Data Reduction - Calculate the line voltage sensitivity as indicated on data sheet 5.5.1 and compare with electrical specifications. The line voltage sensitivity may be calculated for any two data points on the data sheet at any input frequency. The ac maximum and ac minimum are the upper and lower values of ac line voltage that determines the data points. The dc maximum and dc minimum are the corresponding discriminator outputs for the two different ac line voltage values at a given frequency (see data sheet 5.5.1 sample).

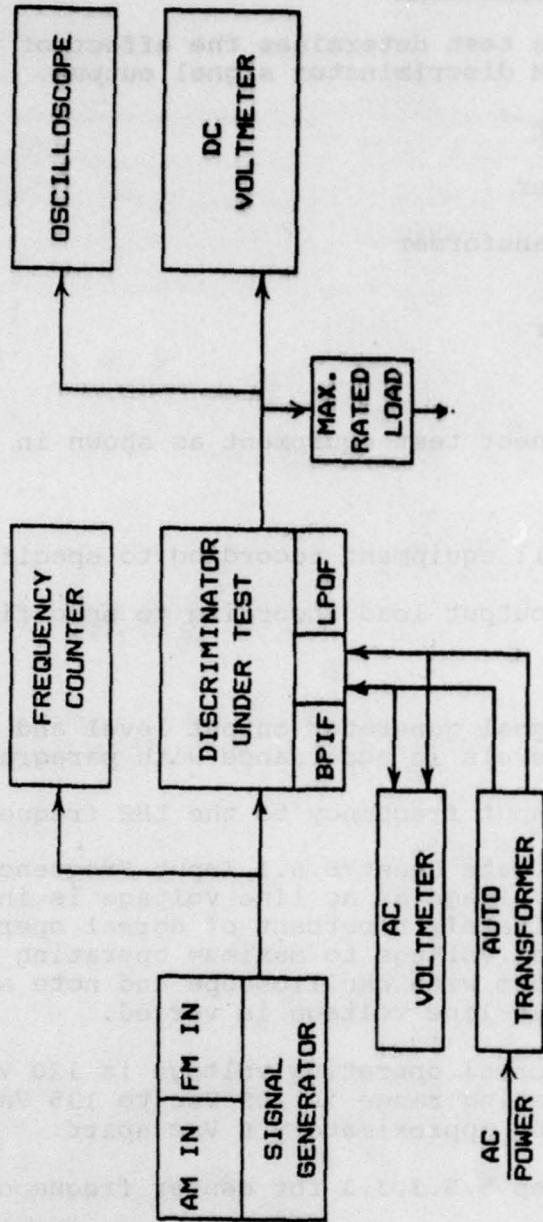


Figure 5.5.1 Test Setup for Line Voltage Sensitivity.

**FM DISCRIMINATORS**

DATA SHEET 5.5.1

**TEST Line Voltage Sensitivity Test**

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_

SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz

LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz

LOW PASS FILTER TYPE -     CA         CD         Other \_\_\_\_\_

TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

ac Operating Range \_\_\_\_\_ Vac                      TO \_\_\_\_\_ Vac  
 % Full Bandwidth Tolerance \_\_\_\_\_ %

Discriminator Inputs

	LBE	Center Freq.	UBE
Specified	_____ kHz	_____ kHz	_____ kHz
Measured	_____ kHz	_____ kHz	_____ kHz

ac Line  
Voltage  
Nominal

Discriminator Outputs (Vdc)

Comments

	(L)		(U)	
_____	_____	_____	_____	
_____	_____	_____	_____	
_____	_____	_____	_____	
_____	_____	_____	_____	
_____	_____	_____	_____	

Line Voltage Sensitivity =  $\frac{dc_{MAX} - dc_{MIN}}{U-L} \times 100\% \text{ per Vac}$   
 $\frac{ac_{max} - ac_{min}}{U-L} \times 100\% \text{ per Vac}$   
 = \_\_\_\_\_ % per Vac

FM DISCRIMINATORS

DATA SHEET 5.5.1 (Sample)

TEST Line Voltage Sensitivity Test

MANUFACTURER XYZ MODEL DEF

SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY 70.0 kHz UPPER BAND EDGE 80.5 kHz

LOWER BAND EDGE 59.5 kHz LOW PASS FILTER CUTOFF 2.1 kHz

LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_

TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

ac Operating Range 105 Vac TO 132 Vac

% Full Bandwidth Tolerance 0.5 %

Discriminator Inputs

	LBE	Center Freq.	UBE
Specified	<u>59.5</u> kHz	<u>70.0</u> kHz	<u>80.5</u> kHz
Measured	<u>59.5000</u> kHz	<u>70.000</u> kHz	<u>80.5000</u> kHz

ac Line Voltage

Nominal

105

112

119

126

132

Discriminator Outputs (Vdc)

	(L)		(U)
	<u>-9.328</u>	<u>-14 mV</u>	<u>+9.981</u>
	<u>-9.328</u>	<u>-15</u>	<u>+9.982</u>
	<u>-9.328</u>	<u>-15</u>	<u>+9.981</u>
	<u>-9.326</u>	<u>-15</u>	<u>+9.979</u>
	<u>-9.326</u>	<u>-15</u>	<u>+9.979</u>
	<u>-9.326</u>	<u>-15</u>	<u>+9.980</u>

Comments

$$\text{Line Voltage Sensitivity} = \frac{dc_{MAX} - dc_{MIN}}{U - L} \times 100 \text{ \% per Vac}$$

$$= \frac{ac_{MAX} - ac_{MIN}}{119 - 105} \times 100 \text{ \% per Vac}$$

$$= \frac{-9.326 + 9.328}{9.981 + 9.328} \times 100 \text{ \% per Vac}$$

$$= 7.4 \times 10^{-4} \text{ \% per Vac}$$

## 5.6 Output Impedance and Current

5.6.1 Purpose - This test measures the output resistance and current drive capability of an FM discriminator.

### 5.6.2 Test Equipment

Signal generator  
Frequency counter  
Digital voltmeter (dc)  
True rms voltmeter  
Variable load  
Ohmmeter

### 5.6.3 Test Method

5.6.3.1 Setup - Connect the test equipment as shown in figure 5.6.1.

#### 5.6.3.2 Conditions

5.6.3.2.1 Warm up all equipment according to specifications.

5.6.3.2.2 Set up signal generator in accordance with standard conditions in paragraph 5.0.

#### 5.6.3.3 Procedure

5.6.3.3.1 Set signal generator to center frequency and adjust discriminator to 0 V output.

5.6.3.3.2 Apply UBE frequency to discriminator input and adjust discriminator for maximum output (see subparagraph 5.0,4.4.2).

5.6.3.3.3 Disconnect load and measure and record open circuit output voltage on data sheet 5.6.1 for UBE frequency.

5.6.3.3.4 Connect a resistive decade box set for maximum resistance to the discriminator.

5.6.3.3.5 Decrease resistance until the output voltage is one-half of the open circuit value.

5.6.3.3.6 Disconnect decade box from circuit and measure and record its resistance on data sheet 5.6.1. This resistance will be used to calculate the maximum output current of the discriminator.

5.6.3.3.7 Repeat procedure and record results using LBE frequency.

5.6.3.3.8 Set the signal generator to a frequency equal to the discriminator center frequency plus 1 percent of the UBE frequency minus the center frequency ( $f_c + 0.01(f_{UBE} - f_c)$ ). Repeat steps 5.6.3.3.3 through 5.6.3.3.5. Disconnect decade box from circuit and measure and record its resistance on data sheet 5.6.1. The measured resistance is the dc output resistance.

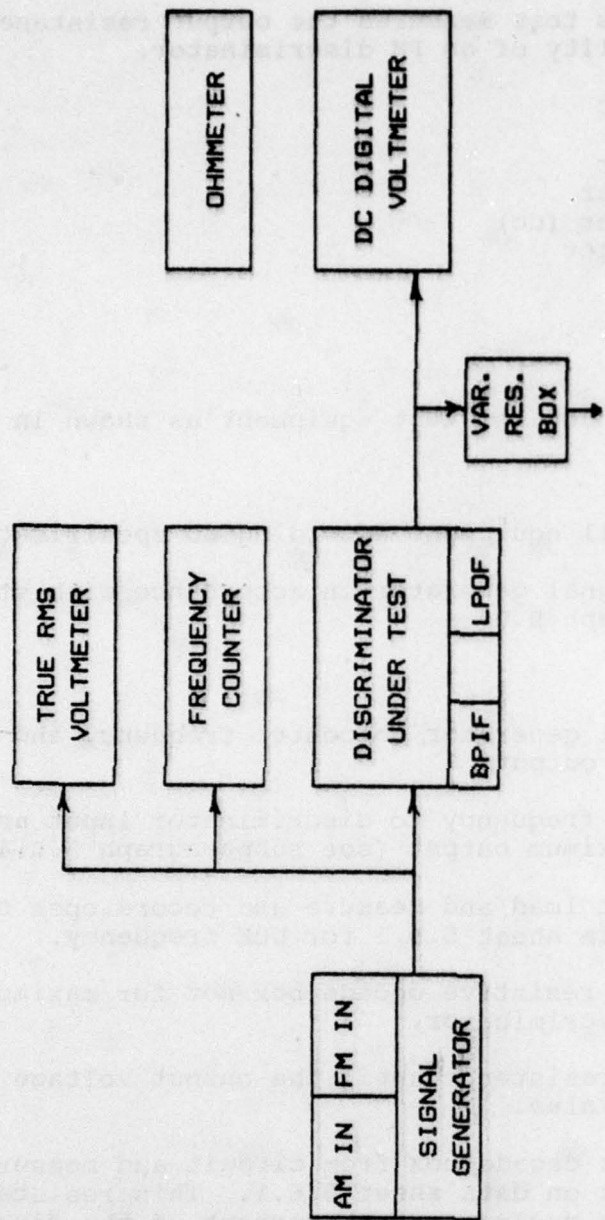


Figure 5.6.1 Test Setup for Output Impedance and Current.

FM DISCRIMINATORS

DATA SHEET 5.6.1

TEST Output Impedance and Current

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_  
 SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz  
 LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz  
 LOW PASS FILTER TYPE:     CA         CD         Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

MAXIMUM OUTPUT CURRENT

Upper Band Edge Frequency \_\_\_\_\_ kHz  
 Open Circuit Voltage \_\_\_\_\_ Vdc  
 Resistance \_\_\_\_\_ Ohms  
 Lower Band Edge Frequency \_\_\_\_\_ kHz  
 Open Circuit Voltage \_\_\_\_\_ Vdc  
 Resistance \_\_\_\_\_ Ohms

Maximum Current =  $V/2R =$  \_\_\_\_\_ mamp.

OUTPUT IMPEDANCE

Center Frequency +0.01 (UBE- $f_c$ ) = \_\_\_\_\_ kHz  
 Open Circuit Voltage = \_\_\_\_\_ Vdc  
 Resistance = \_\_\_\_\_ Ohms  
 Center Frequency -0.01 (UBE- $f_c$ ) = \_\_\_\_\_ kHz  
 Open Circuit Voltage = \_\_\_\_\_ Vdc  
 Resistance = \_\_\_\_\_ Ohms

5.6.3.3.9 Set the signal generator to a frequency equal to the discriminator center frequency minus 1 percent of the UBE frequency minus the center frequency. Repeat steps 5.6.3.3.3 through 5.6.3.3.6.

5.6.4 Data Reduction - Calculate the maximum output current by dividing the open circuit voltage by two times the measured resistance (subparagraph 5.6.3.3.6) (see data sheet 5.6.1 sample).

FM DISCRIMINATORS

DATA SHEET 5.6.1 (Sample)

TEST Output Impedance and Current

MANUFACTURER XYZ MODEL DEF  
 SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY 70.0 kHz UPPER BAND EDGE 80.5 kHz  
 LOWER BAND EDGE 59.5 kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz  
 LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

MAXIMUM OUTPUT CURRENT

Upper Band Edge Frequency 80.5 kHz  
 Open Circuit Voltage +10.083 Vdc  
 Resistance 34 Ohms

Lower Band Edge Frequency 59.5 kHz  
 Open Circuit Voltage -10.084 Vdc  
 Resistance 34 Ohms

Maximum Current =  $V/2R =$  148.3 mamp.

OUTPUT IMPEDANCE

Center Frequency +0.01 (UBE- $f_c$ ) = 70.105 kHz  
 Open Circuit Voltage = 43 mVdc  
 Resistance = 0.31 Ohms

Center Frequency -0.01 (UBE- $f_c$ ) = 69.895 kHz  
 Open Circuit Voltage = -104 mVdc  
 Resistance = 0.32 Ohms

## 5.7 Amplitude Modulation Rejection Test

5.7.1 Purpose - This test determines how well a discriminator rejects amplitude modulation which is present on its input signal.

### 5.7.2 Test Equipment

Signal generator  
Square wave generator  
Frequency counter  
Oscilloscope (dual trace) 2 required  
Scope camera or plotter

### 5.7.3 Test Method

5.7.3.1 Setup - Connect the test equipment as shown in figure 5.7.1.

#### 5.7.3.2 Conditions

5.7.3.2.1 Warm up all equipment according to specifications.

5.7.3.2.2 Set up the discriminator according to the standard conditions in subparagraph 5.0.

5.7.3.2.3 Set up the signal generator according to the standard conditions in subparagraph 5.0.4.1.

#### 5.7.3.3 Procedure

5.7.3.3.1 Set the frequency of the square-wave generator to 5 percent of the LPOF cutoff frequency.

5.7.3.3.2 Adjust the square-wave generator output amplitude and offset to apply a 20-dB step in amplitude at the output of the signal generator. The peak-to-valley voltage relationship of the amplitude modulated subcarrier signal should be a ratio of 10 (voltage peak = 10 x voltage valley).

5.7.3.3.3 Measure and record on data sheet 5.7.1 the peak-to-peak discriminator output voltage. Take a photograph of the oscilloscope trace and attach to the data sheet.

5.7.3.3.4 Repeat steps 5.7.3.3.2 and 5.7.3.3.3 for the UBE frequency.

5.7.3.3.5 Repeat steps 5.7.3.3.2 and 5.7.3.3.3 for the LBE frequency.

5.7.3.3.6 This test may be repeated for other signal levels as required by actual usage.

5.7.4 Data Reduction - Compare the data with the specification. (see data sheet 5.7.1 sample).

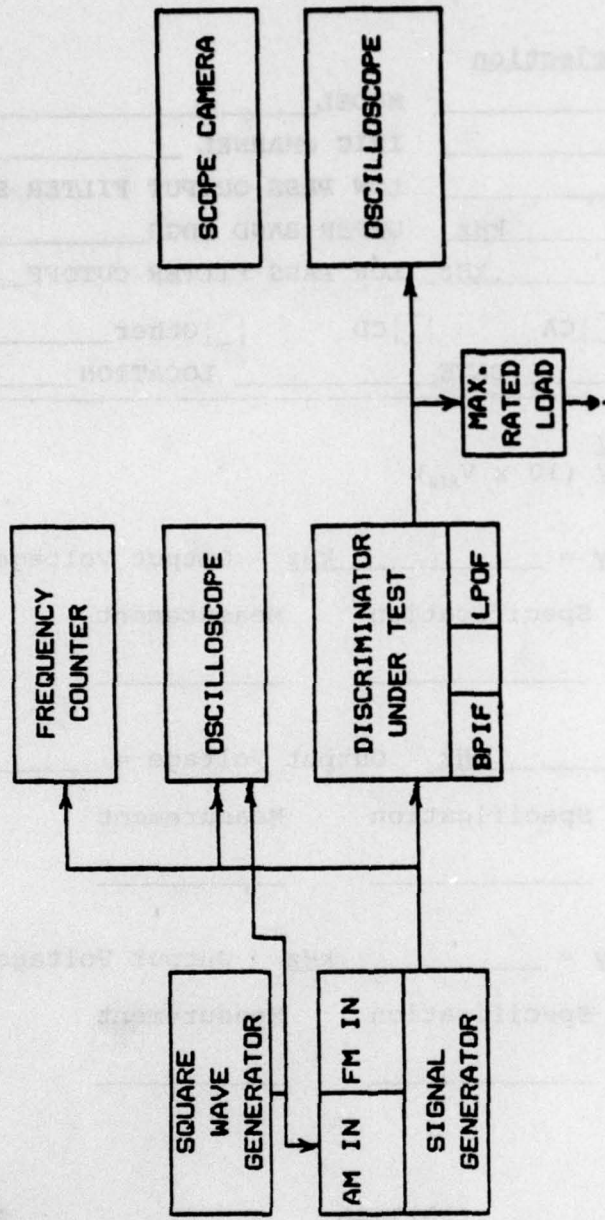


Figure 5.7.1 Test Setup for Amplitude Modulation Rejection.

FM DISCRIMINATORS

DATA SHEET 5.7.1

TEST Amplitude Modulation Rejection

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_

SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz

LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz

LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_

TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

$$\frac{V_{MIN}}{V_{MAX}} = \frac{V}{V} (10 \times V_{MIN})$$

Lower Band Edge Frequency = \_\_\_\_\_ kHz Output Voltage = \_\_\_\_\_ Vdc

	Specification	Measurement
Peak-to Peak Output Voltage (V)	_____	_____

Center Frequency = \_\_\_\_\_ kHz Output Voltage = \_\_\_\_\_ Vdc

	Specification	Measurement
Peak-to Peak Output Voltage (V)	_____	_____

Upper Band Edge Frequency = \_\_\_\_\_ kHz Output Voltage = \_\_\_\_\_ Vdc

	Specification	Measurement
Peak-to Peak Output Voltage (V)	_____	_____

Attach  
Photograph  
Here

Attach  
Photograph  
Here

Attach  
Photograph  
Here

Lower Band Edge

Center Frequency

Upper Band Edge

FM DISCRIMINATORS

DATA SHEET 5.7.1 (Sample)

TEST Amplitude Modulation Rejection

MANUFACTURER XYZ MODEL DEF  
 SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY 70. kHz UPPER BAND EDGE 80.5 kHz  
 LOWER BAND EDGE 59.5 kHz LOW PASS FILTER CUTOFF 2.1 kHz  
 LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

$$V_{MIN} = \underline{30.0} \text{ mV}$$

$$V_{MAX} = \underline{300.} \text{ mV } (10 \times V_{MIN})$$

Lower Band Edge Frequency = 59.500 kHz Output Voltage = -9.424 Vdc

	Specification	Measurement
Peak-to Peak Output Voltage (V)	_____	<u>613 mV</u>

(See attachment 1 for lower band edge.)

Center Frequency = 70.000 kHz Output Voltage = -0.005 Vdc

	Specification	Measurement
Peak-to Peak Output Voltage (V)	<u>200mV</u>	<u>369 mV</u>

(See attachment 2 for center frequency.)

Upper Band Edge Frequency = 80.500 kHz Output Voltage = 9.660 Vdc

	Specification	Measurement
Peak-to Peak Output Voltage (V)	_____	<u>806 mV</u>

(See attachment 3 for upper band edge frequency.)

Attach  
Photograph  
Here

Lower Band Edge

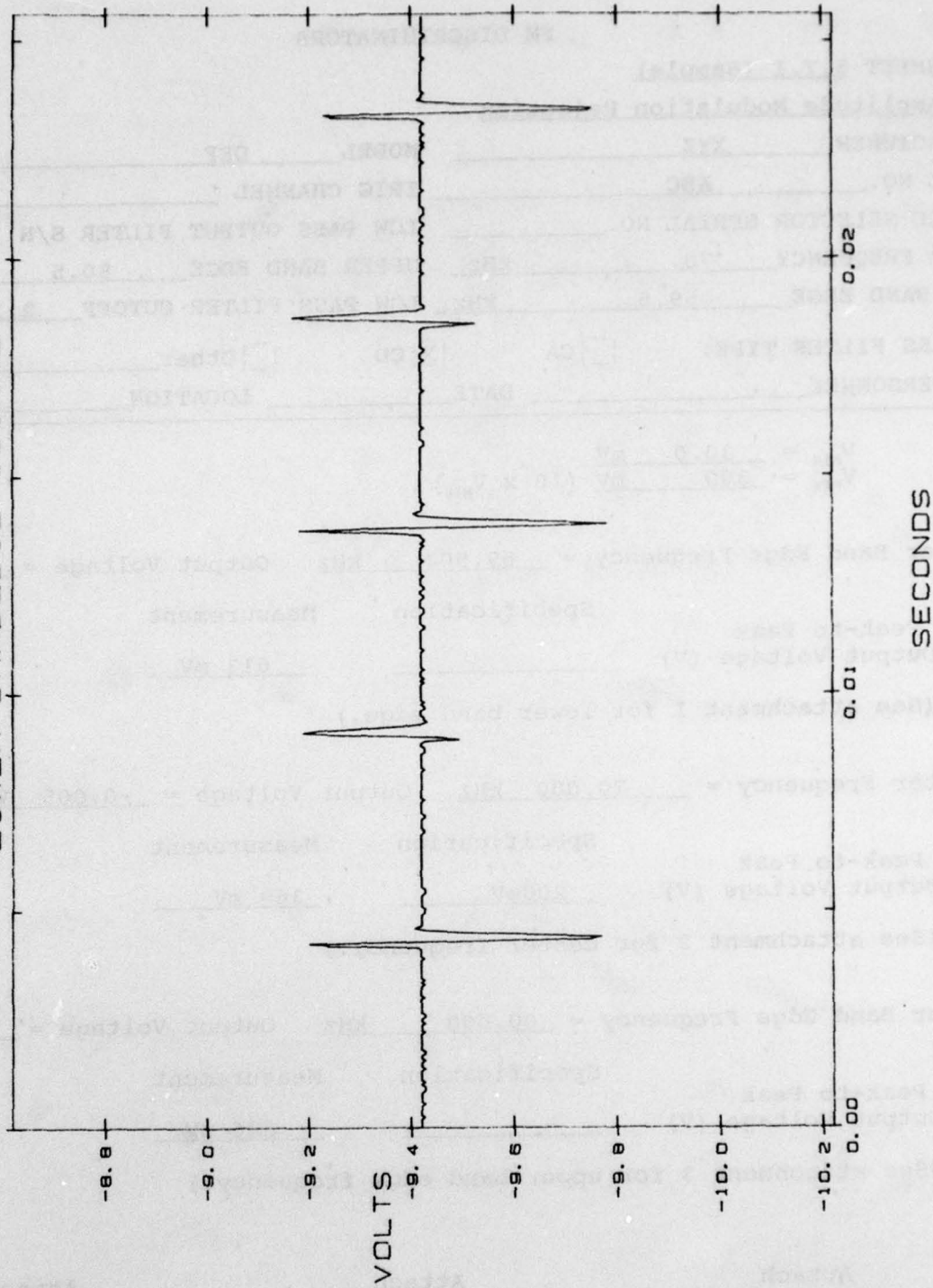
Attach  
Photograph  
Here

Center Frequency

Attach  
Photograph  
Here

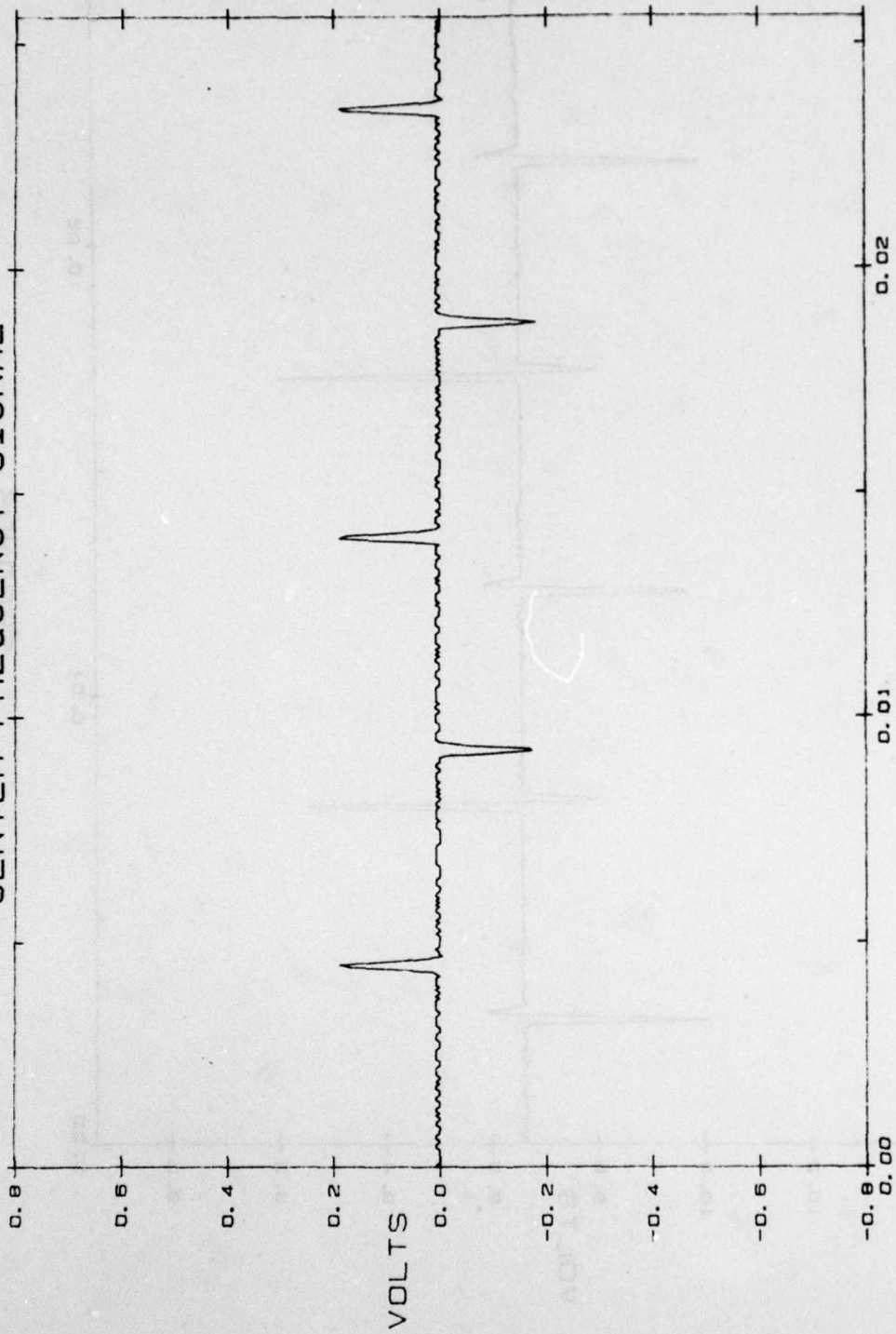
Upper Band Edge

BUF. A1 AMPLITUDE MODULATION REJECTION  
LOWER BANDEDGE SIGNAL



Data Sheet 5.7.1 (Sample) - Lower Band Edge.

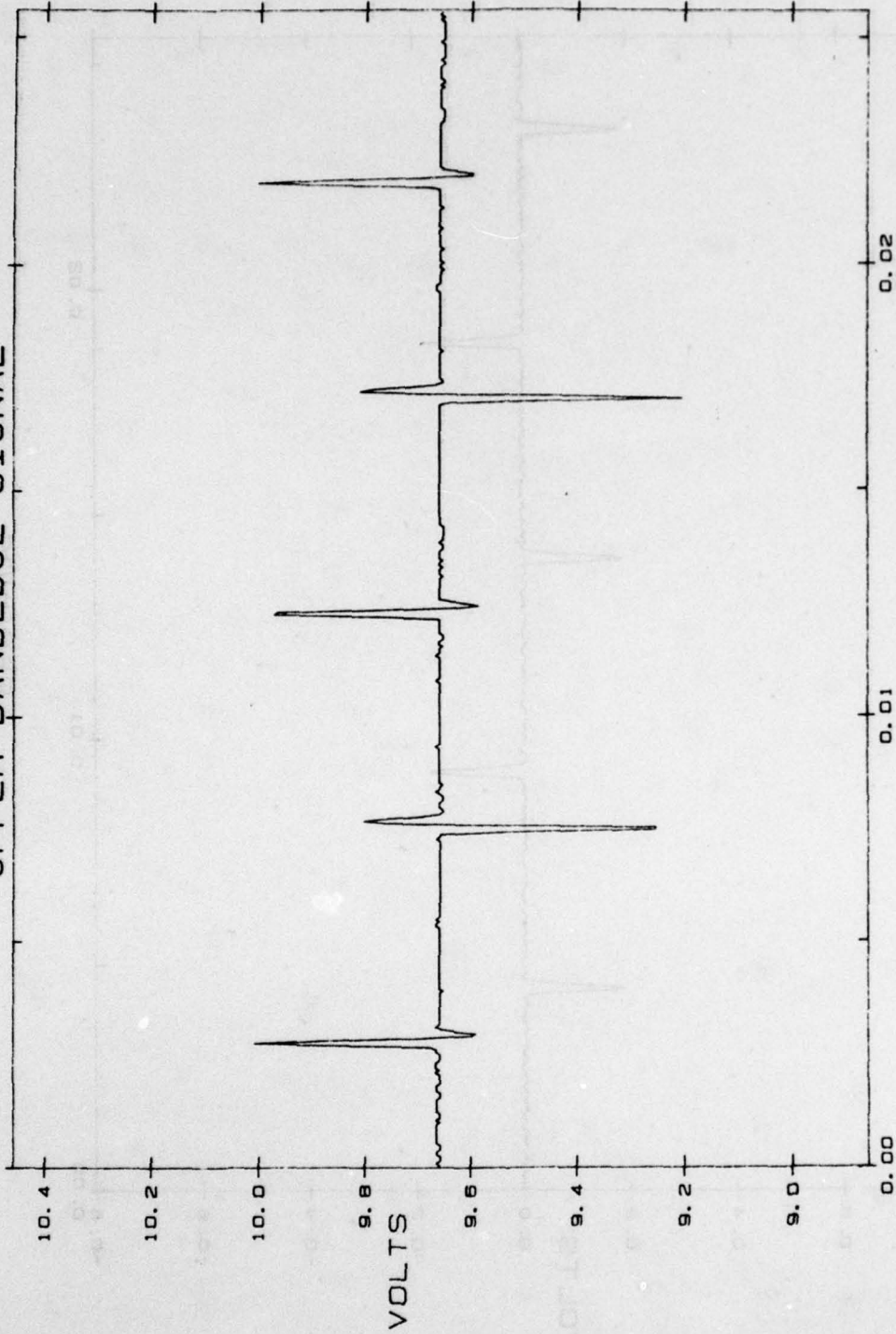
BUF. A1 AMPLITUDE MODULATION REJECTION  
CENTER FREQUENCY SIGNAL



SECONDS

Data Sheet 5.7.1 (Sample) - Center Frequency.

BUF. A1 AMPLITUDE MODULATION REJECTION  
UPPER BANDEDGE SIGNAL



SECONDS  
Data Sheet 5.7.1 (Sample) - Upper Band Edge.

## 5.8 Signal-To-Noise Ratio

5.8.1 Purpose - This test measures output signal-to-noise ratio (SNR) to verify proper performance of the discriminator in the presence of in-band input noise.

### 5.8.2 Test Equipment

Signal generator or voltage controlled oscillator  
Voltmeter (dc)  
White gaussian noise generator  
Active summing network (see note)  
True rms voltmeter  
Oscilloscope  
Frequency counter  
Spectrum analyzer

#### NOTE

A passive summing network can be used if proper precautions are taken to make sure that the summing network output amplitude of the signal or noise, or both, do not vary if the other input is connected or disconnected.

### 5.8.3 Test Method

5.8.3.1 Setup - Connect the test equipment as shown in figure 5.8.1.

5.8.3.2 Conditions - See paragraph 5.0 for general test conditions. Adjust the discriminator output to 0 Vdc with an unmodulated signal at the discriminator center frequency applied to the discriminator input. Set the signal generator to the discriminator UBE and adjust the discriminator output to 5 Vdc. Record on data sheet 5.8.1. Reset the signal generator to the following:

Output frequency = discriminator center frequency  
Output amplitude = 0.3 Vrms at output of summing network.

#### 5.8.3.3 Procedure

5.8.3.3.1 Remove the noise from the summing network. Measure the rms signal voltage at the output of the discriminator bandpass filter. Record this value on data sheet 5.8.1. Measure the rms voltage at the discriminator low pass filter output. Record this value on the line labeled maximum SNR under the heading of low pass filter output noise volts.

5.8.3.3.2 Connect the noise generator to the input of the summing network and remove the signal generator. Set the rms voltage of the noise at the output of the discriminator bandpass filter to be 30 dB less than the rms signal voltage measured above. Connect the

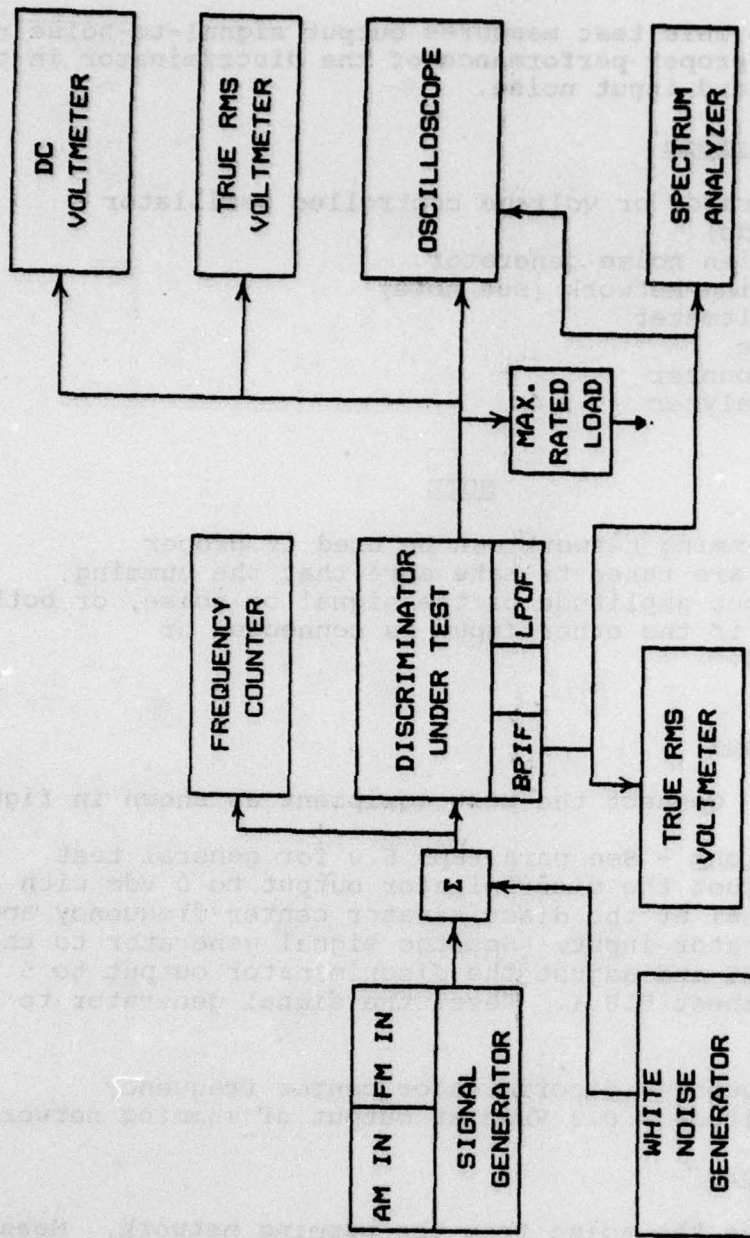


Figure 5.8.1 Test Setup for Signal-to-Noise Ratio.

**FM DISCRIMINATORS**

DATA SHEET 5.8.1

TEST Signal-to-Noise Ratio

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_  
 SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz  
 LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz  
 LOW PASS FILTER TYPE:     CA         CD         Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Discriminator output voltage with UBE frequency input \_\_\_\_\_ Vdc

Signal at output of discriminator bandpass filter \_\_\_\_\_ Vrms

Low Pass Filter Output

Approximate Input SNR(dB)	Noise Volts	Measured SNR <sub>o</sub>	Calculated SNR <sub>t</sub>
<u>30</u>	_____	_____	_____
<u>20</u>	_____	_____	_____
<u>15</u>	_____	_____	_____
<u>12</u>	_____	_____	_____

signal generator to the input of the summing network. Set up the spectrum analyzer to monitor the signal and noise in the discriminator bandpass filter. Note the noise level for future reference. Remove the signal from the summing network. The noise level should not change. If the level changes, a problem exists. Some discriminators have changes in gain when the input signal is too small. Increase the noise level and observe whether the BPIF output level suddenly decreases. If this change occurs, increase the noise level by another 3 to 6 dB and note the level on the rms voltmeter. Reconnect the signal generator and disconnect the noise generator. Set the signal generator to a level 30 dB above the rms value of the noise. Measure the BPIF output voltage and record in place of the value measured in subparagraph 5.8.3.3.1. Reconnect the noise generator and note the noise level on the spectrum analyzer. Disconnect the signal generator. The noise level should not change.

#### NOTE

If the noise level changes, the test probably cannot be performed. Also check the BPIF output with the signal connected to verify that limiting is not occurring. Limiting or automatic gain control (AGC) will invalidate the results of this test.

Record the rms signal value on data sheet 5.8.1.

5.8.3.3.3 Measure the rms voltage at the output of the discriminator low pass filter and record on data sheet 5.8.1.

5.8.3.3.4 Repeat steps 5.8.3.3.2 and 5.8.3.3.3 with the rms voltage of the noise 20, 15, and 12 dB less than the rms voltage of the signal measured in subparagraph 5.8.3.3.1.

#### 5.8.4 Data Reduction

5.8.4.1 Calculate the SNR at the discriminator low pass filter output from

$$SNR_0 = 20 (\log (\text{signal at UBE/noise at low pass filter output})) - 3 \text{ dB.}$$

#### NOTE

The 3 dB is subtracted to convert peak to rms for sine wave.

Record on data sheet 5.8.1.

5.8.4.2 Calculate the expected SNR at the discriminator output from:

$$SNR_T = \frac{3B\rho (\Delta f)^2}{2(f_o)^3}$$

$$SNR_T = 30(\log \frac{UBE - f_c}{f_o}) + 4.77 + SNR_i \text{ (dB)},$$

where B = Discriminator bandpass filter bandwidth =  $2\Delta f$

$\rho$  = SNR at bandpass filter output =  $SNR_i$

$\Delta f$  = Peak deviation

$f_o$  = Low pass filter cutoff frequency

$f_c$  = Discriminator center frequency

UBE = Upper Band Edge Frequency.

Record  $SNR_T$  on data sheet 5.8.1 (see data sheet 5.8.1 sample).

#### NOTE

The first quantity ( $30 \log ( )$ ) in the previous equation takes on the following values for commonly used deviation ratios (peak deviation to low pass filter cutoff frequency):

<u>Deviation Ratio</u>	<u><math>30 \log ( )</math></u>
1	0
2	9.03
4	18.06
5	20.97

The SNR values calculated from the above equation assumes that the filters are ideal; therefore, the results are only approximations for real world filters. Measured values will usually be a few dB lower than the calculated values. The low pass filter cutoff frequency is defined to be the frequency at which the output is reduced by 3 dB relative to the amplitude at dc.

FM DISCRIMINATORS

DATA SHEET 5.8.1 (Sample)

TEST Signal-to-Noise Ratio

MANUFACTURER XYZ MODEL DEF  
 SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY 70.0 kHz UPPER BAND EDGE 80.5 kHz  
 LOWER BAND EDGE 59.5 kHz LOW PASS FILTER CUTOFF 2.1 kHz  
 LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Discriminator output voltage with upper band edge frequency input 5.06 Vdc  
 Signal at output of discriminator bandpass filter 90.6 mVrms

Low Pass Filter Output

Approximate Input SNR(dB)	Noise Volts	Measured SNR <sub>o</sub>	Calculated SNR <sub>t</sub>
	<u>0.94mV</u>	<u>71.6dB</u>	<u>-</u>
<u>30</u>	<u>9.3mV</u>	<u>51.7</u>	<u>55.7dB</u>
<u>20</u>	<u>25.8mV</u>	<u>42.9</u>	<u>45.7</u>
<u>15</u>	<u>46 mV</u>	<u>37.8</u>	<u>40.7</u>
<u>12</u>	<u>65 mV</u>	<u>34.8</u>	<u>37.7</u>

## 5.9 Band Pass Input Filter Shape

5.9.1 Purpose - This test measures the discriminator bandpass filter frequency response. This data can be used to correct the output frequency response for roll-off because of the discriminator bandpass filter.

### NOTE

Two test methods are contained in the procedure. The sine-wave method is the preferred method but it will not work if there is limiting or AGC before the bandpass filter output test point. The sine-wave test consists of applying fixed amplitude sine waves of various frequencies to the discriminator input and measuring the amplitude at the bandpass filter output test point. The white-noise test consists of applying a wide band white-noise signal to the discriminator input and measuring the noise spectrum at the bandpass filter test point. This method is immune to AGC action because all input frequencies will be amplified by the same amount; therefore, the output is representative of the bandpass filter frequency response.

## 5.9.2 Test Equipment

### 5.9.2.1 Procedure 1 - Sine-Wave Method

Signal generator  
True rms voltmeter  
Spectrum analyzer with tracking generator -  
resolution bandwidth  $\leq 10$  percent of specified  
discriminator bandpass filter bandwidth  
Oscilloscope camera (for photographing spectrum analyzer  
display) or plotter

### 5.9.2.2 Procedure 2 - White-Noise Method

Spectrum Analyzer - resolution bandwidth  $\leq 10$  percent of  
specified discriminator bandpass filter bandwidth. Video  
bandwidth  $\leq 1$  percent of resolution bandwidth  
White-noise generator - noise generator with flat output  
spectral density ( $\pm 0.5$  dB) over frequencies of interest.  
True rms voltmeter  
Oscilloscope camera for photographing spectrum analyzer  
display or plotter

### 5.9.3 Test Method

#### NOTE

Procedure 1 will not work for discriminators which have AGC or limiting before the bandpass filter test point. This point can be checked by applying a center frequency sine wave with amplitude of 0.3 Vrms to the discriminator input and measuring the bandpass filter output using the true rms voltmeter. Call this value X dB. Set the input to the following amplitudes and measure the bandpass filter output:

	<u>Output (dB)</u>
0.3 Vrms	X
0.6 Vrms	X + 6
0.095 Vrms	X - 10
0.03 Vrms	X - 20

If the output values are within  $\pm 0.5$  dB of the values in the table, the system is linear and Procedure 1 can be used. If not, either try a different input level or use Procedure 2.

#### 5.9.3.1 Sine-Wave Method (Procedure 1)

5.9.3.1.1 Setup - Connect the test equipment as shown in figure 5.9.1.

5.9.3.1.2 Conditions - See paragraph 5.0 for general test conditions.

#### 5.9.3.1.3 Procedure

5.9.3.1.3.1 Set the signal generator output amplitude to 0.3 Vrms and the frequency to the center frequency of the discriminator under test. Measure the bandpass filter output amplitude using the true rms voltmeter. Record this value on data sheet 5.9.1. Measure and record the bandpass filter output amplitude at the other frequencies shown on data sheet 5.9.1. Keep the input amplitude constant at 0.3 Vrms.

#### NOTE

Other input amplitudes should be used instead of 0.3 Vrms if they are more typical of actual usage or if the system is not linear for an input voltage of 0.3 Vrms.

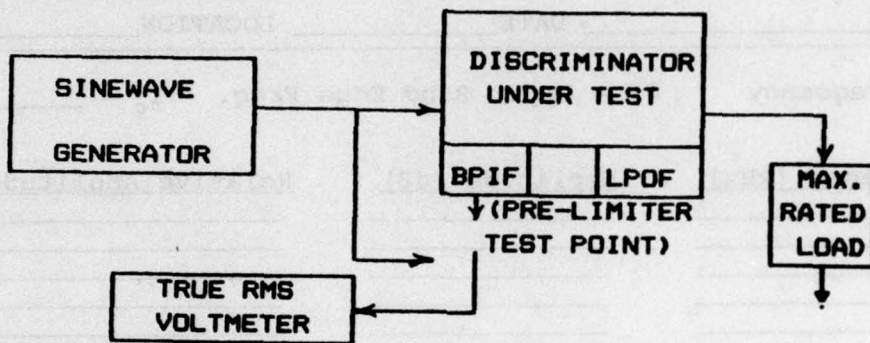


Figure 5.9.1 Test Setup for Bandpass Input Filter Frequency Response.

## FM DISCRIMINATORS

DATA SHEET 5.9.1

**TEST Bandpass Filter Frequency Response**

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_  
 SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz  
 LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz  
 LOW PASS FILTER TYPE:     CA     CD     Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

$f_c$  = Center Frequency       $\Delta f$  = Upper Band Edge Freq. -  $f_c$  = \_\_\_\_\_ kHz

	Frequency (kHz)	Amplitude (dB)	Relative Amplitude (dB)
$f_c$	_____	_____	_____
$f_c + \Delta f/2$	_____	_____	_____
$f_c - \Delta f/2$	_____	_____	_____
$f_c + \Delta f$	_____	_____	_____
$f_c - \Delta f$	_____	_____	_____
$f_c + 2 \Delta f$	_____	_____	_____
$f_c - 2 \Delta f$	_____	_____	_____

**EXAMPLE:**

Relative Amplitude at  $(f_c + \Delta f)$  = Amplitude at  $(f_c + \Delta f)$  - Amplitude at  $f_c$

**Spectrum Analyzer Settings**

Vertical Scale (dB/div) _____	dB	Attach Photograph Here
Lower Frequency _____	kHz	
Upper Frequency _____	kHz	
Resolution Bandwidth _____	Hz	
Video Bandwidth _____	Hz	

5.9.3.1.3.2 Set up the equipment as shown in figure 5.9.2. Set the spectrum analyzer tracking generator output to 0.3 Vrms at the discriminator center frequency ( $f_c$ ). Set the sweep limits at  $f_c - 2.5 \Delta f$  and  $f_c + 2.5 \Delta f$  ( $\Delta f = \text{UBE frequency} - f_c$ ). Set the spectrum analyzer vertical sensitivity to 2 dB/division. Adjust the center frequency level to be 2 dB below top of display. Photograph the spectrum and attach to data sheet 5.9.1.

5.9.3.2 White-Noise Method - (Procedure 2)

5.9.3.2.1 Setup - Connect the noise generator output to the spectrum analyzer input.

5.9.3.2.2 Conditions - Set the spectrum analyzer resolution bandwidth to a value  $\leq 10$  percent of the specified bandpass filter bandwidth of the discriminator under test. Set spectrum analyzer video bandwidth to a value  $\leq 1$  percent of resolution bandwidth. Set spectrum analyzer sweep limits to  $f_c - 2.5 \Delta f$  and  $f_c + 2.5 \Delta f$  respectively (see data sheet 5.9.1). The spectrum analyzer vertical sensitivity should be set to 2 dB/division. Adjust the noise generator output amplitude to 0.5 Vrms. Set the noise generator output frequency response such that the noise is white over the frequency range of interest.

5.9.3.2.3 Verify that the noise spectrum is flat within  $\pm 0.5$  dB over the frequency range of interest.

5.9.3.2.4 Procedure - Connect the equipment as shown in figure 5.9.3. Measure and photograph the spectrum at the discriminator bandpass filter output. Estimate the values at the frequencies shown on data sheet 5.9.1. Attach the photograph to the data sheet.

5.9.4 Data Reduction - Verify that the values recorded on data sheet 5.9.1 meet the required specification (see data sheet 5.9.1 sample).

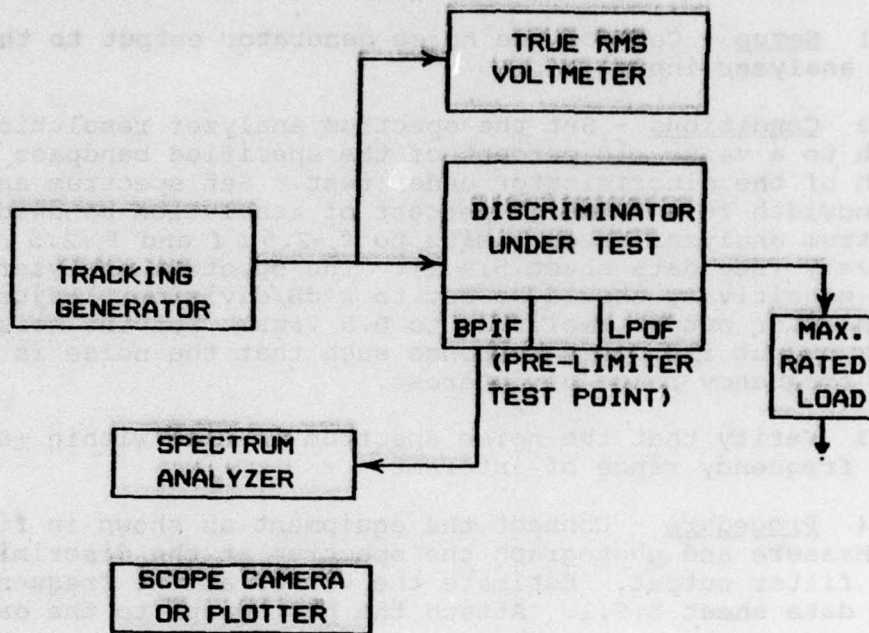


Figure 5.9.2 Test Set-up for Bandpass Input Filter Frequency Response.

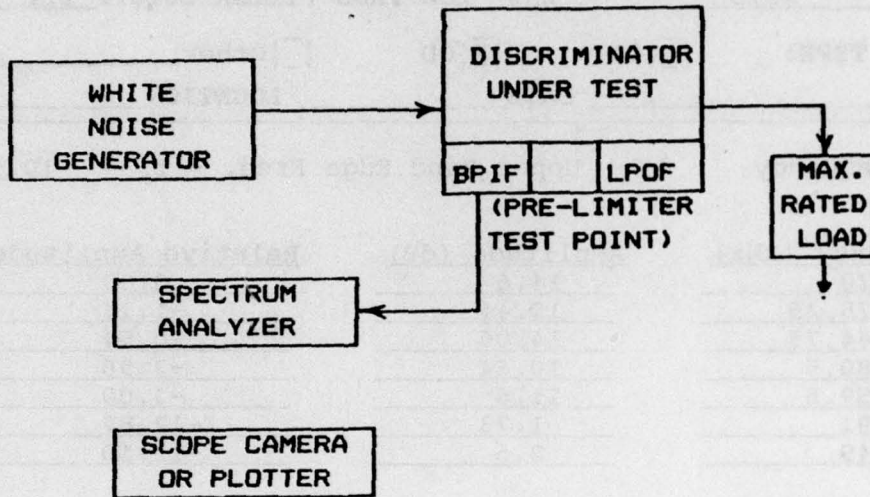


Figure 5.9.3 Test Setup for Bandpass Input Filter Frequency Response.

**FM DISCRIMINATORS**

DATA SHEET 5.9.1 (Sample)

**TEST Bandpass Filter Frequency Response**

MANUFACTURER XYZ MODEL DEF  
 SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY 70.0 kHz UPPER BAND EDGE 80.5 kHz  
 LOWER BAND EDGE 59.5 kHz LOW PASS FILTER CUTOFF 2.1 kHz  
 LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

$f_c$  = Center Frequency       $\Delta f$  = Upper Band Edge Freq. -  $f_c$  = 10.5 kHz

	Frequency (kHz)	Amplitude (dB)	Relative Amplitude (dB)
$f_c$	<u>70</u>	<u>14.6</u>	<u>0.00</u>
$f_c + \Delta f/2$	<u>75.25</u>	<u>13.44</u>	<u>-1.14</u>
$f_c - \Delta f/2$	<u>64.75</u>	<u>14.06</u>	<u>-0.54</u>
$f_c + \Delta f$	<u>80.5</u>	<u>10.64</u>	<u>-3.96</u>
$f_c - \Delta f$	<u>59.5</u>	<u>11.6</u>	<u>-3.00</u>
$f_c + 2 \Delta f$	<u>91</u>	<u>1.73</u>	<u>-12.87</u>
$f_c - 2 \Delta f$	<u>49</u>	<u>2.5</u>	<u>-12.10</u>

**EXAMPLE:**

Relative Amplitude at  $(f_c + \Delta f)$  = Amplitude at  $(f_c + \Delta f)$  - Amplitude at  $f_c$

**Spectrum Analyzer Settings**

Vertical Scale (dB/div) 10 dB  
 Lower Frequency 43.75 kHz  
 Upper Frequency 96.25 kHz  
 Resolution Bandwidth 1000 Hz  
 Video Bandwidth 10 Hz

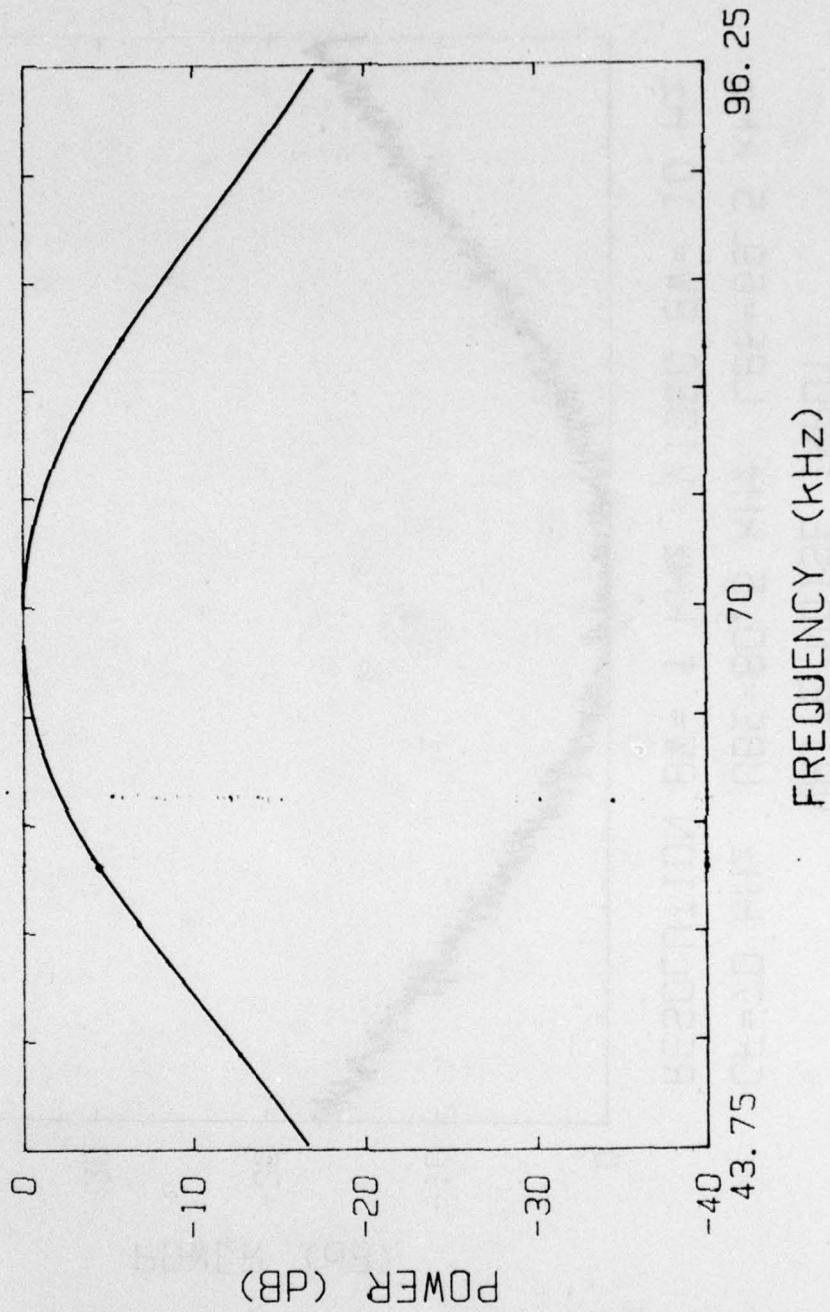
Attach  
 Photograph  
 Here

(See attachments 1 and 2.)

DISCRIMINATOR BPF OUTPUT

SINE WAVE INPUT

CF=70 KHZ UBE=80.5 KHZ LBE=69.5 KHZ



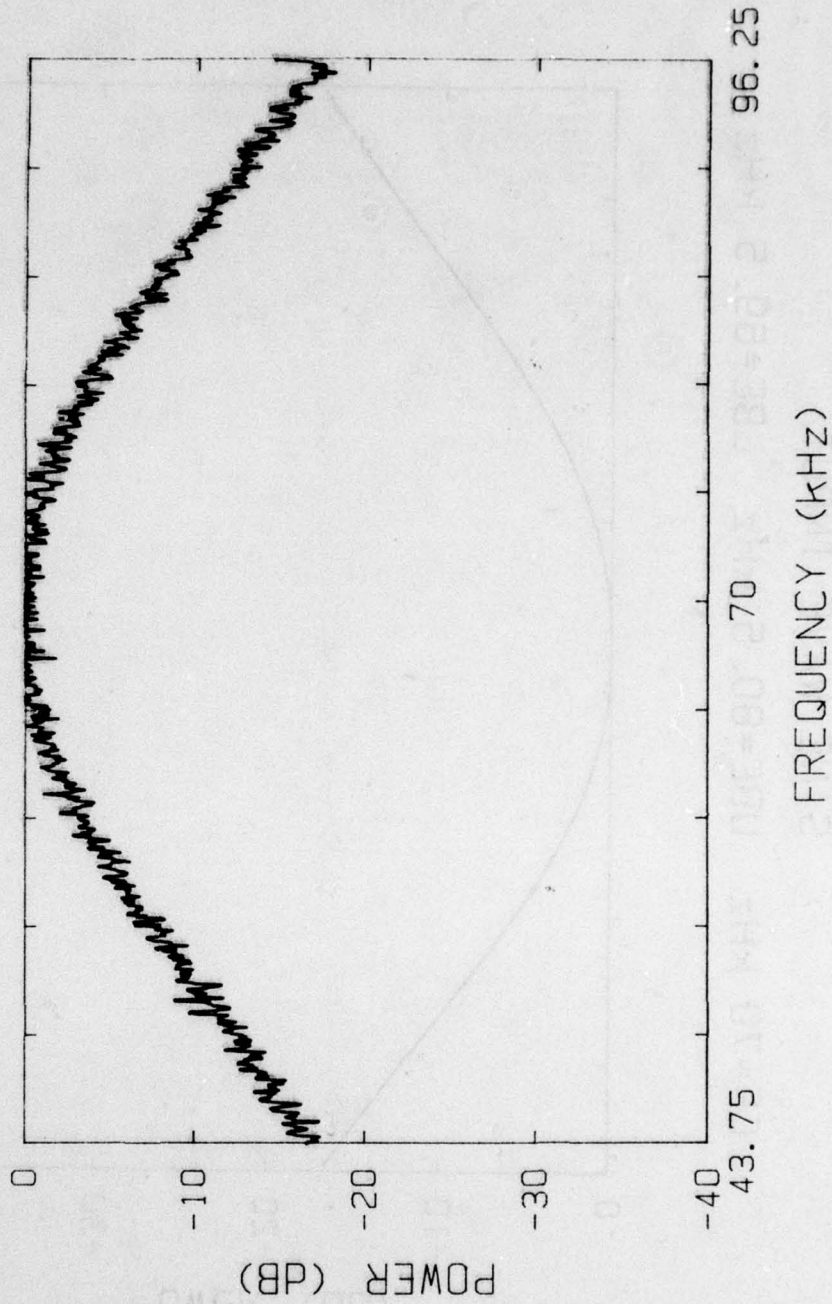
Data Sheet 5.9.1 (Sample) - Bandpass Filter Characteristic - Sine Wave Input.

DISCRIMINATOR BPF OUTPUT

WHITE NOISE INPUT

CF=70 KHZ UBE=80.5 KHZ LBE=69.5 KHZ

RESOLUTION BW= 1 KHZ VIDEO BW= 10 HZ



Data Sheet 5.9.1 (Sample) - Bandpass Filter Characteristic - White Noise Input.

## 5.10 Out-of-Band Frequency Rejection

5.10.1 Purpose - This test measures the frequency and amplitude of spurious signals at the discriminator output when signals outside the discriminator pass band are applied to the input.

### 5.10.2 Test Equipment

Signal generator or voltage controlled oscillator  
which can be frequency modulated  
Sine-wave generator with sweep capability  
Sine-wave generator  
Summing network  
X-Y recorder  
True rms voltmeter  
Spectrum analyzer

### 5.10.3 Test Method

5.10.3.1 Setup - Connect the test equipment as shown in figure 5.10.1.

5.10.3.2 Conditions - See paragraph 5.0 for general test conditions. Set up the spectrum analyzer as follows:

Minimum frequency: 0 Hz  
Maximum frequency: 10 times discriminator low pass filter  
cutoff frequency  
Resolution bandwidth:  $\leq 10$  percent of discriminator low pass  
filter cutoff frequency  
Vertical sensitivity: 10 dB/division

### 5.10.3.3 Procedure

5.10.3.3.1 Set the signal generator to the following:

Amplitude at input to discriminator: 0.3 Vrms  
Frequency: Discriminator center frequency  
Peak deviation: Discriminator band edge  
Modulating frequency: One half of discriminator low pass  
filter cutoff frequency

Measure the discriminator full scale signal output level on the spectrum analyzer. Set this level to be near the top of the display and record on data sheet 5.10.1.

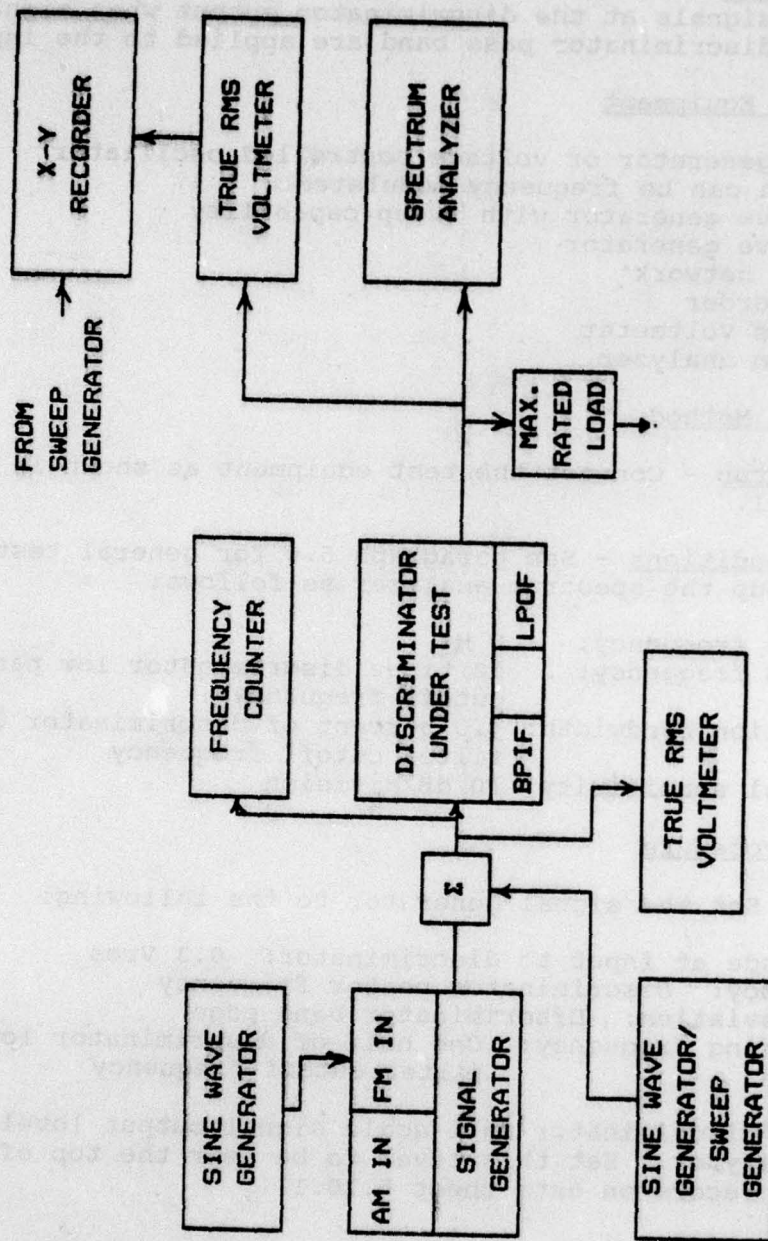


Figure 5.10.1 Test Setup for Out-of-Band Frequency Rejection.

**FM DISCRIMINATORS**

DATA SHEET 5.10.1

**TEST Adjacent Channel or Unwanted Frequency Rejection**

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_

SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz

LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz

LOW PASS FILTER TYPE:     CA         CD         Other \_\_\_\_\_

TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Full Scale Signal \_\_\_\_\_ dBm

Out-of-Band Frequency At Input	Unwanted Frequency At Discriminator Output	Relative To Full Scale Signal
_____ kHz	_____ kHz    _____ dBm	_____ dB
_____ kHz	_____ kHz    _____ dBm	_____ dB
_____ kHz	_____ kHz    _____ dBm	_____ dB
_____ kHz	_____ kHz    _____ dBm	_____ dB
_____ kHz	_____ kHz    _____ dBm	_____ dB
_____ kHz	_____ kHz    _____ dBm	_____ dB

5.10.3.3.2 Set the sine-wave generator to the following conditions:

Amplitude at input to discriminator: 0.3 Vrms  
Frequency: Center frequency of the next adjacent usable channel below discriminator under test  
Modulation: Disconnected

Measure the amplitude of any spurious signals in the spectral display and record the frequency and amplitude of these signals on data sheet 5.10.1.

5.10.3.3.3 Repeat step 5.10.3.3.2 with the sine-wave generator set to the following frequencies:

a. The UBE frequency of the adjacent usable channel below discriminator under test.

b. The LBE frequency of the adjacent usable channel above discriminator under test.

c. Center frequency of the adjacent usable channel above discriminator under test.

5.10.3.3.4 Remove the modulation from the signal generator. Set the sine-wave generator to sweep mode and sweep slowly between the following frequencies:

a. The 100 Hz to UBE frequency of the adjacent usable channel below discriminator under test.

b. The LBE frequency of the adjacent usable channel above discriminator under test to 1 MHz.

If any spurious output signals are detected, go to the frequency that caused the problem and record the input frequency, output frequency and level on data sheet 5.10.1. The X-Y recorder can be used to detect spurious signals.

5.10.4 Data Reduction - Subtract the full-scale signal level from each of the out-of-band frequency levels and record under relative column on data sheet 5.10.1 (see data sheet 5.10.1 sample).

FM DISCRIMINATORS

DATA SHEET 5.10.1 (Sample)

TEST Adjacent Channel or Unwanted Frequency Rejection

MANUFACTURER XYZ MODEL DEF  
 SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY 64 kHz UPPER BAND EDGE 68 kHz  
 LOWER BAND EDGE 60 kHz LOW PASS FILTER CUTOFF 2 kHz  
 LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Full Scale Signal -4.3 dBm

Out-of-Band Frequency At Input	Unwanted Frequency At Discriminator Output	Relative To Full Scale Signal
_____ kHz	_____ kHz _____ dBm	_____ dB
_____ kHz	_____ kHz _____ dBm	_____ dB
_____ kHz	_____ kHz _____ dBm	_____ dB
_____ kHz	_____ kHz _____ dBm	_____ dB
_____ kHz	_____ kHz _____ dBm	_____ dB
_____ kHz	_____ kHz _____ dBm	_____ dB

No spurious signals detected.  
 All spurious signals at least  
 50 dB below full scale sine wave.

## 5.11 Pulse Response

5.11.1 Purpose - This test measures the response of the discriminator to an input signal which is modulated by pulses, for example, pulse amplitude modulation (PAM) or pulse code modulation (PCM).

### 5.11.2 Test Equipment

Signal generator which can be frequency modulated  
Square-wave generator  
Frequency counter  
Oscilloscope  
Oscilloscope camera or plotter

### 5.11.3 Test Method

5.11.3.1 Setup - Connect the test equipment as shown in figure 5.11.1.

5.11.3.2 Conditions - See paragraph 5.0.

#### 5.11.3.3 Procedure

5.11.3.3.1 Frequency modulate the signal generator with a square wave. The square-wave frequency should be equal to 0.1 times the discriminator LPOF cutoff frequency. The peak deviation of the signal generator should be 0.5 times the UBE frequency minus the center frequency of the discriminator. Take a photograph of the oscilloscope display. Measure the rise time, overshoot, and settling time, and record on data sheet 5.11.1.

5.11.3.3.2 Repeat step 5.11.3.3.1 with a peak deviation equal to the UBE frequency minus the center frequency.

5.11.4 Data reduction - Compare the results with the specification (see data sheet 5.11.1 sample).

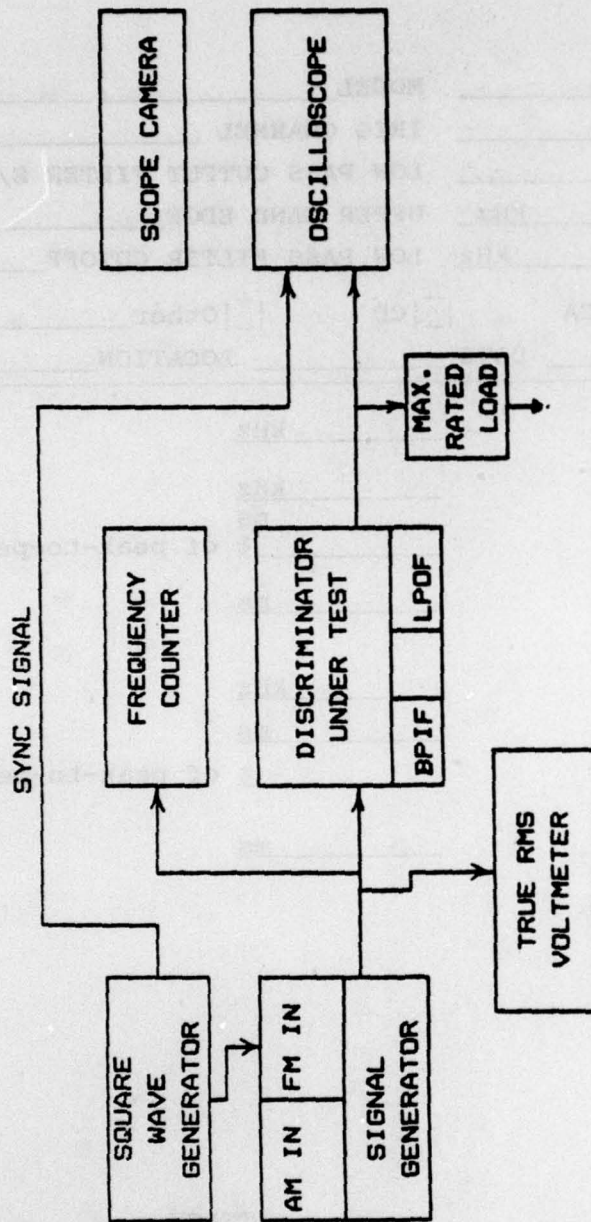


Figure 5.11.1 Test Setup for Pulse Response.

FM DISCRIMINATORS

DATA SHEET 5.11.1

TEST Pulse Response

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_

SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz

LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz

LOW PASS FILTER TYPE:     CA         CD         Other \_\_\_\_\_

TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Square Wave Frequency \_\_\_\_\_ kHz  
 Peak Deviation \_\_\_\_\_ kHz  
 10 to 90% Rise Time \_\_\_\_\_ ms  
 Overshoot \_\_\_\_\_ % of peak-to-peak amplitude  
 Settling Time to Within 2% of Step \_\_\_\_\_ ms

Peak Deviation \_\_\_\_\_ kHz  
 10 to 90% Rise Time \_\_\_\_\_ ms  
 Overshoot \_\_\_\_\_ % of peak-to-peak amplitude  
 Settling Time to Within 2% of Step \_\_\_\_\_ ms

ATTACH  
PHOTO

ATTACH  
PHOTO

FM DISCRIMINATORS

DATA SHEET 5.11.1 (Sample)

TEST Pulse Response

MANUFACTURER XYZ MODEL DEF  
 SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY 80 kHz UPPER BAND EDGE 84.0 kHz  
 LOWER BAND EDGE 76.0 kHz LOW PASS FILTER CUTOFF 1.0 kHz  
 LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Square Wave Frequency 0.100 kHz  
 Peak Deviation 4. kHz  
 10 to 90% Rise Time 0.35 ms  
 Overshoot 0.8 % of peak-to-peak amplitude  
 Settling Time to Within 2% of Step 0.600 ms

(See attachment 1.)

Peak Deviation 2. kHz  
 10 to 90% Rise Time 0.35 ms  
 Overshoot 0.7 % of peak-to-peak amplitude  
 Settling Time to Within 2% of Step 0.650 ms

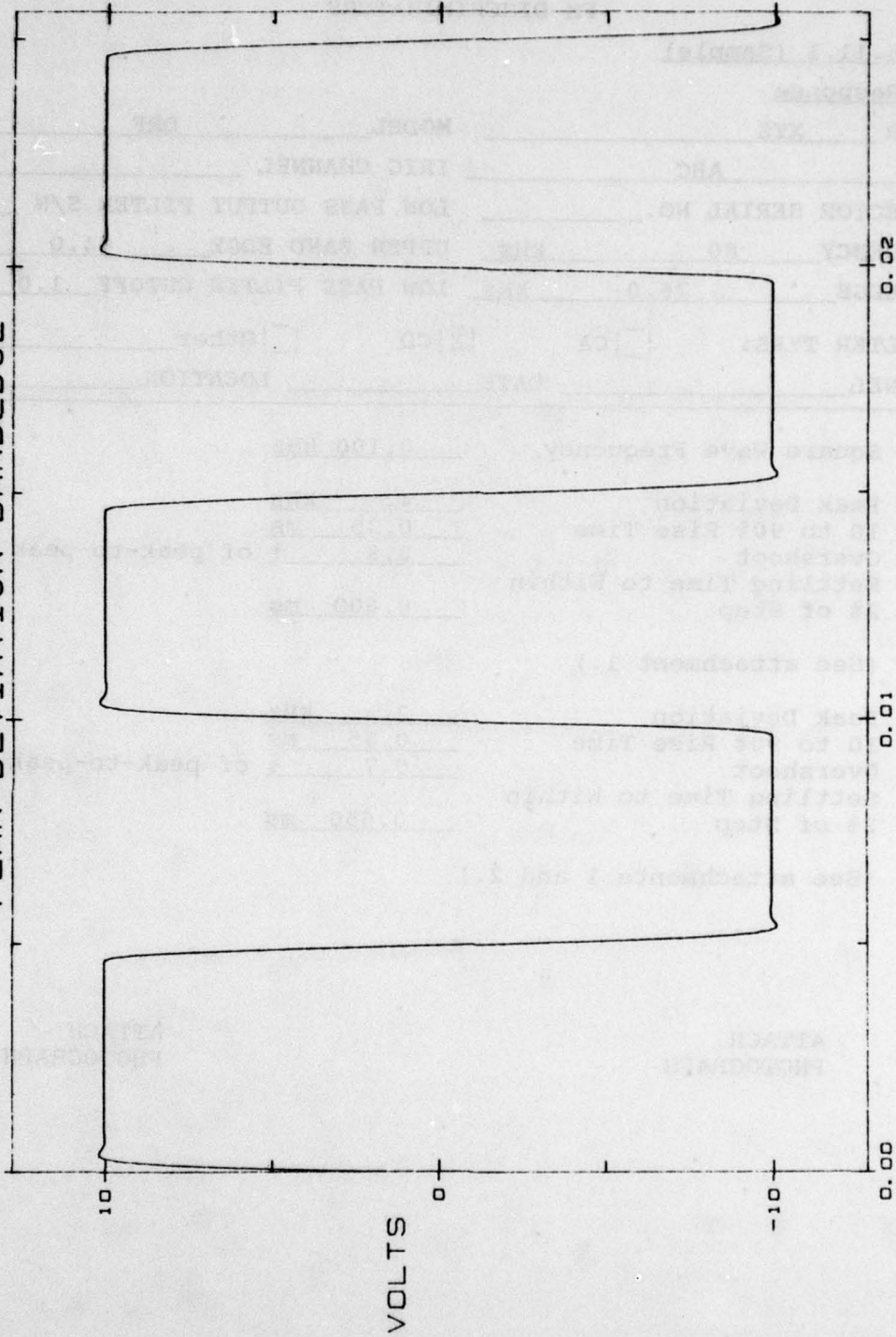
(See attachments 1 and 2.)

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PHOTOGRAPH

ATTACH  
PHOTOGRAPH

BUF. A1

PULSE RESPONSE TEST  
PEAK DEVIATION=BANDEDGE

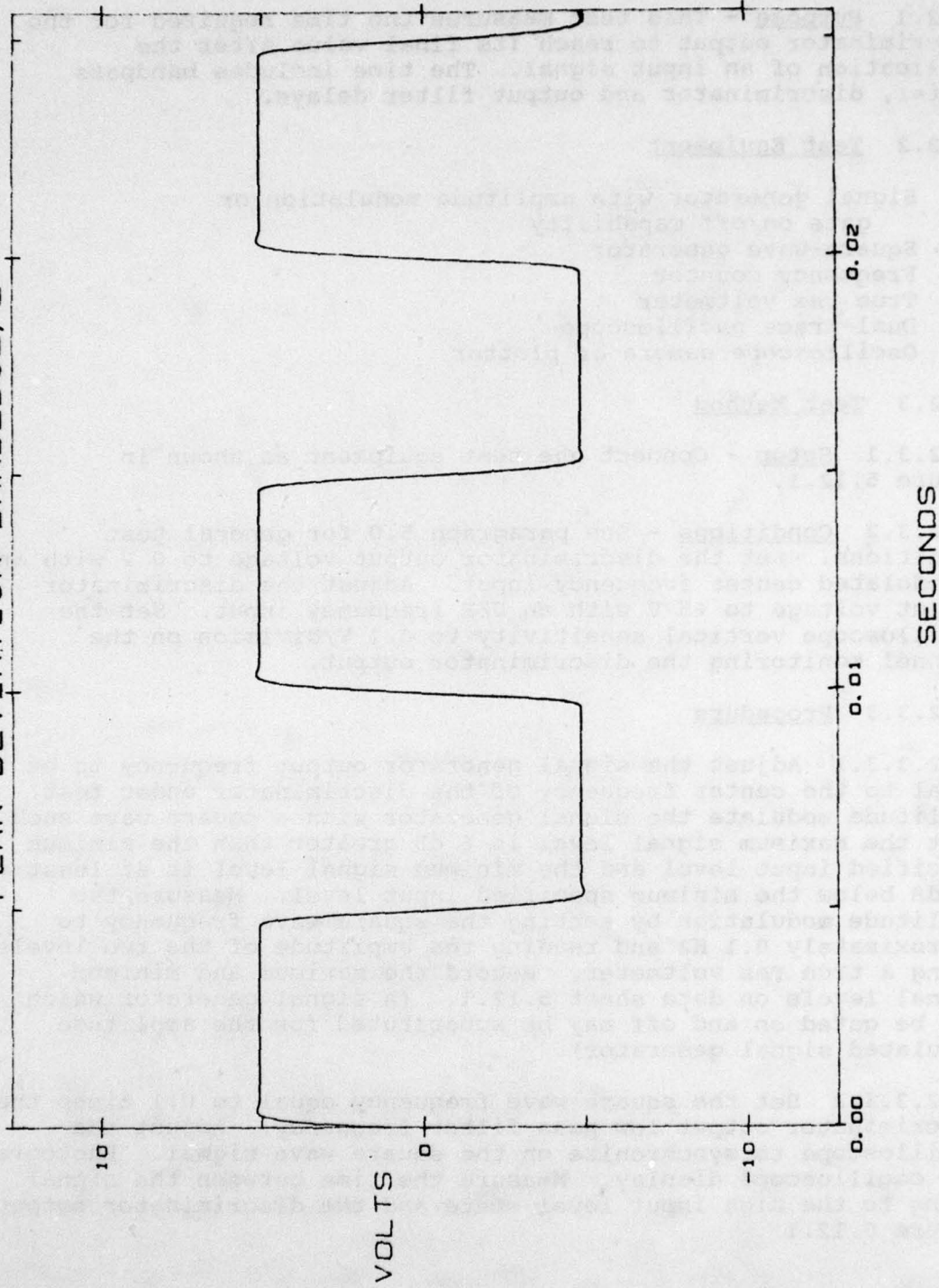


SECONDS

Data Sheet 5.11.1 (Sample) - Pulse Response Peak Deviation - 4kHz.

BUF. A1

PULSE RESPONSE TEST  
PEAK DEVIATION=BANDEDGE/2



Data Sheet 5.11.1 (Sample) - Pulse Response Peak Deviation - 2kHz.

## 5.12 Acquisition and Settling Time

5.12.1 Purpose - This test measures the time required for the discriminator output to reach its final value after the application of an input signal. The time includes bandpass filter, discriminator and output filter delays.

### 5.12.2 Test Equipment

Signal generator with amplitude modulation or  
gate on/off capability  
Square-wave generator  
Frequency counter  
True rms voltmeter  
Dual-trace oscilloscope  
Oscilloscope camera or plotter

### 5.12.3 Test Method

5.12.3.1 Setup - Connect the test equipment as shown in figure 5.12.1.

5.12.3.2 Conditions - See paragraph 5.0 for general test conditions. Set the discriminator output voltage to 0 V with an unmodulated center frequency input. Adjust the discriminator output voltage to +5 V with an UBE frequency input. Set the oscilloscope vertical sensitivity to 0.1 V/division on the channel monitoring the discriminator output.

#### 5.12.3.3 Procedure

5.12.3.3.1 Adjust the signal generator output frequency to be equal to the center frequency of the discriminator under test. Amplitude modulate the signal generator with a square wave such that the maximum signal level is 6 dB greater than the minimum specified input level and the minimum signal level is at least 20 dB below the minimum specified input level. Measure the amplitude modulation by setting the square wave frequency to approximately 0.1 Hz and reading the amplitude of the two levels using a true rms voltmeter. Record the maximum and minimum signal levels on data sheet 5.12.1. (A signal generator which can be gated on and off may be substituted for the amplitude modulated signal generator).

5.12.3.3.2 Set the square wave frequency equal to 0.1 times the discriminator output low pass filter frequency. Adjust the oscilloscope to synchronize on the square wave signal. Photograph the oscilloscope display. Measure the time between the signal going to the high input level state and the discriminator output Figure 5.12.1

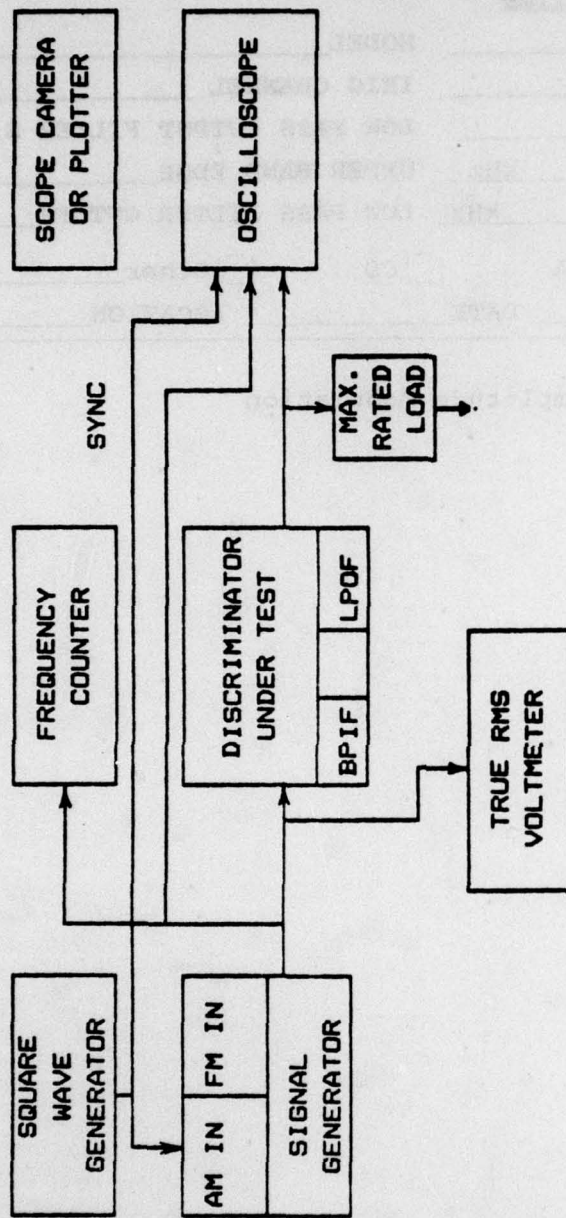


Figure 5.12.1 Test Setup for Acquisition and Settling Time.

FM DISCRIMINATORS

DATA SHEET 5.12.1

TEST Acquisition and Settling Time

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_  
SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_  
CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz  
LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz  
LOW PASS FILTER TYPE:     CA         CD         Other \_\_\_\_\_  
TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Signal Generator Levels With Amplitude Modulation

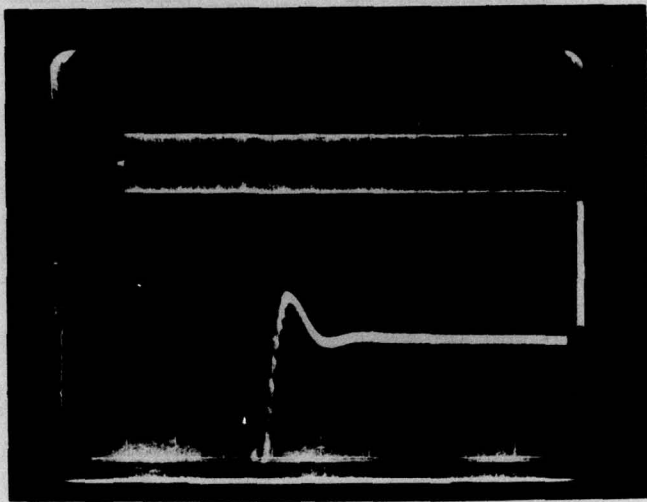
Input to discriminator

Maximum \_\_\_\_\_ mVrms

Minimum \_\_\_\_\_ mVrms

settling to within one vertical division (1 percent of peak-to-peak output voltage swing) of its final value. The square wave frequency and oscilloscope horizontal time base may have to be adjusted to obtain the desired accuracy. A sample oscilloscope display is shown in figure 5.12.2. Record the results on data sheet 5.12.1.

5.12.4 Data Reduction - Compare the results with the specification (see data sheet 5.12.1 sample).



Center Frequency: 128 kHz  
Bandpass Filter Bandwidth: 8 kHz  
Low Pass Filter Bandwidth: 4 kHz  
Horizontal Sensitivity: 0.1 ms/major division  
Settling time to within 1% of full scale: 0.36 ms  
Final value: 2 major divisions up from bottom of display

Figure 5.12.2 Photograph of Oscilloscope Display for Acquisition and Settling Time Test.

FM DISCRIMINATORS

DATA SHEET 5.12.1 (Sample)

TEST Acquisition and Settling Time

MANUFACTURER XYZ MODEL DEF  
SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_  
CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
CENTER FREQUENCY 64 kHz UPPER BAND EDGE 68 kHz  
LOWER BAND EDGE 60 kHz LOW PASS FILTER CUTOFF 2 kHz  
LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Signal Generator Levels With Amplitude Modulation

Input to discriminator

Maximum 20. mVrms

Minimum 0.2 mVrms

### 5.13 Data Frequency Response

5.13.1 Purpose - This test measures the data frequency response of an FM discriminator.

#### 5.13.2 Test Equipment

Audio oscillator (sine wave)  
Signal generator or voltage controlled oscillator which can be frequency modulated  
Frequency counter  
Oscilloscope  
Voltmeters, rms, 2 required  
Spectrum analyzer  
Wave analyzer (optional)

#### 5.13.3 Test Method

5.13.3.1 Setup - Connect the test equipment as shown in figure 5.13.1.

5.13.3.2 Conditions - See paragraph 5.0 for general test conditions. The signal generator should be set to the following:

Output frequency = discriminator center frequency  
Output amplitude = 0.3 Vrms  
The discriminator output should be set to 0V dc with an unmodulated center frequency input.

#### 5.13.3.3 Procedure

5.13.3.3.1 The first step in this procedure will be to set the signal generator peak deviation equal to the (UBE frequency - center frequency) of the discriminator.

#### NOTE

The Bessel null method is described here. Other methods of setting the peak deviation may be used if desired.

Set the audio oscillator frequency to the desired peak deviation/2.405 (first Bessel carrier null). Decrease the audio oscillator amplitude to a minimum. Slowly increase the amplitude until the first carrier null is observed on the spectrum analyzer.

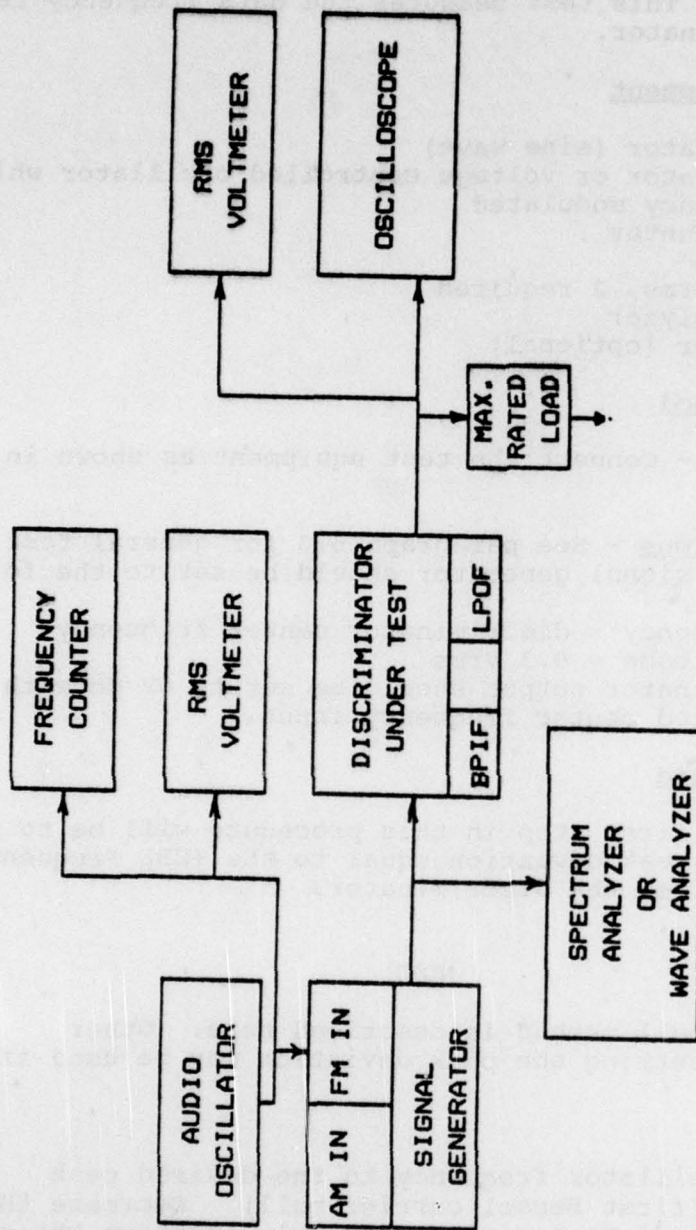


Figure 5.13.1 Test Setup for Data Frequency Response.

Measure this amplitude using the rms voltmeter and record on data sheet 5.13.1. Increase the audio oscillator frequency until it is equal to the peak deviation. Measure the difference (in dB) between the modulated carrier amplitude and the amplitudes of the first sideband pair. This difference should be 4.8 dB (sidebands lower than modulated carrier). If both sidebands are not between 4.3 and 5.3 dB lower than the modulated carrier, the frequency response of the signal generator is not adequate for this test, and a different signal generator or voltage controlled oscillator must be used.

5.13.3.3.2 Set the audio oscillator frequency to one-tenth of the discriminator low pass filter cutoff frequency. Adjust the audio oscillator amplitude to be equal to the value determined in step 5.13.3.3.1, that is, the value which results in the desired peak deviation. Measure the discriminator output on the rms voltmeter and record on data sheet 5.13.1.

5.13.3.3.3 Set the audio oscillator to the frequencies listed on data sheet 5.13.1 while maintaining the output amplitude constant. The highest audio oscillator frequency will be equal to four times the discriminator low-pass filter cutoff frequency. Measure and record the discriminator output on data sheet 5.13.1 for each frequency.

5.13.4 Data Reduction - Subtract the discriminator output amplitude (in dB) at one-tenth the low-pass filter cutoff frequency from the amplitude at each of the other frequencies. Record on data sheet 3.1 (see data sheet 5.13.1 sample).

**FM DISCRIMINATORS**

DATA SHEET 5.13.1

**TEST Data Frequency Response**

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_  
 SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz  
 LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz

LOW PASS FILTER TYPE:     CA     CD     Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Rms voltage at FM input of the signal generator \_\_\_\_\_ Vrms

<u>% of LPOF Cutoff Frequency</u>	<u>Frequency(Hz)</u>	<u>Discriminator Output Amplitude (dBm)</u>	<u>Discriminator Relative Amplitude (dB)</u>
10	_____	_____	0
40	_____	_____	_____
70	_____	_____	_____
100	_____	_____	_____
200	_____	_____	_____
300	_____	_____	_____
400	_____	_____	_____
_____	_____	_____	_____
_____	_____	_____	_____

**FM DISCRIMINATORS**

DATA SHEET 5.13.1 (Sample)

TEST Data Frequency Response

MANUFACTURER XYZ MODEL DEF  
 SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY 64 kHz UPPER BAND EDGE 68 kHz  
 LOWER BAND EDGE 60 kHz LOW PASS FILTER CUTOFF 2.0 kHz

LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Rms voltage at FM input of the signal generator 0.641 Vrms

<u>% of LPOF Cutoff Frequency</u>	<u>Frequency(Hz)</u>	<u>Discriminator Output Amplitude (dBm)</u>	<u>Discriminator Relative Amplitude (dB)</u>
<u>10</u>	<u>200</u>	<u>29.05</u>	<u>0</u>
<u>40</u>	<u>800</u>	<u>28.50</u>	<u>-0.55</u>
<u>70</u>	<u>1400</u>	<u>27.28</u>	<u>-1.77</u>
<u>100</u>	<u>2000</u>	<u>25.3</u>	<u>-3.75</u>
<u>200</u>	<u>4000</u>	<u>11.72</u>	<u>-17.33</u>
<u>300</u>	<u>6000</u>	<u>-6.89</u>	<u>-35.94</u>
<u>400</u>	<u>8000</u>	<u>-23.09</u>	<u>-52.14</u>
_____	_____	_____	_____
_____	_____	_____	_____

## 5.14 Tape Speed Compensation

5.14.1 Purpose - This test measures the performance of the tape speed compensation (TSC) circuitry in an FM demodulation system.

### NOTE

A reference discriminator and associated delay line are needed to perform this test.

## 5.14.2 Test Equipment

Two stable signal generators with FM inputs  
Reference discriminator and delay line  
Baseband spectrum analyzer  
X-Y recorder  
Baseband frequency sweep generator  
Oscilloscope (preferably with dual trace)

## 5.14.3 Test Method

5.14.3.1 Setup - Connect the test equipment as shown in figure 5.14.1.

5.14.3.2 Conditions - Disconnect the baseband frequency sweep generator from the inputs of the signal generators. Set the output frequency of the signal generator driving the reference discriminator to the center frequency of the reference discriminator and the output frequency of the signal generator driving the discriminator under test to the center frequency of the discriminator under test. While monitoring the outputs of the discriminators, vary the output of each signal generator  $\pm 3$  percent of the center frequency and note the positions of the trace on the oscilloscope. Set the signal generators back to the respective center frequencies and reconnect the baseband frequency sweep generator. Adjust the output level so that the peaks of the output signals from the discriminators are at the trace positions noted earlier. A voltage divider may be needed on the FM input of the most sensitive of the two signal generators to create an equal percent deviation sensitivity on both signal generators. The spectrum analyzer should be set up to the following conditions:

Start Frequency: Between 0 Hertz and discriminator low-pass filter cutoff frequency/100

Stop Frequency: Discriminator low-pass filter cutoff frequency.

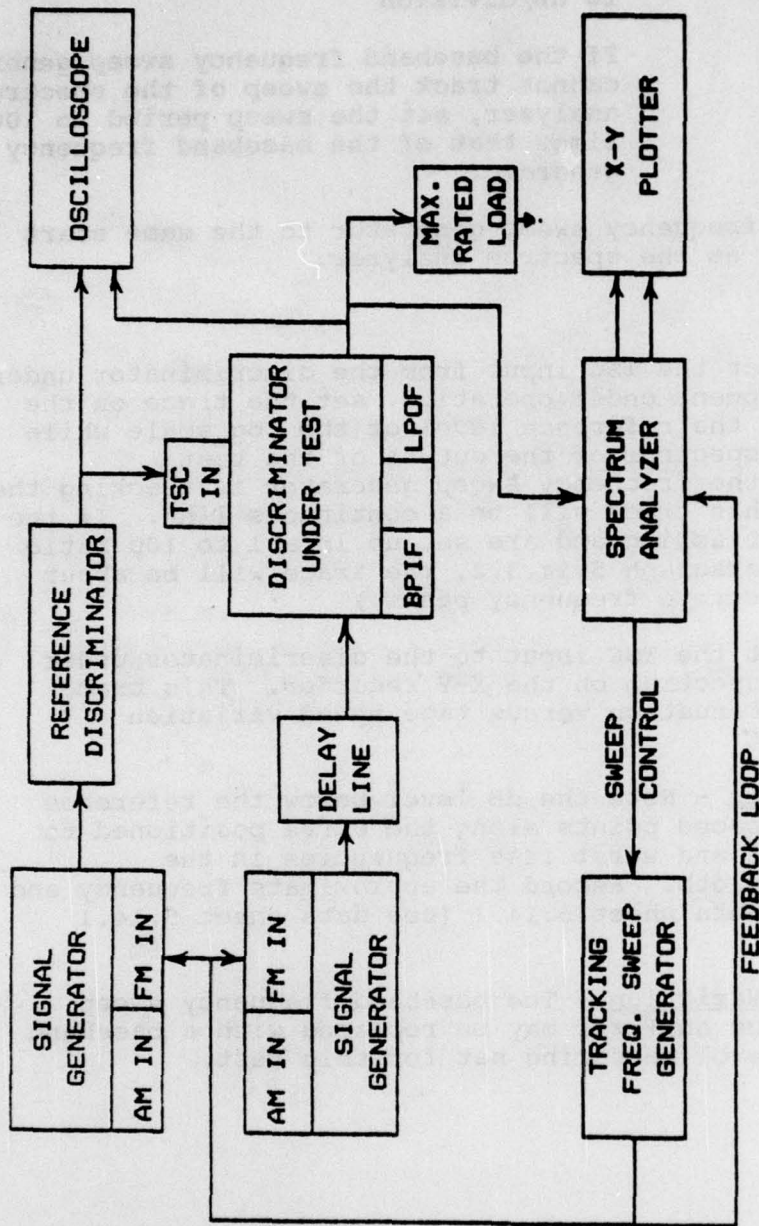


Figure 5.14.1 Test Setup for Tape Speed Compensation Test.

Resolution bandwidth: Less than or equal to stop frequency/100

Vertical scale: 10 dB/division

Sweep rate: If the baseband frequency sweep generator cannot track the sweep of the spectrum analyzer, set the sweep period to 100 times that of the baseband frequency sweep generator

Set up the baseband frequency sweep generator to the same start and stop frequencies as the spectrum analyzer.

#### 5.14.3.3 Procedure

5.14.3.3.1 Disconnect the TSC input from the discriminator under test. With the equipment under operation, set the trace on the spectrum analyzer to the reference level of the log scale while measuring the power spectrum of the output of the test discriminator. (If the frequency sweep generator is tracking the spectrum analyzer, this trace will be a continuous line. If the sweep rates are not tracking and are set up in a 1 to 100 ratio as described in subparagraph 5.14.3.2, the trace will be about 100 evenly spaced discrete frequency peaks.)

5.14.3.3.2 Reconnect the TSC input to the discriminator under test and record the spectrum on the X-Y recorder. This trace will be the level attenuation versus tape speed variation frequency for the TSC.

5.14.4 Data Reduction - Note the dB level below the reference level at 10 evenly spaced points along the curve positioned to pick up both the best and worst case frequencies in the discriminator's bandwidth. Record the approximate frequency and amplitude levels on data sheet 5.14.1 (see data sheet 5.14.1 sample).

5.14.5 Measurement Variation - The baseband frequency sweep generator and spectrum analyzer may be replaced with a baseband frequency response level measuring set for this test.

FM DISCRIMINATORS

DATA SHEET 5.14.1

TEST Tape Speed Compensation

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_

SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz

LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz

LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_

TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Reference Oscillator Frequency \_\_\_\_\_ kHz

Reference Discriminator Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Delay Line Model \_\_\_\_\_ Serial No. \_\_\_\_\_

<u>Frequency (Hz)</u>	<u>TSC Improvement (dB)</u>
_____	_____
_____	_____
_____	_____
_____	_____
_____	_____
_____	_____
_____	_____
_____	_____
_____	_____
_____	_____

**FM DISCRIMINATORS**

DATA SHEET 5.14.1 (Sample)

TEST Tape Speed Compensation

MANUFACTURER XYZ MODEL DEF

SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY 70 kHz UPPER BAND EDGE 75.25 kHz

LOWER BAND EDGE 64.75 kHz LOW PASS FILTER CUTOFF 1.05 kHz

LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_

TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Reference Oscillator Frequency 100 kHz

Reference Discriminator Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Delay Line Model \_\_\_\_\_ Serial No. \_\_\_\_\_

Frequency (Hz)	TSC Improvement (dB)
<u>100</u>	<u>31</u>
<u>200</u>	<u>24</u>
<u>300</u>	<u>20</u>
<u>400</u>	<u>18</u>
<u>500</u>	<u>16</u>
<u>600</u>	<u>14</u>
<u>700</u>	<u>13</u>
<u>800</u>	<u>12</u>
<u>900</u>	<u>11</u>
<u>1000</u>	<u>10</u>

## 5.15 Discriminator Phase Response

5.15.1 Purpose - This test determines phase response characteristics of a discriminator including bandpass input and LPOF. This test should be of value where phase distortion or nonlinearity is the cause of data quality or phase-related processing problems.

### 5.15.2 Test Equipment

#### 5.15.2.1 For Procedure 1 - Incremental Method

Audio oscillator  
Oscilloscope with dual trace or phase meter  
Voltage-controlled signal generator without filter  
Frequency counter

#### 5.15.2.2 For Procedure 2 - Quick-Look Spectral Method

White noise generator  
Voltage-controlled signal generator without filter  
Dual-channel spectrum analyzer with transfer function  
and display and plotting capability

### 5.15.3 Test Method

#### 5.15.3.1 Procedure 1 - Incremental Method

This method involves measuring delay through the discriminator as a function of intelligence frequency. The delay may be measured using either an oscilloscope or a phase meter.

##### 5.15.3.1.1 Setup 1

Connect equipment as shown in figure 5.15.1.

##### 5.15.3.1.2 Condition 1

Both procedures 1 and 2 depend on negligible relative contribution to phase nonlinearity by the signal generator. This condition is ensured only through use of a small, central, highly linear portion of the signal generator range, and both procedures are, therefore, less valid for large percentage deviation cases. The discriminator should already be set for 0 V out at center frequency and a nominal band edge voltage appropriate for the unit under test.

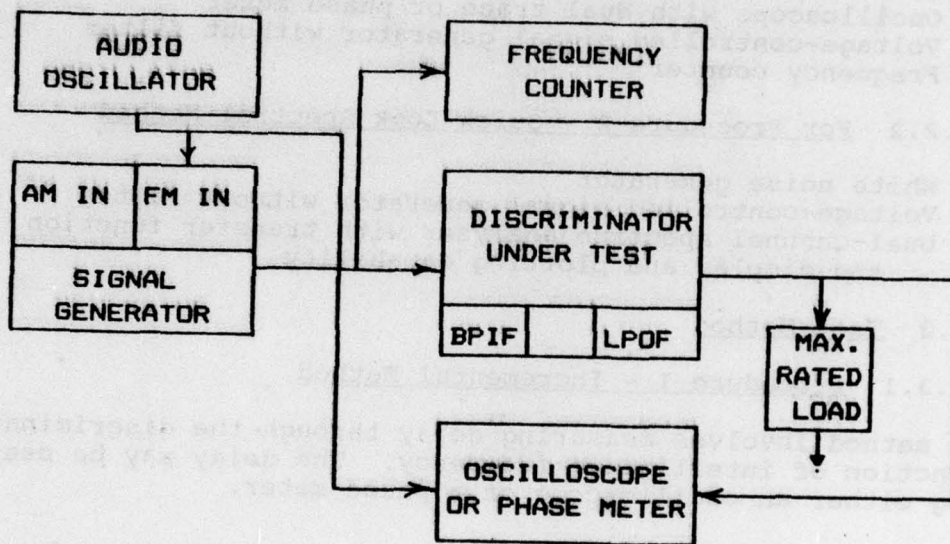


Figure 5.15.1 Test Setup for Discriminator Phase Response.

### 5.15.3.1.3 Procedure 1

5.15.3.1.3.1 Set the audio oscillator frequency equal to the discriminator UBE frequency minus the center frequency. Set the audio oscillator amplitude to produce a band-edge-to-band-edge deviation of the signal generator. This procedure produces a signal with a modulation index equal to one. The two traces on the oscilloscope are the audio oscillator output and the discriminator output. The delay of the discriminator output relative to the audio oscillator output is the quantity being measured.

5.15.3.1.3.2 Measure the time difference between the zero crossings of the two traces and record on data sheet 5.15.1 (see data sheet 5.15.1 sample). Repeat for other modulation frequencies as desired. (Modulation frequencies of 0.25, 0.5, 0.75, and 1 times the peak deviation provide a reasonable data base for most applications.) This test may be repeated for other peak deviations as desired.

### 5.15.3.2 Quick-look Spectral Method (Procedure 2)

This method involves using a dual-channel spectrum analyzer/display to observe the phase response curve given a white noise driven signal generator as input to the discriminator.

5.15.3.2.1 Setup 2 - Connect equipment as shown in figure 5.15.2.

#### 5.15.3.2.2 Condition 2

This method uses a dual channel spectrum analyzer with phase response plotting capability. Resolution/accuracy of phase measurement will depend on dynamic range, numerical cursor readout availability, and other features of a given analyzer. The discriminator should already be set for 0 V output at center frequency and a nominal band edge voltage appropriate for the unit under test.

#### 5.15.3.2.3 Procedure 2

Use one channel of the dual-channel analyzer on the input to the signal generator and the second channel on the discriminator output. Select the phase portion of transfer function or cross-spectral mode of the analyzer. Adjust analyzer gain and white-noise amplitude to avoid overrange or saturation. If necessary to avoid saturation, low-pass filter the white noise prior to the signal generator. Any prefiltering of the signal generator input must be wider than the LPOF in use and have linear phase characteristics. Select a frequency analysis range greater than that of the discriminator LPOF in use. Observe and hard copy the phase versus frequency plot and attach to data sheet 5.15.2.

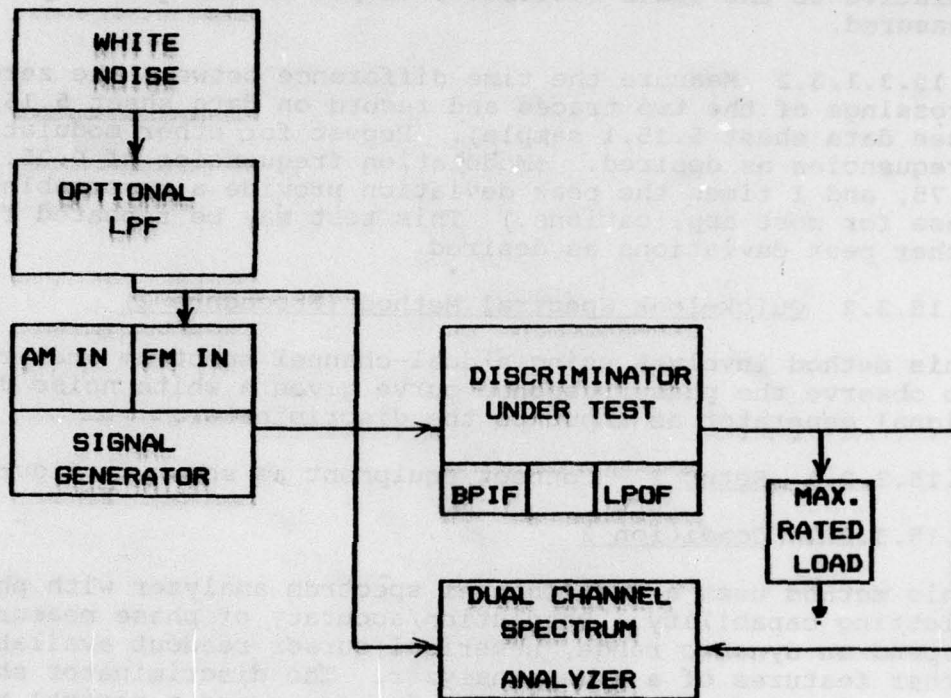


Figure 5.15.2 Test Setup for Discriminator Phase Response (Procedure 2).

FM DISCRIMINATORS

DATA SHEET 5.15.1

TEST Discriminator Phase Response (Procedure 1)

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_

SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz

LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz

LOW PASS FILTER TYPE:     CA     CD     other \_\_\_\_\_

TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Frequency at Signal Generator Input = $f_i$ _____	Modulation Index (Peak Dev./ $f_i$ ) _____	Delay (D) Measured with Oscilloscope _____	Relative Phase Angle (Degrees) ( $=360 \times D \times f_i$ ) _____
_____	1.0	_____	_____
_____	_____	_____	_____
_____	_____	_____	_____
_____	_____	_____	_____
_____	_____	_____	_____

FM DISCRIMINATORS

DATA SHEET 5.15.1 (Sample)

TEST Discriminator Phase Response (Procedure 1)

MANUFACTURER XYZ MODEL DEF  
 SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY 128 kHz UPPER BAND EDGE 132 kHz  
 LOWER BAND EDGE 124 kHz LOW PASS FILTER CUTOFF 4 kHz  
 LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Frequency at Signal Generator Input = $f_i$	Modulation Index (Peak Dev./ $f_i$ )	Delay (D) Measured with Oscilloscope	Relative Phase Angle (Degrees) ( $=360 \times D \times f_i$ )
<u>4 kHz</u>	<u>1.0</u>	<u>207 us</u>	<u>298.1</u>
<u>3</u>	<u>1.33</u>	<u>207</u>	<u>223.6</u>
<u>2</u>	<u>2</u>	<u>207</u>	<u>149.</u>
<u>1</u>	<u>4</u>	<u>207</u>	<u>74.5</u>
<u>2</u>	<u>1</u>	<u>207</u>	<u>149.</u>

FM DISCRIMINATORS

DATA SHEET 5.15.2

TEST Discriminator Phase Response (Procedure 2)

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_  
SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_  
CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz  
LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz  
LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Signal Generator \_\_\_\_\_ Spectrum Analyzer \_\_\_\_\_

White Noise Generator \_\_\_\_\_

Attach spectral plots with full annotation.

NOTE

Procedure 2 does not involve incremental point collection but provides an immediate response curve picture. The technique used is the same as plotting the transfer function or phase characteristic, or both, of a filter. In this case, the signal generator discriminator combination is the "filter" under test.

5.15.4 Data Reduction

5.15.4.1 Procedure 1 (see data sheet 5.15.1)

The data in tabular form consists of an independent variable (frequency) and a dependent variable (delay). These variables should be plotted on a large enough scale to show phase nonlinearity (nonconstant delay) to the degree required. Delay may be converted to phase angle and entered on the last data sheet column. Convert delay to angle by multiplying the delay value by the frequency of the audio oscillator sine wave times  $360^\circ$  (see data sheet 5.15.1 sample).

5.15.4.2 Procedure 2 - The analyzer provides the phase versus frequency plot directly. These graphics should be attached to data sheet 5.15.2 (see data sheet 5.15.2 sample).

FM DISCRIMINATORS

DATA SHEET 5.15.2 (Sample)

TEST Discriminator Phase Response (Procedure 2)

MANUFACTURER XYZ MODEL DEF

SERIAL NO. ABC IRIG CHANNEL 10

CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_

CENTER FREQUENCY 5.400 kHz UPPER BAND EDGE 5.805 kHz

LOWER BAND EDGE 4.995 kHz LOW PASS FILTER CUTOFF 0.081 kHz

LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_

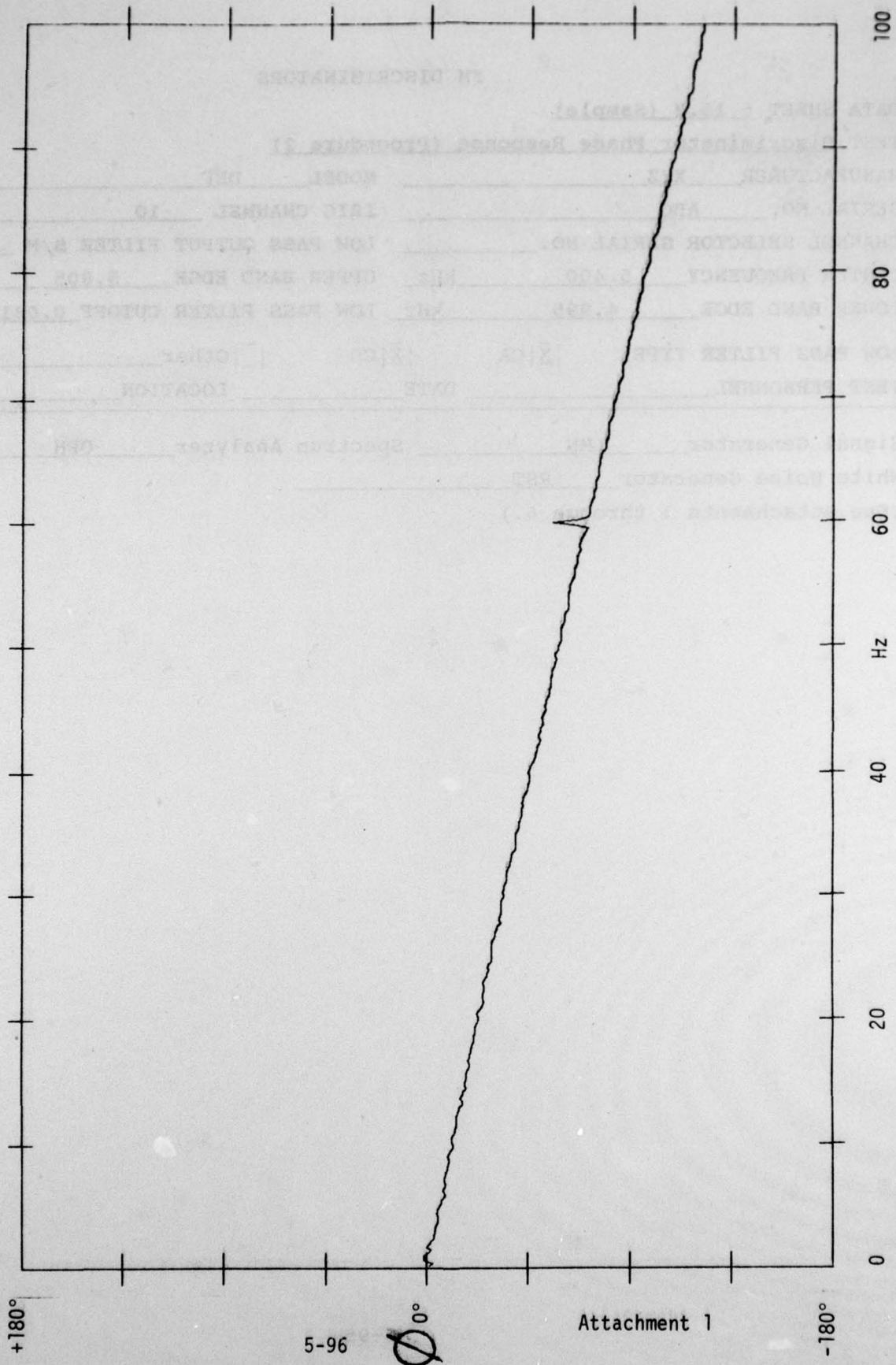
TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Signal Generator LMN Spectrum Analyzer OPH

White Noise Generator RST

(See attachments 1 through 6.)

C.F. 5.4 kHz  
L.P.F. 81 Hz C.A.



5-96

$\emptyset$  0°

Attachment 1

-180°

0

20

40

60

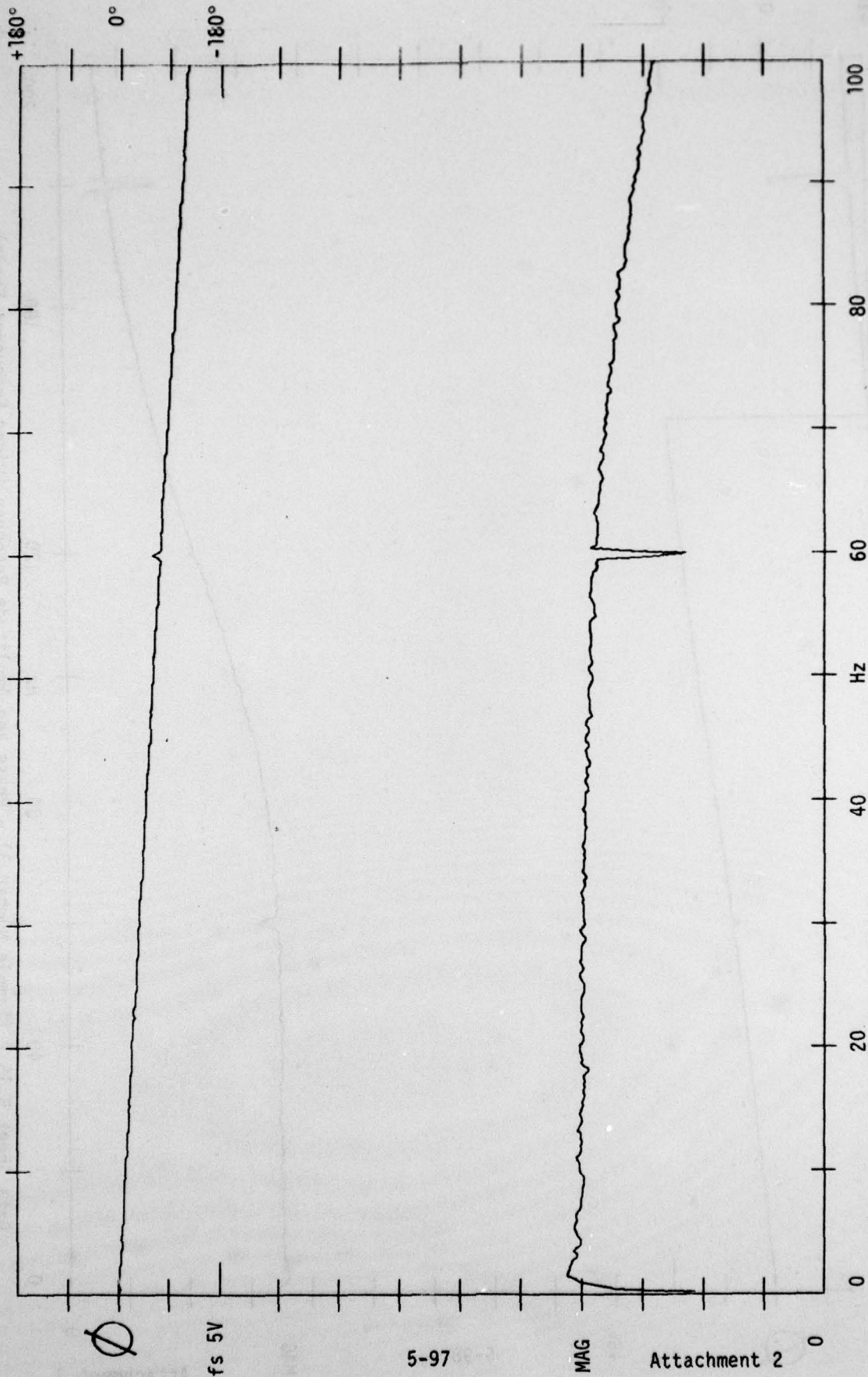
Hz

80

100

Data Sheet 5.15.2 (Sample Number 1) (60Hz Noise) - Constant Amplitude Phase Response.

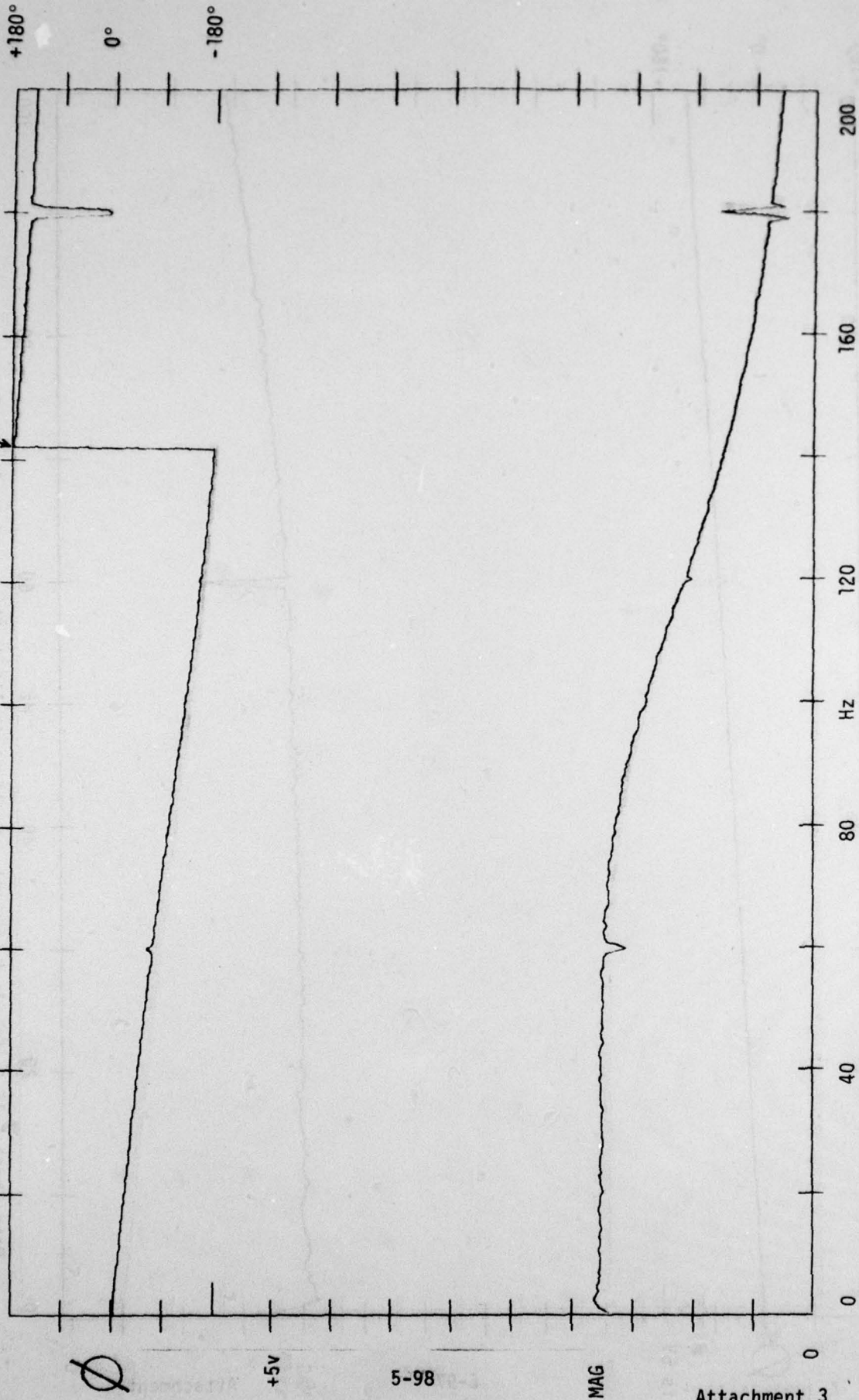
C.F. 5.4 kHz  
L.P.F. 81 Hz C.A.



Data Sheet 5.15.2 (Sample Number 2) - Constant Amplitude Phase and Amplitude Response.

C.F. 5.4 KHZ  
L.P.F. 81 HZ C.A.

142 Hz



Data Sheet 5.15.2 (Sample Number 3) - Phase and Amplitude Response (Wider Frequency Scale).

Ø

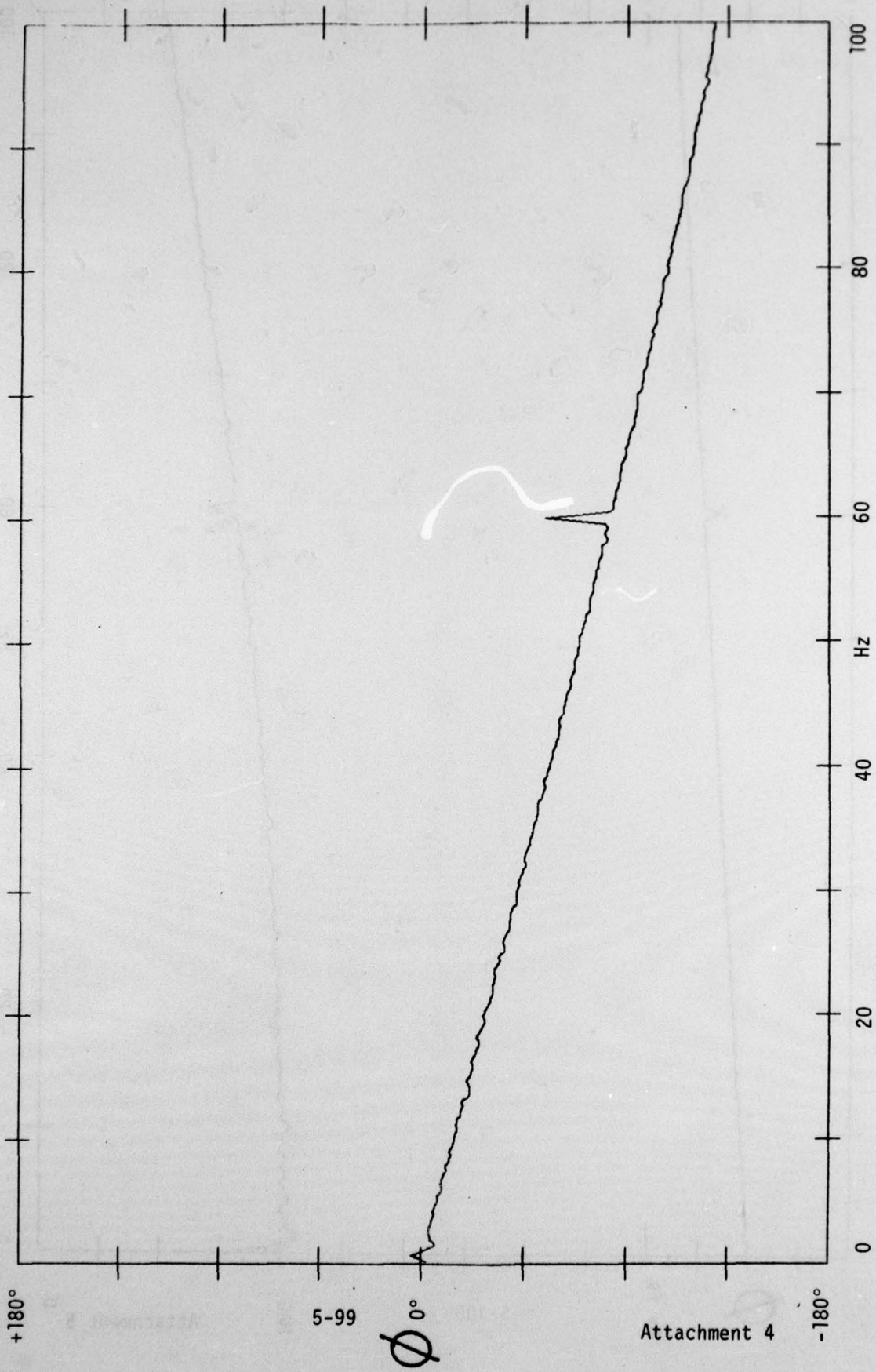
+5v

5-98

MAG

Attachment 3

C.F. 5.4 KHz  
L.P.F. 81 Hz C.D.



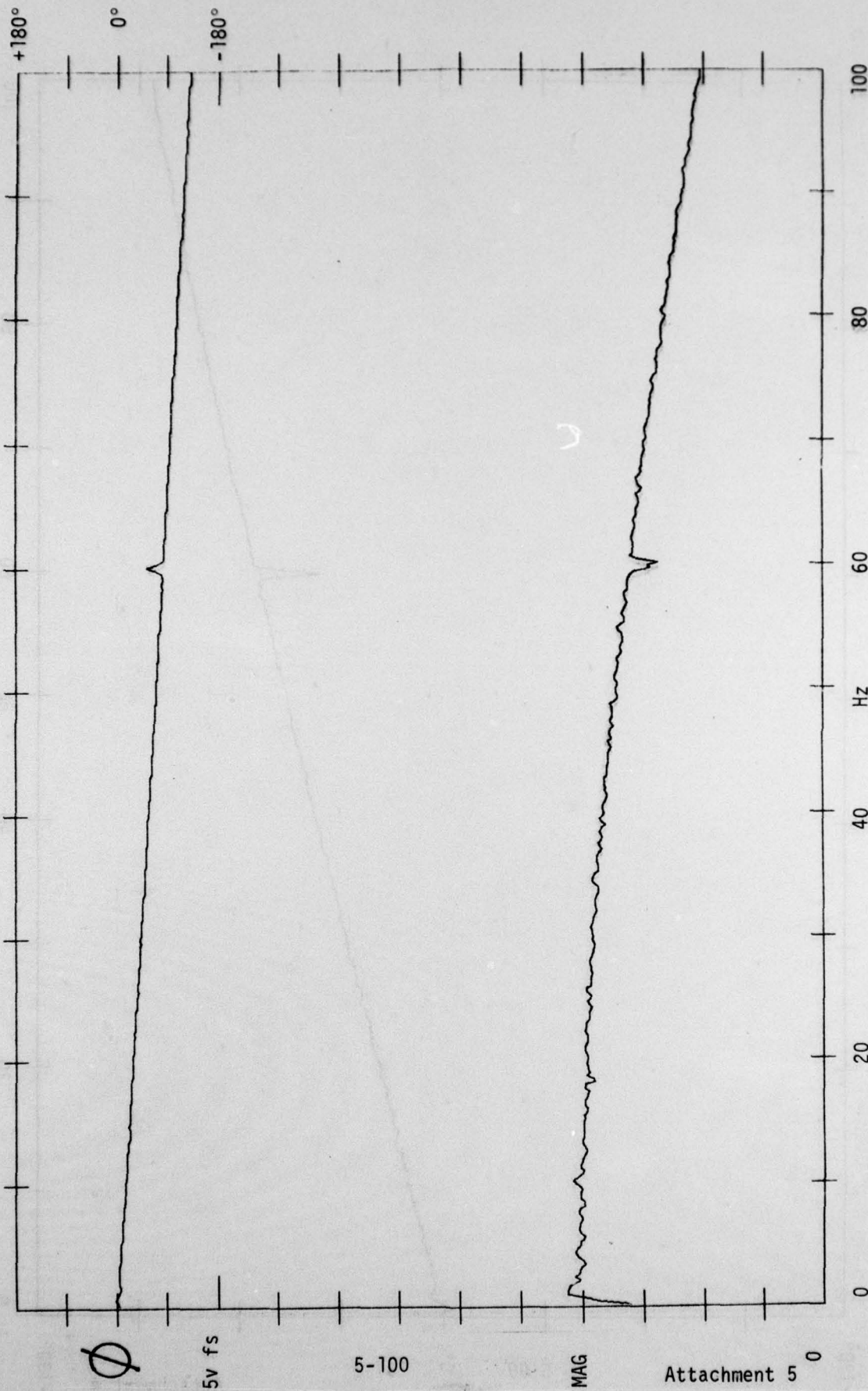
5-99

$\phi$  0°

Attachment 4

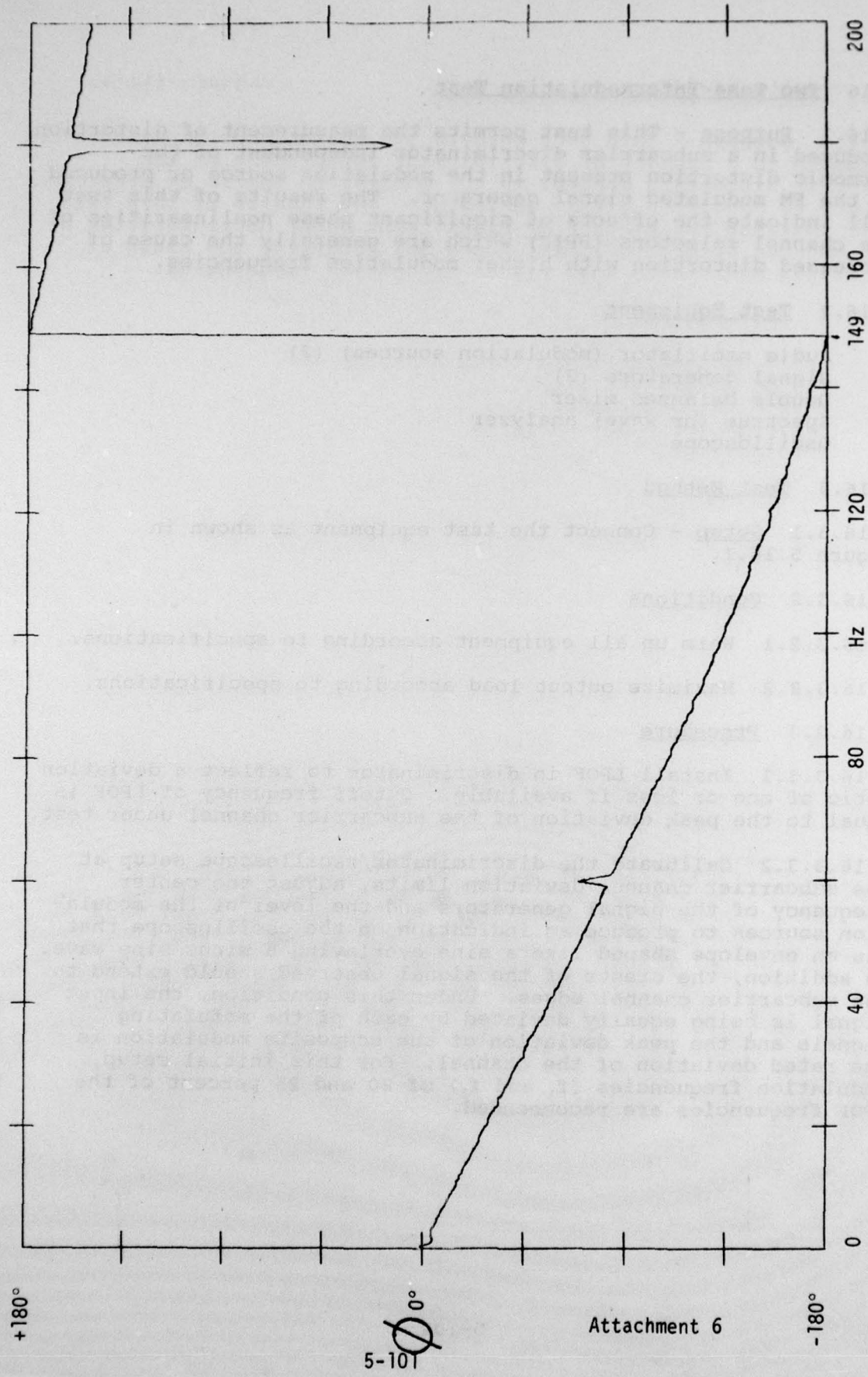
Data Sheet 5.15.2 (Sample Number 4) - Constant Delay Phase Response.

C.F. 5.4 kHz  
L.P.F. 81 Hz C.D.



Data Sheet 5.15.2 (Sample Number 5) - Phase and Amplitude Response.

C.F. 5.4 kHz  
L.P.F. 81 Hz C.D.



Data Sheet 5.15.2 (Sample Number 6) - Phase Response (Wide Frequency Scale).

5-101  $\emptyset 0^\circ$

## 5.16 Two Tone Intermodulation Test

5.16.1 Purpose - This test permits the measurement of distortion produced in a subcarrier discriminator independent of the harmonic distortion present in the modulation source or produced in the FM modulated signal generator. The results of this test will indicate the effects of significant phase nonlinearities of the channel selectors (BPIF) which are generally the cause of increased distortion with higher modulation frequencies.

### 5.16.2 Test Equipment

- Audio oscillator (modulation sources) (2)
- Signal generators (2)
- Double balanced mixer
- Spectrum (or wave) analyzer
- Oscilloscope

### 5.16.3 Test Method

5.16.3.1 Setup - Connect the test equipment as shown in figure 5.16.1.

#### 5.16.3.2 Conditions

5.16.3.2.1 Warm up all equipment according to specifications.

5.16.3.2.2 Maximize output load according to specifications.

#### 5.16.3.3 Procedure

5.16.3.3.1 Install LPOF in discriminator to reflect a deviation ratio of one or less if available. Cutoff frequency of LPOF is equal to the peak deviation of the subcarrier channel under test.

5.16.3.3.2 Calibrate the discriminator/oscilloscope setup at the subcarrier channel deviation limits, adjust the center frequency of the signal generators and the level of the modulation sources to produce an indication on the oscilloscope that has an envelope shaped like a sine overlaying a minus sine wave. In addition, the crests of the signal observed should extend to the subcarrier channel edges. Under this condition, the input signal is being equally deviated by each of the modulating signals and the peak deviation of the composite modulation is the rated deviation of the channel. For this initial setup, modulation frequencies ( $f_1$  and  $f_2$ ) of 20 and 25 percent of the LPOF frequencies are recommended.

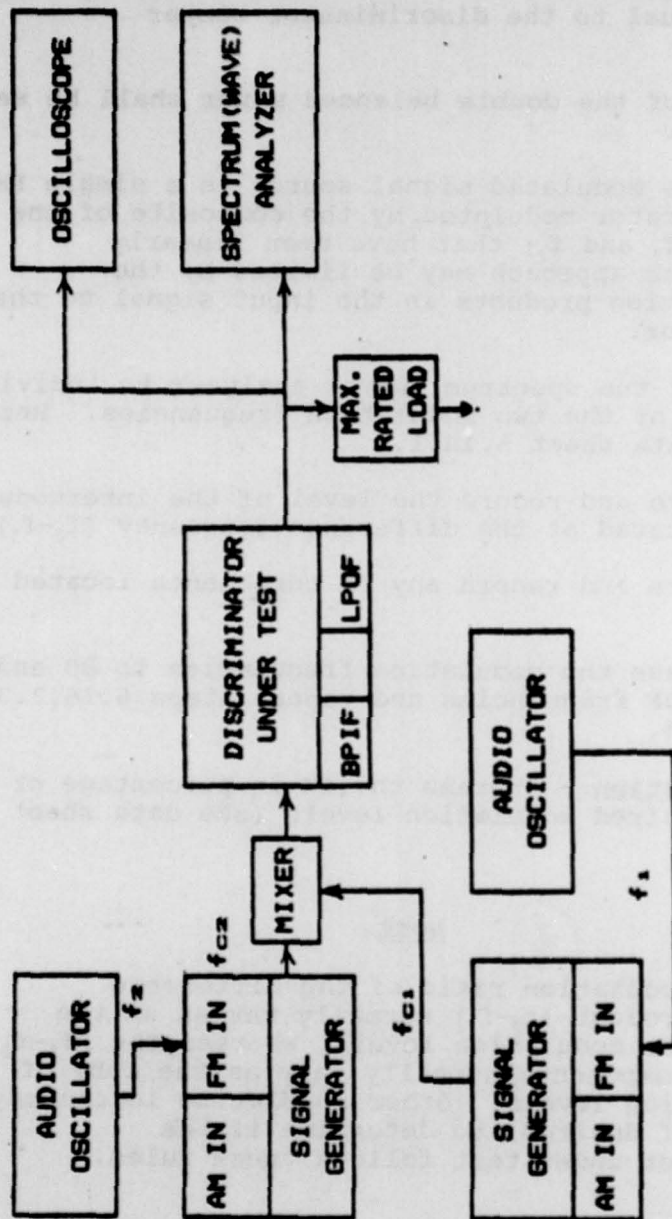


Figure 5.16.1 Test Setup for Two Tone Intermodulation Test.

NOTE

The center frequencies of the signal generators ( $f_{c1}$  and  $f_{c2}$ ) shall be set such that their difference ( $f_{c1} - f_{c2}$ ) is equal to the discriminator center frequency.

The output of the double balanced mixer shall be set to 0.3 Vrms.

An alternate modulated signal source is a single FM signal generator modulated by the composite of the two tones ( $f_1$  and  $f_2$ ) that have been linearly summed. This approach may be limited by the intermodulation products in the input signal to the discriminator.

5.16.3.3.3 Adjust the spectrum (wave) analyzer to individually measure the level of the two modulation frequencies. Record these levels on data sheet 5.16.1.

5.16.3.3.4 Measure and record the level of the intermodulation (IM) component located at the difference frequency ( $f_2 - f_1$ ).

5.16.3.3.5 Measure and record any IM components located at  $2f_1 - f_2$  and  $2f_2 - f_1$ .

5.16.3.3.6 Increase the modulation frequencies to 80 and 90 percent of the LPOF frequencies and repeat steps 5.16.3.3.3 through 5.16.3.3.5.

5.16.4 Data Reduction - Express the IM in percentage or in dB with respect to the desired modulation levels (see data sheet 5.16.1 sample).

NOTE

The IM to modulation ratio of the difference frequency product ( $f_2 - f_1$ ) normally varies as the square of the modulation levels, whereas the  $2f_1 - f_2$  and  $2f_2 - f_1$  components normally vary as the cube of the modulation levels. Other modulation levels may be tried, if desired, to determine if the discriminator under test follows these rules.

**FM DISCRIMINATORS**

DATA SHEET 5.16.1

**TEST Two Tone Intermodulation Test**

MANUFACTURER \_\_\_\_\_ MODEL \_\_\_\_\_  
 SERIAL NO. \_\_\_\_\_ IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY \_\_\_\_\_ kHz UPPER BAND EDGE \_\_\_\_\_ kHz  
 LOWER BAND EDGE \_\_\_\_\_ kHz LOW PASS FILTER CUTOFF \_\_\_\_\_ kHz  
 LOW PASS FILTER TYPE:     CA     CD     Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Low Frequency Test

$f_1 = 20\%$  of LPOF Frequency = \_\_\_\_\_ Amplitude of  $f_1 =$  \_\_\_\_\_ V, dB\*  
 $f_2 = 25\%$  of LPOF Frequency = \_\_\_\_\_ Amplitude of  $f_2 =$  \_\_\_\_\_ V, dB\*  
 Amplitude of  $f_2 - f_1$  Freq. Component = \_\_\_\_\_ V, dB\*  
 Amplitude of  $2f_1 - f_2$  Freq. Component = \_\_\_\_\_ V, dB\*  
 Amplitude of  $2f_2 - f_1$  Freq. Component = \_\_\_\_\_ V, dB\*

High Frequency Test

$f_1 = 80\%$  of LPOF Frequency = \_\_\_\_\_ Amplitude of  $f_1 =$  \_\_\_\_\_ V, dB\*  
 $f_2 = 90\%$  of LPOF Frequency = \_\_\_\_\_ Amplitude of  $f_2 =$  \_\_\_\_\_ V, dB\*  
 Amplitude of  $f_2 - f_1$  Freq. Component = \_\_\_\_\_ V, dB\*  
 Amplitude of  $2f_1 - f_2$  Freq. Component = \_\_\_\_\_ V, dB\*  
 Amplitude of  $2f_2 - f_1$  Freq. Component = \_\_\_\_\_ V, dB\*

\* Strike out unused units (either V or dB).  
 (See attachments 1 and 2.)

FM DISCRIMINATORS

DATA SHEET 5.16.1 (Sample)

TEST Two Tone Intermodulation Test

MANUFACTURER XYZ MODEL DEF  
 SERIAL NO. ABC IRIG CHANNEL \_\_\_\_\_  
 CHANNEL SELECTOR SERIAL NO. \_\_\_\_\_ LOW PASS OUTPUT FILTER S/N \_\_\_\_\_  
 CENTER FREQUENCY 64 kHz UPPER BAND EDGE 68 kHz  
 LOWER BAND EDGE 60 kHz LOW PASS FILTER CUTOFF 4 kHz  
 LOW PASS FILTER TYPE:  CA  CD  Other \_\_\_\_\_  
 TEST PERSONNEL \_\_\_\_\_ DATE \_\_\_\_\_ LOCATION \_\_\_\_\_

Low Frequency Test

$f_1 = 20\%$  of LPOF Frequency = 800 Hz Amplitude of  $f_1 =$  -9.1 XV,dB\*  
 $f_2 = 25\%$  of LPOF Frequency = 1000 Hz Amplitude of  $f_2 =$  -9.1 XV,dB\*  
 Amplitude of  $f_2 - f_1$  Freq. Component = XV,dB\*  
 Amplitude of  $2f_1 - f_2$  Freq. Component = XV,dB\*  
 Amplitude of  $2f_2 - f_1$  Freq. Component = -60.6 XV,dB\*  
 $f_2+f_1$  -60.6 dB

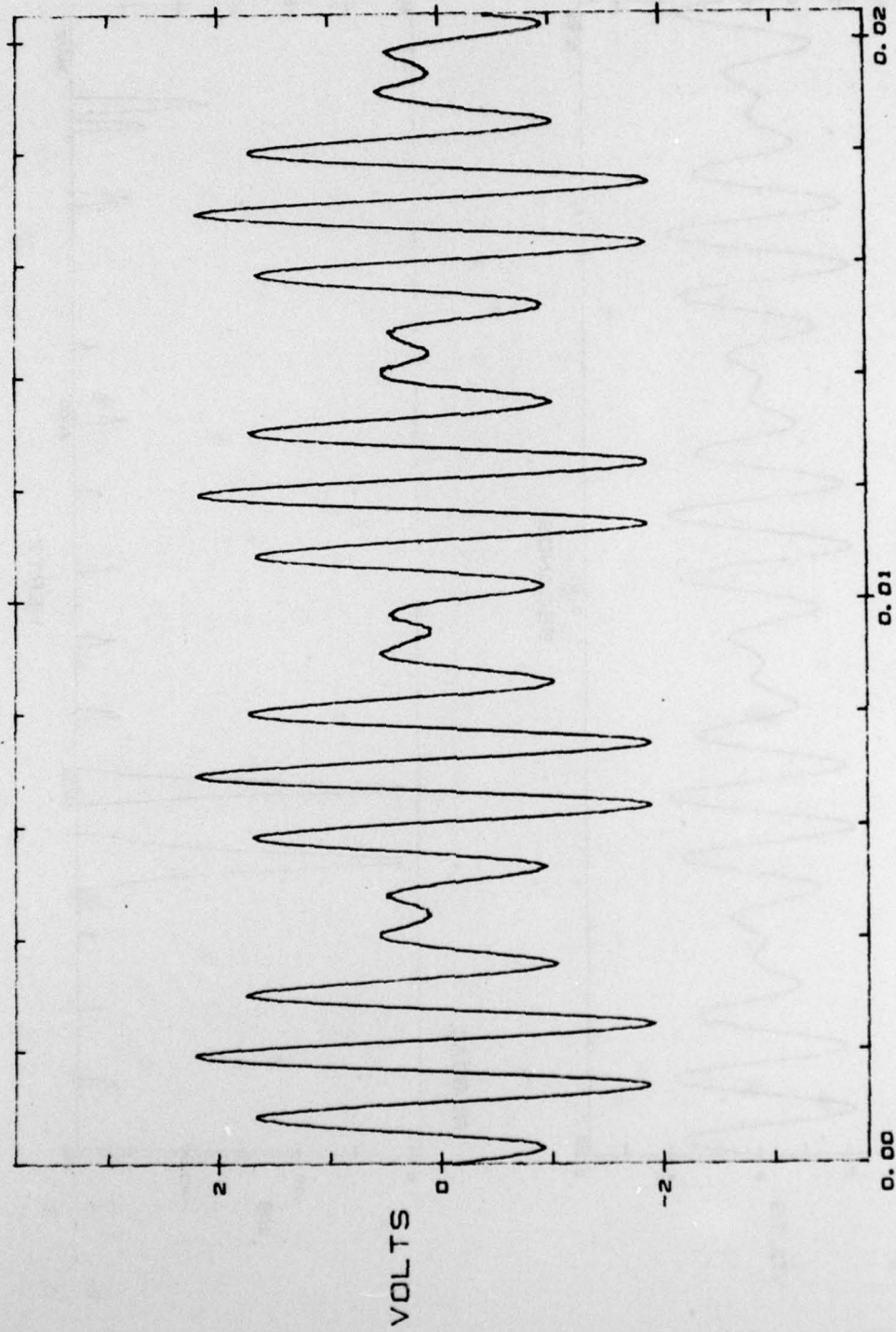
High Frequency Test

$f_1 = 80\%$  of LPOF Frequency = 3200 Hz Amplitude of  $f_1 =$  -9.6 XV,dB\*  
 $f_2 = 90\%$  of LPOF Frequency = 3600 Hz Amplitude of  $f_2 =$  -9.7 XV,dB\*  
 Amplitude of  $f_2 - f_1$  Freq. Component = -62.9 XV,dB\*  
 Amplitude of  $2f_1 - f_2$  Freq. Component = -42.1 XV,dB\*  
 Amplitude of  $2f_2 - f_1$  Freq. Component = -46.1 XV,dB\*  
 $f_2+f_1$  -49.1 dB

\* Strike out unused units (either V or dB).

(See attachments 1 and 2.)

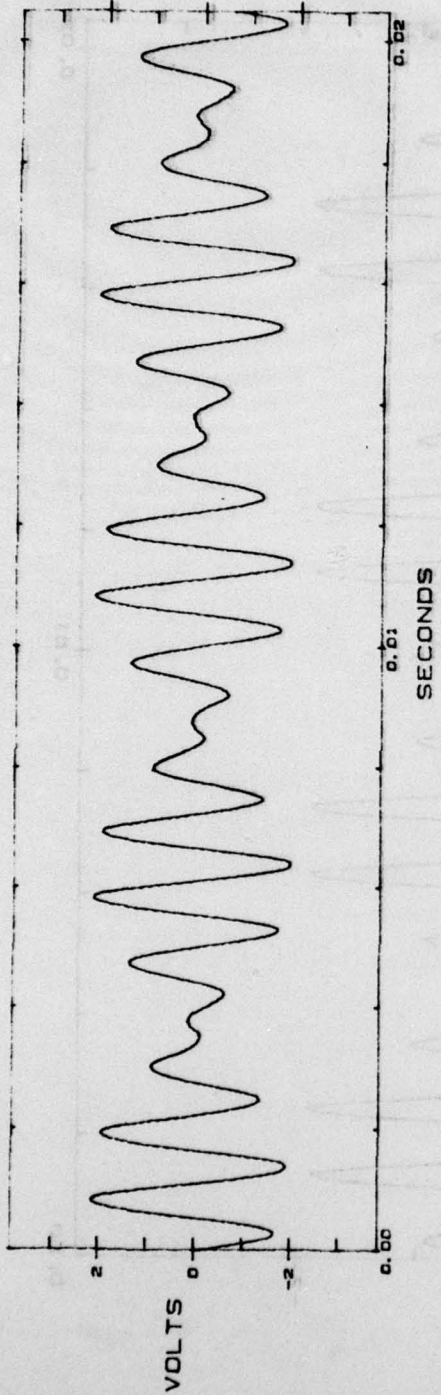
BUF. A1



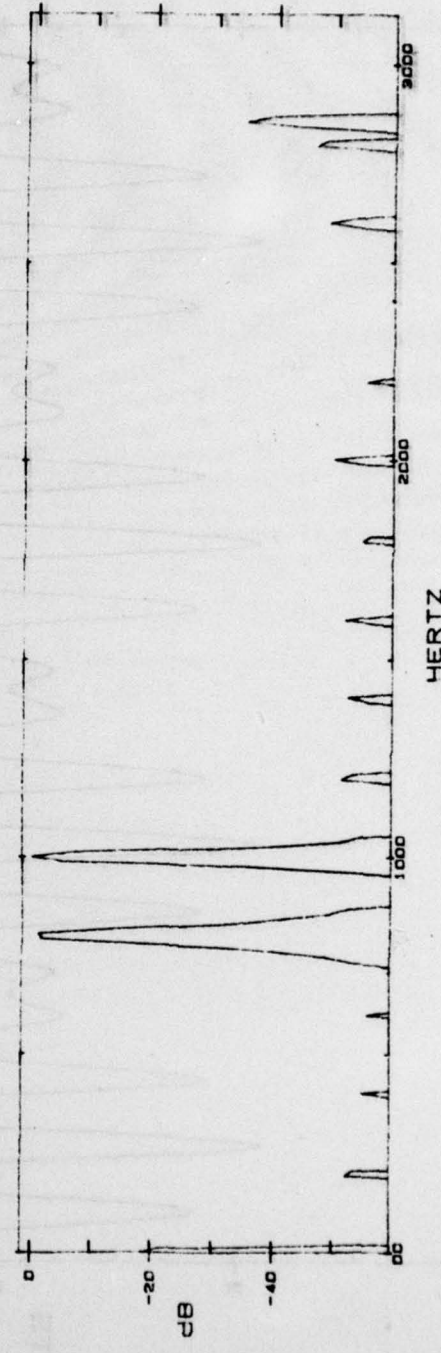
SECONDS

Data Sheet 5.16.1 (Sample) - Discriminator LPF Output Two Tone Test.

BUF. A1



RLOGA 1



Data Sheet 5.16.1 (Sample) - Discriminator LPF Output Two Tone Test.